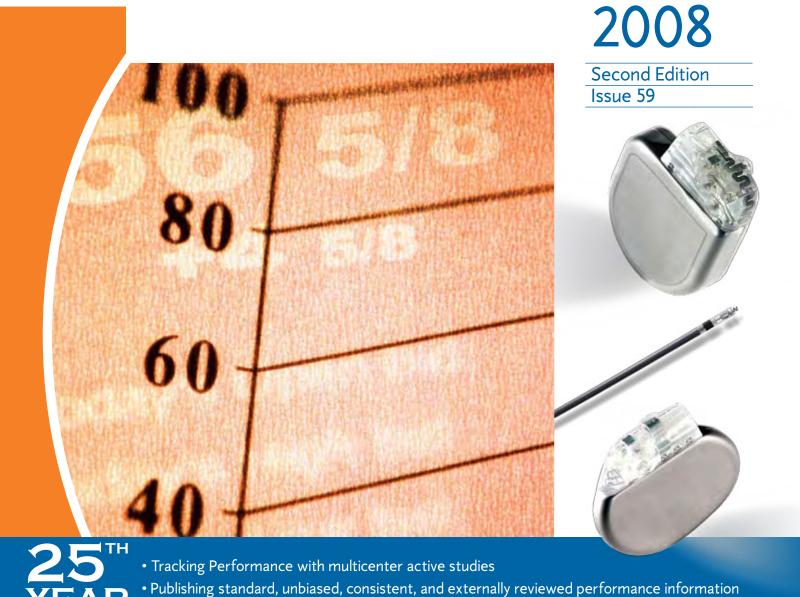


## CARDIAC RHYTHM DISEASE MANAGEMENT

Product Performance Report

Important Patient Management Information for Physicians



## A Message from the Vice President

Dear Customer,

Quality and Regulatory has been the primary focus of my 26-year career at Medtronic. It is a privilege for me to take on the leadership of our CRDM quality efforts, working with hundreds of employees whom I know, respect, and trust. They are passionately dedicated to serving you and your patients. Striving without reserve for the greatest possible quality and reliability is our shared mission and commitment.

To keep you informed, Medtronic now provides two ways to access regularly updated Sprint Fidelis® lead performance data. This Product Performance Report (PPR) contains System Longevity Study (SLS) performance data for the Sprint Fidelis lead and other Medtronic leads and devices. The PPR is produced every six months with both current and past reports available at <a href="https://www.CRDMPPR.medtronic.com">www.CRDMPPR.medtronic.com</a>. Every three months, Sprint Fidelis lead information from both SLS and Medtronic CareLink® data is also posted online at <a href="https://www.medtronic.com/fidelis">www.medtronic.com/fidelis</a>. Sprint Fidelis lead performance continues to be in line with the information provided in October 2007 and May 2008, and, in consultation with our Independent Physician Quality Panel, our patient management recommendations remain unchanged.

September 4, 2008, we announced the US and EU approval of Medtronic's Lead Integrity Alert (LIA) software, which provides patients with certain Medtronic defibrillators and defibrillator leads with more advance notice – via an audible sound – of a potential lead fracture that could result in an unnecessary shock. We believe it will become a standard-of-care tool to aid in shock reduction. Data shows that with LIA, approximately 76 percent of the patients with Sprint Fidelis leads are expected to receive three or more days advance warning of a potential lead fracture which could result in an unnecessary shock, compared to 49 percent who could receive two or more days advance notice without LIA.

Lead Integrity Alert was developed as a software upgrade for nearly all (98 percent) of the Medtronic implantable cardioverter defibrillators (ICDs) and cardiac resynchronization therapy defibrillators (CRT-Ds) implanted in the United States and into 93 percent implanted worldwide. Pending further regulatory approvals, LIA will be included in all future Medtronic implantable defibrillators.

As I move into my new role, I know there will be both new opportunities and challenges. To best serve you and those in your care, please know that your insight, feedback, and collaboration are crucially important. I welcome your calls, email, and input.

Thank you and best regards,

Tim Samsel

Vice President, Quality and Regulatory

Medtronic Cardiac Rhythm Disease Management

Medtronic, Inc.

#### **Contact Information**

We invite our customers to use these telephone numbers to call with suggestions, inquiries, or specific problems related to our products.

#### **US Technical Services Department**

Phone: 1 (800) 723-4636 (Tachy)

1 (800) 505-4636 (Brady)

Fax: 1 (800) 824-2362

www.medtronic.com/corporate/contact.jsp

#### **International Technical Centers**

Europe (Heerlen NL) +31-45-566-8844 Japan (Tokyo) +81-3-5753-4116

#### For questions related to this CRDM Product Performance Report, please call US Technical Services at the number above, or write to:

Timothy Smith Medtronic, Inc. 8200 Coral Sea Street NE MS MVN61 Mounds View, MN 55112 USA

email: tim.smith@medtronic.com

## For questions related to returning explanted product or returning product that shows signs of malfunction, please contact:

Outside the United States:

Your Medtronic representative or international technical center at the number above.

Within the United States:

Your Medtronic representative or

CRDM Returned Product Analysis Laboratory

Medtronic, Inc.

7000 Central Avenue NE MS RCE172 Minneapolis, MN 55432-3576 USA

Phone: 1 (800) 328-2518, ext. 44800

email: crdm.returnedproduct@medtronic.com

#### **Editorial Staff**

#### Independent Physician Quality Panel

Angelo Auricchio, MD, Lugano, Switzerland Hugh Calkins, MD, Baltimore, MD Steven J. Compton, MD, Anchorage, AK John P. DiMarco, MD, PhD, Charlottesville, VA Kevin Hackett, MD, Columbus, OH Mariell Jessup, MD, Philadelphia, PA R. Hardwin Mead, MD, Palo Alto, CA

#### **Editor**

Tim Samsel, Vice President, CRDM Quality and Regulatory

#### **Authors**

Timothy Smith, Senior Principal Product Performance Engineer, CRDM, Product Performance Reporting Corrine Buchanan, Senior Clinical Trial Leader Scott McRae, Statistician, CRDM Tim Hamann, Graphic Designer, CRDM

#### Medtronic Review Board

David Steinhaus, MD, Vice President and Medical Director, CRDM Lonny Stormo, Vice President, CRDM, Therapy Delivery Subu Mangipudi, Director, Product Vigilance and Reliability

#### Trademarks of Medtronic, Inc.

Adapta® AT500® Attain®® CapSure® CapSure Sense® CapSureFix® Capture Management® CareLink® Concerto® EnPulse® EnRhythm® EnTrust® GEM® InSync® InSync ICD® InSync Marquis™  $InSync \ II \ Marquis^{\scriptscriptstyle{\mathsf{TM}}}$ InSync III Marquis™ InSync Maximo® InSync II Protect™

InSync III Protect™ InSync Sentry® Intrinsic® Jewel® Kappa® Legend® Marquis® Maximo® Medtronic CareAlert® Medtronic CareLink® Micro Jewel® Micro Minix® Minix® Minuet®  $MVP^{\otimes}$  $Onyx^{\scriptscriptstyle (\!0\!)}$ Patient Alert™ Preva® Prevail®

Relia™ SelectSecure® Sensia® Sensing Assurance™ Sigma®  $Spectraflex^{\scriptscriptstyle\mathsf{TM}}$ Sprint™ Sprint Fidelis® Sprint Quattro® Sprint Quattro Secure® SureFix® Target Tip® Tenax™ Thera®-i Transvene™ Versa® Virtuoso\*

Prodigy®

Quick Look™

## **CRDM Product Performance Report**

Introduction 4
Method for Estimating CRT, ICD, and IPG Device Performance 9

#### CRT Cardiac Resynchronization Therapy 13

CRT Survival Summary 18 CRT Reference Chart 20

#### ICD Implantable Cardioverter Defibrillators 21

ICD Survival Summary 30 ICD Reference Chart 33 ICD Connector Styles 35

#### **IPG** Implantable Pulse Generators 36

IPG Survival Summary 63 IPG Reference Chart 71

#### Leads

Method for Estimating Lead Performance 74

#### Left-Heart Leads 77

Lead Survival Summary 79 US Returned Product Analysis Summary 79 Reference Chart 79

#### Defibrillation Leads 80

Lead Survival Summary 88 US Returned Product Analysis Summary 89 Reference Chart 90

#### Pacing Leads 91

Lead Survival Summary 123 US Returned Product Analysis Summary 127 Reference Chart 129

#### Epi/Myocardial Pacing Leads 131

Lead Survival Summary 134 US Returned Product Analysis Summary 135 Reference Chart 135

#### VDD Single Pass Pacing Leads 136

Lead Survival Summary 137 US Returned Product Analysis Summary 137 Reference Chart 137

#### ICD and CRT-D Charge Time Performance 138

#### Advisories 144

(in order of communication date, from most recent to oldest)

#### Performance Notes 153

Clinical Management of VCM near Elective Replacement 153
Ensuring the Accuracy of Battery Longevity Estimates 154
Interactions between Cardiac Pacing and Ventricular Arrhythmia Initiation 155
AT500 Pacing System Follow-Up Protocol 156
Insertion of the Lead into the Device 157
GEM II DR/VR and GEM III DR/VR/AT ICD Battery Discharge Behavior 158
General Follow-Up and Replacement of ICD Leads 159
Clinical Management of High Voltage Lead System Oversensing 160
Tests and Observations for Clinical Assessment of Chronic Pacing Leads 161

#### Index 162

## 2008 Second Edition Issue 59

Date cutoff for this edition is July 31, 2008

This report is available online at www.CRDMPPR.medtronic.com

## Introduction

All product performance reports are not created equal. For 25 years, Medtronic has monitored performance via both returned product analysis and multicenter clinical studies.

This Product Performance Report (PPR) presents device survival estimates, advisory summaries, performance notes, and other information pertinent to assessing the performance of Medtronic implantable pulse generators (IPGs), implantable cardioverter defibrillators (ICDs), Cardiac Resynchronization Therapy (CRT) devices, and implantable pacing and defibrillation leads.

This Product Performance Report has been prepared in accordance with International Standard ISO 5841- 2:2000(E).

The survival estimates provided in this report are considered to be representative of worldwide performance.

#### Survival Estimates

Medtronic Cardiac Rhythm Disease Management (CRDM) uses both returned product analysis and multicenter clinical studies to monitor performance.

Medtronic, like other companies, monitors CRT, ICD, and IPG device performance using returned product analysis. We also monitor CRT, ICD, and IPG device performance using an active multicenter clinical study. Medtronic CRDM is unique in the industry in that we track CRT, ICD, and IPG device survival using both methods.

Returned product analysis is a passive approach to assessing product performance. This approach provides a suitable measure of product performance only when a significant number of explanted products are returned to the manufacturer. Returned product analysis provides a measure of hardware performance, but not necessarily the total clinical performance (e.g., the incidence of complications such as infection, erosion, muscle stimulation, etc. are not estimated).

The survival estimates provided in this report for CRT, ICD, and IPG devices are based on returned product analysis. This approach is suitable because a significant number of explanted generators are returned for analysis.

Lead performance is monitored differently. In contrast to CRT, ICD, and IPG devices, a very small percentage of leads are returned to the manufacturer due to the difficulty of explanting them. For leads, an active clinical study provides more accurate survival estimates compared to estimates based solely on returned product analysis.

Survival estimates for leads are based on clinical observations recorded via Medtronic CRDM's System Longevity Study. This multicenter clinical study is

designed to record clinical observations representative of the total clinical experience. Therefore, the lead survival estimates include both lead hardware failure and lead related medical complications, and do not differentiate a lead hardware failure from other clinical events such as exit block, perforation, dislodgement, or concurrent pulse generator failure.

The actuarial life table method is applied to the data collected for CRT, ICD, and IPG devices and leads to provide the survival estimates included in this report. A general introduction to understanding this method of survival analysis is given later in this introduction.

#### **ICD Charge Times**

Since May 2000, Medtronic has provided important information on charge time performance of ICDs. The information provided in this report shows how ICD charge time can vary during the time a device is implanted. The information is presented in graphical format showing charge time as a function of implant time. The data for charge times are collected from devices enrolled in the System Longevity Study.

#### **Advisory Summaries**

This Product Performance Report includes summaries of all advisories applicable to the performance of the products included in the report. An advisory is added to the report when any product affected by the advisory remains in service and at risk of experiencing the behavior described in the advisory. The advisory will remain in the report until Medtronic estimates no product affected by the advisory remains active, or the risk of experiencing the behavior described in the advisory has passed.

For most advisories, the products subject to the advisory retain essentially the same survival probability as the products of the same model(s) not affected by the advisory. For those advisories where the survival probabilities of the affected and non-affected populations do differ significantly Medtronic will provide separate survival data for each population. The separate survival data will remain in the report until Medtronic estimates no affected product remains in active service.

#### Performance Notes

This report concludes with a number of Performance Notes developed by Medtronic to provide additional product performance information relevant to follow-up practice and patient management.

Medtronic urges all physicians to return explanted product and to notify Medtronic when a product is no longer in use, regardless of reason for explant or removal from use.

#### How You Can Help

Medtronic urges all physicians to return explanted product and to notify Medtronic when a product is no longer in use, regardless of the reason for explant or removal from use. The procedures for returning product vary by geographic location.

Mailer kits with prepaid US postage are available for use within the United States to send CRTs, ICDs, IPGs, and leads to Medtronic's CRDM Returned Product Analysis Lab. These mailers are sized to accommodate the devices and leads from a single patient or clinical event and are designed to meet postal regulations for mailing biohazard materials.

If the product being returned is located outside the United States, please contact your local Medtronic representative for instructions.

Medtronic also requests the return of explanted product from non-clinical sources such as funeral homes, and will assume responsibility for storage and disposal of the product once received. For return of larger quantities of explanted products than the mailer can accommodate, Medtronic has handling and shipping guidelines available upon request.

Both mailers and guidelines can be requested by contacting the Returned Product Lab. For information on how to contact the Lab, refer to Contact Information on page 2 of this report.

We continually strive to improve this CRDM Product Performance Report. In keeping with this philosophy, we ask for your suggestions on the content and format of this report, as well as any information you have regarding the performance of Medtronic products. For information on how to comment on this report, see Contact Information on page 2 of this report.

#### Overview of Survival Analysis

Medtronic uses the Cutler-Ederer actuarial life table method to estimate the length of time over which devices and leads will perform within performance limits established by Medtronic. This probability to perform within performance limits over time is called the *survival probability*.

Devices and leads are followed until an *event* occurs where the device or lead ceases to operate within performance limits. The length of time from implant to the event is recorded for each individual device and lead in the *population sample*. The population sample for CRT, ICD, and IPG devices is made up of patients whose devices are registered as implanted in the United States. For leads, the population sample is the patients enrolled in our multicenter, international prospective System Longevity Study.

For IPGs and ICDs, the events can be normal battery depletion or a device malfunction. For leads, the events are complications as defined for the study.

The actuarial life table method allows Medtronic to account for devices and leads removed from service for reasons unrelated to performance. Devices and leads removed for these reasons are said to be *suspended*. Examples include devices and leads:

- still in service at the time the analysis is performed
- removed to upgrade the device or lead
- no longer in service due to the death of the patient for reasons unrelated to the device or leads, or
- implanted in patients who are lost to follow-up.

For each suspension, the device or lead has performed within performance limits for a period of time, after which its performance is unknown.

#### An Example

The following example describes the survival analysis method used to establish the survival probability estimates for Medtronic CRDM devices and leads. The example is intended to provide an overview of the analysis process. The definitions of malfunctions and complications, and other details specific to calculating device and lead survival estimates, are provided in the articles Method for Estimating CRT, ICD, and IPG Device Performance (page 9) and Method for Estimating Lead Performance (page 74).

This simple example describes the survival analysis method used to establish the survival probability estimates for Medtronic CRDM devices and leads.

#### Figure 1

Implant times for devices of 16 patients. Gray bars with an orange X indicate devices removed from service due to an event. Blue bars indicate suspended devices.

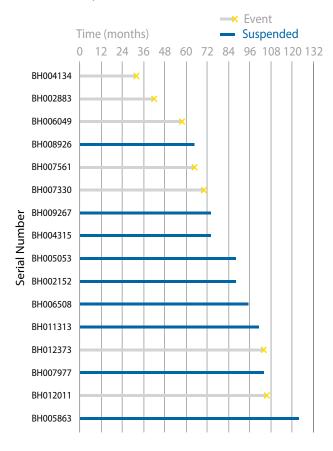


Figure 1 illustrates 16 patients who have implanted devices. The first patient's device (serial number BH004134) operated within performance limits for 32 months. At that time an event occurred. The fourth patient's device (serial number BH008926) did not have an event but is suspended, perhaps because it was still in service at the time of the analysis. This patient had 66 months of implant experience. In this example, Figure 1 shows that 7 of the 16 devices suffered events, and 9 are suspended.

The first step in the life table method is to divide the implant time into intervals of a specific length. This example will use 12-month intervals. The number of devices entered, suspended, and removed due to an event are counted and summarized as shown in Table 1. For the first two intervals, all 16 devices survived and none were removed. In the interval (24-36 months), device BH004134 was removed due to an event. Therefore the table entries show that 16 entered the interval, none were suspended, and one was removed due to an event.

For interval from 36-48 months, only 15 devices entered the interval and one was removed for an event. The remaining intervals are examined and the data entered in columns A, B, and C in like manner. The rest of the columns are filled in using calculations on the data in columns A, B, and C.

The Effective Sample Size (D) is the number of devices with full opportunity to experience a qualifying event in the interval. This is computed by subtracting one half the number suspended in the interval from the number that entered the interval. This calculation more accurately reflects the number of devices that could have experienced a qualifying event than simply using the number that entered the interval. Using the number of devices that enter an interval overestimates the sample size because the suspended devices do not complete the interval. Ignoring the suspended devices under-estimates the sample size because suspended devices are not credited with their full service time. Using one half the number of suspended devices effectively splits the difference.

The next column in the table is the *Proportion with Event* (E). This is the proportion of devices that had an event in the interval. It is calculated by dividing the *Number of Events* (C) by the *Effective Sample Size* (D). The number can be interpreted as the estimated rate at which events occur in the time interval.

The Interval Survival Probability (**F**) is the estimate of probability of surviving to the end of the interval assuming the device was working at the beginning of the interval. It is calculated as 1 minus the Proportion With Event (**E**). This number can be interpreted as the estimated rate at which events **do not** occur in the time interval.

The Cumulative Survival Probabilities from (G) the last column of the life table can be plotted versus time intervals in the first column to give a survival curve. Figure 2 shows the survival curve for the data shown in Table 1.

**Table 1** Life Table for Figure 1

	Α	В	C	D	E	F	G
Interval in Months	Number Entered	Number Suspended	Number of Events	Effective Sample Size	Proportion with Event	Interval Survival Probability	Cumulative Survival Probability
0	16	0	0	16	0.000		1.000
0-12	16	0	0	16	0.000	1.000	1.000
12-24	16	0	0	16	0.000	1.000	1.000
24-36	16	0	1	16	0.063	0.938	0.938
36-48	15	0	1	15	0.067	0.933	0.875
48-60	14	0	1	14	0.071	0.929	0.813
60-72	13	1	2	12.5	0.160	0.840	0.683
72-84	10	2	0	9	0.000	1.000	0.683
84-96	8	3	0	6.5	0.000	1.000	0.683
96-108	5	2	2	4	4 0.500		0.341
108-120	1	0	0	1	0.000	1.000	0.341
120-132	1	1	0	0.5	0.5 0.000		0.341

#### **Definitions:**

A Number Entered	B Number Suspended	C Number of Events	D Effective Sample Size	E Proportion with Event	F Interval Survival Probability	G Cumulative Survival Probability
Number of devices active at the start of the interval	Number of devices removed from service for reasons other than an event	Number of units removed from service due to an event	Number of units with full opportunity to experience a qualifying event in the interval. Computed by subtracting one half the Number Suspended from the Number Entered	Proportion of devices that had an event in the interval. Computed by dividing the Number of Events by the Effective Sample Size	The probability of surviving to the end of the interval, assuming the device was working at the beginning of the interval. Computed as 1 minus the Proportion With Event	The overall probability of surviving to the end of the interval. Computed by multiplying the Interval Survival Probability by the previous interval's Cumulative Survival Probability

Cumulative Survival Probability (G) is the estimate of the unconditional probability of surviving to the end of the interval. It is computed by multiplying the Interval Survival Probability (F) by the previous interval's Cumulative Survival Probability. The probability of surviving to 132 months in the example is estimated for the table to be 0.341, or 34.1%.

The *Cumulative Survival Probabilities* (G) of the life table can be plotted versus time intervals in the first column to give a survival curve. Figure 2 shows the survival curve for the data in Table 1.

Cumulative Survival Probability (%)

100 90 80 70 60 50 30 12 24 48 108 120 36 60 72 84 96 Time (months) 36 48 60 72 96 108 120  $\cap$ 12 84 132 100 93.8 87.5 81.3 68.3 68.3 68.3 34.1 34.1 100 100 34.1 16 16 16 16 15 12.5 0.5 **Effective Sample Size** 

Figure 2 Survival Curve for Data Given in Table 1

#### **Confidence Intervals**

Since survival curves are based on a sample of the device and lead population, they are only estimates of survival. The larger the effective sample size, the more confident the estimate. A confidence interval can be calculated to assess the confidence in an estimate. In the Product Performance Report, Medtronic provides a 95% confidence interval. This can be interpreted as meaning that 95% of the time, the true survival of the device will fall somewhere in the interval.

## Survival Curves in the Product Performance Report

Since the survival estimate can become very imprecise with small effective sample sizes, Medtronic truncates the survival curve when the effective sample size is less than 100 for CRTs, ICDs, and IPGs, and when the number entered is less than 50 for leads. The survival charts in the Product Performance Report show the effective sample size for each year interval where Medtronic has experience. When the effective sample size reaches 100 for CRTs, ICDs, and IPGs or when the number entered reaches 50 for leads, the next data point is added to the survival curve.

Although the report provides tabular data in one-year intervals, the curves are actually computed and plotted using one-month intervals (for CRT, ICD, and IPG devices) or three-month intervals (for leads).

A number of references are available for additional information on survival analysis using the Cutler-Ederer life table method.<sup>1</sup>

<sup>&</sup>lt;sup>1</sup> Lee, Elisa T.(2003) Statistical Methods for Survival Data Analysis – 3rd Edition (Wiley Series in Probability and Statistics)

## Method for Estimating CRT, ICD, and IPG Device Performance

Medtronic urges all physicians to return explanted product and to notify Medtronic when a product is no longer in use, regardless of reason for explant or removal from use.

The performance of CRT, ICD, and IPG devices is expressed in terms of device survival estimates, where "survival" refers to the function of the device, not the survival of the patient. These survival estimates are intended to illustrate the probability that a device will survive for a given number of years with neither malfunction nor battery depletion.

The survival estimates are determined from the analysis of Medtronic CRDM's United States device registration data and United States returned product analysis data. These data are presented graphically and numerically.

Because this analysis is based on returned product analysis, the performance data does not reflect any device-related medical complications, such as erosion, infection, muscle stimulation, or muscle inhibition.

#### Categorization of Depleted and Malfunctioning Devices for Survival Analysis

For survival estimation, every device returned to Medtronic CRDM and analyzed in the CRDM Returned Product Analysis laboratory is assigned to one of three categories. The device 1) has functioned normally, 2) has reached normal battery depletion, or 3) has malfunctioned. This categorization is combined with data from our device registry for the total number of implants and the implant durations to create the survival curves presented on the following pages.

#### **Definition of Malfunction**

Medtronic CRDM considers a device as having malfunctioned whenever the analysis shows that any parameter was outside the performance limits established by Medtronic while implanted and in service. To be considered a malfunction or battery depletion, the device must have been returned to Medtronic and analyzed.

Devices damaged after explant, damaged due to failure to heed warnings or contraindications in the labeling, or damaged due to interaction with other implanted devices (including leads) are not considered device malfunctions.

A device subject to a safety advisory is not considered to have malfunctioned unless it has been returned to Medtronic CRDM and found, through analysis, to actually have performed outside the performance limits established by Medtronic.

Not all malfunctions expose the patient to a loss of pacing or defibrillation therapy. Some malfunctions included in the following survival estimates may not have been detected at all by the physician or the patient. These malfunctions, however, are included in the survival estimates and provide important feedback to our product development organization.

To provide insight into the nature of malfunctions, each malfunction is categorized as Malfunction with Compromised Therapy Function or Malfunction without Compromised Therapy Function. A summary of these malfunctions is presented for the most recently market-released models.

For this report, Normal Battery Depletion, Malfunction with Compromised Therapy Function and Malfunction without Compromised Therapy Function are defined as follows:

#### Normal Battery Depletion - The condition when

- (a) A device is returned with no associated complaint and the device has reached its elective replacement indicator(s) with implant time that meets or exceeds the nominal (50 percentile) predicted longevity at default (labeled) settings, or
- (b) A device is returned and the device has reached its elective replacement indicator(s) with implant time exceeding 80% of the expected longevity calculated using the available device setting information.

Medtronic CRDM establishes expected longevity by statistically characterizing the power consumed by the device and the power available from the device battery. This characterization is applied to a number of parameter configurations to derive a statistical mean longevity value and standard deviation for each parameter configuration. The statistical mean value minus three standard deviations is used as the expected longevity for determining if a battery depleted normally.

## Method for Estimating CRT, ICD, and IPG Device Performance, continued

The Standard Actuarial Method is used to estimate IPG and ICD survival. This product performance report has been prepared in accordance with International Standard ISO 5841-2:2000(E).

For reference purposes, the following pages include estimated longevities for each model. The actual longevity achieved for any device while implanted will depend on the actual programmed parameters and patient factors, and may differ significantly from these estimates.

#### Malfunction with Compromised Therapy Function

The condition when a device is found to have malfunctioned in a manner that compromised pacing or defibrillation therapy (including complete loss or partial degradation), while implanted and in service, as confirmed by returned product analysis.

Examples: Sudden loss of battery voltage; accelerated current drain such that low battery was not detected before loss of therapy; sudden malfunction during defibrillation therapy resulting in aborted delivery of therapy, intermittent malfunction where therapy is compromised while in the malfunction state.

#### Malfunction without Compromised Therapy Function

The condition when a device is found to have malfunctioned in a manner that *did not* compromise pacing or defibrillation therapy, while implanted and in service, as confirmed by returned product analysis.

Examples: Error affecting diagnostic functions, telemetry function, data storage; malfunction of a component that causes battery to lose power quickly enough to cause premature battery depletion, but slowly enough that the condition is detected through normal follow-up before therapy is lost; mechanical problems with connector header that do not affect therapy.

#### **Expanded Malfunction Detail**

The malfunctions are further divided into categories that identify the subject area of the malfunction. The malfunctions are divided into the following subject areas:

Electrical Component – findings linked to electrical components such as integrated circuits, resistors, capacitors, diodes, etc.

Electrical Interconnect – findings linked to the connections between electrical components such as wires, solder joints, wire bonds, etc.

Battery - findings linked to the battery and its components

Software/Firmware - findings linked to software or firmware function

Possible Early Battery Depletion - findings where the actual reported implant time is less than 80% of the expected longevity calculated using the available device setting information with no device malfunction observed. There may not be sufficient device setting information to determine conclusively if battery depletion was normal or premature in the absence of a specific root cause finding. However, returned devices meeting the above criteria are conservatively classified as Possible Early Battery Depletion malfunctions.

Other – findings related to other components such as insulators, grommets, setscrews, and packaging, and findings where analysis is inconclusive.

#### **Returned Product Analysis Process**

Analysis of returned product is performed according to written procedures. These procedures determine the minimum analysis required. The analysis required varies depending on the type of device, age of the device, the associated information received with the device, actual experience with models of similar design, and other factors. Additional analysis is performed as necessary to investigate a performance concern from a customer, or to collect specific reliability data.

When a device is returned with a performance concern from a customer, the general analysis process includes a preliminary analysis of the device in its as-received condition, followed by an automated functional test using test equipment equivalent to the equipment used in manufacturing.

When a malfunction is identified, failure analysis is performed to provide the detailed information necessary to investigate possible causes and actions. Medtronic CRDM maintains in-house expertise and performs its failure analysis using facilities it owns and supports. This capability permits detailed failure analysis.

## Method for Estimating CRT, ICD, and IPG Device Performance, continued

Medtronic CRDM adjusts all-cause survival estimates to account for underreporting. While this lowers our all-cause survival estimates, we feel it gives a more accurate perspective on real performance.

#### Statistical Methods for Survival Analysis

Of the several different statistical methods available for survival analysis, the Standard Actuarial Method, with suspensions assumed distributed across the intervals (Cutler-Ederer Method), is used to determine estimates of IPG and ICD survival. This method is commonly used by medical researchers and clinicians.

Implant times are calculated from the implant date to the earlier of the explant date or the cutoff date of the report. From this data an estimate of the probability of device survival is calculated at each monthly interval.

On the following pages, each graph includes a survival curve where events include malfunctions and normal battery depletions. This survival curve is a good representation of the probability a device will survive a period of time without malfunction and without battery depletion. For example, if a device survival probability is 95% after 5 years of service, then the device has a 5% chance of being removed due to battery depletion or malfunction in the first five years following implant.

In addition, a second curve is included to show survival excluding normal battery depletion. This curve is a good representation of the probability for a device to survive without malfunction. This curve includes only malfunctions as events and excludes normal battery depletion.

Since the survival estimate can become very imprecise with small effective sample sizes, Medtronic truncates the survival curve when the effective sample size is less than 100 for CRT, ICD, and IPG devices. The survival charts in the Product Performance Report show the effective sample size for each year interval where we have experience. When the effective sample size reaches 100, the next data point is added to the survival curve.

Although the report provides tabular data in one-year intervals, the curves are actually computed and plotted using one-month intervals.

The data in the tables are rounded to the nearest tenth of one percent. Occasionally, a graph may show 100% survival, but have 1 or more malfunctions or battery depletions. This occurs because even with the malfunctions or battery depletions, the data rounds to 100%.

The survival curves are statistical estimates. As performance experience accumulates, the estimation improves. Confidence intervals are provided as a way

to indicate the degree of certainty of the estimates. Greenwood's formula is used to calculate corresponding 95% confidence intervals for the standard errors and the complementary log-log method is used to produce the confidence bounds.

## Sample Size and How the Population and Population Samples Are Defined

The population sample from which the survival estimates are derived is comprised of the devices registered as implanted in the United States as of the report cutoff date. The number of registered implants, as well as an estimate of the number that remain in active service, is listed for each model. To be included in the population, the device must have been registered with Medtronic's registration system and implanted for at least one day.

This sample based on US implants is considered to be representative of the worldwide population, and therefore the survival estimates shown in this report should be representative of the performance worldwide of these models.

A CRT, ICD, or IPG model or model family will be included in this report when it has accumulated at least 10,000 implant months, and will remain in the report as long as at least 500 devices remain active.

## Methods Used to Adjust for Underreporting of Malfunction and Battery Depletion

The tables on the following pages show the actual number of malfunctions and battery depletions recorded by the analysis lab for US registered devices. Since not all devices are returned to Medtronic CRDM for analysis, these numbers underestimate the true number of malfunctions and battery depletions. To more accurately estimate the all-cause device survival probabilities, the number of malfunctions and battery depletions used to plot each interval of the all-cause survival curves is adjusted (multiplied) by a factor that is based on an estimate of the magnitude of underreporting. The magnitude of underreporting is estimated by analyzing experience in clinical studies (including the System Longevity Study) and the device registration system.

## Method for Estimating CRT, ICD, and IPG Device Performance, continued

However, at this time, no adjustment for underreporting is applied to the malfunction-free survival curve because a method for estimating malfunction-only underreporting has not been developed.

#### Adjustments to Registered Implants to Compensate for Unreported Devices Removed from Service

Devices are at times removed from service for reasons other than device malfunction or battery depletion. Examples are devices removed from service due to non-device related patient mortality and devices removed due to changes in the patient's medical condition. Because an accurate estimate of device survival depends on an accurate estimate of the number of devices in service, it is important not to overstate the number of devices in service.

To ensure the number of devices in service is not overstated, the patient mortality rate derived from our device registration system is monitored and compared to published mortality rates for comparable patient populations. If, during calculation of the survival curves, the patient mortality indicated by the data in our device registration is significantly different from published rates, an adjustment is applied to correct the difference.

#### 7272 InSync ICD

US Market Release	Jul-02
Registered US Implants	13,000
Estimated Active US Implants	2,000
Normal Battery Depletions (US)	629
Advisories	None

#### **Product Characteristics**

205

191

2

25

5

159

14

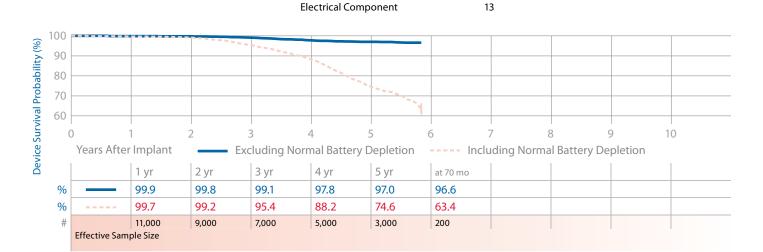
1

74

63 1

11

NBD Code	VVED
Serial Number Prefix	PJP
Max Delivered Energy	34 J
<b>Estimated Longevity</b>	See page 20



Malfunctions (US)

Battery

Battery

**Therapy Function Not Compromised** 

Possible Early Battery Depletion

**Therapy Function Compromised** 

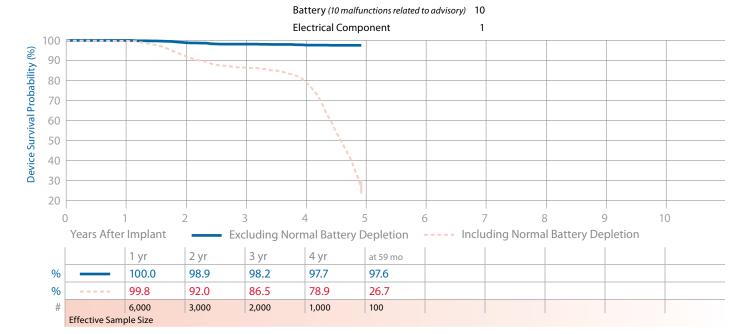
**Electrical Component** 

Software/Firmware

#### 7277 InSync Marquis

US Market Release	Mar-03	Malfunctions (US)
Registered US Implants	7,000	Therapy Function Not Compromised
Estimated Active US Implants	200	Battery
Normal Battery Depletions (US)	483	Electrical Component
Advisories: See page 146 – 2005 Potential		Software/Firmware
Premature Battery Depletion Due to Battery Short		Possible Early Battery Depletion
bactery short		Therapy Function Compromised

NBD Code	VVED
Serial Number Prefix	PLT
Max Delivered Energy	30 J
<b>Estimated Longevity</b>	See page 20



#### 7289 InSync II Marquis

US Market Release	Jul-03
Registered US Implants	28,000
<b>Estimated Active US Implants</b>	5,000
Normal Battery Depletions (US)	2,298

Advisories: See page 146 – 2005 Potential Premature Battery Depletion Due to Battery Short

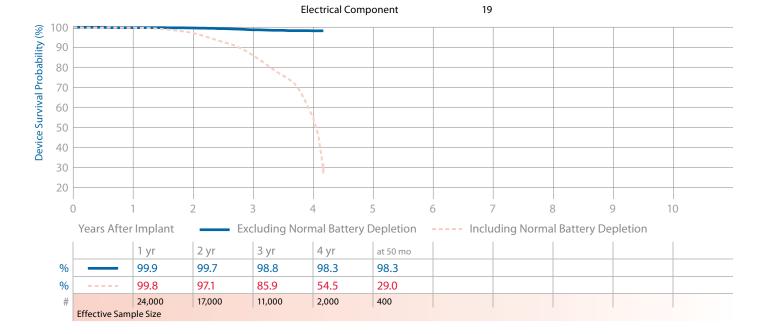
# Malfunctions (US)235Therapy Function Not Compromised206Electrical Component14Software/Firmware1Possible Early Battery Depletion191Therapy Function Compromised29

Battery (8 malfunctions related to advisory)

10

#### **Product Characteristics**

VVED
PRJ
30 J
See page 20

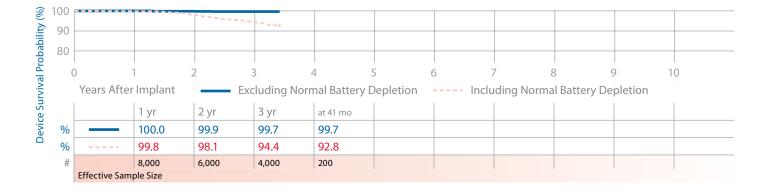


#### 7297 InSync Sentry

US Market Release	Nov-04
Registered US Implants	9,000
Estimated Active US Implants	5,000
Normal Battery Depletions (US)	167
Advisories	None

Malfunctions (US)	17
Therapy Function Not Compromised	16
Battery	1
Electrical Component	5
Possible Early Battery Depletion	10
Therapy Function Compromised	1
Electrical Component	1

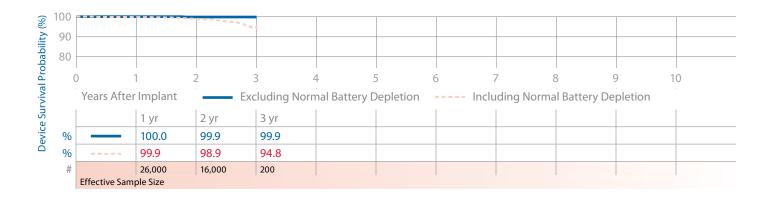
NBD Code	VVED
Serial Number Prefix	PRK
Max Delivered Energy	35 J
Estimated Longevity	See page 20





#### 7299 InSync Sentry

US Market Release	Apr-05	Malfunctions (US)	17	NBD Code	VVED
Registered US Implants	31,000	Therapy Function Not Compromised	13	Serial Number Prefix	PRK
<b>Estimated Active US Implants</b>	21,000	<b>Electrical Component</b>	4	Max Delivered Energy	35 J
Normal Battery Depletions (US)	185	Software/Firmware	2	<b>Estimated Longevity</b>	See page 20
Advisories	None	Possible Early Battery Depletion	7		
		Therapy Function Compromised	4		
		Electrical Component	4		



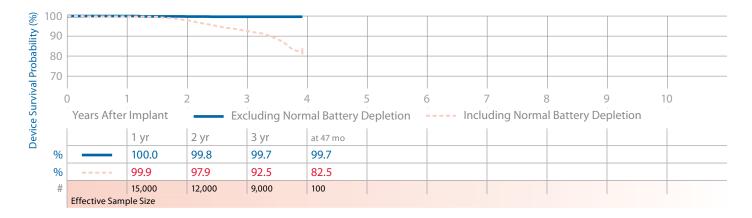
#### 7303 InSync Maximo

US Market Release	Jun-04
Registered US Implants	17,000
Estimated Active US Implants	8,000
Normal Battery Depletions (US)	548
Advisories	None

Malfunctions (US)	40
Therapy Function Not Compromised	35
Electrical Component	5
Software/Firmware	2
Possible Early Battery Depletion	28
Therapy Function Compromised	5
Electrical Component	5

#### **Product Characteristics**

NBD Code	VVED
Serial Number Prefix	PRL
Max Delivered Energy	35 J
<b>Estimated Longevity</b>	See page 20

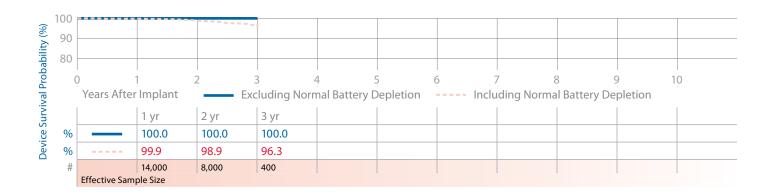


#### 7304 InSync Maximo

US Market Release	Apr-05
Registered US Implants	18,000
<b>Estimated Active US Implants</b>	12,000
Normal Battery Depletions (US)	97
Advisories	None

#### **Product Characteristics**

Malfunctions (US)	6	NBD Code	VVED
Therapy Function Not Compromised	5	Serial Number Prefix	PRL
Battery	1	Max Delivered Energy	35 J
Electrical Component	4	Estimated Longevity	See page 20
Therapy Function Compromised	1		



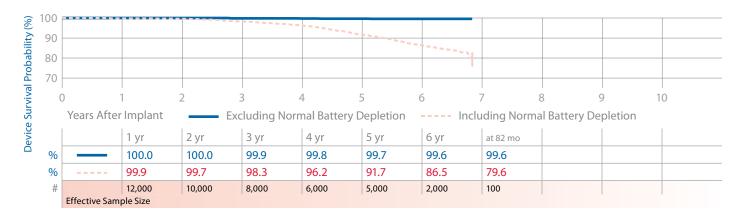
**Electrical Component** 

#### 8040 InSync

US Market Release	Aug-01
Registered US Implants	15,000
Estimated Active US Implants	4,000
Normal Battery Depletions (US)	381
Advisories	None

Malfunctions (US)	28
Therapy Function Not Compromised	7
Electrical Component	4
Possible Early Battery Depletion	3
Therapy Function Compromised	21
Electrical Interconnect	21

NBD Code	DDDR
Serial Number Prefix	PIN
Estimated Longevity	See page 20



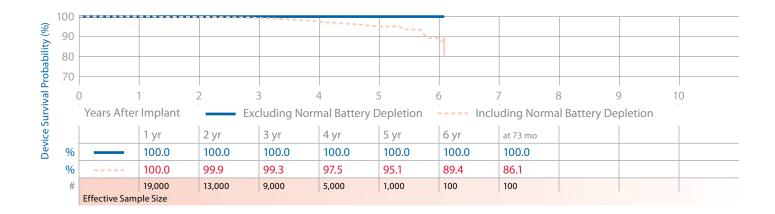
**DDDR** PKF See page 20



#### 8042 InSync III

•				
US Market Release	Feb-03	Malfunctions (US)	5	NBD Code
Registered US Implants	27,000	Therapy Function Not Compromised	3	Serial Number Prefix
Estimated Active US Implants	15,000	Electrical Component	2	Estimated Longevity
Normal Battery Depletions (US)	147	Possible Early Battery Depletion	1	
Advisories	None	Therapy Function Compromised	2	

**Electrical Interconnect** 



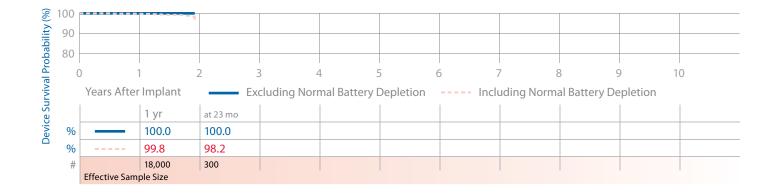
#### C154DWK, C164AWK, C174AWK Concerto

#### **Product Characteristics**

**Product Characteristics** 

2

US Market Release	May-06	Malfunctions (US)	15	NBD Code	VVED
Registered US Implants	52,000	Therapy Function Not Compromised	7	Serial Number Prefix	PVU, PVT, PVR
<b>Estimated Active US Implants</b>	46,000	<b>Electrical Component</b>	2	Max Delivered Energy	35 J
Normal Battery Depletions (US)	38	Possible Early Battery Depletion	5	<b>Estimated Longevity</b>	See page 20
Advisories	None	Therapy Function Compromised	8		
		<b>Electrical Component</b>	7		
		Electrical Interconnect	1		



Device Survival Summary (95% Confidence Interval)

The following table shows CRT device survival estimates with 95% confidence intervals. Estimates are shown both with and without normal battery depletions included.

Name					ŀ	Malfund	alfunctions (US)	S)		Device S	Device Survival Probability (%)	obability	(%)					
1   1   1   1   1   1   1   1   2   2			jistered Implants	SU 9vi		npromised	rapy iction Not npromised	la		Years Aft	er Implan	±.						
CD   Jul-02   13,000   2,000   629   14 + 191   2.05   Recruding   100.0-13   40,04.01	Family		N2 I Beg	tэА		Cor	Fun Cor	toT								7 yr	8 yr	10 yr
Mar-03   7000   200   483   11 + 63   74   Normalisation   10,001   85,002   92,2   92,4   88,2   14,12,12   12,12,12	InSync ICD	Jul-02	13,000	2,000	629				Excluding Normal Battery Depletion				97.8 +0.3/-0.4	-0.5	96.6 +0.5/-0.5 at 70 mo			
Mar-03 7,000 200 483								_	Including Normal Battery Depletion			-0.5			634 +2.7/-2.8 at 70 mo			
Jul-03	InSync Marquis	Mar-03	2,000	200	483				Excluding Normal Battery Depletion					97.6 +0.5/-0.7 at 59 mo				
Jul-03	Advisories: §	see page 14 attery Depl	6 – 2005 P etion Due	otential to Battery S		(10) + (advisory-	(0) = related sub		Including Normal Battery Depletion					26.7 +3.6/-3.5 at 59 mo				
Normal Battery   Depletion   Lincucking   99.8   97.1   85.9   54.5   113.1.3   Lincucking   99.8   97.1   40.2-0.2   40.5-0.6   113.1.3   Lincucking   99.8   97.1   40.2-0.2   40.5-0.6   113.1.3   113.1.3   Lincucking   99.8   113.1.3   113.1.3   Lincucking   99.8   113.1.3   113.1.3   Lincucking   100.0   99.9   99.7   99.7   99.7   99.7   99.7   99.7   99.7   99.7   99.7   99.7   99.7   99.7   99.7   99.7   99.7   99.7   99.7   99.7   99.7   99.8   99.7   99.7   99.8   99.7   99.7   99.8   99.7   99.8   99.7	InSync II Marquis	Jul-03	28,000	2,000	2,298				Excluding Normal Battery Depletion	99.9	-0.1			98.3 +0.2/-0.3 at 50 mo				
Apr-05         31,000         5,000         167         1         + 16         =         17         Normal Battery Depletion         400,011         +01,012         +01,012         +01,012         +01,012         +01,012         +01,012         +01,012         +01,012         +01,012         +01,012         +01,012         +01,012         +01,012         +01,012         +01,012         +01,012         +01,012         +01,012         +01,012         +01,011         +01,012 </td <td>Advisories: § Premature B</td> <td>see page 14 attery Deplo</td> <td><u>6</u> – 2005 P etion Due</td> <td>otential to Battery s</td> <td></td> <td>(8) + (advisory-</td> <td>(0) = related sub</td> <td></td> <th>Including Normal Battery Depletion</th> <td>99.8 +0.1/-0.1</td> <td>/-0.2</td> <td></td> <td></td> <td>29.0 +2.5/-2.4 at 50 mo</td> <td></td> <td></td> <td></td> <td></td>	Advisories: § Premature B	see page 14 attery Deplo	<u>6</u> – 2005 P etion Due	otential to Battery s		(8) + (advisory-	(0) = related sub		Including Normal Battery Depletion	99.8 +0.1/-0.1	/-0.2			29.0 +2.5/-2.4 at 50 mo				
Apr-05 31,000 21,000 185 4 + 13 = 17 Reducting 99.8 98.1 +0.1/-0.1 Poly-0.0	InSync Sentry	Nov-04	000'6	2,000	167				Excluding Normal Battery Depletion			99.7 +0.1/-0.2	99.7 +0.1/-0.2 at 41 mo					
Apr-05 31,000 21,000 185 4 + 13 = 17 Normal Battery								_	Including Normal Battery Depletion				92.8 +0.8/-0.9 at 41 mo					
Jun-04   17,000   8,000   548   5 + 35   5   40   Normal Battery   +0.0/-0.1   +0.1/-0.2   +0.8/-0.9	InSync Sentry	Apr-05	31,000	21,000	185				Excluding Normal Battery Depletion			99.9 +0.1/-0.2						
Jun-04         17,000         8,000         548         5         +         35         =         40         Excluding Depletion         100.0         99.8         99.7           Apr-05         18,000         12,000         97         1         +         5         =         6         Excluding Pattery Po.00.1         +0.00.1         +0.1/-0.1         +0.1/-0.1           Apr-05         18,000         12,000         97         1         +         5         =         6         Excluding Pattery Po.00.1         +0.2/-0.3         +0.5/-0.3         +0.5/-0.3           Apr-05         18,000         12,000         97         1         +         5         =         6         Excluding Pattery Po.00.1         +0.0/-0.1         +0.0/								_	Including Normal Battery Depletion	99.9	-0.2	94.8 +0.8/-0.9						
Apr-05 18,000 12,000 97 1 + 5 = 6 Excluding P9.9 9.9 97.9 97.5 +0.5/-0.5 Popletion Period Popletion Poplet	InSync Maximo	Jun-04	17,000	8,000	548				Excluding Normal Battery Depletion				99.7 +0.1/-0.1 at 47 mo					
Apr-05 18,000 12,000 97 1 + 5 = 6 Excluding 100.0 100.								-	Including Normal Battery Depletion				82.5 +1.5/-1.6 at 47 mo					
99.9 98.9 +0.0/-0.1 +0.2/-0.2	InSync Maximo	Apr-05	18,000	12,000	26				Excluding Normal Battery Depletion	100.0		100.0 +0.0/-0.1						
								_	Including Normal Battery Depletion			96.3 +0.8/-1.0						

		٦,						
		10 yr						
		8 yr						
		7 yr	99.6 +0.1/-0.2 at 82 mo	79.6 +3.3/-3.8 at 82 mo	100.0 +0.0/-0.1 at 73 mo	86.1 +4.2/-5.7 at 73 mo		
		6 yr	99.6 +0.1/-0.2	86.5 +0.9/-1.0	100.0	89.4 +3.2/-4.6		
		5 yr	99.7 +0.1/-0.2	91.7	100.0	95.1 +0.7/-0.8		
(%) A		4 yr	99.8 +0.1/-0.1	96.2 +0.4/-0.4	100.0	97.5 +0.3/-0.4		
Device Survival Probability (%)	nt	3 yr	99.9 +0.0/-0.1	98.3 +0.2/-0.3	100.0	99.3 +0.1/-0.2		
urvival P	Years After Implant	2 yr	100.0	99.7 +0.1/-0.1	100.0	99.9	100.0 +0.0/-0.0 at 23 mo	98.2 +0.8/-1.3 at 23 mo
Device S	Years Af	1 yr	100.0	99.9	100.0	100.0	100.0	99.8 +0.0/-0.1
			Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion
JS)	ls	toT	28		2		15	
ctions (US)	rapy iction Not npromised al	Fun Cor	7 = 28		3 = 5		7 = 15	
Malfunctions (US)	otion Not npromised	The Too			II		8 + 7 = 15	
Malfunctions (US)	npromised seapy setion Not npromised	The Tool The The Tool	+ 7		II		+ 7 =	
Malfunctions (US)	oletions (US) prepy Function mpromised prepy repy trepy trepy promised	Act Imp Mon Dep The Con Fun Fun Con	21 + 7 =		7 + 3		8 + 2	
Malfunctions (US)	ive US blants mal Battery oletions (US) rrapy Function promised promised stron Not oction Not moromised	Esti Happing Mon Mon Mon The Con The Mun Con	381 21 + 7 =		147 2 + 3 =		38 + 7 =	
Malfunctions (US)	Implants imated ive US solution solutio	Regin USI Estin USI Mori Imph Mori Imph The Con The Co	4,000 381 21 + 7 =		15,000 147 2 + 3 =		46,000 38 8 + 7 =	
Malfunctions (US)	pistered implants in a label of the label of	Regin USI Estin USI Mori Imph Mori Imph The Con The Co	15,000 4,000 381 21 + 7 =		27,000 15,000 147 2 + 3 =		52,000 46,000 38 8 + 7 =	



#### **Reference Chart**

The longevity estimates provided are mean values calculated for the parameters given. The actual longevity achieved for any device while implanted will depend on the actual programmed parameters and patient factors, and may differ significantly from these estimates.

					E	stimate	d Longe	vity		Elective	Replacement	
			*			(ERI)***		End of				
Model Number	Family	Connector Style	Volume/ Mass*	Delivered Energy	Charging Frequency**	100% Pacing‡	50% Pacing‡	15% Pacing‡	100% Sensing	Battery Voltage	Charge Time	Life (EOL) Battery Voltage
7272	InSync ICD	DR+LV	66 cc 117 g	34 J	Monthly Quarterly Semiannual	5.4 6.5 6.9	6.3 8.0 8.5	7.3 9.4 10.3	7.8 10.3 11.2	≤ 4.91 V	_	≤ 4.57 V
7277	InSync Marquis	DR+LV split	38 cc 77 g	30 J	Monthly Quarterly Semiannual	3.7 5.0 5.5	4.3 6.0 6.7	4.7 7.0 8.0	4.9 7.5 8.6	≤ 2.62 V	> 16 second charge time	3 months after ERI
7289	InSync II Marquis	DR+LV true	38 cc 76 g	30 J	Monthly Quarterly Semiannual	3.3 4.2 4.5	3.6 4.9 5.4	4.0 5.5 6.1	4.2 5.8 6.6	≤ 2.62 V	> 16 second charge time	3 months after ERI
7295	InSync II Protect	DR+LV true	38 cc 77 g	30 J	Monthly Quarterly Semiannual	3.3 4.2 4.5	3.7 4.9 5.4	4.0 5.5 6.2	4.2 5.9 6.6	≤ 2.62 V	> 16 second charge time	3 months after ERI
7297	InSync Sentry	DR+LV true	40 cc 78 g	35 J	Monthly Quarterly Semiannual	3.3 4.5 5.0	3.7 5.3 6.0	4.1 6.2 7.1	4.3 6.6 7.7	≤ 2.62 V	> 16 second charge time	3 months after ERI
7299	InSync Sentry	DR+LV true	40 cc 78 g	35 J	Monthly Quarterly Semiannual	3.3 4.5 5.0	3.7 5.3 6.0	4.1 6.2 7.1	4.3 6.6 7.7	≤ 2.62 V	> 16 second charge time	3 months after ERI
7303	InSync Maximo	DR+LV true	40 cc 78 g	35 J	Monthly Quarterly Semiannual	3.3 4.5 5.0	3.7 5.3 6.0	4.1 6.2 7.1	4.3 6.6 7.7	≤ 2.62 V	> 16 second charge time	3 months after ERI
7304	InSync Maximo	DR+LV true	40 cc 78 g	35 J	Monthly Quarterly Semiannual	3.3 4.5 5.0	3.7 5.3 6.0	4.1 6.2 7.1	4.3 6.6 7.7	≤ 2.62 V	> 16 second charge time	3 months after ERI

		Estimated Lo	ngevity		
Family	Model Number	Amplitude Setting	500 Lead Ω	1000 Lead $\Omega$	Elective Replacement Time Indicators
InSync	8040	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	11.9 8.9 6.6	13.7 11.4 9.1	**
InSync III	8042	Low 2.5 V (A, RV, LV) Nominal 3.5 V (A, RV, LV) High 5.0 V (A, RV, LV)	8.3 5.9 4.1	9.9 7.8 6.0	**

	Connecto Family Style				Estimated Longevity					Recommended Replacement (RRT)***		
Model Number			Volume/ Mass*		Charging Frequency**	100% Pacing‡	50% Pacing‡	15% Pacing‡	100% Sensing	Battery Voltage	Charge Time	End of Service (EOS)
C154DWK, C164AWK, C174AWK		DR+LV true	38 cm 68 g	35 J	Monthly Quarterly Semiannual	3.8 5.5 6.3	4.3 6.8 8.0	4.8 8.0 9.8	5.0 8.8 11.0	≤ 2.62 V	_	3 month after RRT or > 16-second charge time

<sup>\*</sup> Volume and mass differ by connector style.

<sup>\*\*</sup> A full charge is a full energy therapeutic shock or capacitor reformation.

<sup>\*\*\*</sup> The minimum time between ERI and EOL (or RRT and EOS) is 3 months (100% pacing, two charges per month).

<sup>‡</sup> Pacing mode is DDD for CRT models. Parameter settings; lower rate at 60 ppm, sensing rate at 70 bpm, (A, RV, LV) 3.0 V amplitude, 0.4 ms pulse width, and 510 ohm pace load per applicable channel. CRT models with shared biventricular pacing; InSync Marquis 7277 (LV impedance set to 510 ohms), InSync ICD 7272 (RV amplitude set to 4.0 V).



#### **7227 GEM**

	US Ma	rket Release		Oct-9	8 Malf	unctions (US)		143	NBD (	Code		VVEV
	Regist	ered US Impl	ants	22,00	0				Serial	Number Prefix	(	PIP, PLN,
	Estima	ated Active U	S Implants	4,00	0							PLP, PLR
	Norma	al Battery De	pletions (US)	1,38	3				Max [	Delivered Energ	ЭУ	35 J
		<mark>ories: </mark> See pa t Overload	ge 148 – 1999	Potential					Estim	ated Longevity	/	See page 33
(%)	100											
	90							****				
abil	80											
Device Survival Probability	70											
ival	60											
Sur	50											
vice	40											
De	30											
	20											
	10											
	(	) Years Aftei			3 Judina No	4 rmal Battery I		6 7		8 nal Battery De	9 enletion	10
		rears Arter		ı						1	i	1
			1 yr	2 yr	3 yr	4 yr	5 yr	-	7 yr	8 yr	9 yr	at 111 mo
	%		99.7	99.6	99.5	99.4	99.2	99.2	99.1	99.1	99.1	99.1
	%		99.3	99.0	98.7	98.2	97.4	95.4	83.4	66.6	37.3	18.8
	#		20,000	17,000	15,000	13,000	11,000	8,000	5,000	3,000	500	100

#### **7229 GEM II VR**

229 GEM II VR	Product Characteristics				
US Market Release	Jul-99	Malfunctions (US)	27	NBD Code	VVEV
Registered US Implants	11,000			Serial Number Prefix	PJJ
<b>Estimated Active US Implants</b>	300			Max Delivered Energy	30 J
Normal Battery Depletions (US)	1,738			Estimated Longevity	See page 33

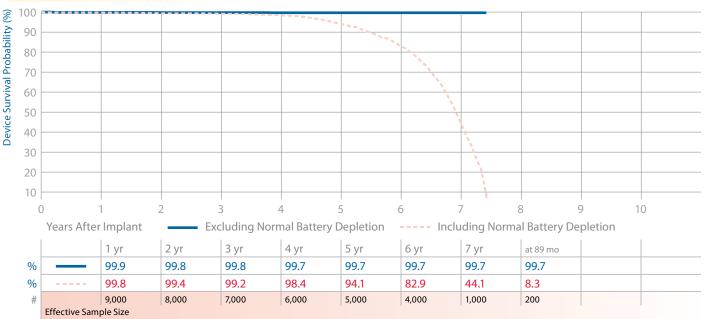
Advisories: See page 148 – 1999 Potential

Circuit Overload

also see page 158 - Performance note on ICD

Battery Discharge Behavior

Effective Sample Size





#### 7230 Marquis VR

US Market Release	Dec-02
Registered US Implants	19,000
Estimated Active US Implants	9,000
Normal Battery Depletions (US)	27
Advisories: See page 146 – 2005 Pot Premature Battery Depletion Due to Battery Short	

Malfunctions (US)	23
Therapy Function Not Compromised	16
<b>Electrical Component</b>	10
Possible Early Battery Depletion	5
Other	1
Therapy Function Compromised	7

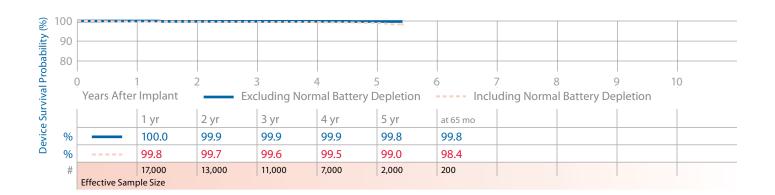
Battery (1 malfunction related to advisory)

**Electrical Component** 

2 5

#### **Product Characteristics**

NBD Code	VVEV
Serial Number Prefix	PKD, PLW, PLY
Max Delivered Energy	30 J
Estimated Longevity	See page 33



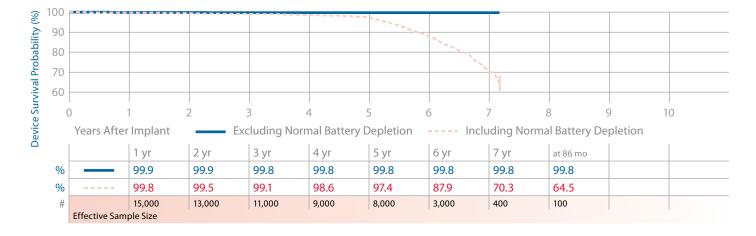
#### **7231 GEM III VR**

US Market Release	Dec-00
Registered US Implants	17,000
Estimated Active US Implants	8,000
Normal Battery Depletions (US)	541
Performance Note: see page 158 –	

Performance note on ICD Battery
Discharge Behavior

Malfunctions (US)	31
Therapy Function Not Compromised	23
Battery	1
Electrical Component	18
Possible Early Battery Depletion	4
Therapy Function Compromised	8
Battery	1
Electrical Component	7

NBD Code	VVEV
Serial Number Prefix	PJL
Max Delivered Energy	30 J
Estimated Longevity	See page 33





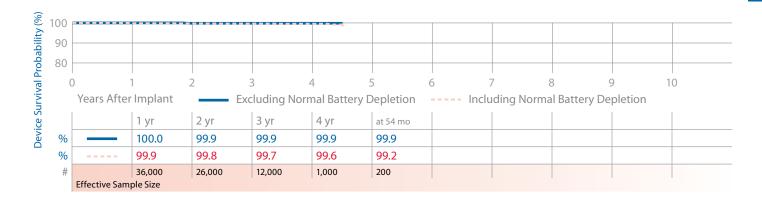
#### 7232 Maximo VR

US Market Release	Oct-03
Registered US Implants	42,000
<b>Estimated Active US Implants</b>	32,000
Normal Battery Depletions (US)	23
Advisories: See page 146 – 2005 Pote Premature Battery Depletion Due to Battery Short	ential

Malfunctions (US)	22
Therapy Function Not Compromised	13
Electrical Component	6
Possible Early Battery Depletion	
Therapy Function Compromised	
Electrical Component	7
Electrical Interconnect	1
Possible Early Battery Depletion	1

<b>Product Characteristics</b>	
NBD Code	VVED

NBD Code	VVED
Serial Number Prefix	PRN
Max Delivered Energy	35 J
Estimated Longevity	See page 33

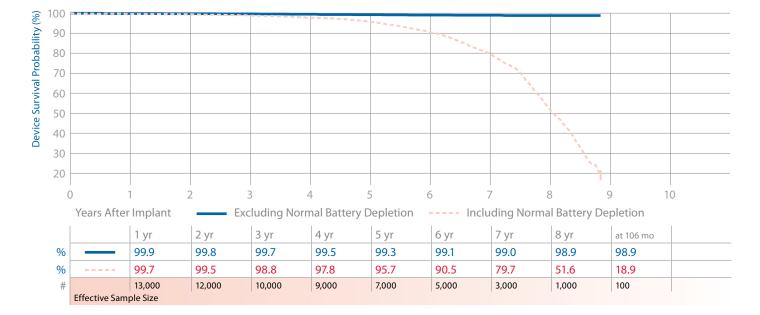


Malfunctions (US)

#### **7271 GEM DR**

Oct-98
15,000
2,000
1,032
None

NBD Code	VVED
Serial Number Prefix	PIM
Max Delivered Energy	27 J
Estimated Longevity	See page 33





#### 7274 Marquis DR

US Market Release	Mar-02
Registered US Implants	48,000
Estimated Active US Implants	18,000
Normal Battery Depletions (US)	872

Advisories: See page 146 – 2005 Potential Premature Battery Depletion Due to Battery Short

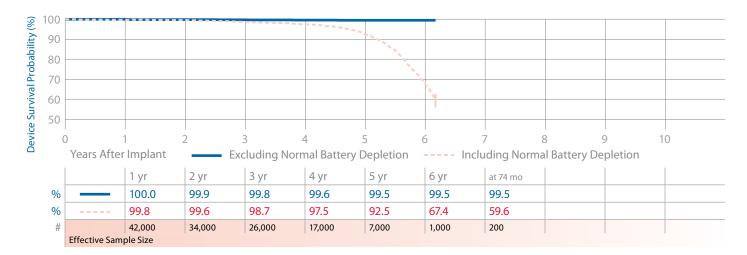
Malfunctions (US)	130
Therapy Function Not Compromised	63
Battery (3 malfunctions related to advisory)	5
Electrical Component	22
Possible Early Battery Depletion	36
Therapy Function Compromised	67
Battery (36 malfunctions related to advisory)	44

**Electrical Component** 

#### **Product Characteristics**

23

NBD Code	VVED
Serial Number Prefix	PKC
Max Delivered Energy	30 J
Estimated Longevity	See page 33



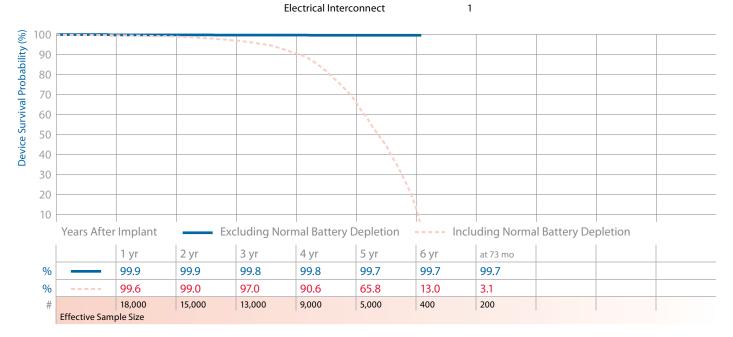
#### 7275 GEM III DR

US Market Release	Nov-00
Registered US Implants	20,000
<b>Estimated Active US Implants</b>	2,000
Normal Battery Depletions (US)	3,056

Performance Note: see page 158 – Performance note on ICD Battery Discharge Behavior

Malfunctions (US)	40
Therapy Function Not Compromised	29
Battery	1
Electrical Component	11
Software/Firmware	1
Possible Early Battery Depletion	16
Therapy Function Compromised	11
Battery	2
Electrical Component	8

NBD Code	VVED
Serial Number Prefix	PJM
Max Delivered Energy	30 J
Estimated Longevity	See page 33





#### **7276 GEM III AT**

US Market Release	Feb-01	Malfunctions (US)	41
Registered US Implants	14,000	Therapy Function Not Compromised	34
Estimated Active US Implants	1,000	Electrical Component	7
Normal Battery Depletions (US)	2,306	Software/Firmware	1
Performance Note: see page 158	_	Possible Early Battery Depletion	26
Performance note on ICD Battery Discharge Behavior		Therapy Function Compromised	7
Discharge Denavior			_

Product Characteristics	
NBD Code	DDED
Serial Number Prefix	PKE
Max Delivered Energy	30 J
Estimated Longevity	See page 33

00											
90											
80											
70											
60											
50					``						
40						1					
40						1					
30											
20											
10						1					
(	)	1	2 :	3 4	4 !	5	6	7	8	9	10
	Years After	r Implant	Exc	luding Norn	nal Battery [	Depletion	Inclu	uding Norm	al Battery De	epletion	
		1 yr	2 yr	3 yr	4 yr	5 yr	at 69 mo				
%		99.9	99.9	99.8	99.5	99.5	99.5				
%		99.7	98.9	96.3	86.3	52.9	7.6				
		12,000	10,000	9,000	6,000	2,000	200				

**Electrical Component** 

7

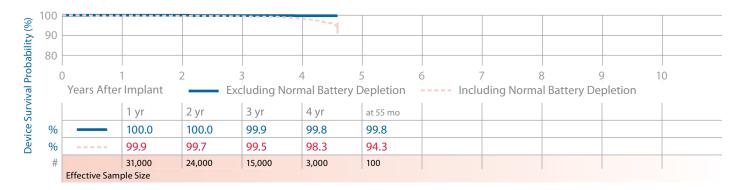
#### 7278 Maximo DR

US Market Release	Oct-03
Registered US Implants	36,000
<b>Estimated Active US Implants</b>	26,000
Normal Battery Depletions (US)	82
Advisories: See page 146 – 2005 Potent Premature Battery Depletion Due to Battery Short	tial

Malfunctions (US)	24
Therapy Function Not Compromised	16
Electrical Component	10
Possible Early Battery Depletion	6
Therapy Function Compromised	8
Electrical Component	7
Possible Early Battery Depletion	1

Proc	luct C	harac	ter	istics

NBD Code	VVED
Serial Number Prefix	PRM
Max Delivered Energy	35 J
Estimated Longevity	See page 33





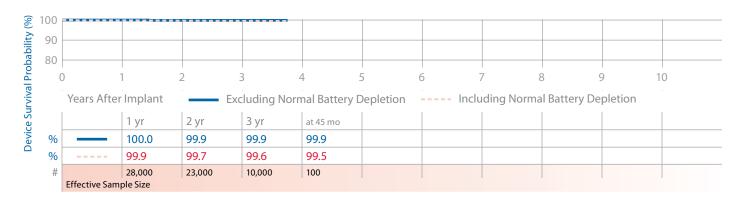
#### 7288 Intrinsic

US Market Release	Aug-04
Registered US Implants	31,000
Estimated Active US Implants	23,000
Normal Battery Depletions (US)	28
Advisories	None

#### Troduct characteristic

Malfunctions (US)	22	N
Therapy Function Not Compromised	16	S
Battery	2	Ν
Electrical Component	7	Ε
Software/Firmware	1	
Possible Early Battery Depletion	6	
Therapy Function Compromised	6	
Electrical Component	6	



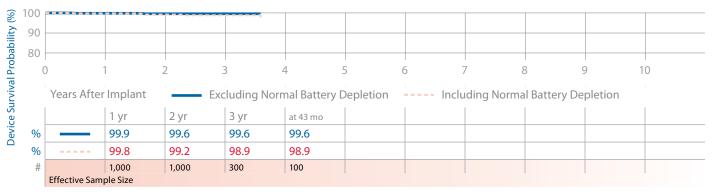


#### 7290 Onyx

US Market Release	Mar-04
Registered US Implants	1,000
Estimated Active US Implants	1,000
Normal Battery Depletions (US)	1
Advisories	None

Malfunctions (US)
Therapy Function Not Compromised
Electrical Component
Therapy Function Compromised
Electrical Component

3	NBD Code	VVEV
2	Serial Number Prefix	PRP
2	Max Delivered Energy	30 J
1	Estimated Longevity	See page 33
1		

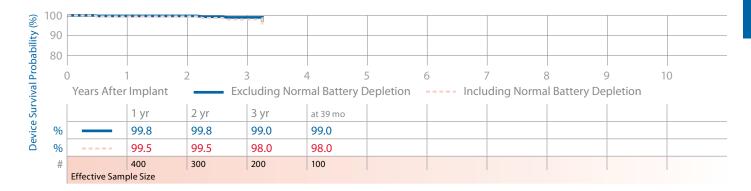




#### D153ATG, D153DRG EnTrust

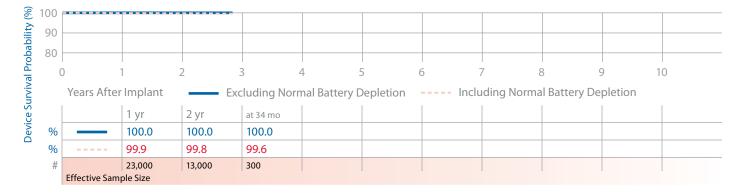
#### **Product Characteristics**

US Market Release	Jun-05	Malfunctions (US)	3	NBD Code	DDED, VVED
Registered US Implants	400	Therapy Function Not Compromised	2	Serial Number Prefix	PNR
<b>Estimated Active US Implants</b>	300	Possible Early Battery Depletion	2	Max Delivered Energy	30 J
Normal Battery Depletions (US)	0	Therapy Function Compromised	1	<b>Estimated Longevity</b>	See page 34
Advisories	None	Electrical Component	1		



#### D154ATG, D154DRG EnTrust

US Market Release	Jun-05	Malfunctions (US)	10	NBD Code	DDED, VVED
Registered US Implants	27,000	<b>Therapy Function Not Compromised</b>	6	Serial Number Prefix	PNR
<b>Estimated Active US Implants</b>	23,000	Electrical Component	2	Max Delivered Energy	35 J
Normal Battery Depletions (US)	15	Possible Early Battery Depletion	4	Estimated Longevity	See page 34
Advisories	None	Therapy Function Compromised	4		
		Electrical Component	4		

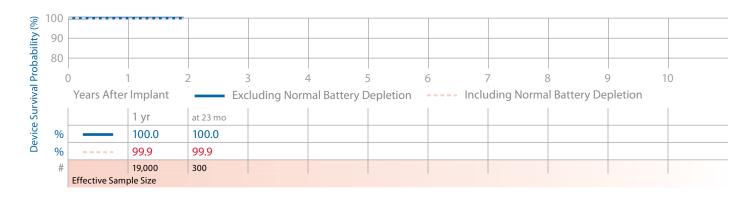




#### D154AWG, D164AWG Virtuoso

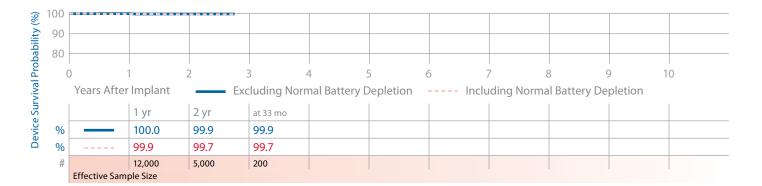
#### **Product Characteristics**

US Market Release	May-06	Malfunctions (US)	11	NBD Code	VVED
Registered US Implants	49,000	Therapy Function Not Compromised	2	Serial Number Prefix	PVV, PUL
<b>Estimated Active US Implants</b>	45,000	Electrical Component	2	Max Delivered Energy	35 J
Normal Battery Depletions (US)	6	Therapy Function Compromised	9	Estimated Longevity	See page 34
Advisories	None	Electrical Component	9		



#### D154VRC EnTrust Product Characteristics

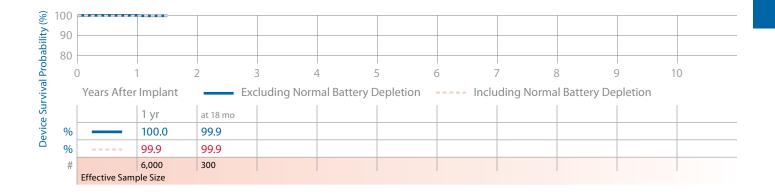
US Market Release	Jun-05	Malfunctions (US)	11	NBD Code	VVEV
Registered US Implants	14,000	Therapy Function Not Compromised	8	Serial Number Prefix	PNT
Estimated Active US Implants	12,000	Electrical Component	3	Max Delivered Energy	35 J
Normal Battery Depletions (US)	4	Possible Early Battery Depletion	5	Estimated Longevity	See page 34
Advisories	None	Therapy Function Compromised	3		
		Electrical Component	3		





#### D154VWC, D164VWC Virtuoso

US Market Release	May-06	Malfunctions (US)	6	NBD Code	VVEV
Registered US Implants	20,000	Therapy Function Not Compromised	2	Serial Number Prefix	PUN
Estimated Active US Implants	19,000	Electrical Component	1	Max Delivered Energy	35 J
Normal Battery Depletions (US)	3	Electrical Interconnect	1	<b>Estimated Longevity</b>	See page 34
Advisories	None	Therapy Function Compromised	4		
		Electrical Component	4		





Device Survival Summary (95% Confidence Interval)

The following table shows ICD device survival estimates with 95% confidence intervals. Estimates are shown both with and without normal battery depletions included.

		10 yr	99.1 +0.2/-0.2 at 111 mo	18.8 +2.9/-2.7 at 111 mo									98.9 +0.2/-0.3 at 106 mo	18.9 +2.6/-2.4 at 106 mo		
		8 yr	99.1	66.6 +1.2/-1.3	99.7 +0.1/-0.2 at 89 mo	8.3 +1.6/-1.4 at 89 mo			99.8 +0.1/-0.1 at 86 mo	64.5 +3.7/-4.0 at 86 mo			98.9	51.6 +1.9/-2.0		
	-	7 yr	99.1 +0.1/-0.2	83.4 +0.8/-0.9	99.7 +0.1/-0.2	44.1			99.8 +0.1/-0.1	70.3			99.0 +0.2/-0.2	79.7	99.5 +0.1/-0.1 at 74 mo	59.6 +3.3/-3.4 at 74 mo
		6 yr	99.2 +0.1/-0.1	95.4 +0.4/-0.4	99.7 +0.1/-0.1	82.9	99.8 +0.1/-0.1 at 65 mo	98.4 +0.5/-0.7 at 65 mo	99.8 +0.1/-0.1	87.9 +0.8/-0.8			99.1	90.5	99.5	67.4 +1.9/-2.0
		5 yr	99.2 +0.1/-0.1	97.4 +0.2/-0.3	99.7 +0.1/-0.1	94.1	99.8 +0.1/-0.1	99.0	99.8 +0.1/-0.1	97.4 +0.3/-0.3	99.9 +0.0/-0.0 at 54 mo	99.2 +0.4/-1.0 at 54 mo	99.3 +0.1/-0.2	95.7	99.5 +0.1/-0.1	92.5
:y (%)		4 yr	99.4 +0.1/-0.1	98.2 +0.2/-0.2	99.7 +0.1/-0.1	98.4 +0.3/-0.3	99.9 +0.0/-0.1	99.5	99.8 +0.1/-0.1	98.6 +0.2/-0.2	99.9	99.6 +0.1/-0.1	99.5	97.8 +0.3/-0.3	99.6 +0.1/-0.1	97.5
Device Survival Probability (%)	ant	3 yr	99.5 +0.1/-0.1	98.7 +0.2/-0.2	99.8 +0.1/-0.1	99.2 +0.2/-0.2	99.9 +0.0/-0.1	99.6	99.8 +0.1/-0.1	99.1 +0.1/-0.2	99.9	99.7 +0.1/-0.1	99.7 +0.1/-0.1	98.8 +0.2/-0.2	99.8 +0.0/-0.1	98.7
Survival F	Years After Implant	2 yr	99.6 +0.1/-0.1	99.0	99.8 +0.1/-0.1	99.4 +0.1/-0.2	99.9 +0.0/-0.1	99.7	99.9 +0.0/-0.1	99.5 +0.1/-0.1	99.9	99.8 +0.0/-0.1	99.8 +0.1/-0.1	99.5	99.9	99.6
Device	Years A	1 yr	99.7 +0.1/-0.1	99.3 +0.1/-0.1	99.9 +0.0/-0.1	99.8	100.0	99.8	99.9 +0.0/-0.1	99.8 +0.1/-0.1	100.0	99.9	99.9 +0.0/-0.1	99.7 +0.1/-0.1	100.0 +0.0/-0.0	99.8
			Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion
JS)	ls	201	ŵ	1	7			_								e -
		†oT	143	1	27		23	(1) subset)	31		22	(0) ubset)	92		130	(39) ubset)
nctions	erapy Action Not Mpromised	Fun Cor	14	ı	7	1	16 =	(0) (1) ry-related subset	23 =		13 =	+ (0) = (0) ry-related subset)	_ 92		63 =	+ (3) = (39 ry-related subset)
Malfunctions (US)	oM noitor	The fun Too		1	7.	1	Ш	ted sub	Ш		Ш	= ted subs	92		II	= ed sub
Malfunctions	mpromised erapy action Mot	Ther Ther Ther Ther Ther	1,383 — — 14	verload — — —	1,738 — — 2	verload; — — — ery	+ 16		+ 23 =	<b>.</b>	+ 13	(0) + (0) =  (advisory-related subs	1,032 — 92		+ 63 =	(36) + (3) = (advisory-related sub
Malfunctions	pletions (US) srapy Function mpromised srapy to Not	toM looM looM looM looM looM looM looM l	1	ial Circuit Overload — — — — —		ial Circuit Overload; — — — — — on ICD Battery	7 + 16 =		8 + 23 =	ICD Battery	9 + 13 =	(0) + (0) =  (advisory-related subs	1		67 + 63 =	(36) + (3) = (advisory-related sub
Malfunctions	ive US  Jants  mal Battery pletions (US)  srapy Function myromised  myromised	Esti Act Imp Imp Moi Dep The Con The Con	1,383 — —	1999 Potential Circuit Overload — — — — —	1,738 — —	1999 Potential Circuit Overload; — — — — — — — — — — — — — — — — — — —	27 7 + 16 =		541 8 + 23 =	ice note on ICD Battery	23 9 + 13 =	(0) + (0) =  (advisory-related subs	1,032 — —		872 67 + 63 =	(36) + (3) = (advisory-related sub
Malfunctions	Implants inve US size US solutes rmal Battery pletions (US) reapy Function mpromised reapy reapy Function propries size size size size size size size s	Reli Reg US Imp Imp Inp Inp Con	4,000 1,383 — —	- page 148 – 1999 Potential Circuit Overload	300 1,738 — —	page 148 – 1999 Potential Circuit Overload; — — — — — — — — — — — — — — — — — — —	9,000 27 + 16 =		8,000 541 8 + 23 =	Performance note on ICD Battery	32,000 23 9 + 13 =	(0) + (0) =  (advisory-related subs	2,000 1,032 — —		18,000 872 67 + 63 =	(36) + (3) = (advisory-related sub
Malfunctions	gistered implants imated sive US sharts sharts sharts sharts sharts (US) sharts	Reli Reg US Imp Imp Inp Inp Con	22,000 4,000 1,383 — —	Advisories: see page 148 – 1999 Potential Circuit Overload	11,000 300 1,738 — —	Advisories: see page 148 – 1999 Potential Circuit Overload; — — also see page 158 – Performance note on ICD Battery Discharge Behavior	19,000 9,000 27 + 16 =	Advisories: see page 146 – 2005 Potential Premature  Battery Depletion Due to Battery Short (advisory-related subset)	17,000 8,000 541 8 + 23 =	see page 158 – Performance note on ICD Battery Discharge Behavior	42,000 32,000 23 9 + 13 =	Advisories: see page $146 - 2005$ Potential Premature  Battery Depletion Due to Battery Short (advisory-related subset)	15,000 2,000 1,032 — —		48,000 18,000 872 67 + 63 =	Advisories: see page 146 – 2005 Potential Premature Battery Depletion Due to Battery Short (advisory-related subset)

	4 yr 5 yr
plant	3 yr
Years After Implant	2 yr
Years	1 yr
erapy nction Not mpromised al	un
erapy Function npromised	поЭ
olants rmal Battery pletions	
	tuo l
bətsmi SU əvi	İΣ
<b>ZU 9vi</b>	USU Esti
etnelqml bətemi SU əvi	Rele USI USI Esti
əsaə yistered stnalqml stnalqmi Vətemi	Rele USI USI Esti

		8 yr						
		7 yr						
		6 yr						
		5 yr						
(%)		4 yr						
Device Survival Probability (%)	nt	3 yr			99.9 +0.0/-0.1 at 33 mo	99.7 +0.1/-0.2 at 33 mo		
Survival P	Years After Implant	2 yr	100.0 +0.0/-0.0 at 23 mo	99.9 +0.0/-0.0 at 23 mo	99.9 +0.0/-0.1	99.7 +0.1/-0.1	99.9 +0.0/-0.1 at 18 mo	99.9 +0.1/-0.1 at 18 mo
Device !	Years Af	1 yr	100.0	99.9	100.0	99.9 +0.0/-0.1	100.0	99.9
			Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion
	ls	toT	=		=		9	
ctions	ction Not npromised	Fun Cor	2 = 11		8 =====================================		2 = 6	
Malfunctions	npromised	The fun Toor	II		II		II	
Malfunctions	rapy stapy staion Not notromised	Ther Too The The Tun Too	+ 2 =		Ⅱ ∞ +		+ 2 =	
Malfunctions	srepy Function propy Function npromised repy town Not besimonared	Act Imp Mon pel The Con The Fun Fun Con	9 + 5		& + & & & & & & & & & & & & & & & & &		4 + 2 =	
Malfunctions	ive US hlants mal Battery sletions repy Function npromised rety rety srapy notion Not notion Not	Esting Hands (1981)  Horizontal Hands (1981)	9 + 5 =		4 E + 8 H		3 + 2 = =	
Malfunctions	mated ive US so Ivi mal Battery snoised repy Function promised scion Not oction Not besimoran	Region US I	45,000 6 9 + 2 =		12,000 4 3 + 8 =		19,000 3 4 + 2 =	
Malfunctions	passe instered mated ve US live US lints mal Battery mal Battery srapy Function promised repy repy	Region US I	49,000 45,000 6 9 + 2 =		14,000 12,000 4 3 + 8 =		20,000 19,000 3 4 + 2 =	



#### **Reference Chart**

The longevity estimates provided are mean values calculated for the parameters given. The actual longevity achieved for any device while implanted will depend on the actual programmed parameters and patient factors, and may differ significantly from these estimates.

					E	stimate	d Longe	vity		Elective	Replacement	
					**						ERI)***	End of
Model Number	Family	Connector Style	Volume/ Mass*	Delivered Energy	Charging Frequency**	100% Pacing‡	50% Pacing‡	15% Pacing‡	100% Sensing	Battery Voltage	Charge Time	Life (EOL) Battery Voltage
7227	GEM	B, Cx, D, E	49 cc* 90 g	35 J	Monthly Quarterly Semiannual	5.3 7.7 8.8	5.7 8.5 10.0	6.0 9.3 11.0	6.1 9.6 11.5	≤ 2.55 V	_	≤ 2.40 V <sup>§</sup>
7229	GEM II VR	Сх	39 cc 77 g	30 J	Monthly Quarterly Semiannual	3.6 5.0 5.6	3.9 5.5 6.3	4.1 6.0 6.9	4.2 6.2 7.1	≤ 2.55 V	_	≤ 2.40 V
7230	Marquis VR	B, Cx, E	36 cc 75 g	30 J	Monthly Quarterly Semiannual	4.9 7.3 8.5	5.2 8.0 9.3	5.4 8.5 10.0	5.5 8.7 10.4	≤ 2.62 V	> 16-second charge time	3 months after ERI
7231	GEM III VR	Сх	39 cc 77 g	30 J	Monthly Quarterly Semiannual	4.3 6.0 6.6	4.7 6.8 7.5	5.0 7.4 8.5	5.2 7.8 8.9	≤ 2.55 V	_	≤ 2.40 V
7232	Maximo VR	B, Cx, E	39 cc 76 g	35 J	Monthly Quarterly Semiannual	4.4 7.0 8.2	4.7 7.5 9.0	4.8 8.0 9.7	4.9 8.3 10.0	≤ 2.62 V	> 16-second charge time	3 months after ERI
7271	GEM DR	DR	62 cc 115 g	35 J	Monthly Quarterly Semiannual	6.0 7.4 7.9	6.9 8.4 9.0	7.5 9.3 10.0	7.8 9.8 10.6	≤ 4.91 V	_	≤ 4.57 V <sup>§</sup>
7274	Marquis DR	DR+LV	36 cc 75 g	30 J	Monthly Quarterly Semiannual	4.0 5.6 6.2	4.4 6.4 7.2	4.8 7.1 8.1	4.9 7.5 8.6	≤ 2.62 V	> 16-second charge time	3 months after ERI
7275	GEM III DR	DR	39.5 cc 78 g	30 J	Monthly Quarterly Semiannual	3.3 4.2 4.5	3.8 5.0 5.5	4.3 5.8 6.5	4.4 6.3 7.0	≤ 2.55 V	_	≤ 2.40 V
7276	GEM III AT	DR	39 cc 77 g	30 J	Monthly Quarterly Semiannual	3.3 4.3 4.5	3.8 5.1 5.5	4.3 5.9 6.5	4.5 6.3 7.0	≤ 2.55 V	_	≤ 2.40 V
7278	Maximo DR	DR	39 cc 77 g	35 J	Monthly Quarterly Semiannual	3.7 5.3 6.0	4.1 6.1 7.0	4.3 6.8 8.0	4.5 7.1 8.5	≤ 2.62 V	> 16-second charge time	3 months after ERI
7287	Intrinsic 30	DR	36 cc 75 g	30 J	Monthly Quarterly Semiannual	4.0 5.5 6.2	4.3 6.3 7.2	4.7 7.0 8.2	4.8 7.4 8.6	≤ 2.62 V	> 16-second charge time	3 months after ERI
7288	Intrinsic	DR	38 cc 76 g	35 J	Monthly Quarterly Semiannual	3.7 5.4 6.1	4.1 6.1 7.0	4.3 6.8 8.0	4.5 7.1 8.5	≤ 2.62 V	> 16-second charge time	3 months after ERI
7290	Onyx	Сх	39 cc 77 g	30 J	Monthly Quarterly Semiannual	3.8 5.0 5.4	4.1 5.6 6.1	4.3 6.2 6.7	4.5 6.4 7.0	≤ 2.55 V	> 16-second charge time	≤ 2.40 V

<sup>\*</sup> Volume and mass differ by connector style.

 $<sup>\</sup>ensuremath{^{**}}$  A full charge is a full energy the rapeutic shock or capacitor reformation.

 $<sup>^{***}</sup>$  The minimum time between ERI and EOL is 3 months (100% pacing, two charges per month).

<sup>‡</sup> Pacing mode is VVI for single chamber models and DDD for dual chamber and CRT models. Parameter settings; lower rate at 60 ppm, sensing rate at 70 bpm, (A, RV, LV) 3.0 V amplitude, 0.4 ms pulse width, and 510 ohm pace load per applicable channel. CRT models with shared biventricular pacing; InSync Marquis 7277 (LV impedance set to 510 ohms), InSync ICD 7272 (RV amplitude set to 4.0 V).

<sup>##</sup> For Model 7223 devices, if charge time exceeds 60 seconds, the devices are at EOL. If 2 consecutive charge cycles exceed 60 seconds, the "charge circuit inactive" indicator is tripped and all therapies except emergency output VVI pacing are disabled.

<sup>§</sup> For Model 7271 and 7227 devices, if charge time exceeds 30 seconds, the device is at EOL. Immediate replacement is recommended. If 3 consecutive charge cycles exceed 30 seconds, the "charge circuit inactive" indicator is tripped and all therapies except emergency VVI pacing are disabled.



#### Reference Chart continued

					E	stimate	d Longe	vity		Recommended Replacement			
					**					RT)***	_		
Model Number	Family	Connector Style	Volume/ Mass*	Delivered Energy	Charging Frequency**	100% Pacing‡	50% Pacing‡	15% Pacing‡	100% Sensing	Battery Voltage	Charge Time	End of Service (EOS)	
D153ATG, D153DRG	EnTrust	DR	33 cc 63 g	30 J	Monthly Quarterly Semiannual	3.5 4.8 5.3	3.8 5.4 6.1	4.1 6.0 6.9	4.2 6.3 7.2	≤ 2.61 V	_	3 months after RRT or > 16-second charge time	
D153VRC	EnTrust	Сх	32 cc 63 g	30 J	Monthly Quarterly Semiannual	4.4 6.8 7.9	4.7 7.4 8.7	4.9 7.9 9.5	5.0 8.1 9.8	≤ 2.61 V	_	3 months after RRT or > 16-second charge time	
D154ATG, D154DRG	EnTrust	DR	35 cc 68 g	35 J	Monthly Quarterly Semiannual	3.8 5.5 6.1	4.2 6.1 7.0	4.4 6.8 7.9	4.6 7.0 8.3	≤ 2.61 V	_	3 months after RRT or > 16-second charge time	
D154AWG, D164AWG	Virtuoso	DR	37 cc 68 g	35 J	Monthly Quarterly Semiannual	4.1 6.3 7.3	4.5 7.3 8.7	4.8 8.3 10.1	5.0 8.8 11.0	≤ 2.62 V	_	3 months after RRT or > 19-second charge time	
D154VRC	EnTrust	Сх	35 cc 68 g	35 J	Monthly Quarterly Semiannual	4.8 7.5 9.0	5.0 8.3 10.0	5.2 8.8 10.7	5.3 9.0 11.0	≤ 2.61 V	_	3 months after RRT or > 16-second charge time	
D154VWC, D164VWC	Virtuoso	Сх	37 cc 68 g	35 J	Monthly Quarterly Semiannual	4.8 8.1 10.0	5.1 9.0 11.2	5.3 9.6 12.3	5.4 10.0 12.9	≤ 2.62 V	_	3 months after RRT or > 19-second charge time	

<sup>\*</sup> Volume and mass differ by connector style.

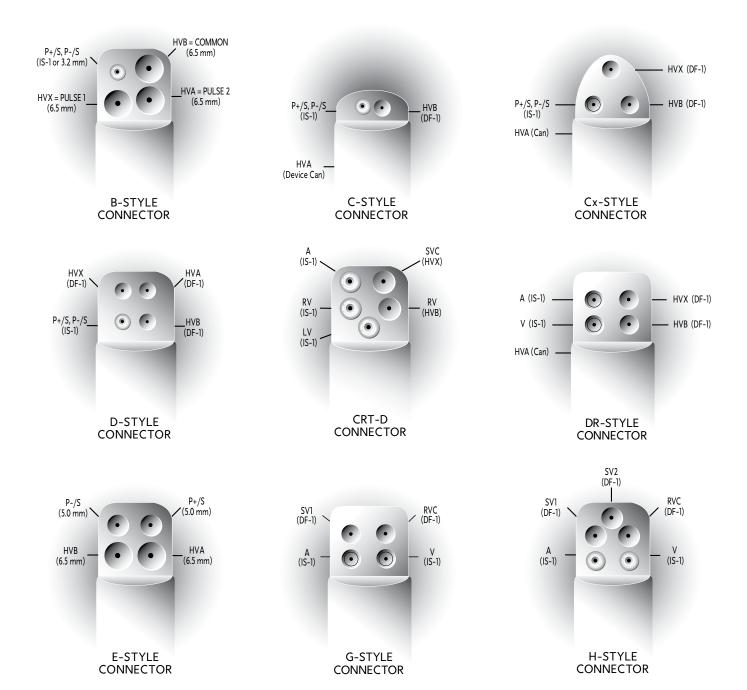
 $<sup>\</sup>ensuremath{^{**}}$  A full charge is a full energy the rapeutic shock or capacitor reformation.

<sup>\*\*\*</sup> The minimum time between RRT and EOS is 3 months (100% pacing, two charges per month).

<sup>‡</sup> Pacing mode is VVI for single chamber models and DDD for dual chamber models. Parameter settings; lower rate at 60 ppm, sensing rate at 70 bpm, (A, RV, LV) 3.0 V amplitude, 0.4 ms pulse width, and 510 ohm pace load per applicable channel.



#### **ICD Connector Styles**



Effective Sample Size

%

#

100.0

29,000

100.0

400

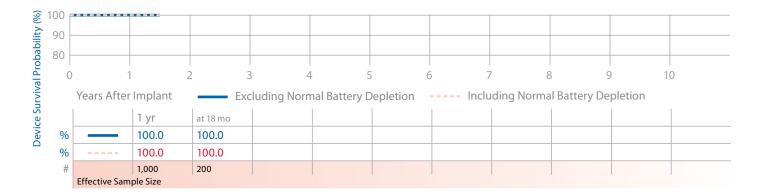
### Adapta DR ADDR01, ADDR03, ADDR06, ADD01

### **Product Characteristics**

apta Di	MEENON, MEENO			110000	.c character	150005					
US Market F	Release	Jul-06	Malfun	ctions (US)			4	NBG Co	de		DDDR, DDD
Registered	US Implants	86,000	Thera	py Function I	Not Compron	nised	3	Serial N	umber Prefix	(	PWB, PWD,
Estimated F	Active US Implants	79,000	Ele	ctrical Comp	onent		3				PWC
Normal Bat	tery Depletions (US)	0	Thera	py Function (	Compromised	l	1	Estimat	ed Longevity	1	See page 7
Advisories		None	Ele	Electrical Component			1				
90 80 0											
	1 rs After Implant	2 3 Evelue	4 dina Norm	nal Battery D			7 Judin	a Norma	Battery De	9 enletion	10
Yeaı 		Exclus	allig North	iai battery b	Pepietion	1110	ıuuııı	g Nomia	Dattery De	pietion	ı
	1 yr	at 21 mo									
% -	100.0	100.0									
%	100.0	100.0									

### Adapta DR ADDRL1 **Product Characteristics**

US Market Release	Jul-06	Malfunctions (US)	0	NBG Code	SSIR
Registered US Implants	7,000	Therapy Function Not Compromised	0	Serial Number Prefix	PWM, PWP,
<b>Estimated Active US Implants</b>	6,000	Therapy Function Compromised	0		PWN
Normal Battery Depletions (US)	0			<b>Estimated Longevity</b>	See page 71
Advisories	None				

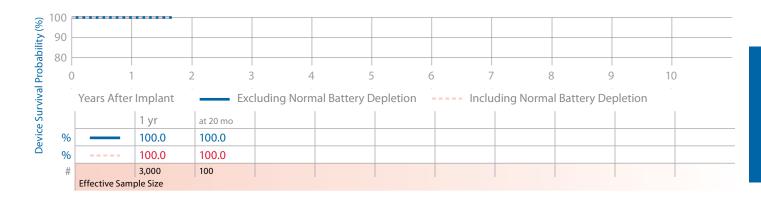




### Adapta DR ADDRS1

### **Product Characteristics**

US Market Release	Jul-06	Malfunctions (US)	1	NBG Code	SSIR
Registered US Implants	8,000	Therapy Function Not Compromised	0	Serial Number Prefix	PWM, PWP,
<b>Estimated Active US Implants</b>	7,000	Therapy Function Compromised	1		PWN
Normal Battery Depletions (US)	0	Electrical Component	1	Estimated Longevity	See page 71
Advisories	None				



### Adapta SR ADSR01, ADSR03, ADSR06

US Ma	arket Release		Jul-06	Malfur	nctions (US)			0	NBG Co	de		SSIR	
Regis	tered US Impla	ints	17,000	Thera	py Function	Not Compro	mised	0	Serial N	umber Prefix	(	PWM, PWP	
Estim	ated Active US	Implants	15,000	Thera	py Function	Compromise	ed	0				PWN	
Norm	al Battery Dep	letions (US)	0						Estimat	Estimated Longevity			
Advis	ories		None										
100													
80								-					
(	) 1	2	2 3	4	1 !	5	6	7	8	3	9	10	
	Years After	Implant	Exclu	ıding Norr	mal Battery [	Depletion	Ind	cludin	ig Norma	al Battery De	epletion		
		1 yr	at 20 mo										
%		100.0	100.0										
0/-		100.0	100.0										

### AT500 AT501, 7253

### **Product Characteristics**

US M	arket Release		Mar-03	Malfund	tions (US)			10	NBG Code			DDDRP
Regis	tered US Implar	nts	11,000	Therap	y Function l	Not Compro	mised	5	Serial Numbe	er Prefix		IJF
Estim	ated Active US	Implants	6,000	Ele	ctrical Comp	onent		2	Estimated Lo	ngevity		See page 7
Norm	al Battery Depl	etions (US)	232	Pos	sible Early B	attery Deplet	ion	3				
Perfo	rmance Note: se	e page 156 –		Therap	y Function (	Compromise	ed	5				
	mance note on Al n Follow-Up Proto			Ele	ctrical Comp	onent		3				
				Ele	ctrical Interc	onnect		1				
				Pos	sible Early B	attery Deplet	tion	1				
100												
8 100												
90						)						
pab 08						1						
<b>a</b> 70						- N						
Device Survival Probability (%)  20 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0												
Surv 50												
ice	0 1	2	2 3	4	L	  - 	6	7	8	(	)	10
Oev		-				,		,				
_												
	Years After I	mplant	Exclu	ding Norm	al Battery D	epletion	In	cludin	g Normal Bat	tery De	pletion	
		1 yr	2 yr 3	yr	4 yr	5 yr	at 64 mo					

99.9

84.0

1,000

99.9

63.3 100

### EnPulse DR E1DR01, E1DR03, E1DR06

Effective Sample Size

%

100.0

99.9

10,000

100.0

99.9

9,000

100.0

99.6

8,000

99.9

98.2

5,000

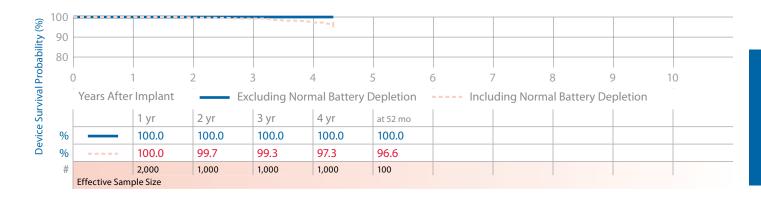
US Ma	rket Release		Dec-0	3 Malfu	ınctions (US)			1	NBG Co	de		DDDR
Regist	ered US Impla	ants	7,000	) The	apy Functio	n Not Compro	omised	1	Serial N	umber Pref	ix	PRA
Estima	ated Active US	S Implants	4,000	) E	lectrical Cor	nponent		1	Estimat	ed Longevit	ty	See page 7
Norma	al Battery Dep	oletions (US)	10	5 The	apy Functio	n Compromis	ed	0				
Adviso	ories		None	9								
100												
90												
80												
00	) 1	 	) ) :		4	5	6	7	8		9	10
		Implant	_			_	_	-ludin		, I Battery D		10
	Years After	ппріапі			mai Battery	/ Depletion	1110	Juain	g Norma	i battery L	epietion	1
		1 yr	2 yr	3 yr	4 yr	at 53 mo						
%		100.0	100.0	100.0	100.0	100.0						
%		100.0	100.0	99.9	99.3	99.2						
#		6,000	5,000	5,000	4,000	200						
	Effective Samp	ole Size										



### EnPulse DR E1DR21

### **Product Characteristics**

US Market Release	Dec-03	Malfunctions (US)	0	NBG Code	DDDR
	DEC 03	. ,	U		DDDIN
Registered US Implants	2,000	Therapy Function Not Compromised	0	Serial Number Prefix	PPT
<b>Estimated Active US Implants</b>	1,000	Therapy Function Compromised	0	<b>Estimated Longevity</b>	See page 71
Normal Battery Depletions (US)	16				
Advisories	None				



### EnPulse 2 DR E2DR01, E2DR03, E2DR06

100.0

90,000

Effective Sample Size

%

### **Product Characteristics**

US Ma	rket Release		Feb-0	4 Ma	Ifunctions (US	5)		9	NBG Code		DDDR
Regist	ered US Impl	ants	101,000	0 <b>Tł</b>	nerapy Functi	on Not Compr	omised	6	Serial Number P	refix	PNB, PNC,
Estima	ated Active U	S Implants	74,000	0	Electrical Co	mponent		6			PNH
Norma	al Battery De	oletions (US)	34	4 Tł	nerapy Functi	on Compromis	sed	3	Estimated Long	evity	See page 71
Adviso	ories		None	e	Battery			1			
					Electrical Co	mponent		2			
90 80											
80											
C	)	1 :	2 3	3	4	5	6	7	8	9	10
	Years After	Implant	Exc	luding N	lormal Batter	y Depletion	1	ncludir	g Normal Batter	y Depletio	n
		1 yr	2 yr	3 yr	4 yr	at 51 mo					
%		100.0	100.0	100.0	100.0	100.0					
0/6		100.0	100.0	99.9	00.8	00.8					

99.8

100

99.8

3,000

100.0

68,000

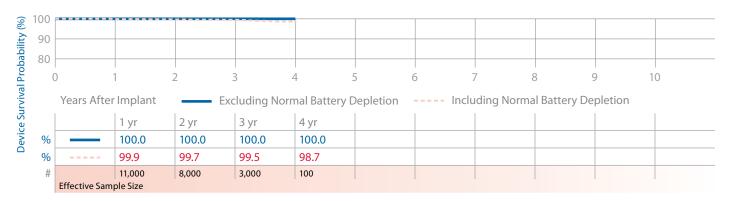
99.9

32,000

### EnPulse 2 DR E2DR21

### **Product Characteristics**

US Market Release	Feb-04	Malfunctions (US)	1	NBG Code	DDDR
Registered US Implants	12,000	Therapy Function Not Compromised	0	Serial Number Prefix	PMU
<b>Estimated Active US Implants</b>	9,000	Therapy Function Compromised	1	Estimated Longevity	See page 71
Normal Battery Depletions (US)	26	Electrical Component	1		
Advisories	None				



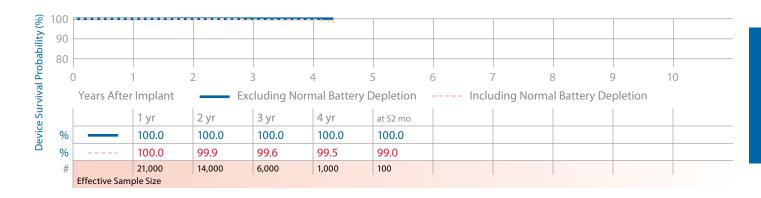
### EnPulse 2 DR E2DR31, E2DR33

US Ma	arket Release		Feb-0	4 Malfur	nctions (US)			0	NBG Co	de		DDDR
Regist	tered US Impl	ants	1,00	0 <b>Thera</b>	py Function	Not Compro	mised	0	Serial N	umber Prefix	x	PNL
Estim	ated Active U	S Implants	50	0 <b>The</b> ra	py Function	Compromise	d	0	Estimat	ed Longevit	y	See page 71
Norm	al Battery Dep	oletions (US)		0								
Advis	ories		Non	e								
<b>%</b> 100					T	T	T					
babil 80												
9	) .	 1	) :	] }	4	5	I б	7	8	 	9	10
val.		ا اسمىمامىمە	_					, , , al : .a.				10
Σ	Years After	ппріапі	ı	iuaing Norr	nal Battery [	epietion	Incl	uain	g Norma	l Battery D	epietion	ı
S		1 yr	2 yr	3 yr	at 37 mo							
% eKi		100.0	100.0	100.0	100.0							
۵ %		100.0	100.0	100.0	100.0							
#		1,000	400	100	100							
	Effective Sam	nle Size										



### EnPulse 2 SR E2SR01, E2SR03, E2SR06

US Market Release	Dec-03	Malfunctions (US)	3	NBG Code	SSIR
Registered US Implants	25,000	<b>Therapy Function Not Compromised</b>	2	Serial Number Prefix	PMW, PMY,
Estimated Active US Implants	17,000	Electrical Component	1		PNA
Normal Battery Depletions (US)	20	Possible Early Battery Depletion	1	<b>Estimated Longevity</b>	See page 71
Advisories	None	Therapy Function Compromised	1		
		Other	1		



### EnPulse 2 VDD E2VDD01

### **Product Characteristics**

	US Ma	rket Release		Dec-03	3 Malfur	nctions (US)			0	NBG Co	de		VDD
	Regist	tered US Impl	ants	1,000	) Thera	py Function	Not Compro	mised	0	Serial N	umber Prefix		PMV
	Estima	ated Active U	S Implants	500	) Thera	py Function	Compromise	ed	0	Estimate	ed Longevity		See page 71
	Norm	al Battery De	oletions (US)	(	)								
	Advis	ories		None	9								
(6	100												
itv (%	90												
abil	80												
rob	(	) .	1	2 3	3	4	5	6	7	8		9 1	10
Device Survival Probability (%)		Years After	Implant	—— Ехс	luding Norr	mal Battery [	epletion	Inc	ludin	g Norma	l Battery De	pletion	
Sur			1 yr	2 yr	3 yr	at 39 mo							
N i	%		100.0	100.0	100.0	100.0							
۵	%		100.0	100.0	100.0	100.0							
	#		1,000	400	200	100							
		Effective Sam	ole Size										

### EnRhythm DR P1501DR

### **Product Characteristics**

US Mai	rket Release		May-0	5 Ma	Ifunctions (US)			25	NBG Co	de		DDDRP
Registe	ered US Impl	ants	71,00	0 <b>Th</b>	erapy Function	Not Compro	mised	5	Serial N	umber Prefix	<	PNP
Estima	ited Active U	S Implants	59,00	0	Electrical Component			5	Estimat	ed Longevity	y	See page
Normal Battery Depletions (US)			1 <b>Th</b>	Therapy Function Compromised			20					
Advisories		Non	e	Electrical Component			19					
					Possible Early E	Battery Deple	etion	1				
100												
90												
80 -												
0	,	1	2	3	4	5	6	7	8	3	9	10
90   80   0	Years After	Implant	Exc	luding N	ormal Battery	Depletion		Includir	ng Norma	l Battery De	epletion	
		1 yr	2 yr	3 yr	at 37 mo							
%		100.0	100.0	99.9	99.9							
%		100.0	99.9	99.8	99.8							
#		52,000	26,000	1,000	200							
	Effective Samp	ple Size										

### Kappa 400 DR KDR401, KDR403

	rket Release		Jan		Malfunctions (US			22	NBG Co		<b>c</b>	DDD/RO
	ered US Impl				Therapy Function		romised	13		umber Pre		PER, PET
	ated Active U	•		000	Electrical Co	•		9	Estimat	ed Longev	ity	See page 7
	al Battery De <sub>l</sub>	oletions (US)		679	Electrical Int			1				
Adviso	ories		No	one	Other	y Battery Dep	letion	2				
					Therapy Function	on Compromi	icad	9				
					Electrical Co		seu	7				
					Electrical Int	-		2				
					Licetricarine	creomicet		_				
100												
90												
80												
70												
60												
50												
40										1		
30										1		
20										1		
(	)	1	2	3	4	5	6	7	8	3	9	10
	Years After	Implant	E	xcluding	Normal Batter	y Depletion	Ir	ncluding	g Norma	ıl Battery l	Depletion	
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 y	r	8 yr	at 101 mo	
%		100.0	100.0	100.0	100.0	99.9	99.9	99.	9	99.9	99.9	
%		99.9	99.9	99.8	99.6	99.1	97.4	88.	6	55.3	17.2	
#		42,000	38,000	33,000	29,000	25,000	20,000	13,0	000	4,000	1,000	



### Kappa 400 SR KSR401, KSR403

### **Product Characteristics**

app	a 400 SK K	SK401, KSK	403						Produc	t Character	ISTICS	
US	Market Release		Feb-98	8 Malfur	ctions (US)			4	NBG Co	de		SSI/R
Reg	gistered US Impl	lants	15,000	Thera	py Function	Not Compro	mised	3	Serial N	umber Prefix		PEU, PGD
Est	imated Active U	S Implants	3,000	) Ele	ectrical Comp	onent		3	Estimat	ed Longevity		See page 71
No	rmal Battery De	pletions (US)	714	Thera	py Function	Compromise	ed	1				
Ad	visories		None	e Ele	ectrical Interc	onnect		1				
_ 10	)() =====											
Device Survival Probability (%)	90											
oility									-			
bak	30											
Pre 1	70											
is exis	50									1		
Sur	50											
vice 7	10											
De	30											
	20											
2												
	0	Ι	2 3		10.00		6	/			9	10
	Years After	rimplant			nal Battery [	pepletion	Incl	uding	g Norma	l Battery De	pietion	
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yı		8 yr	9 yr	at 112 mo
	%	100.0	100.0	100.0	100.0	100.0	100.0	100	0.0	100.0	100.0	100.0

99.3

7,000

98.1

5,000

93.7

3,000

72.7

2,000

37.3

300

22.9

100

Effective Sample Size

99.9

13,000

99.9

11,000

%

99.8

9,000

99.5

8,000

IC 1.4.	ulas Dalasas		lan	00 14-	lf+: / LIC	`		27	NDC C-	. al a		DDD/00
	rket Release		Jan-		Ifunctions (US			27	NBG Co			DDD/RO
	ered US Imp		24,0		nerapy Function	•	romised	3	Serial N	lumber Pref	İΧ	PHF, PHH, PHG
	ited Active U	•	4,0		Electrical Co	•		3				
		pletions (US)	1,8	58 <b>T</b> ł	nerapy Function	on Comprom	ised	24	Estimat	ed Longevit	ty	See page 7
	<mark>ories: See pa</mark> red Power S	ge 147 – 2002	Potential		Electrical Co	•		2				
ractu	red Power 3	upply wires			Electrical Inte	erconnect ns related to adv	icory)	22				
					(12 manunction	is related to day	1301 y)					
100												
90												
80									1			
70												
60												
50										1		
40										1		
30												
20										1		
0	,		2	3	4	5	6	7		8	9	10
	Years Afte	rımpıant	E>	cluding N	ormal Batter	y Depletion	11	nciudin	g Norma	al Battery D	epletion	
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 y	r	8 yr	at 104 mo	
%		100.0	100.0	100.0	99.9	99.9	99.9	99.	.8	99.8	99.8	
%		99.9	99.9	99.8	99.5	98.8	96.8	88	.2	59.8	22.8	
#	Effective Sam	21,000	19,000	17,000	15,000	13,000	11,000	9,00	00	2,000	200	

Mar-01

14,000

6,000

333

### Kappa 600 DR KDR651, KDR653

**US Market Release** 

Registered US Implants

**Estimated Active US Implants** 

Normal Battery Depletions (US)

Fractured Power Supply Wires

Advisories: See page 147 - 2002 Potential

Malfunctions (US)	12
Therapy Function Not Compromised	2
Electrical Component	1
Possible Early Battery Depletion	1
Therapy Function Compromised	10
Electrical Component	1

Electrical Interconnect (1 malfunction related to advisory)

### **Product Characteristics**

9

NBG Code	DDD/RO
Serial Number Prefix	PLJ, PLK
Estimated Longevity	See page 71

JO											
90											
30							*				
70											
0	)	1	2	3	4	5	6	7	8	9	10
0	Years After	1 Implant	2 E	3 xcluding No	4 ormal Batter	5 y Depletion	_	7 luding Nor	_		
0		1 Implant 1 yr	2 E	3 xcluding No   3 yr	4 ormal Batter 4 yr		_	7 luding Nori 7 yr	_		
			1	1		y Depletion	Inc	_	_		
% %		1 yr	2 yr	3 yr	4 yr	y Depletion 5 yr	6 yr	7 yr	_		

### Kappa 700 D KD701, KD703, KD706

US Market Release	Jan-99
Registered US Implants	300
<b>Estimated Active US Implants</b>	100
Normal Battery Depletions (US)	9

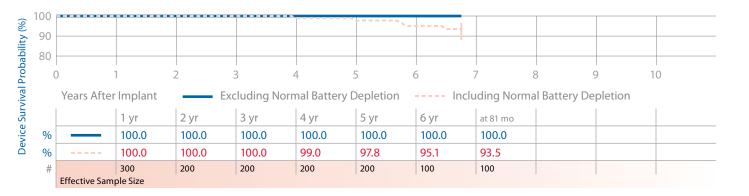
Advisories: See page 147 – 2002 Potential Fractured Power Supply Wires

Malfunctions (US)	0
Therapy Function Not Compromised	0
Therapy Function Compromised	0

### NBG Code DDD Serial Number Prefix PHK

**Product Characteristics** 

Serial Number Prefix PHK
Estimated Longevity See page 72

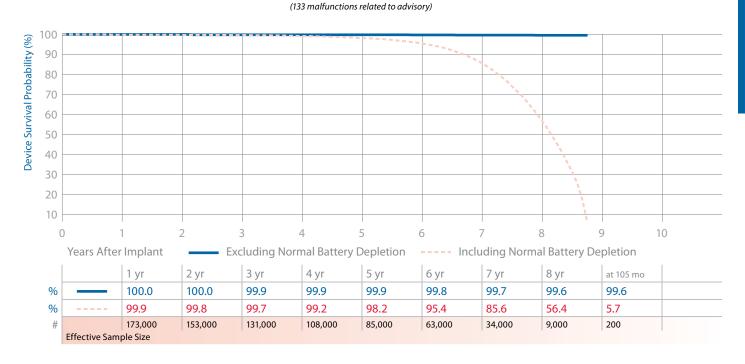




### Kappa 700 DR KDR701, KDR703, KDR706

US Market Release	Feb-99	Malfunctions (US)	277
Registered US Implants	192,000	Therapy Function Not Compromised	28
<b>Estimated Active US Implants</b>	68,000	Battery	1
Normal Battery Depletions (US)	9,076	Electrical Component	21
Advisories: See page 147 – 2002 Po	otential	Electrical Interconnect	1
Fractured Power Supply Wires		Possible Early Battery Depletion	3
		Other	2
		Therapy Function Compromised	249
		Electrical Component	15
		Electrical Interconnect	234

NBG Code	DDD/RO
Serial Number Prefix	PGU, PGY, PGW
Estimated Longevity	See page 72



### **IPG**

### Kappa 700 DR KDR721

US Market Release	Feb-99
Registered US Implants	10,000
<b>Estimated Active US Implants</b>	400
Normal Battery Depletions (US)	1,144

Advisories: See page 147 – 2002 Potential Fractured Power Supply Wires

### Malfunctions (US) Therapy Function Not Compromised Electrical Component Therapy Function Compromised Electrical Interconnect

(4 malfunctions related to advisory)

### **Product Characteristics**

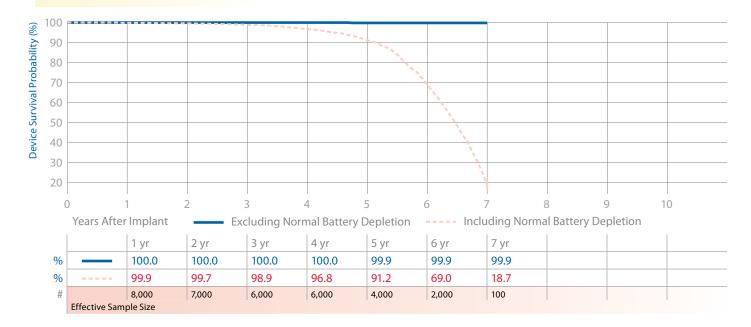
5

1

4

4

NBG Co	de	DDD/RO
Serial N	umber Prefix	PGR
Estimat	ed Longevity	See page 72

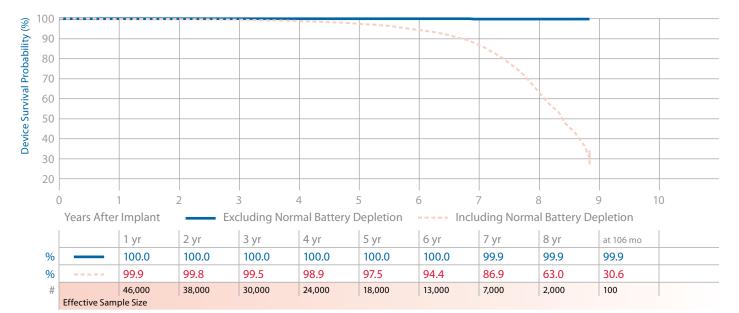


### Kappa 700 SR KSR701, KSR703, KSR706

US Market Release	Feb-99
Registered US Implants	55,000
Estimated Active US Implants	16,000
Normal Battery Depletions (US)	1,685
Advisories	None

Malfunctions (US)	11
Therapy Function Not Compromised	3
Electrical Component	2
Possible Early Battery Depletion	1
Therapy Function Compromised	8
Electrical Component	4
Flectrical Interconnect	4

NBG Code	SSI/R
Serial Number Prefix	PHT, PHW, PHU
Estimated Longevity	See page 72





### Kappa 700 VDD KVDD701

Jan-99	Malfu
2,000	Ther
200	Ther
129	Е
	2,000

Advisories: See page 147 – 2002 Potential Fractured Power Supply Wires

### unctions (US) 3 rapy Function Not Compromised 0 rapy Function Compromised 3 Electrical Interconnect 3 (3 malfunctions related to advisory)

### **Product Characteristics**

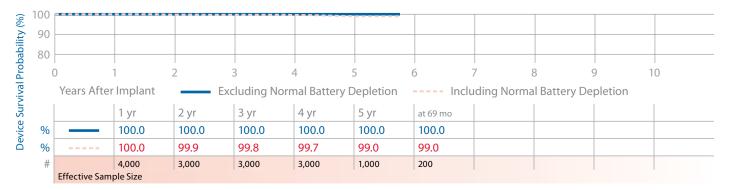
NBG Code	VDD/RO
Serial Number Prefix	PHP
Estimated Longevity	See page 72

00											
90											
80											
70							``				
60								1			
50											
40											
(	)	1 2	2 :	3 4	4	5 (	6	7	8	9	10
	Years After	Implant	Exc	luding Norn	nal Battery [	Depletion	Inclu	iding Norma	al Battery De	pletion	
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	at 90 mo		
%		99.9	99.9	99.9	99.8	99.8	99.7	99.7	99.7		
%		99.7	99.7	99.4	98.9	98.5	94.8	69.4	51.9		
		1,000	1,000	1,000	1,000	1,000	1,000	300	100		

### Kappa 800 DR KDR801, KDR803

### **US Market Release** Jan-02 Registered US Implants 4,000 **Estimated Active US Implants** 2,000 Normal Battery Depletions (US) 12 Advisories None

Malfunctions (US)	0	NBG Code	DDD/RO
Therapy Function Not Compromised	0	Serial Number Prefix	PKW, PKY
Therapy Function Compromised	0	Estimated Longevity	See page 72



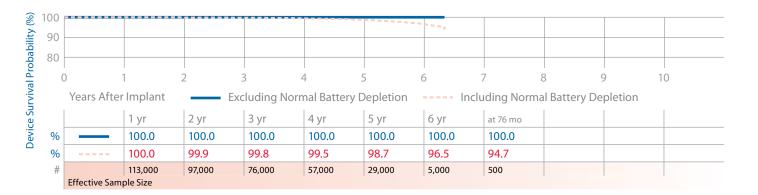
### Kappa 900 DR KDR901, KDR903, KDR906

US Market Release	Jan-02
Registered US Implants	125,000
Estimated Active US Implants	76,000
Normal Battery Depletions (US)	486
Advisories	None

Malfunctions (US)	24
Therapy Function Not Compromised	11
Electrical Component	11
Therapy Function Compromised	13
Electrical Component	8
Electrical Interconnect	5

### **Product Characteristics**

NBG Code	DDD/RO
Serial Number Prefix	PKM, PKN, PKP
Estimated Longevity	See page 72



### Kappa 920 DR KDR921

US Market Release	Jan-02
Registered US Implants	16,000
Estimated Active US Implants	7,000
Normal Battery Depletions (US)	536
Advisories	None

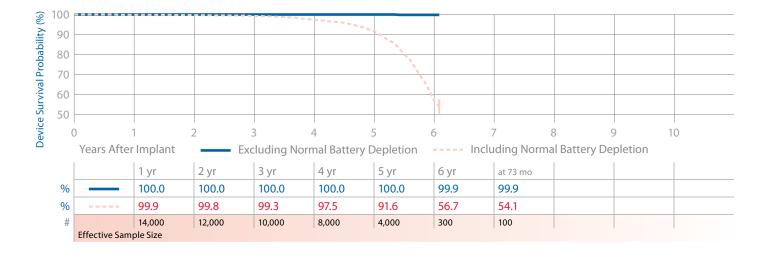
Malfunctions (US)	
Therapy Function Not Comprom	nised
Therapy Function Compromised	i
Electrical Interconnect	

### **Product Characteristics**

2 0 2

2

NBG Code	DDD/RO
Serial Number Prefix	PKR
Estimated Longevity	See page 72

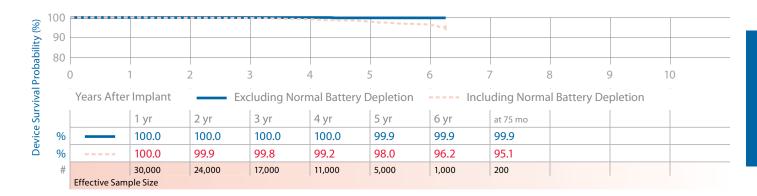




### Kappa 900 SR KSR901, KSR903, KSR906

US Market Release	Jan-02	Malfunctions (US)	10	NBG Code
Registered US Implants	37,000	Therapy Function Not Compromised	8	Serial Number
Estimated Active US Implants	19,000	Electrical Component	7	
Normal Battery Depletions (US)	133	Possible Early Battery Depletion	1	Estimated Long
Advisories	None	Therapy Function Compromised	2	
		Electrical Interconnect	2	

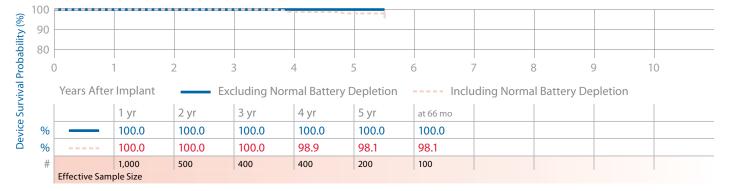
## Product Characteristics NBG Code VVEV Serial Number Prefix PLF, PLG, PLH Estimated Longevity See page 72



### Kappa 900 VDD KVDD901

US Market Release	Jan-02
Registered US Implants	1,000
Estimated Active US Implants	300
Normal Battery Depletions (US)	5
Advisories	None

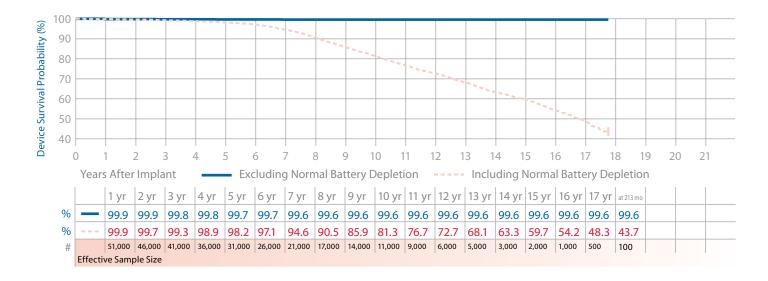
Malfunctions (US)	0	NBG Code	VDD
Therapy Function Not Compromised	0	Serial Number Prefix	PLE
Therapy Function Compromised	0	Estimated Longevity	See page 72



### Legend 8416, 8417, 8417M, 8418, 8419

### **Product Characteristics**

US Market Release	Aug-89	Malfunctions (US)	143	NBG Code	SSIRO
Registered US Implants	57,000			Serial Number Prefix	XT, WJ, WN,
<b>Estimated Active US Implants</b>	2,000				ZT
Normal Battery Depletions (US)	2,841			<b>Estimated Longevity</b>	See page 72
Advisories	None				



### Legend II 8424, 8426, 8427

Effective Sample Size

Nov-91	Malfunctions (US)	36	NBG Code	SSIRO
59,000			Serial Number Prefix	2P, 2T, 2U
4,000			Estimated Longevity	See page 7
2,089				
None				
			**************************************	
	59,000 4,000 2,089	59,000 4,000 2,089 None	59,000 4,000 2,089 None	59,000 Serial Number Prefix 4,000 Estimated Longevity None





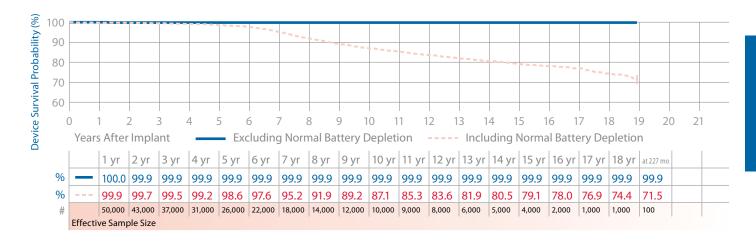
Advisories

### Minix/Minix ST 8330, 8331, 8331M, 8340, 8341, 8341M, 8342

### **Product Characteristics**

US Market Release	Dec-89	Malfunctions (US)	49	NBG Code	SSIRO
Registered US Implants	58,000			Serial Number Prefix	2P, 2T, 2U
<b>Estimated Active US Implants</b>	4,000			Estimated Longevity	See page 72
Normal Battery Depletions (US)	1,559				

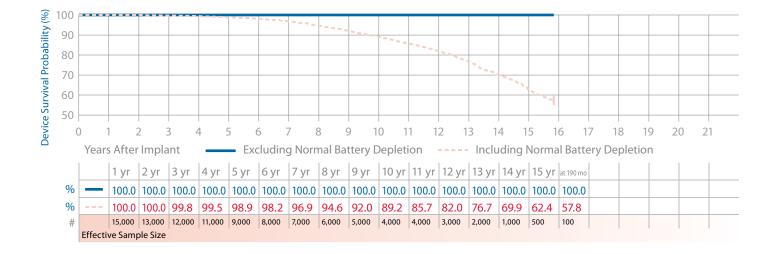
Advisories: See page 152 – 1991 Potential Delayed Restoration of Permanent Settings



### Minuet 7107, 7108 Product Characteristics

None

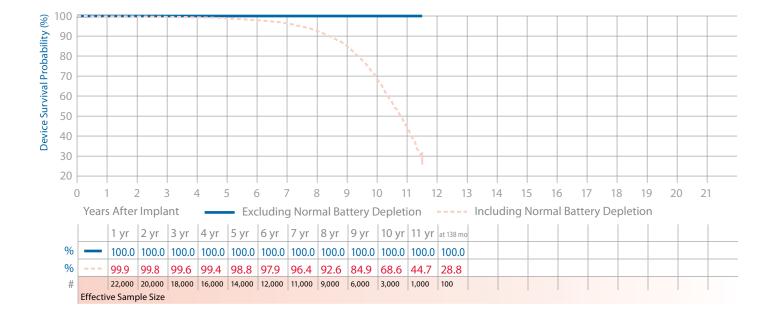
US Market Release	Mar-92	Malfunctions (US)	4	NBG Code	DDDCO
Registered US Implants	17,000			Serial Number Prefix	1Z1, 2G1
<b>Estimated Active US Implants</b>	2,000			Estimated Longevity	See page 72
Normal Battery Depletions (US)	712				



### Preva DR 7088, 7089

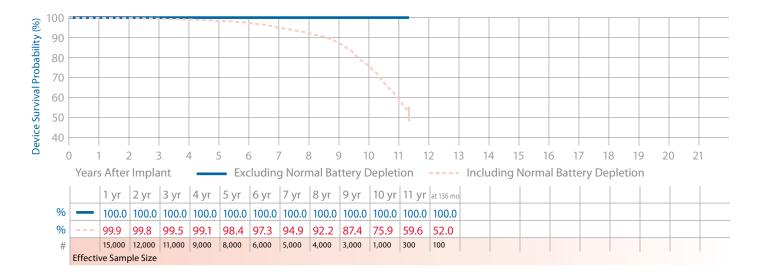
### **Product Characteristics**

US Market Release	Jul-96	Malfunctions (US)	4	NBG Code	DDD/RO
Registered US Implants	26,000			Serial Number Prefix	PGJ, PGK
<b>Estimated Active US Implants</b>	4,000			Estimated Longevity	See page 72
Normal Battery Depletions (US)	1,512				
Advisories	None				



### Preva SR 8088, 8089

US Market Release	Jul-96	Malfunctions (US)	1	NBG Code	SSI/R
Registered US Implants	18,000			Serial Number Prefix	PGL, PGM
<b>Estimated Active US Implants</b>	2,000			Estimated Longevity	See page 72
Normal Battery Depletions (US)	596				
Advisories	None				



None

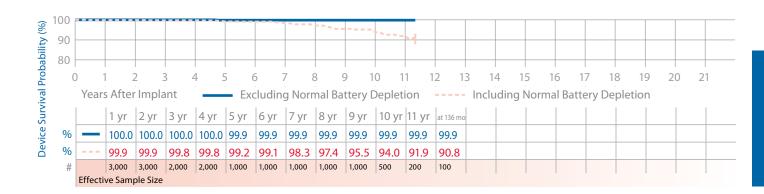


### **Prevail S** 8085, 8086

Advisories

### **Product Characteristics**

US Market Release	Oct-95	Malfunctions (US)	1	NBG Code	SSI
Registered US Implants	4,000			Serial Number Prefix	PGL, PGM
Estimated Active US Implants	1,000			Estimated Longevity	See page 72
Normal Battery Depletions (US)	31				



### Prodigy D 7864, 7865, 7866

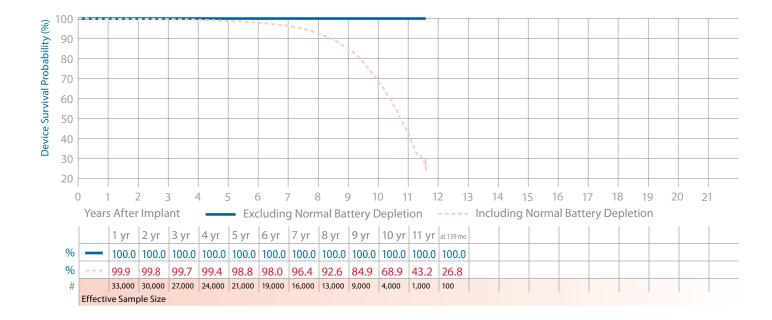
S Market Release	Oct-95	Malfunctions (US)		0	NBG Code	DDDCO
egistered US Implants	3,000				Serial Number Prefix	PDL, PDM,
stimated Active US Implants	400					PDN
ormal Battery Depletions (US)	140				Estimated Longevity	See page 73
dvisories	None					
90						
00						
80						
70			1			

7	Years	s After	Impla	nt		Excluding Normal Battery Depletion								Inclu	ıding l	Vorma	al Batte	ery De	pletio	n	
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	at 135 mo								
%	_	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0								
%		99.9	99.7	99.4	98.8	98.6	97.6	96.8	95.1	88.8	75.2	59.7	55.9								
#		2,000	2,000	2,000	2,000	2,000	1,000	1,000	1,000	1,000	400	100	100								
	Effecti	ve Samp	ole Size																		

### Prodigy DR 7860, 7861, 7862

### **Product Characteristics**

US Market Release	Oct-95	Malfunctions (US)	11	NBG Code	DDD/RO
Registered US Implants	38,000			Serial Number Prefix	PDH, PDJ,
<b>Estimated Active US Implants</b>	5,000				PDK
Normal Battery Depletions (US)	2,116			Estimated Longevity	See page 73
Advisories	None				



### Prodigy S 8164, 8165, 8166

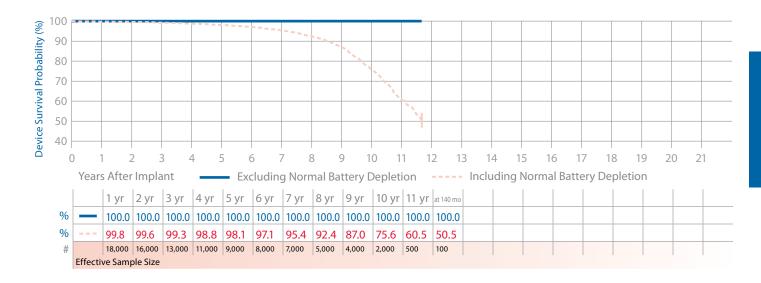
JS Ma	rket Re	lease				Oct-9	5	Malfun	ctions	(US)				C	)	NBG Co	ode				SS	SIC	
Regist	ered U	S Impl	ants			2,00	0									Serial N	lumbe	r Prefi	Х			G, Pl	EH,
Estima	ated Ad	tive US	5 Impla	nts		30	0														PI	<u>-</u> J	
Norma	al Batte	ry Dep	oletion	s (US)		3	5									Estima	ted Lor	ngevit	y		Se	ee pa	ge 7
Advisc	ories					Non	e																
100									=														
90 -											****									_			
80 -											-	•											
0	) 1		) :	)	1 5			7 8		) 1	 ∩ 1	1 1	) )	] 2 1,	4	 1 <i>5</i> 1	  6	17	10	19	20	21	1
O		Δftor	Impla		† .	_ Evc	ludina		-	ttany Γ	Depleti	ion		ا امران	t dina	Norma		17 :arv D	anla		20	_	ı
	rears						_								unig	INOTITIE	ai Datt	.cry D	cpic	LIOIT			
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	at 134 mo										
%	_	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0										
%		99.8	99.8	99.7	99.1	99.1	99.1	98.8	97.2	93.3	90.1	84.6	84.6										
#		2,000	1,000	1,000	1,000	1,000	1,000	1,000	1,000	400	300	100	100										
			ole Size																				



### Prodigy SR 8158, 8160, 8161, 8162

### **Product Characteristics**

US Market Release	Oct-95	Malfunctions (US)	5	NBG Code	SSI/R
Registered US Implants	22,000			Serial Number Prefix	PEM, PED,
<b>Estimated Active US Implants</b>	3,000				PEE, PEF
Normal Battery Depletions (US)	728			Estimated Longevity	See page 73
Advisories	None				



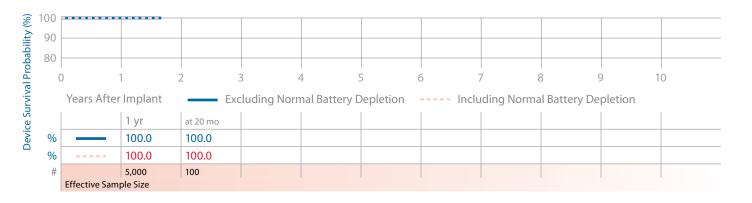
### Sensia DR SEDR01, SED01

US Ma	arket Release		Jul-0	6	Malfur	ctions (US)			0	NBG Co	de		SSI/R	
Regist	tered US Impl	lants	30,00	0	Thera	py Functio	n Not Cor	mpromised	0	Serial N	umber Prefi	x	DDD, DD	DDF
Estima	ated Active U	S Implants	27,00	0	Thera	py Functio	n Compre	omised	0	Estimat	ed Longevit	у	See page	e 7
Norm	al Battery De	pletions (US)		0										
Advis	ories		Non	e										
100														
90														
90														
80														_
	0	1	2	3	4	1	5	6	7	3	3	9	10	
	Years After	r Implant	- Exc	cludi	ng Norn	nal Battery	/ Depletion	on	Includin	ng Norma	l Battery D	epletion	1	
		1 yr	at 20 mo											
%		100.0	100.0											_
%		100.0	100.0											
#		9,000	300											
	Effective Sam	ple Size											·	

### Sensia SR SESR01, SES01

### **Product Characteristics**

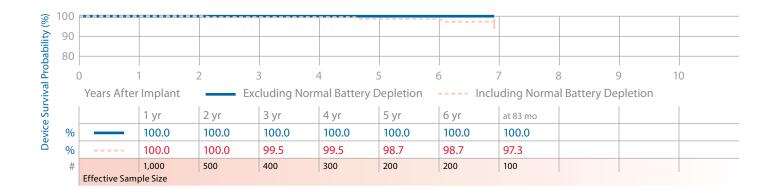
US Market Release	Jul-06	Malfunctions (US)	0	NBG Code	SSIR, SSI
Registered US Implants	19,000	Therapy Function Not Compromised	0	Serial Number Prefix	PWR, PWS
Estimated Active US Implants	16,000	Therapy Function Compromised	0	Estimated Longevity	See page 73
Normal Battery Depletions (US)	0				
Advisories	None				



### Sigma 100 S SS103, SS106

Advisories: See page 145 – 2005 Potential Separation of Interconnect Wires

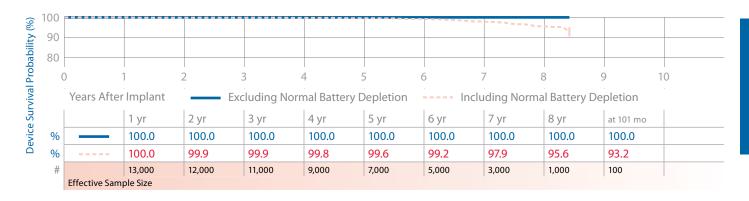
US Market Release	Aug-99	Malfunctions (US)	0	NBG Code	SSI
Registered US Implants	1,000	<b>Therapy Function Not Compromised</b>	0	Serial Number Prefix	PJG, PJH
Estimated Active US Implants	200	Therapy Function Compromised	0	Estimated Longevity	See page 73
Normal Battery Depletions (US)	4				





### Sigma 200 DR SDR203

US Market Release	Aug-99	Malfunctions (US)	5	NBG Code	DDD/RO
Registered US Implants	16,000	Therapy Function Not Compromised	1	Serial Number Prefix	PJD
Estimated Active US Implants	7,000	Electrical Component	1	Estimated Longevity	See page 73
Normal Battery Depletions (US)	73	Therapy Function Compromised	4		
Advisories: See page 145 – 2005 Po	tential	<b>Electrical Component</b>	1		
Separation of Interconnect Wires		Electrical Interconnect (1 malfunction related to advisory)	3		



### Sigma 200 SR SSR203

US Market Release Sep-99
Registered US Implants 12,000
Estimated Active US Implants 4,000
Normal Battery Depletions (US) 42

Malfunctions (US)

Therapy Function Not Compromised

Therapy Function Compromised

Electrical Interconnect
(3 malfunctions related to advisory)

**Product Characteristics** 

4

0

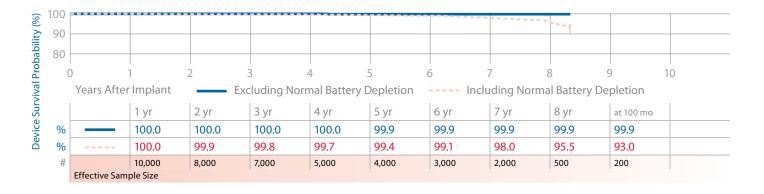
4

4

**Product Characteristics** 

NBG Code SSI/R Serial Number Prefix PJG Estimated Longevity See page 73

Advisories: See page 145 – 2005 Potential Separation of Interconnect Wires



### Sigma 300 DR SDR303, SDR306

US Market Release	Aug-99
Registered US Implants	106,000
Estimated Active US Implants	57,000
Normal Battery Depletions (US)	260
Advisories: See page 145 – 2005 F	otential

Malfunctions (US)	55
Therapy Function Not Compromised	5
Electrical Component	4
Possible Early Battery Depletion	1
Therapy Function Compromised	50
Electrical Component	6

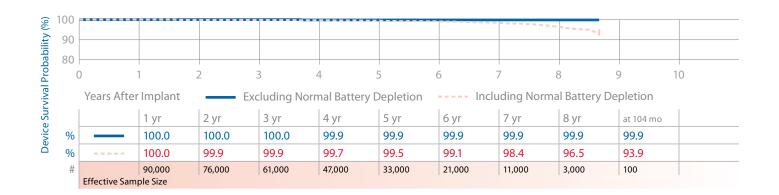
44

**Electrical Interconnect** 

(15 malfunctions related to advisory)

### **Product Characteristics**

NBG Code	DDD/RO
Serial Number Prefix	PJD, PJE
Estimated Longevity	See page 73



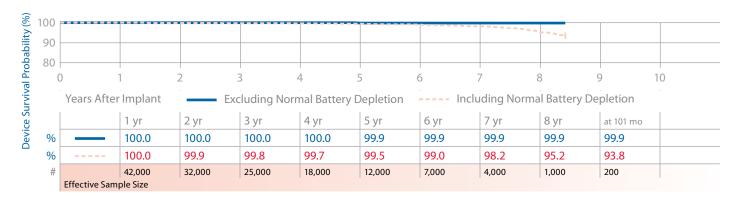
### Sigma 300 SR SSR303, SSR306

US Market Release	Sep-99
Registered US Implants	54,000
Estimated Active US Implants	22,000
Normal Battery Depletions (US)	121
Advisories: See page 145 - 2005 Pote	ntial

Advisories: See page 145 – 2005 Potential Separation of Interconnect Wires

Malfunctions (US)	11
Therapy Function Not Compromised	1
Electrical Component	1
Therapy Function Compromised	10
Electrical Component	3
Electrical Interconnect (4 malfunctions related to advisory)	7

NBG Code		SSI/R
Serial Number Pr	refix	PJG, PJH
Estimated Longe	evity	See page 73



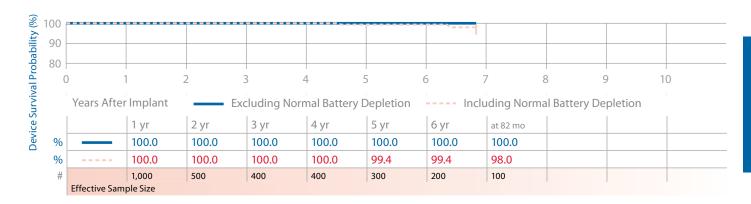


### Sigma 300 VDD SVDD303

### **Product Characteristics**

US Market Release	Sep-99	Malfunctions (US)	0	NBG Code	VDDD
Registered US Implants	1,000	Therapy Function Not Compromised	0	Serial Number Prefix	PJD
Estimated Active US Implants	300	Therapy Function Compromised	0	Estimated Longevity	See page 73
Normal Battery Depletions (US)	3				

Advisories: See page 145 – 2005 Potential Separation of Interconnect Wires



### Thera-i D 7964i, 7965i, 7966i

**Effective Sample Size** 

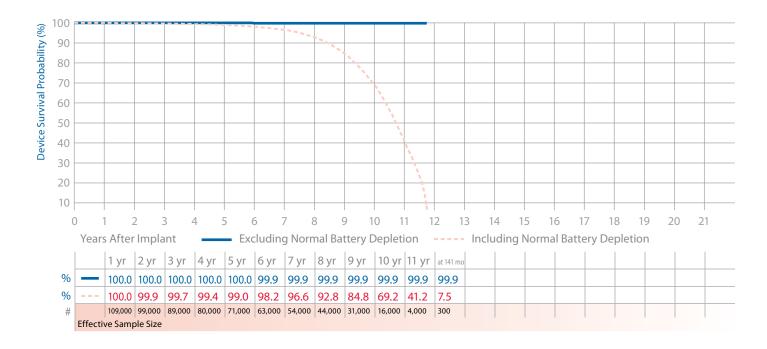
US Ma	rket Re	elease				Oct-9	5	Malfur	nctions	(US)				1		NBG Co	ode				DD	DCO
Regist	ered U	JS Impl	ants			3,00	0									Serial N	lumbe	er Pref	ix			E, PDF,
Estima	ated A	ctive U	S Impla	ants		40	0														PD	G
Norma	al Batte	ery Dep	oletion	s (US)		18	0									Estima	ted Lo	ngevit	ty		See	e page 73
Adviso	ories					Non	e															
100																						
90																						
80																						
70											1											
60																						
50												1										
40												1										
0	)	1 2	2 3	3 4	4 !	5 6	5 7	7 8	3 9	9 1	0 1	1 1	2 1	3 14		15	16	17	18	19	20	21
	Years	s After	Impla	nt		<b>E</b> xc	ludin	g Norr	nal Ba	ttery [	Deplet	ion		Includ	ling	Norma	al Bati	tery D	eple	tion		
			2 yr	3 yr	4 yr	5 yr							at 140 mo						i			
%			100.0	-	100.0	-	-	-	-	-	_		100.0									
%		100.0		99.5	99.4	99.0	97.5	96.2	93.8	87.8	78.5	61.4	46.0									
#					2,000								100									

### Thera-i DR 7960i, 7961i, 7962i

Advisories

### **Product Characteristics**

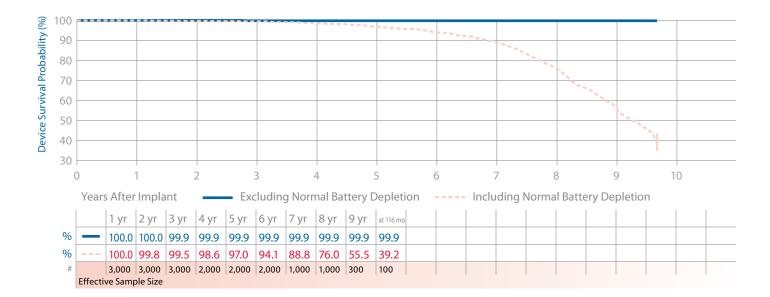
US Market Release	Oct-95	Malfunctions (US)	50	NBG Code	DDD/RO
Registered US Implants	122,000			Serial Number Prefix	PDB, PDC,
<b>Estimated Active US Implants</b>	10,000				PDD
Normal Battery Depletions (US)	8,841			Estimated Longevity	See page 73
Advisories	None				



### Thera-i DR 7968i Product Characteristics

None

US Market Release	Jul-96	Malfunctions (US)	3	NBG Code	DDD/RO
Registered US Implants	4,000			Serial Number Prefix	PGH
Estimated Active US Implants	200			Estimated Longevity	See page 73
Normal Battery Depletions (US)	282				

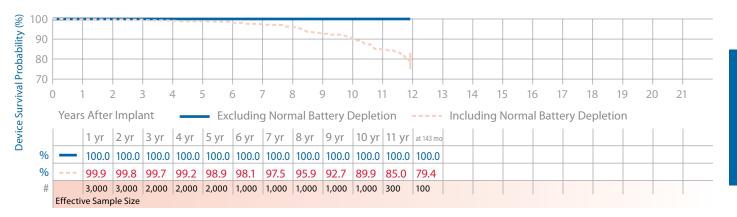


### **IPG**

### Thera-i S 8964i, 8965i, 8966i

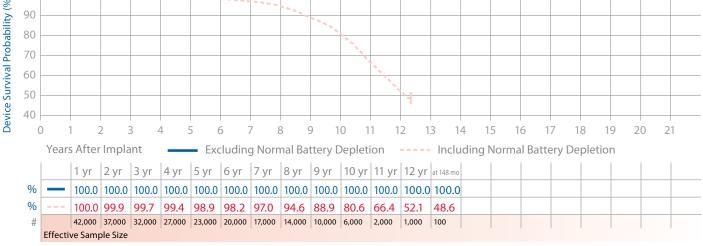
### **Product Characteristics**

US Market Release	Oct-95	Malfunctions (US)	1	NBG Code	SSIR
Registered US Implants	4,000			Serial Number Prefix	PDY, PEA,
<b>Estimated Active US Implants</b>	1,000				PEB
Normal Battery Depletions (US)	74			Estimated Longevity	See page 73
Advisories	None				



### Thera-i SR 8960i, 8961i, 8962i

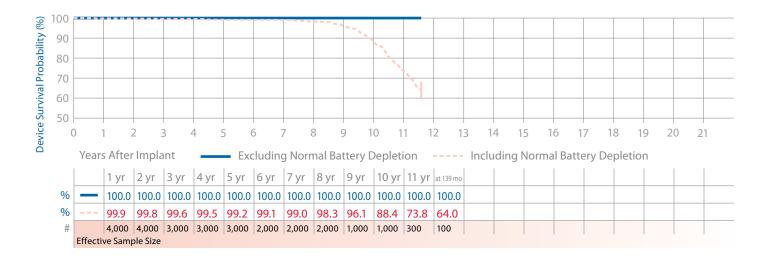
	US Market Release	Oct-95	Malfunctions (US)	7	NBG Code	SSIR
	Registered US Implants	50,000			Serial Number Prefix	PDU, PDV,
	<b>Estimated Active US Implants</b>	6,000				PDW
	Normal Battery Depletions (US)	1,792			Estimated Longevity	See page 73
	Advisories	None				
(3	100					



### Thera-i VDD 8968i

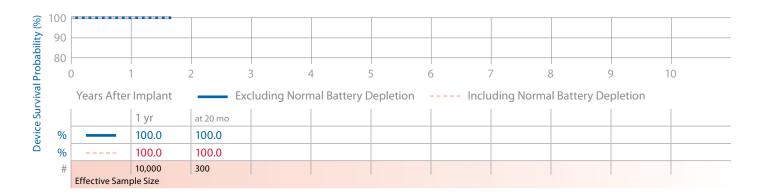
### **Product Characteristics**

US Market Release	Mar-96	Malfunctions (US)	0	NBG Code	VDD
Registered US Implants	5,000			Serial Number Prefix	PEC
Estimated Active US Implants	1,000			Estimated Longevity	See page 73
Normal Battery Depletions (US)	151				
Advisories	None				



### Versa DR vedR01 Product Characteristics

US Market Release	Jul-06	Malfunctions (US)	1	NBG Code	DDDR
Registered US Implants	29,000	<b>Therapy Function Not Compromised</b>	1	Serial Number Prefix	PWH
<b>Estimated Active US Implants</b>	27,000	<b>Electrical Component</b>	1	Estimated Longevity	See page 73
Normal Battery Depletions (US)	0	Therapy Function Compromised	0		
Advisories	None				





# Device Survival Summary (95% Confidence Interval)

The following table shows IPG device survival estimates with 95% confidence intervals. Estimates are shown both with and without normal battery depletions included.

		16 yr														
		14 yr														
		12 yr														
		10 yr														
		8 yr														
		6 yr 7									99.9 +0.1/-0.1 at 64 mo	63.3 +5.4/-6.0 at 64 mo				
													0.1 m o	-0.4 mo	0.0 mo	1.7 mo
(%		5 yr									99.9	84.0 +2.1/-2.3	100.0 1 +0.0/-0.1 at 53 mo	99.2 +0.3/-0.4 at 53 mo	100.0 0 +0.0/-0.0 at 52 mo	96.6 +1.1/-1.7 at 52 mo
bility (		4 yr									99.9 +0.1/-0.1	98.2 +0.3/-0.4	100.0	99.3 +0.2/-0.3	100.0	97.3 +0.8/-1.2
al Proba	plant	3 yr									100.0	99.6 +0.1/-0.1	100.0	99.9 +0.1/-0.1	100.0 +0.0/-0.0	99.3
Device Survival Probability (%)	Years After Implant	2 yr	100.0 +0.0/-0.0 at 21 mo	100.0 +0.0/-0.0 at 21 mo	100.0 +0.0/-0.0 at 18 mo	100.0 +0.0/-0.0 at 18 mo	100.0 +0.0/-0.1 at 20 mo	100.0 +0.0/-0.1 at 20 mo	100.0 +0.0/-0.0 at 20 mo	100.0 +0.0/-0.0 at 20 mo	100.0	99.9	100.0	100.0 +0.0/-0.0	100.0	99.7
Device	Years A	1 yr	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	99.9	100.0	100.0	100.0	100.0
			Excluding ial Battery Depletion	Including nal Battery Depletion	Excluding lal Battery Depletion	Including nal Battery Depletion	Excluding nal Battery Depletion	Including nal Battery Depletion	Excluding hal Battery Depletion	Including ial Battery Depletion	Excluding Ial Battery Depletion	Including nal Battery Depletion	Excluding al Battery Depletion	Including al Battery Depletion	ding ttery ttion	Including ial Battery Depletion
			Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion
()	Įe	ъtоТ	4 Exclu Normal Ba Depl	Incl Normal Be Depl	0 Excli Normal Ba	Inclu Normal Ba Depl	1 Excl Normal Ba	Incl Normal Ba Dep	O Exclu Normal Ba Depl	Incli Normal Ba Depl	10 Excl Normal Ba Depl	Inclu Normal Ba Depl	1 Exclu Normal Ba Deple	Inclu Normal Bat Deple	0 Exclu Normal Ba	Inclu Normal Ba Deple
ns (US)	npromised	no⊃		Incl Normal Ba Depl	Norm	Incle Normal Ba Depl	Norm	Incl Normal B: Dep		Incli Normal Ba Depl		Inclu Normal Ba Depl		Inclu Normal Ba' Deple		Inclu Normal Ba Depk
unctions (US)		no⊃	8 = 4	Incl Normal Ba Depl	0 = 0 Norm	Incli Normal Ba Depl	0 = 1	Ind Normal Bi Dep	0 = 0	Incl Normal Ba Depl	5 = 10	Inclu Normal Ba Depl	- -	Inclu Normal Ba' Deplé	0 = 0	Inclu Normal Ba Depla
Malfunctions (US)	npromised	The fun Toon	4	Indi Normal Ba Depl	= 0 Norm	Incle Normal Ba Depl	= 1 Norm	Ind Normal B: Dep	0	Indi Normal Ba Depl	= 10	Indi Normal Ba Depl		inclu Normal Ba' Deple	0	Indu Normal Ba Depi
Malfunctions (US)	besimonqn srapy tob noito besimonqn	The Con The The Tun Toon	+ 3 = 4	Indi Normal Ba Depl	+ 0 = 0 + Norm	India Normal Ba Normal Ba Depl	+ 0 = 1	Incl Normal Ba Dep	0 = 0 +	Indi Normal Ba Depl	+ 5 = 10	Norm	+	Inclu Normal Bar Deple	0 = 0 +	Inclu Normal Ba Depi
Malfunctions (US)	oletions (US) repy Function npromised repy repy repy repy totion Not bestimored	Acti Mori Dep The Con The Tun Tun Tun Tun Tun		Incli Normal Ba Depti	0 + 0 = Norm	India Normal Ba Normal Ba Depl	1 + 0 = 1 Norm	Incl. Normal B. Dep	0 = 0 + 0	Incl. Normal Ba Dept	5 + 5 = 10	Norm	+ +	Inclu Normal Bar Deple	0 = 0 + 0	Indu Normal Ba Depi
Malfunctions (US)	ive US Inlants Imal Battery Solutions (US) Inspy Function Inspy Function Inspy Function Inspy Function Inspy Function Inspy Insp Inspy Insp Inspy Inspy Insp Inspy Insp Insp Insp Inspy Insp Insp Insp Insp Insp Insp Insp Insp	Esting Honor Inc. Inc. Inc. Inc. Inc. Inc. Inc. Inc.	0 1 + 3 = 4	Incli Normal Ba Dept	0 = 0 + 0 Norm	India Normal Ba Normal Ba Depl	0 1 + 0 = 1 Norm	Incl. Normal B. Dep	0	Incl. Normal Bs	232 5 + 5 = 10	Norm	16 0 + 1 = 1	Inclu Normal Bat Deple	0 + 0 = 0	Indu Normal Ba Depli
Malfunctions (US)	mated by be be maded by be U.S. U.S. U.S. Indiants.  mal Battery mal Battery (CV) to make the man be made by Function been moton with the material	Rejd USI Esti Mori Imp Mori Dep The Con	79,000 0 1 + 3 = 4	Incli Normal Ba Normal Ba Dept	Norm	India Normal Ba Normal Ba Depl	7,000 0 1 + 0 = 1 Norm	Incl. Normal B. Dep	15,000 0 + 0 = 0	Incl. Normal Ba Depl	6,000 232 5 + 5 = 10	Norm	4,000 16 0 + 1 = 1	Inclu Normal Bat Deple	1,000 16 0 + 0 = 0	Indu Normal Ba Depli
Malfunctions (US)	Market ease jistered mplants ve US ve US sinal Battery sinaly Function mpromised mpromised	Regular Regula	86,000 79,000 0 1 + 3 = 4	Incli Normal Ba Normal Ba Dept	7,000 6,000 0 0 + 0 = 0 Norm	India Normal Ba Normal Ba Depl	8,000 7,000 0 1 + 0 = 1 Norm	Incl. Normal B. Dep	$\begin{array}{cccccccccccccccccccccccccccccccccccc$	Incl. Normal Bs	11,000 6,000 232 5 + 5 = 10	see page 156 – Performance note on AT500 Pacing System Follow-Up Protocol Depl	7,000 4,000 16 0 + 1 = 1	Inclu Normal Bat Deple	2,000 1,000 16 0 + 0 = 0	Indu Normal Ba Depli

P	G

continued
Summary
ival
Surv
evice
۵

		14 yr   16 yr																
		12 yr																
		10 yr													99.9 +0.0/-0.0 at 101 mo	17.2 +1.3/-1.3 at 101 mo	100.0 +0.0/-0.1 at 112 mo	22.9 +3.2/-3.1 at 112 mo
		8 yr													99.9	55.3 +1.0/-1.0	100.0	72.7 +1.6/-1.7
		7 yr													99.9	88.6 +0.5/-0.5	100.0	93.7
		6 yr													99.9	97.4 +0.2/-0.2	100.0	98.1 +0.3/-0.4
(		5 yr	100.0 +0.0/-0.0 at 51 mo	99.8 +0.1/-0.1 at 51 mo					100.0 +0.0/-0.0 at 52 mo	99.0 +0.5/-1.0 at 52 mo					99.9	99.1	100.0	99.3
oility (%		4 yr	100.0	99.8 +0.1/-0.1	100.0	98.7 +0.4/-0.6	100.0 +0.0/-0.0 at 37 mo	100.0 +0.0/-0.0 at 37 mo	100.0	99.5 +0.1/-0.2	100.0 +0.0/-0.0 at 39 mo	100.0 +0.0/-0.0 at 39 mo	99.9 +0.1/-0.2 at 37 mo	99.8 +0.1/-0.2 at 37 mo	100.0	99.6 +0.1/-0.1	100.0	99.5
Device Survival Probability (%)	olant	3 yr	100.0	99.9	100.0	99.5 +0.2/-0.2	100.0	100.0	100.0	99.6 +0.1/-0.2	100.0	100.0	99.9	99.8	100.0	99.8	100.0	99.8
Surviva	Years After Implant	2 yr	100.0	100.0	100.0	99.7 +0.1/-0.1	100.0	100.0	100.0	99.9	100.0	100.0	100.0	99.9	100.0	99.9	100.0	99.9
Device	Years A	1 yr	100.0	100.0	100.0	99.9	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	99.9	100.0	99.9
			ng ery on	ng ery on	arg on y	gr yr no	פֿֿבֿב	gr y	פֿֿאַב	gr Z	ם > ב	פֿי אַ פֿ	פֿֿבּב	ם אַ ב	ַסַּ≻בּ	ם לים	ַסַּ≻בּ	פֿר אַ
			Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion
(S	ls	тоТ	9 Excludi Normal Batte Depleti	Includi Normal Batte Depleti	1 Excludi Normal Batte Depleti	Includii Normal Batte Depletii	0 Excludir Normal Batter Depletic	Includir Normal Batte Depletic	3 Excludir Normal Batte Depletic	Includir Normal Batte Depletic	0 Excludin Normal Batte Depletio	Includir Normal Batte Depletic	25 Excludir Normal Batter Depletic	Includin Normal Batter Depletio	22 Excludin Normal Batter Depletio	Includir Normal Batter Depletic	4 Excludin Normal Batter Depletio	Includir Normal Batte Depletic
tions (US)	otion Not npromised	Fun ToD	Norn	Includi Normal Batte Depleti		Includii Normal Batte Depletii	Norn	Includir Normal Batte Depletic		Includir Normal Batte Depletic		Includir Normal Batte Depletic		Includin Normal Batter Depletio		Includir Normal Batte Depletic		Includir Normal Batte Depletic
Malfunctions (US)	npromised	The run <sup>1</sup> Cor	= 9 Norm	includi Normal Batte Depleti	-	Includii Normal Batte Depleti	= 0 Norn	Includir Normal Batte Depletic	m II	Includir Normal Batte Depletic	0 =	Includir Normal Batte Depletic	= 25	Includin Normal Batter Depletio	; = 22	Includir Normal Batte Depletic	4	Includir Normal Batte Depletic
Malfunctions (US)	npromised erapy iction Not npromised	The Cor The The The Tuni	+ 6 = 9 Norm	Includi Normal Batte Depleti	0 +	Includii Normal Batte Depleti	+ 0 = 0 Norn	Includir Normal Batte Depletic	+ 2 = 3	Includir Normal Batte Depletic	0 = 0 +	Includir Normal Batte Depletic	+ 5 = 25	Includin Normal Batter Depletio	+ 13 = 22	Includir Normal Batte Depletic	+ 3 = 4	Includir Normal Batte Depletic
Malfunctions (US)	oletions (US) repy Function mpromised repy repy repy repy repy repy repy repy	Act Imp Mon The Cor Thur Fun Fun Too	3 + 6 = 9 Norm	Includi Normal Batte Depleti	+ 0 "	Includii Normal Batte Depleti	0 + 0 Norn	Includir Normal Batte Depletic	1 + 2 = 3	Includir Normal Batte Depletic	0	Includir Normal Batte Depletic	20 + 5 = 25	Includin Normal Batter Depletio	9 + 13 = 22	Includir Normal Batte	+ + 3 = 4	Includir Normal Batte Depletic
Malfunctions (US)	ive US Inlants Inal Battery Inal Battery Soletions (US) Inapy Function Inpromised Inction Not Inction	Esti Acti Imp Imp Inco Inco Inco Inco Inco Inco Inco Inco	34 3 + 6 = 9 Norm	Includi Normal Batte Depleti	26 1 + 0 = 1	Includii Normal Batte Depleti	500 0 + 0 = 0 Norm	Includir Normal Batte Depletic	20 1 + 2 = 3	Includir Normal Batte Depletic	0     0   + 0   0	Includir Normal Batte Depletic	1 20 + 5 = 25	Includin Normal Batter Depletio	4,679 9 + 13 = 22	Includir Normal Batte	714 1 + 3 = 4	Includir Normal Batte Depletic
Malfunctions (US)	Implants ive US ive US solid in the US solid i	Regl USS Strain Mori Dell The Con The Con	101,000 74,000 34 3 + 6 = 9 Norm	Includi Normal Batte Depleti	12,000  9,000  26  1  +  0  =  1	Includii Normal Batte Depletii	1,000 500 0 0 + 0 = 0 Norm	Includir Normal Batte Depletic	17,000 20 1 + 2 = 3	Includir Normal Batte Depletic	1,000 500 0 + 0 = 0	Includir Normal Batte	71,000 59,000 1 20 + 5 = 25	Includin Normal Batter Depletio	6,000 $4,679$ $9 + 13 = 22$	Includir Normal Batte	15,000 3,000 714 1 + 3 = 4	Includir Normal Batte Depletic
Malfunctions (US)	pease implants imated ive US solid ive US solid imal Battery imal Battery imal Battery (CU) imply Function promised imply West	Region No. 10 State of No. 10	74,000 34 3 + 6 = 9 Norm	Includi Normal Batte Depleti	9,000 26 1 + 0 = 1	Includii Normal Batte Depleti	500 0 + 0 = 0 Norm	Includir Normal Batte Depletic	25,000 17,000 20 1 + 2 = 3	Includir Normal Batte Depletic	0 = 0 + 0 0 005	Includir Normal Batte	59,000 1 20 + 5 = 25	Includin Normal Batter Depletio	47,000  6,000  4,679  9  +  13  =  22	Includir Normal Batte	3,000 714 1 + 3 = 4	Includir Normal Batte Depletic

# **Device Survival Summary** continued

		16 yr														
		14 yr														
		12 yr														
		10 yr	99.8 +0.1/-0.1 at 104 mo	228 +2.5/-2.4 at 104 mo					99.6 +0.0/-0.1 at 105 mo	5.7 +1.2/-1.1 at 105 mo			99.9 +0.0/-0.1 at 106 mo	30.6 +3.6/-3.5 at 106 mo		
		8 yr	99.8	59.8 +1.2/-1.3					99.6 +0.0/-0.1	56.4 +0.6/-0.6			99.9 +0.0/-0.1	63.0 +1.3/-1.4	99.7 +0.2/-0.6 at 90 mo	51.9 +5.1/-5.4 at 90 mo
		7 yr	99.8 +0.1/-0.1	88.2 +0.6/-0.6	99.7 +0.2/-0.4	81.2 +1.9/-2.1	100.0 +0.0/-0.0 at 81 mo	93.5 +3.0/-5.4 at 81 mo	99.7 +0.0/-0.0	85.6 +0.3/-0.3	99.9 +0.0/-0.1	18.7	99.9	86.9 +0.6/-0.6	99.7 +0.2/-0.6	69.4
		6 yr	99.9 +0.0/-0.1	96.8 +0.3/-0.3	99.9 +0.0/-0.1	95.1 +0.5/-0.5	100.0	95.1 +2.4/-4.7	99.8	95.4 +0.1/-0.1	99.9	69.0	100.0	94.4 +0.3/-0.3	99.7 +0.2/-0.6	94.8 +1.3/-1.6
(0		5 yr	99.9 +0.0/-0.1	98.8 +0.2/-0.2	100.0 +0.0/-0.1	98.2 +0.3/-0.3	100.0	97.8 +1.4/-3.6	99.9	98.2 +0.1/-0.1	99.9	91.2 +0.7/-0.8	100.0	97.5 +0.2/-0.2	99.8 +0.1/-0.5	98.5
bility (%		4 yr	99.9	99.5 +0.1/-0.1	100.0	99.4 +0.1/-0.2	100.0	99.0 +0.8/-3.1	99.9 +0.0/-0.0	99.2	100.0	96.8	100.0	98.9 +0.1/-0.1	99.8 +0.1/-0.5	98.9
al Proba	plant	3 yr	100.0	99.8 +0.0/-0.1	100.0+0.0/-0.0	99.8 +0.1/-0.1	100.0	100.0 +0.0/-0.0	99.9	99.7	100.0 +0.0/-0.1	98.9 +0.2/-0.3	100.0	99.5	99.9 +0.1/-0.4	99.4
Device Survival Probability (%)	Years After Implant	2 yr	100.0 +0.0/-0.0	99.9 +0.0/-0.1	100.0	99.9	100.0	100.0 +0.0/-0.0	100.0	99.8 +0.0/-0.0	100.0	99.7	100.0	99.8 +0.0/-0.0	99.9 +0.1/-0.4	99.7
Device	Years /	1 yr	100.0	99.9	100.0	100.0 +0.0/-0.1	100.0	100.0 +0.0/-0.0	100.0	99.9	100.0	99.9	100.0	99.9	99.9 +0.1/-0.4	99.7
			פֿ ≻ ב	ary on	gr yo	ng ery on	ery ion	ling tery tion	in g ion	ing ery ion	ery ion	ing ery ion	in g ion	ing ery ion	ling tery tion	ing ery ion
			Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion
(5/	ls	toT .	27 Excludir Normal Batte Depletic		12 Excludi Normal Batto Depleti		0 Excludi Normal Batt, Depleti	Norm	277 Exclud Normal Batt	Norm	5 Exclud Normal Batt Deplet	Norm	11 Exclud Normal Batt	Includ Normal Batt Deplet	3 Exclud Normal Batt Deplet	(3) Includ Normal Batt Deplet
tions (US)	iction Not npromised	nu1 ToD	Norn			æ.		Norm		Norm	Norm	Norm		Includ Normal Batt Deplet	Norm	Norm
Malfunctions (US)	pesimorqn	The Tun Too	= 27 Norn		= 12		0	Norm	+ 28 = 277	+ (0) = (133) Norm ory-related subset)	5 Norm	(0) = (4) Normelated subset)	=	Includ Normal Batt Deplet	= 3 Norm	= (3) Norm
Malfunctions (US)	npromised seapy setion Not mpromised	The Con The The The	+ 3 = 27 Norn	$\frac{(12)}{\text{advisory-related subset}} = \frac{(12)}{\text{advisory-related subset}}$	+ 2 = 12	$\frac{(1)}{(advisory-related subset)}$	0	(0) + (0) = (0) Norm (advisory-related subset)	28 = 277	$\frac{(133) + (0)}{\text{Norm}}$	+ 1 = 5 Norm	$\frac{(4) + (0)}{(advisory-related subset)} = (4)$	+ 3 11	Includ Normal Batt Deplet	+ 0 = 3	(3) + (0) = (3) Norm
Malfunctions (US)	ive US sharts mal Battery cletions (US) srapy Function mpromised srapy srapy notion Not mpromised	Hori Dep The Con The Fun Fun Con	1,858 24 + 3 = 27 Norn	$\frac{(12)}{\text{advisory-related subset}} = \frac{(12)}{\text{advisory-related subset}}$	333 10 + 2 = 12	$\frac{(1)}{(advisory-related subset)}$	0 = 0 + 0	(0) + (0) = (0) Norm (advisory-related subset)	9,076 249 + 28 = 277	$\frac{(133) + (0)}{\text{Norm}}$	1,144 4 + 1 = 5 Norm	$\frac{(4) + (0)}{(advisory-related subset)} = (4)$	1,685 8 + 3 = 11	Includ Normal Batt Deplet	129 3 + 0 = 3 Norm	(3) + (0) = (3) Norm
Malfunctions (US)	imated joe US signits mal Battery pletions (US) mpromised mpromised srapy retion Not	Esti Act Imp Mon Mon Dept The Con The Con	4,000 1,858 24 + 3 = 27 Norm	$\frac{(12)}{\text{advisory-related subset}} = \frac{(12)}{\text{advisory-related subset}}$	6,000 333 $10 + 2 = 12$	$\frac{(1)}{(advisory-related subset)}$	0 = 0 + 0	(0) + (0) = (0) Norm (advisory-related subset)	68,000 9,076 249 + 28 = 277	$\frac{(133) + (0)}{\text{Norm}}$	400 1,144 4 + 1 = 5 Norm	$\frac{(4) + (0)}{(advisory-related subset)} = (4)$	16,000 1,685 8 + 3 = 11	Includ Normal Batt	200 129 3 + 0 = 3 Norm	(3) + (0) = (3) Norm
Malfunctions (US)	ive US sharts mal Battery cletions (US) srapy Function mpromised srapy srapy notion Not mpromised	Esting Head of the control of the co	24,000 4,000 1,858 24 + 3 = 27 Norn	$\frac{(12)}{\text{advisory-related subset}} = \frac{(12)}{\text{advisory-related subset}}$	14,000  6,000  333  10  +  2  =  12	$\frac{(1)}{(advisory-related subset)}$	300 100 9 0 + 0 = 0	(0) + (0) = (0) Norm (advisory-related subset)	192,000 68,000 9,076 249 + 28 = 277	$\frac{(133) + (0)}{\text{Norm}}$	10,000 400 1,144 4 + 1 = 5 Norm	$\frac{(4) + (0)}{(advisory-related subset)} = (4)$	55,000 16,000 1,685 8 + 3 = 11	Includ Normal Batt Deplet	2,000 200 129 3 + 0 = 3 Norm	(3) + (0) = (3) Norm
Malfunctions (US)	imated ive US solaris	Region No. 1 Per Per Per Per Per Per Per Per Per Per	Jan-99 24,000 4,000 1,858 24 + 3 = 27 Norm	$\frac{(12)}{\text{advisory-related subset}} = \frac{(12)}{\text{advisory-related subset}}$	Mar-01 14,000 6,000 333 10 + 2 = 12	$\frac{(1)}{(advisory-related subset)}$	100 9 0 + 0 = 0	(0) + (0) = (0) Norm (advisory-related subset)	Feb-99 192,000 68,000 9,076 249 + 28 = 277	$\frac{(133) + (0)}{\text{Norm}}$	400 1,144 4 + 1 = 5 Norm	$\frac{(4) + (0)}{(advisory-related subset)} = (4)$	16,000 1,685 8 + 3 = 11	Includ Normal Batt Deplet	Jan-99 2,000 200 129 3 + 0 = 3 Norm	(3) + (0) = (3) Norm
Malfunctions (US)	pistered Implants in a land batter in a	Mun Regis US US Regis Mon Imp Mon Inp Con	24,000 4,000 1,858 24 + 3 = 27 Norn		14,000  6,000  333  10  +  2  =  12	(0) = (1) -related subset)	300 100 9 0 + 0 = 0	(0) = (0) Norm-related subset)	192,000 68,000 9,076 249 + 28 = 277	+ (0) = (133) Norm ory-related subset)	10,000 400 1,144 4 + 1 = 5 Norm	(0) = (4) Normelated subset)	55,000 16,000 1,685 8 + 3 = 11	Includ Normal Batt Deplet	2,000 200 129 3 + 0 = 3 Norm	+ (0) = (3)

ď)
=
_
-
$\equiv$
=
0
$\circ$
$\rightarrow$
~
_
=
_
$\subseteq$
$\overline{}$
.=
S
<u></u>
<u>a</u>
Val
ival
vival
rvival
urvival
urviv
Survival
Surviva
urviv
Surviva
Surviva
Surviva
Surviva

		16 yr											99.6 +0.1/-0.1 at 213 mo	43.7 +2.2/-2.2 at 213 mo	99.9 +0.0/-0.0 at 195 mo	59.8 +2.3/-2.4 at 195 mo
		14 yr											99.6 +0.1/-0.1	63.3	99.9	71.6
		12 yr											99.6 +0.1/-0.1	72.7 +0.7/-0.7	99.9	82.6
		10 yr											99.6 +0.1/-0.1	81.3 +0.6/-0.6	99.9	89.0
		8 yr											99.6 +0.1/-0.1	90.5 +0.4/-0.4	99.9	94.8 +0.3/-0.3
		7 yr			100.0 +0.0/-0.0 at 76 mo	94.7 +0.8/-1.0 at 76 mo	99.9 +0.0/-0.1 at 75 mo	95.1 +1.1/-1.4 at 75 mo			99.9 +0.0/-0.2 at 73 mo	54.1 +3.6/-3.8 at 73 mo	99.6 +0.1/-0.1	94.6 +0.3/-0.3	99.9	97.2 +0.2/-0.2
		6 yr	100.0 +0.0/-0.0 at 69 mo	99.0 +0.4/-0.5 at 69 mo	100.0	96.5	99.9	96.2	100.0 +0.0/-0.0 at 66 mo	98.1 +1.1/-2.4 at 66 mo	99.9	56.7	99.7 +0.1/-0.1	97.1 +0.2/-0.2	99.9	98.1
		5 yr	100.0	99.0	100.0	98.7 +0.1/-0.1	99.9	98.0	100.0	98.1	100.0	91.6	99.7 +0.0/-0.1	98.2 +0.1/-0.1	99.9	98.8
oility (%		4 yr	100.0	99.7	100.0	99.5	100.0	99.2 +0.1/-0.2	100.0	98.9	100.0	97.5 +0.3/-0.3	99.8 +0.0/-0.0	98.9 +0.1/-0.1	99.9	99.2
Device Survival Probability (%)	olant	3 yr	100.0	99.8 +0.1/-0.2	100.0+0.0/-0.0	99.8	100.0+0.0/-0.0	99.8	100.0	100.0	100.0	99.3 +0.1/-0.2	99.8 +0.0/-0.0	99.3 +0.1/-0.1	100.0	99.5
Surviva	Years After Implant	2 yr	100.0	99.9	100.0	99.9	100.0	99.9	100.0	100.0	100.0	99.8	99.9 +0.0/-0.0	99.7 +0.0/-0.1	100.0	99.7
Device	Years A	1 yr	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	99.9	99.9	99.9	100.0	99.9
			ing ery ion	ng ery on	وتر	ng rry on	פר זים קיר	ng ery on	gr v	ng ry on	r gr	ng rry on	ng on	ng ry on	ary on	ng ery on
			Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion
	Įe	510T	0 Excludi Normal Batt	Includi Normal Batte Depleti	24 Excludii Normal Batte Depleti	Includi Normal Batte Depleti	10 Excludii Normal Batte Depleti	Includi Normal Batte Depleti	0 Excludii Normal Batte Depletii	Includii Normal Batte Depletii	2 Excludii Normal Batte Depletii	Includi Normal Batte Depleti	143 Excludi Normal Batte Depleti	Includi Normal Batte Depleti	36 Excludi Normal Batte Depleti	Includi Normal Batt Depleti
ns	npromised	uoɔ	Norm	Includi Normal Batto Depleti	Norm	Includi Normal Batte Depleti	Norm	includi Normal Batte Depleti	Norm	Includi Normal Batte Depleti		Includi Normal Batte Depleti		Includi Normal Batte Depleti		Includi Normal Batto Depleti
nctions		uoɔ	0 = 0 Norm	Includi Normal Batto Depleti	11 = 24 Norm	Includi Normal Batte Depleti	8 = 10 Norm	Includi Normal Batte Depleti	0 = 0 Norm	Includi Normal Batte Depleti	0 = 2	Includi Normal Batte Depleti		Includi Normal Batte Depleti		Includi Normal Batto Depleti
Malfunctions	npromised	Con The Con	Norm	Includi Normal Batto Depleti	= 24 Norm	Includi Normal Batte Depleti	= 10 Norm	Includi Normal Batte Depleti	Norm	Includi Normal Batte Depleti	= 2	Includi Normal Batte Depleti		Includi Normal Batte Depleti		Includi Normal Batt Depleti
Malfunctions	rapy rapy ction Not pezimorqu	The Con The The no Ton	+ 0 = 0 +	Includi Normal Batt Depleti	+ 11 = 24 Norm	Includi Normal Batte Depleti	+ 8 = 10 Norm	Includi Normal Batte Depleti	+ 0 = 0 Norm	Includi Normal Batte Depleti	+ 0 = 2	Includi Normal Batte Depleti		Includi Normal Batte Depleti		Includi Normal Batt Depleti
Malfunctions	yletions repy Function inpromised repy repy repy repy repy repy	Acti Mor Dep The Con The The Ton Oon	0 = 0 + 0	Includi Normal Batt Depleti	13 + 11 = 24 Norm	Includi Normal Batte Depleti	2 + 8 = 10 Norm	Includi Normal Batte Depleti	0 + 0 = Norm	Includi Normal Batte Depleti	2 + 0 = 2	Includi Normal Batte Depleti	143	includi Normal Batte Depleti	36	Includi Normal Batt Depleti
Malfunctions	ive US inlants mal Battery shetions repy Function mpromised repy repy	Esti Acti Imp Mor Dep The Con The Fun Con	12 0 + 0 = 0 Norm	Includi Normal Batt Depleti	486 13 + 11 = 24 Norm	Includi Normal Batte Depleti	133 2 + 8 = 10 Norm	Includi Normal Batte Depleti	S 0 + 0 = 0 Norm	Includi Normal Batte Depleti	536 2 + 0 = 2	Includi Normal Batte Depleti	2,841 — — 143	includi Normal Batte Depleti	2,089 — — 36	Includi Normal Batt Depleti
Malfunctions	mated sive US  ive US  ive US  inal Battery  inal Battery  inapy Function  repy f	Rele USI Esti Acti Imp Mon Dep The Con The Con	2,000 12 0 + 0 = 0 Norm	Includi Normal Batt Depleti	76,000 486 13 + 11 = 24 Norm	Includi Normal Batte Depleti	19,000 133 2 + 8 = 10 Norm	Includi Normal Batte Depleti	300 5 0 + 0 = 0 Norm	Includi Normal Batte Depleti	7,000 536 2 + 0 = 2	Includi Normal Batte Depleti	2,000 2,841 — — 143	includi Normal Batte Depleti	4,000 2,089 36	Includi Normal Batt
Malfunctions	Market ease jistered implants mal Battery slants viety repy Function mpromised repy repy	Rejd Rejd USI Estif Imp Imp Imp Inp Con	4,000 2,000 12 0 + 0 = 0 Norm	Includi Normal Batt Depleti	125,000 76,000 486 13 + 11 = 24 Norm	Includi Normal Batte Depleti	37,000 19,000 133 2 + 8 = 10 Norm	Includi Normal Batte Depleti	1,000 300 5 0 + 0 = 0 Norm	Includi Normal Batte Depleti	16,000  7,000  536  2  +  0  =  2	Includi Normal Batte Depleti	57,000 2,000 2,841 — — 143	Includi Normal Batte Depleti	59,000 4,000 2,089 — — 36	Includi Normal Batt

7001400	COLLUNION
Cimmory	
	つしてい
^	٦

		16 yr	99.9 +0.0/-0.0 at 227 mo	71.5 +2.2/-2.4 at 227 mo	100.0 +0.0/-0.1 at 190 mo	57.8 +2.8/-2.9 at 190 mo										
		14 yr	99.9	80.5	100.0 +0.0/-0.1	69.9										
		12 yr	99.9	83.6 +0.6/-0.6	100.0 +0.0/-0.1	82.0 +1.0/-1.1	100.0 +0.0/-0.1 at 138 mo	28.8 +3.1/-3.1 at 134 mo	100.0 +0.0/-0.1 at 136 mo	52.0 +3.6/-3.7 at 136 mo	99.9 +0.1/-0.4 at 136 mo	90.8 +2.3/-3.0 at 136 mo	100.0 +0.0/-0.0 at 135 mo	55.9 +4.7/-5.0 at 135 mo	100.0 +0.0/-0.0 at 139 mo	26.8 +2.8/-2.8 at 139 mo
		10 yr	99.9 +0.0/-0.0	87.1 +0.5/-0.5	100.0 +0.0/-0.1	89.2 +0.7/-0.8	100.0 +0.0/-0.1	68.6 +1.2/-1.2	100.0 +0.0/-0.1	75.9 +1.5/-1.5	99.9 +0.1/-0.4	94.0 +1.5/-1.9	100.0	75.2 +2.9/-3.3	100.0	68.9
		8 yr	99.9 +0.0/-0.0	91.9	100.0 +0.0/-0.1	94.6 +0.5/-0.5	100.0	92.6 +0.5/-0.5	100.0	92.2	99.9 +0.1/-0.4	97.4 +0.8/-1.2	100.0	95.1 +1.0/-1.3	100.0	92.6
		7 yr		95.2 +0.3/-0.3	100.0 +0.0/-0.1	96.9	100.0	96.4 +0.3/-0.3	100.0	94.9 +0.5/-0.5	99.9 +0.1/-0.4	98.3	100.0	96.8 +0.8/-1.0	100.0	96.4 +0.3/-0.3
		6 yr	99.9	97.6 +0.2/-0.2	100.0 +0.0/-0.1	98.2 +0.2/-0.3	100.0 +0.0/-0.0	97.9 +0.2/-0.2	100.0	97.3 +0.3/-0.4	99.9 +0.1/-0.4	99.1 +0.4/-0.6	100.0	97.6 +0.6/-0.8	100.0	98.0 +0.2/-0.2
		5 yr	99.9	98.6 +0.1/-0.1	100.0 +0.0/-0.1	98.9 +0.2/-0.2	100.0 +0.0/-0.0	98.8 +0.2/-0.2	100.0 +0.0/-0.1	98.4 +0.2/-0.3	99.9 +0.1/-0.4	99.2 +0.3/-0.6	100.0	98.6 +0.4/-0.6	100.0	98.8
bility (%		4 yr	99.9	99.2 +0.1/-0.1	100.0 +0.0/-0.1	99.5 +0.1/-0.1	100.0 +0.0/-0.0	99.4 +0.1/-0.1	100.0 +0.0/-0.1	99.1 +0.2/-0.2	100.0 +0.0/-0.0	99.8 +0.1/-0.2	100.0	98.8 +0.4/-0.6	100.0	99.4
Device Survival Probability (%)	plant	3 yr	99.9	99.5 +0.1/-0.1	100.0 +0.0/-0.0	99.8 +0.1/-0.1	100.0 +0.0/-0.0	99.6 +0.1/-0.1	100.0 +0.0/-0.0	99.5 +0.1/-0.1	100.0 +0.0/-0.0	99.8 +0.1/-0.2	100.0	99.4 +0.3/-0.4	100.0	99.7 +0.1/-0.1
Surviva	Years After Implant	2 yr	99.9	99.7 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	99.8 +0.0/-0.1	100.0 +0.0/-0.0	99.8 +0.1/-0.1	100.0 +0.0/-0.0	99.9 +0.1/-0.2	100.0	99.7 +0.2/-0.3	100.0 +0.0/-0.0	99.8
Device	Years /	1 yr	100.0	99.9	100.0+0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	99.9 +0.0/-0.0	100.0	99.9 +0.0/-0.1	100.0	99.9 +0.1/-0.2	100.0	99.9 +0.1/-0.2	100.0	99.9
			מ > כ	D > C	c	m > c		70 > C								
			Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion
	ין	5toT	49 Excluding Normal Batter Depletion	Including Normal Batter Depletion	4 Excluding Normal Battery Depletion	Including Normal Battery Depletion	4 Excluding Normal Battery Depletion	Including Normal Battery Depletion	1 Excluding Normal Battery Depletion	Including Normal Battery Depletion	1 Excluding Normal Battery Depletior	Including Normal Battery Depletior	0 Excluding Normal Battery Depletior	Including Normal Battery Depletior	11 Excluding Normal Battery Depletior	Including Normal Battery Depletior
ctions	yqer Ston Not bəsimorqı İı	Fun Con		Normal Batter  Depletion		Including Normal Battery Depletior		Including Normal Battery Depletion		Including Normal Battery Depletion		including Normal Battery Depletior		Including Normal Battery Depletior		Including Normal Battery Depletior
Malfunctions	ton Not besimorqi	Con The The		Norm		Including Normal Battery Depletion	4	Including Normal Battery Depletion	<del>-</del>	Including Normal Battery Depletion	-	Including Normal Battery Depletior		Including Normal Battery Depletior		Including Normal Battery Depletion
Malfunctions	peromised rapy ction Not promised	Dep Con The Fun Con		Norm		Including Normal Batten Depletion	4	Including Normal Battery Depletion	<del>-</del>	Including Normal Battery Depletion	-	Including Normal Battery Depletior		Including Normal Battery Depletior		Including Normal Battery Depletion
Malfunctions	letions rapy Function rapy rapy ction Not tion Not ppromised	Acti Imp Nor Dep The Con The Fun	- 49	Norm	4	Including Normal Batten Depletion	4	Including Normal Battery Depletion	-	Including Normal Battery Depletion	-	Including Normal Battery Depletion	0	Including Normal Battery Depletior	-	Including Normal Battery Depletion
Malfunctions	Ve US lants mal Battery letions rapy Function promised rapy rapy rapy rapy rapy rapy rapy rapy	Estin Acti Imp Mor Mor Dep The Com	1,559 — — 49	Norm	712 — 4	Including Normal Batten Depletion	1,512 — 4	Including Normal Batter Depletion	596 — — 1	Including Normal Battery Depletion	31 — — 1	Including Normal Battery Depletion	140 — 0	Including Normal Battery Depletion	2,116 — — 11	Including Normal Battery Depletion
Malfunctions	istered mplants we US ve US lants mal Battery letions rapy Function promised ction Not rapy	Regg USI Lestii Acti Imp Mor Mor The Com	4,000 1,559 — — 49	Norm	2,000 712 — 4	Including Normal Batten Depletion	4,000 1,512 — 4	Including Normal Battery Depletion	2,000 596 — — 1	Including Normal Battery Depletion	1,000 31 — — 1	Including Normal Battery Depletion	400 140 0	Including Normal Battery Depletion	5,000 2,116 — — 11	Including Normal Battery Depletion
Malfunctions	istered mplants mylants ve US lants mal Battery letions rapy Function promised myrants	Regie Regie US I Regie US I Latin Imp Imp Imp Imp Imp Imp Imp Imp Imp Imp	58,000 4,000 1,559 — — 49	Norm	17,000 2,000 712 — 4	Including Normal Batten Depletion	26,000 4,000 1,512 — 4	Including Normal Batter Depletion	18,000 2,000 596 — — 1	Including Normal Battery Depletion	4,000 1,000 31 — — 1	Including Normal Battery Depletion	3,000 400 140 0	Including Normal Battery Depletion	38,000 5,000 2,116 — — 11	Including Normal Battery Depletion

parinitad

ntinued
ry cor
mmal
al Su
urviv
ice S
De

Device Survival Probability (%)	Years After Implant	2   1 yr   2 yr   3 yr   4 yr   5 yr   6 yr   7 yr   8 yr   10 yr   12 yr   14 yr   16 yr	0 Excluding 100.0	Including         99.8         99.7         99.1         99.1         99.1         99.1         99.1         99.1         99.1         99.1         98.8         97.2         90.1         84.6           Normal Battery         +0.1/-0.3         +0.1/-0.3         +0.2/-0.4         +0.4/-0.7         +0.4/-0.7         +0.5/-0.9         +1.0/-1.5         +2.3/-3.0         +3.4/-4.2           Depletion	5         Excluding Depletion         100.0	Including         99.8         99.6         99.3         98.8         98.1         97.1         95.4         75.6         50.5           Normal Battery         +0.0/-0.1         +0.1/-0.1         +0.2/-0.2         +0.2/-0.3         +0.3/-0.3         +0.4/-0.4         +0.6/-0.6         +1.4/-1.4         +37/-3.9           Depletion         Performance         Performance         Performance         Performance         Performance         Performance         Performance	0 Excluding 100.0 100.0 100.0 Depletion at 20 mo	Including   100,0   100,0   100,0   Normal Battery   +0.0/−0.0   at 20 mo   = 0 Excluding 100.0 100.0 100.0 Populatery +0.0/-0.0 at 20 mo	Including         100.0         100.0           Normal Battery         +0.0/-0.0         +0.0/-0.0           Depletion         at 20 mo	= 0 Excluding 100.0 100.	= (0) Including 100.0 100.0 99.5 99.5 98.7 98.7 97.3 10.9/2.4 41.5/3.6 red subset) Depletion	= 5 Excluding 100.0 100.	= (1) Including 100.0 99.9 99.9 99.8 99.6 99.2 99.8 99.6 99.2 97.9 95.6 93.2 17-0.1 1-0.1/-0.1 1-0.1/-0.2 1-0.2/-0.2 1-0.	4 Excluding 100.0 100.0 100.0 100.0 99.9 99.9 99.9	- (3) Including 100.0 99.9 99.8 99.7 99.4 99.1 98.0 95.5 93.0 Normal Battery +0.0/-0.1 +0.1/-0.1 +0.1/-0.1 +0.1/-0.2 +0.2/-0.2 +0.2/-0.3 +0.5/-0.6 +1.1/-1.5 +2.1/-2.9	
nctions	rapy ction Not npromised	uoɔ	I				0 +		0 +		0 +	+ (0) :	<del>-</del>	+ (0) = ry-related si	0 +	= (0) +
Malfunctions	rapy Function rapy Function rapy rapy ction Not bestimoraph	The Con The Tun Tun Tun	36		728 — —				0 + 0		0 + 0	(0) + (0) (advisory-related		(1) + (0) = (advisory-related s		
	Function besimorqu qes yqes ction Not besimorqn	Acti Mor Dep The Con The The The Toon	300 36		3,000 728 — —		0 + 0		+		+	(0) + (0) (advisory-rela	+ +	(1) + (0) (advisory-rela	4 + 0	(3) + (0)
	ilants mal Battery nal Battery rapy Function npromised rapy rapy rapy npromised rapy	Esti Acti Imp Mor Dep The Con The Fun Con					0 + 0		+ 0		1,000 200 4 0 +	(0) + (0) (advisory-rela	16,000 7,000 73 4 + 1	(1) + (0) (advisory-rela	42 4 + 0	(3) + (0)
	mated live US live US liants mal Battery lietions rapy Function map Function rapy Function rapy Function rapy Function rapy Function rapy rapy	Reget USI	300		3,000		Jul-06 30,000 27,000 0 0 + 0		16,000 0 +		200 4 0 +	(0) + (0) (advisory-rela	7,000 73 4 + 1	(1) + (0) (advisory-rela	4,000 42 4 + 0	(3) + (0)
	Market Jesse istered mplants we US We US Jents Mations mal Battery Mations rapy Function npromised rapy	Rejection of the control of the cont	2,000 300		22,000 3,000		30,000 27,000 0 0 + 0		19,000 16,000 0 +		1,000 200 4 0 +	Advisories: see page 145 – 2005 Potential (0) + (0) separation of Interconnect Wires (advisory-related	16,000 7,000 73 4 + 1	Advisories: see page 145 – 2005 Potential Separation of Interconnect Wires (advisory-related s	12,000 4,000 42 4 + 0	(0)

S	
Ħ,	
Ĕ	
=	
<u>8</u>	

		16 yr														
		14 yr														
	-	12 yr							100.0 +0.0/-0.2 at 140 mo	46.0 +5.0/-5.1 at 140 mo	99.9 +0.0/-0.0 at 141 mo	7.5 +1.1/-1.0 at 141 mo			100.0 +0.0/-0.3 at 143 mo	79.4 +3.7/-4.4 at 143 mo
		10 yr	99.9 +0.0/-0.0 at 104 mo	93.9 +1.5/-1.9 at 104 mo	99.9 +0.0/-0.0 at 101 mo	93.8 +1.3/-1.7 at 101 mo			100.0	78.5 +2.5/-2.7	99.9	69.2 +05/-0.5	99.9 +0.1/-0.2 at 116 mo	39.2 +4.4/-4.4 at 116 mo	100.0 +0.0/-0.3	89.9 +1.8/-2.2
		8 yr	99.9	96.5	99.9	95.2 +0.8/-1.0			100.0	93.8 +1.1/-1.4	99.9	92.8 +0.2/-0.2	99.9	76.0 +2.3/-2.5	100.0	95.9 +0.9/-1.2
	_	7 yr	99.9	98.4 +0.2/-0.2	99.9	98.2 +0.3/-0.3	100.0 +0.0/-0.0 at 82 mo	98.0 +1.3/-3.6 at 82 mo	100.0 +0.0/-0.2	96.2 +0.8/-1.0	99.9	96.6 +0.1/-0.1	99.9 +0.1/-0.2	88.8 +1.4/-1.6	100.0	97.5
		6 yr	99.9	99.1 +0.1/-0.1	99.9 +0.0/-0.0	99.0 +0.2/-0.2	100.0 +0.0/-0.0	99.4 +0.5/-1.8	100.0 +0.0/-0.2	97.5 +0.6/-0.8	99.9	98.2 +0.1/-0.1	99.9 +0.1/-0.2	94.1 +1.0/-1.1	100.0 +0.0/-0.3	98.1
(0	_	5 yr	99.9 +0.0/-0.0	99.5	99.9 +0.0/-0.0	99.5	100.0	99.4 +0.5/-1.8	100.0	99.0 +0.3/-0.5	100.0	99.0	99.9	97.0 +0.6/-0.8	100.0	98.9
bility (%		4 yr	99.9	99.7 +0.0/-0.0	100.0 +0.0/-0.0	99.7 +0.1/-0.1	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0	99.4 +0.2/-0.4	100.0	99.4 +0.0/-0.1	99.9 +0.1/-0.2	98.6 +0.4/-0.6	100.0	99.2 +0.3/-0.5
Device Survival Probability (%)	plant	3 yr	100.0	99.9	100.0 +0.0/-0.0	99.8	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0	99.5 +0.2/-0.4	100.0	99.7 +0.0/-0.0	99.9 +0.1/-0.2	99.5 +0.2/-0.3	100.0	99.7
Surviva	Years After Implant	2 yr	100.0	99.9	100.0 +0.0/-0.0	99.9	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0	99.9 +0.1/-0.2	100.0	99.9	100.0 +0.0/-0.0	99.8 +0.1/-0.2	100.0	99.8 +0.1/-0.3
Device	Years /	1 yr	100.0	100.0 +0.0/-0.0	100.0	100.0 +0.0/-0.0	100.0+0.0/-0.0	100.0 +0.0/-0.0	100.0	100.0 +0.0/-0.0	100.0	100.0 +0.0/-0.0	100.0	100.0 +0.0/-0.0	100.0	99.9
			פאב	ع ج <u>م</u>	ם > ב	و کے <del>د</del>	פֿֿאַ	פר אי מ	פֿיַב	gΣς	פידים	و <del>ک</del> د	פֿיַב	פר ער מ	פֿֿיַבֿינ	פֿ אַ בּ
			Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion
	le:	<b>T</b> ot	55 Excludin Normal Batter Depletio	Norm	=	Norm	0 Norm	Norm	1 Excludir Normal Batte Depletii	Includir Normal Batte Depletic	50 Excludii Normal Batte Depletii	Includir Normal Batte Depletic	3 Excludir Normal Batte Depletii	Includir Normal Batte Depletic	1 Excludii Normal Batte Depletii	Includir Normal Batte Depletic
ctions	ygese Mpromotor Jesimongm Jesi	nu7 102	Norm	Norm		Norm	Norm	Norm	Norm	Includir Normal Batte Depletic						
Malfunctions	ofion Not mpromised	The Thun Tun Too	= 55 Norm	= (15) Norm	=======================================	= (4) Norm	Norm	= (0) Norm	Norm	Includir Normal Batte Depletic	Norm	Includir Normal Batte Depletic	Norm	Includii Normal Batte Depletii	Norm	Includir Normal Batte Depletic
Malfunctions	pesimorqm erapy ton Not mpromised	The Cor The The Fund	+ 5 = 55 Norm	Norm	+	Norm	0 = 0 +	Norm	Norm	Includir Normal Batte Depletic						
Malfunctions	pletions prespy Function mpromised prespy rction Not mpromised	Act Imp Moi Dep The Cor The Fun Fun	260 50 + 5 = 55 Norm	(15) + (0) = (15) (advisory-related subset)	121 10 + 1 = 11	(4) + (0) = (4) Norm (advisory-related subset)	3 0 + 0 = 0 Norm	(0) + (0) = (0) Norm (advisory-related subset)	Norm	Includir Normal Batte Depletic	8,841 — 50 Norm	Includir Normal Batte Depletic	282 — — 3 Norm	Includii Normal Batte Depletii	74 — 1 Norm	Includir Normal Batte Depletic
Malfunctions	Implants imated sive US solates solate	SU  State	57,000 260 50 + 5 = 55 Norm	(15) + (0) = (15) (advisory-related subset)	22,000 121 10 + 1 = 11	(4) + (0) = (4) Norm (advisory-related subset)	300 3 0 + 0 = 0 Norm	(0) + (0) = (0) Norm (advisory-related subset)	400 180 — 1 Norm	Includir Normal Batte Depletic	10,000 8,841 — 50 Norm	Includir Normal Batte Depletic	200 282 — — 3 Norm	Includii Normal Batte Depletii	1,000 74 — 1 Norm	Includir Normal Batte Depletic
Malfunctions	pease finplants finated sive US solution sinal Battery pletions pletions mpromised my Function my Function seapy Function action Not forest	Regles Regles Regles Regles USS Act I I I I I I I I I I I I I I I I I I I	106,000 57,000 260 50 + 5 = 55 Norm	(15) + (0) = (15) (advisory-related subset)	54,000 22,000 121 10 + 1 = 11	(4) + (0) = (4) Norm (advisory-related subset)	1,000 300 3 0 + 0 = 0 Norm	(0) + (0) = (0) Norm (advisory-related subset)	3,000 400 180 — 1 Norm	Includir Normal Batte Depletic	122,000 10,000 8,841 — 50 Norm	Includir Normal Batte Depletic	4,000 200 282 — — 3 Norm	Includir Normal Batte Depletit	4,000 1,000 <b>74</b> — 1 Norm	Includir Normal Batte Depletic
Malfunctions	Market ease jistered implants inve US sive US plants plants pletions prapy Function mpromised myromised	Registration of the control of the c	Aug-99 106,000 57,000 260 50 + 5 = 55 Norm	(15) + (0) = (15) (advisory-related subset)	Sep-99 54,000 22,000 121 10 + 1 = 11	(4) + (0) = (4) Norm (advisory-related subset)	Sep-99 1,000 300 3 0 + 0 = 0 Norm	(0) + (0) = (0) Norm (advisory-related subset)	Oct-95 3,000 400 180 — — 1 Norm	Includir Normal Batte Depletic	Oct-95 122,000 10,000 8,841 — — 50 Norm	Includir Normal Batte Depletic	Jul-96 4,000 200 282 — — 3 Norm	Includir Normal Batte	Oct-95 4,000 1,000 74 — — 1 Norm	Includir Normal Batte Depletic
Malfunctions	pease finplants finated sive US solution sinal Battery pletions pletions mpromised my Function my Function seapy Function action Not forest	Mun US Red US Esti Imp Imp Inp Inp Inp Inp Inp Inp Inp Inp Inp In	106,000 57,000 260 50 + 5 = 55 Norm	Norm	54,000 22,000 121 10 + 1 = 11	Norm	1,000 300 3 0 + 0 = 0 Norm	Norm	3,000 400 180 — 1 Norm	Includir Normal Batte Depletic	122,000 10,000 8,841 — 50 Norm	Includir Normal Batte Depletic	4,000 200 282 — — 3 Norm	Includii Normal Batte	4,000 1,000 <b>74</b> — 1 Norm	Includir Normal Batte Depletic

U	Implantal	ble	Pulse G	enerat	tors, co	ontinue	ed	
		16 yr						
		14 yr	100.0 +0.0/-0.0 at 148 mo	48.6 +2.3/-2.4 at 148 mo				
		10 yr   12 yr   14 yr	100.0	80.6 52.1 +0.7/-0.8 +1.8/-1.8	100.0 +0.0/-0.0 at 139 mo	64.0 +4.2/-4.6 at 139 mo		
		10 yr	100.0 100.0 100.0 100.0 100.0 100.0 +0.0/-0.0 +0.0/-0.0	80.6 +0.7/-0.8	100.0	88.4 +1.6/-1.9		
		8 yr	100.0	98.2 97.0 94.6 +0.2/-0.2 +0.2/-0.3	100.0	99.1 99.0 98.3 +0.3/-0.4 +0.3/-0.4 +0.4/-0.6		
		7 yr	100.0 100.0 +0.0/-0	97.0 +0.2/-0.2	100.0 +0.0/-0.0 +0.0/-0.0	99.0		
		6 yr	100.0		100.0	99.1 +0.3/-0.4		
(9)		5 yr	100.0 100.0 100.0 100.0 100.0 100.0 +0.0/-0.0	98.9 +0.1/-0.1	100.0 10			
ability (9		4 yr	100.0					
Device Survival Probability (%)	Years After Implant	3 yr	100.0	100.0 +0.0/-0.0 +0.0/-0.0 +0.1/-0.1	100.0	99.6		
		2 yr	100.0	99.9	100.0	99.8	100.0 +0.0/-0.0 at 20 mo	100.0 +0.0/-0.0
		1 yr			100.0	99.9	100.0	
			Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion
	le	stoT	7		0		-	
ctions	rapy ction Not promised	un	I		I		-	
Malfunctions	Therapy Function Compromised		1		T		+	
-	mal Battery snoiteli		1,792	0				
Estimated Active US Implants			000'9		1,000		27,000	
US Market Release Registered US Implants			50,000		2,000		29,000	
			Oct-95		Mar-96		Jul-06	
	del nber	ooM	8960i, 8961i, 8962i		8968i		VEDR01	
	بزار	Family			Thera-i VDD		Versa DR	



### **Reference Chart**

The longevity estimates provided are mean values calculated for the parameters given. The longevity estimates shown here assume a lower rate of 60 ppm, 100% pacing, and pulse width of 0.4 ms unless noted otherwise. The actual longevity achieved for any device while implanted will depend on the actual programmed parameters and patient factors, and may differ significantly from these estimates. The elective replacement time is indicated via telemetry indication, and rate and mode change to 65 ppm and VVI respectively (VOO/65 with magnet), unless noted otherwise.

		Estimated I	ongevity.		
Family	Model Number	Amplitude Setting	500 Lead Ω	1000 Lead Ω	Elective Replacement Indicators
Adapta DR	ADDR01, ADDR03, ADDR06, ADD01	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.4 6.0 4.5	8.2 7.3 6.0	**
Adapta DR	ADDRS1	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	5.5 4.3 3.2	6.1 5.4 4.4	**
Adapta DR	ADDRL1	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	9.1 7.4 5.4	10.1 9.0 7.3	**
Adapta SR	ADSR01, ADSR03, ADSR06	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	7.3 6.4 5.0	7.8 7.4 6.2	**
Adapta VDD	ADVDD01	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	6.2 5.5 4.4	6.5 6.2 5.4	**
AT500	AT501, 7253	Low 2.0 V (A, RV) Nominal 3.0 V (A, RV) High 5.0 V (A, RV)	7.7 5.8 3.7	8.3 7.0 5.2	Telemetry indication. Pacing mode and rate (magnet and non-magnet) as programmed.
EnPulse DR	E1DR01, E1DR03, E1DR06	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.5 6.2 4.4	8.5 7.6 5.9	**
EnPulse DR	E1DR21	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	5.4 4.3 3.0	6.0 5.4 4.2	**
EnPulse 2 DR	E2DR01, E2DR03, E2DR06	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.5 6.2 4.4	8.5 7.6 5.9	**
EnPulse 2 DR	E2DR21	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	5.4 4.3 3.0	6.0 5.4 4.2	**
EnPulse 2 DR	E2DR31, E2DR33	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	9.0 7.4 5.2	10.1 9.1 7.1	**
EnPulse 2 SR	E2SR01, E2SR03, E2SR06	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.2 6.3 4.8	7.7 7.3 6.1	**
EnPulse 2 VDD	E2VDD01	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	6.1 5.5 4.3	6.5 6.2 5.4	**
EnRhythm DR	P1501DR	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	10.6 8.0 5.4	12.3 10.3 7.8	**
Kappa 400 DR	KDR401, KDR403	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.8 6.4 5.1	8.5 7.5 6.5	**
Kappa 400 SR	KSR401, KSR403	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	7.9 6.9 5.8	8.4 7.7 7.0	**
Kappa 600 DR	KDR601, KDR603, KDR606	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.7 6.3 4.4	8.6 7.7 6.0	**
Kappa 600 DR	KDR651, KDR653	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.7 6.3 4.4	8.6 7.7 6.0	**

<sup>\*\*</sup>Telemetry indication. Rate and mode change to 65 ppm and VVI respectively (VOO/65 with magnet).

continued



### Reference Chart continued

		Estimated Long	evity		
Family	Model Number	Amplitude Setting	500 Lead Ω	1000 Lead Ω	Elective Replacement Indicators
Kappa 700 D	KD701, KD703, KD706	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.7 6.3 4.4	8.6 7.7 6.0	**
Kappa 700 DR	KDR701, KDR703, KDR706	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.7 6.3 4.4	8.6 7.7 6.0	**
Kappa 700 DR	KDR721	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	5.5 4.4 3.0	6.1 5.5 4.2	**
Kappa 700 SR	KSR701, KSR703, KSR706	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	7.4 6.5 4.9	7.9 7.5 6.2	**
Kappa 700 VDD	KVDD701	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	6.2 5.6 4.4	6.6 6.3 5.3	**
Kappa 800 DR	KDR801, KDR803	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.7 6.3 4.4	8.6 7.7 6.0	**
Kappa 900 DR	KDR901, KDR903, KDR906	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.7 6.3 4.4	8.6 7.7 6.0	**
Kappa 920 DR	KDR921	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	5.5 4.4 3.0	6.1 5.5 4.3	**
Kappa 900 SR	KSR901, KSR903, KSR906	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	7.3 6.4 4.9	7.9 7.4 6.1	**
Kappa 900 VDD	KVDD901	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	6.2 5.6 4.4	6.6 6.3 5.4	**
Legend	8416, 8417, 8417M, 8418, 8419	Low 2.5 V (RV) Nominal 3.3 V (RV) High 5.0 V (RV)	15.6 11.3 9.0	17.7 14.5 12.5	If programmed to non-rate responsive mode (e.g. VVI), rate decrease of 10% from programmed rate. Telemetry indication. If programmed to rate responsive mode (e.g. VVIR), rate change to 65 ppm and mode change to VVI. Telemetry indication.
Legend II	8424, 8426, 8427	Low 2.5 V, 0.36 ms (RV) Nominal 3.3 V, 0.36 ms (RV) High 5.0 V, 0.36 ms (RV)	12.9 9.4 7.8	14.5 11.8 10.5	If programmed to non-rate responsive mode (e.g. VVI), rate decrease of 10% from programmed rate. Telemetry indication. If programmed to rate responsive mode (e.g. VVIR), rate change to 65 ppm and mode change to VVI. Telemetry indication.
Minix	8340, 8341, 8341M, 8342	Low 2.5 V (RV) Nominal 3.3 V (RV) High 5.0 V (RV)	14.9 10.2 7.9	17.3 13.6 11.3	Telemetry indication. Rate decrease of 10% from programmed rate.
Minix ST	8330, 8331, 8331M	Low 2.5 V (RV) Nominal 5.0 V (RV) High 8.0 V (RV)	14.9 7.9 4.0	17.3 11.4 7.0	Telemetry indication. Rate decrease of 10% from programmed rate.
Minuet	7107, 7108	Low 2.5 V, 0.36 ms (A, RV) Nominal 4.0 V, 0.36 ms (A, RV) High 5.0 V, 0.36 ms (A, RV)	12.5 7.7 4.7	15.6 10.9 7.6	**
Preva DR	7088, 7089	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	9.9 7.4 5.4	11.3 9.4 7.5	**
Preva SR	8088, 8089	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	9.8 8.0 6.4	10.7 9.5 8.1	**
Prevail S	8085, 8086	Low 2.5 V, 0.42 ms (RV) Nominal 3.3 V, 0.42 ms (RV) High 5.0 V, 0.42 ms (RV)	16.4 10.8 8.6	19.4 14.4 12.4	Telemetry indication. Rate decrease of 10% from programmed rate.

 $<sup>^{**}\</sup>mbox{Telemetry}$  indication. Rate and mode change to 65 ppm and VVI respectively (VOO/65 with magnet).

continued



### Reference Chart continued

### **Estimated Longevity**

		Estimated	ongevity		
Family	Model Number	Amplitude Setting	500 Lead Ω	1000 Lead Ω	Elective Replacement Indicators
Prodigy D	7864, 7865, 7866	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	10.0 7.4 5.4	11.4 9.5 7.6	**
Prodigy DR	7860, 7861, 7862	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	9.9 7.4 5.4	11.3 9.4 7.5	**
Prodigy S	8164, 8165, 8166	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	10.0 8.1 6.4	10.9 9.6 8.2	**
Prodigy SR	8158, 8160, 8161, 8162	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	9.8 8.0 6.4	10.7 9.5 8.1	**
Sensia DR	SEDR01, SED01	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.5 6.1 4.5	8.3 7.4 6.0	**
Sensia DR	SEDRL1	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	9.1 7.4 5.4	10.1 9.0 7.3	**
Sensia SR	SESR01, SES01	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	7.3 6.4 5.0	7.8 7.4 6.2	**
Sigma 100 S	SS103, SS106	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	10.1 8.2 6.4	11.1 9.8 8.4	**
Sigma 200 DR	SDR203	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	10.1 7.5 5.5	11.7 9.6 7.8	**
Sigma 200 SR	SSR203	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	10.1 8.2 6.4	11.1 9.8 8.4	**
Sigma 300 DR	SDR303, SDR306	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	10.1 7.5 5.5	11.7 9.6 7.8	**
Sigma 300 SR	SSR303, SSR306	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	10.1 8.2 6.4	11.1 9.8 8.4	**
Sigma 300 VDD	SVDD303	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	8.9 7.3 5.8	9.7 8.6 7.4	**
Thera-i D	7964i, 7965i, 7966i	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	10.0 7.4 5.4	11.4 9.5 7.6	**
Thera-i DR	7960i, 7961i, 7962i	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	9.9 7.4 5.4	11.3 9.4 7.5	**
Thera-i DR	7968i	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.2 5.4 3.9	8.3 6.9 5.5	**
Thera-i S	8964i, 8965i, 8966i	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	10.0 8.1 6.4	10.9 9.6 8.2	**
Thera-i SR	8960i, 8961i, 8962i	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	9.8 8.0 6.4	10.7 9.5 8.1	**
Thera-i VDD	8968i	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	11.5 9.6 7.7	12.4 11.1 9.7	**
Versa DR	VEDR01	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.5 6.1 4.5	8.3 7.4 6.0	**

 $<sup>^{**}\</sup>mbox{Telemetry}$  indication. Rate and mode change to 65 ppm and VVI respectively (VOO/65 with magnet).

## **Method for Estimating Lead Performance**

Medtronic CRDM has tracked lead survival for over 20 years with its multicenter, global chronic lead studies.

#### **Leads Performance Analysis**

Implanted leads operate in the challenging biochemical environment of the human body and the body's response to foreign objects. Implanted leads are also subject to mechanical stresses associated with heart motion, body motion, and patient anatomy.

In this environment, pacemaker and defibrillation leads cannot be expected to last forever. While IPGs and ICDs have a battery that will deplete after a predictable length of time, a lead's longevity cannot be predicted nor are there simple indicators that a lead is approaching the end of its service life. Therefore, regular monitoring while implanted, and evaluation of lead integrity upon IPG or ICD replacement, is necessary to determine if a lead may be approaching the end of its service life.

### **Returned Product Analysis Shortfalls**

All leads and lead segments returned to Medtronic are analyzed to determine whether or not they meet performance limits established by Medtronic. Although returned product analyses are valuable for gaining insight into lead failure mechanisms, this data cannot be used by itself for determining the survival probability of leads because only a small fraction of leads are explanted and returned for analysis. Additionally, those leads which are returned cannot be assumed to be statistically representative of the performance of the total population for a given lead model. Partial or total lead extraction can result in significant damage to a lead, making a definitive analysis of a suspected failure and its cause impossible. Thus, lead survival probabilities are more appropriately determined through a clinical surveillance study. Although returned product analysis results are presented in this report, Medtronic tracks lead survival through its System Longevity Study.

#### System Longevity Study (SLS)

The SLS is a prospective, multicenter, global study designed to monitor the performance of marketreleased cardiac therapy products. Medtronic has been monitoring the performance of its cardiac therapy products for 25 years and has evaluated the performance of more than 75,000 leads, with data reported from 14 countries on 4 continents.

Patients are eligible for enrollment in the study if

- 1 They are within 6 months post-implant of a Medtronic market-released lead connected to a market-released CRT, ICD, or IPG device, and the lead is used for a pacing, sensing, or defibrillation application, or
- 2 They participated in a qualifying study of a market-released Medtronic cardiac therapy product; complete implant and follow-up data are available; and the data is appropriately and legally released for use in the study.

#### **Lead Complications**

The SLS complication criteria are defined below. These criteria do not, however, enable a lead integrity or "hardware" failure to be conclusively differentiated from other clinical events such as an undetected lead dislodgement, exit block, or concurrent pulse generator failure manifested as a sensing or capture problem.

A lead-related complication is considered to have occurred if at least one of the following clinical observations is reported and at least one of the following clinical actions is made 30 days or more after the implant.

#### **Clinical Observations**

- Failure to capture
- Failure to sense/undersensing
- Oversensing
- Abnormal pacing impedance (based on lead model, but normal range is typically 200-3000 ohms)
- Abnormal defibrillation impedance (based on lead model, but normal range is typically 20-200 ohms)
- Insulation breach, observed visually, that has degraded system performance
- Conductor fracture, observed visually or radiographically
- Extracardiac stimulation
- Cardiac perforation
- Lead dislodgement

continued

## Method for Estimating Lead Performance continued

#### The Standard Actuarial Method is used to determine estimates of lead survival.

#### **Clinical Actions**

- Lead surgically abandoned/capped
- Lead electrically abandoned/capped
- Lead explanted
- Lead replaced
- Polarity reprogrammed (i.e., bipolar to unipolar; unipolar to bipolar)
- Lead use continued based on medical judgment despite a known clinical performance issue
- Other lead-related surgery performed (e.g., lead mechanical alteration or unsuccessful repositioning)

Note: Successful lead repositioning is not a qualifying action.

#### Methods

The performance of leads is expressed in terms of lead survival estimates, where "survival" refers to the function of the lead, not the survival of the patient. These survival estimates are intended to illustrate the probability that a lead will survive for a given number of years without a lead-related complication.

The survival estimates are determined from the analysis of the data collected through the SLS. These data are presented graphically and numerically.

The SLS protocol requires regular follow-up reporting on all leads actively followed in the study. Each study center must inform Medtronic whenever a lead complication has occurred or when a patient is no longer participating in the study. Under the study protocol, each lead is assumed to be normally active unless a lead-related complication is confirmed, the lead is abandoned or explanted, or the patient is no longer available for follow-up. The data analyses assume that the patient is still part of the study and there are no lead complications at the time of the report cutoff date unless specifically reported by the center.

Medtronic evaluates center compliance with study protocol through, at a minimum, annual clinical monitoring at each study site. Additionally, study center personnel must be trained in the study procedures prior to participating and they must adhere to the policies and procedures of their local ethics boards.

Implant times are calculated from the implant date to the earlier of the complication date, out-of-service date (for example, patient leaves the study or the lead is no longer being used), or the cutoff date of the report. If a lead experiences more than one complication, the first is used to calculate survival time; although all complications associated with a lead are reported in PPR tables.

Of the several different statistical methods available for survival analysis, the Standard Actuarial Method, with suspensions assumed distributed across the intervals (Cutler-Ederer Method), is used to determine estimates of lead survival. This method is commonly used by medical researchers and clinicians.

On the following pages, each graph includes a survival curve where events include qualifying lead-related complications. This survival estimate is a good representation of the probability a lead will survive a period of time without a lead-related complication. For example, if a survival probability is 95% after 5 years of service, then the lead has a 5% chance of experiencing a lead-related complication in the first 5 years following implant.

Since the survival estimate can become very imprecise with small effective sample sizes, Medtronic truncates the survival curve when the number of leads entering an interval is less than 50 leads. When the number of leads entering an interval reaches 50, the next data point is added to the survival curve.

Although the report provides tabular data in one year intervals, the curves are actually computed and plotted using three-month intervals.

The data in the tables is rounded to the nearest tenth of one percent. Occasionally, a graph may show 100% survival, but have 1 or more complications. This occurs because even with the complications, the data rounds to 100%.

The survival curves are statistical estimates. As performance experience accumulates, the estimation improves. Confidence intervals are provided as a way to indicate the degree of certainty of the estimates. Greenwood's formula is used to calculate corresponding 95% confidence intervals for the standard errors, and the complementary log-log method is used to produce the confidence bounds.

continued

## Method for Estimating Lead Performance continued

Medtronic urges all physicians to return explanted product and to notify Medtronic when a product is no longer in use, regardless of reason for explant or removal from use.

### Sample Size and How the Population and Population Samples Are Defined

The population sample from which the survival estimates are derived is comprised of the patients successfully enrolled in the SLS as of the report cutoff date. The number of enrolled implants is listed for each model.

This sample based on SLS enrollments is considered to be representative of the worldwide population, including data from 14 countries on 4 continents, and therefore the survival estimates shown in this report should be representative of the performance worldwide of these models.

In general, a model or model family will be included in this report when more than 100 leads have been enrolled and no fewer than 50 leads followed for at least 6 months. Models will remain in the report as long as Medtronic estimates at least 500 leads remain active in the United States, based on estimated US implants.

### **Returned Product Analysis Results**

Every lead or lead portion returned to Medtronic receives an analysis. Although the returned product analysis data is not used to generate the survival estimates, the data provides valuable insight into the causes of lead malfunction.

For reporting returned product analysis results, Medtronic CRDM considers a lead as having malfunctioned whenever the analysis shows that any parameter was outside the performance limits established by Medtronic while implanted and in service. To be considered a malfunction for returned product analysis reporting, the lead must have been returned to Medtronic and analyzed.

Lead malfunctions are divided into three categories: Implant Damage, Electrical, and Other. Typical examples of implant damage are stylet perforation, cut or torn insulation, bent or distorted conductors, over-retracted helixes, and conductor fracture due to overtorquing. An electrical malfunction is defined as a hardware malfunction resulting in a break in the insulation or a break in the conductor that could affect the electrical performance of the lead. A break in the insulation is defined as a breach allowing entry of body fluids, or inappropriate current flow between the conductors, or between the conductor and the body. Examples include cuts, tears, depressions, environmental stress cracking (ESC), and metal ion

oxidation (MIO). A break in the conductor of a lead is defined as the loss of continuity in the metallic components that could interrupt the current flow or voltage. Examples include fractured conductors and defective crimps.

Leads damaged after explant or damaged due to failure to heed warnings or contraindications in the labeling are not considered device malfunctions.

A lead subject to a safety advisory is not considered to have malfunctioned unless it has been returned to Medtronic CRDM and found, through analysis, to actually have performed outside the performance limits established by Medtronic.

For leads designed for either ventricular or atrial use, the numbers listed in the Returned Product Analysis tables include both.

The numbers of malfunctions listed in the Returned Product Analysis tables are the actual numbers confirmed in the returned product analysis from the United States. The numbers of complications listed in the complications tables are the actual numbers observed in the SLS centers around the world.

### **Estimated Number of Implanted** and Active Leads in the United States

In addition to providing the number of leads enrolled in the SLS, this report also provides estimates for the number of leads implanted in the United States and the number remaining active in the United States. The number of US implants is estimated based on the total number of leads sold in the United States. The number of active implants is estimated using the total number of leads sold and projections for normal patient mortality, elective replacement, and lead failure. The number of implanted leads and active leads is adjusted for underreporting of patient mortality, elective replacement, and lead failure.

Some lead models do not have a survival curve presented in this report. These lead models do not have a survival curve because they have insufficient sample size in the System Longevity Study. Returned Product Analysis results for these models are included here for reference and comparison.

## **Left-Heart Leads**

### 2187 Attain

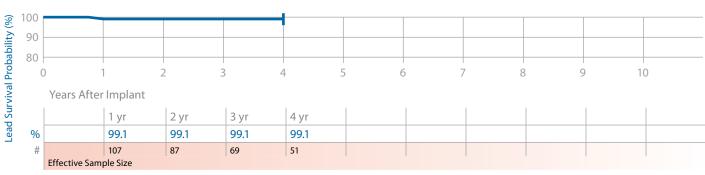
### **Product Characteristics**

US Market Release	Aug-01	Serial Number Prefix	LEY	US Returned Product Analysi	is
Estimated US Implants	17,200	Type and/or Fixation	Transvenous, Left Ventricular Cardiac Vein, Distal Continuous Curve	Implant Damage	7
Estimated US Active	9,700	Polarity	Unipolar	Electrical Malfunction	0
Advisories	None	Steroid	No	Other 1	16

1 Total



Cumulative Months of Follow-Up 5,701
Number of Leads Active in Study 45



### 2188 Attain

### **Product Characteristics**

US Market Release	Aug-01	Serial Number Prefix	LEB	US Returned Product Ana	alysis
Estimated US Implants	2,800	Type and/or Fixation	Transvenous, Coronary Sinus/ Cardiac Vein, Canted	Implant Damage	1
Estimated US Active	1,300	Polarity	Bipolar	Electrical Malfunction	1
Advisories	None	Steroid	No	Other	0

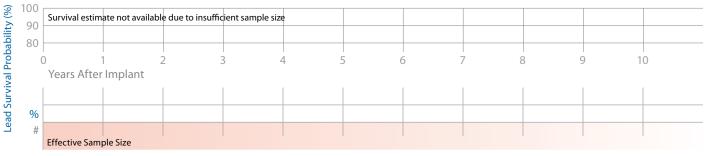
#### **System Longevity Study Results**

### Qualifying Complications 1 Total

1

Extra Cardiac Stimulation

Number of Leads Enrolled in Study 14
Cumulative Months of Follow-Up 386
Number of Leads Active in Study 1



# Left-Heart Leads continued

### 4193 Attain

#### **Product Characteristics**

1193	Attairi				Product Chara	cteristics					
	US Market Rel	ease	May-02	:	Serial Number P	refix B	AA		US Ret	urned Product An	alysis
	Estimated US	Implants	114,500	-	Type and/or Fixa		ransvenous, Left \ ein, Distal Double	Ventricular Cardia e Curve	С	Implant Damage	64
	Estimated US	Active	78,600	1	Polarity	U	nipolar		Elect	rical Malfunction	19
	Advisories		None	9	Steroid	Υ	es			Other	65
ysten	n Longevity St	tudy Resul	lts		(	Qualifying	Complications	34 Total			
	Number of Lea	ads Enrolle	d in Study	670		Cor	nductor Fracture	1	L	ead Dislodgement	13
	Cumulative M	onths of Fo	llow-Up	20,571		Extra Car	diac Stimulation	6		fied Clinical Failure	3
	Number of Lea	ads Active i	n Study	280		Fa	ilure to Capture	11			
<u>§</u> 10	0										
9	0										
8 2	0										
) -	0	1	2	3	4	5	6	7 8		9 10	
VIVa	Years Afte	r Implant									
Lead Survival Probability (%)		1 yr	2 yr	3 yr	4 yr	5 yr	at 63 mo				
	%	95.8	94.7	93.8	93.8	93.8	93.8				
	#	483	358	267	168	64	47				

### 4194 Attain

Effective Sample Size

ו דכוו	rttairi			Toduct Chi	iracterist	ics				
ι	US Market Release	Aug-04	:	Serial Numbe	r Prefix	LFG		US Returne	d Product An	alysis
E	Estimated US Implants 78,400  Estimated US Active 64,500  Advisories None		-	Type and/or Fixation		Transvenous, Left V Cardiac Vein, Distal	Impla	Implant Damage		
E			Polarity			Bipolar		Electrical N	Electrical Malfunction	
,			9	Steroid		Yes		Othe		7
ystem	Longevity Study I	Results			Qualif	ying Complications	6 Total			
1	Number of Leads En	nrolled in Study	433			Failure to Capture	1			
(	Cumulative Months	of Follow-Up	8,577			Lead Dislodgement	5			
1	Number of Leads Ac	ctive in Study	332							
100										
90										
80										
OD OU	0 1	2	3	4	5	6	7 8	9	10	
Survival Probability (%)	Years After Imp		J		3		,		10	
N N	1 yr	2 yr	3 yr							
% Fead	99.2	97.9	97.9							
# <sup>#</sup>	281	141	45							
	Effective Sample Siz	ze								

# Left-Heart Leads continued

## **Lead Survival Summary** (95% Confidence Interval)

	ase			Leads Enrolled Leads Active in Study		nths of udy	Device	Survival	Probabil	ity (%)						
Model Number	Family US Market Release	. Market Rele	US Market Rele Leads Enrolled		Qualifying Complications Cumulative Month: Follow-Up in Study	Years A	fter Impl									
žž		S	٩	Le	ರ ೮	3.5	1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr
2187	Attain	Aug-01	133	45	1	5,701	99.1 +0.8/-5.3	99.1 +0.8/-5.3	99.1 +0.8/-5.3	99.1 +0.8/-5.3						
2188	Attain	Aug-01	14	1	1	386	Survival e	stimate no	t available	due to insu	ıfficient sar	nple size				
4193	Attain	May-02	670	280	34	20,571	95.8 +1.3/-2.0	94.7 +1.6/-2.3	93.8 +1.8/-2.5	93.8 +1.8/-2.5	93.8 +1.8/-2.5	93.8 +1.8/-2.5 at 63 mo				
4194	Attain	Aug-04	433	332	6	8,577	99.2 +0.5/-1.8	97.9 +1.2/-2.7	97.9 +1.2/-2.7							

Source: System Longevity Study Data as of July 31, 2008

## **US Returned Product Analysis Summary**

Model Number	Family	US Market Release	Estimated US Implants	Estimated US Active	lmplant Damage	Electrical Malfunction	Other
2187	Attain	Aug-01	17,200	9,700	7	0	16
2188	Attain	Aug-01	2,800	1,300	1	1	0
4193	Attain	May-02	114,500	78,600	64	19	65
4194	Attain	Aug-04	78,400	64,500	93	6	7

Source: Returned Product Analysis
Data as of July 31, 2008

### **Reference Chart**

Model Number	Family	Туре	Insulation	Conductor Material	Tip Electrode	Connector Type
2187	Attain	Transvenous Cardiac Vein Preformed Body	Polyurethane (55D)	MP35N	Platinized Platinum	IS-1 UNI
2188	Attain	Transvenous Cardiac Vein Preformed Body	Polyurethane (55D)	MP35N	Platinized Platinum	IS-1 BI
4193	Attain	Transvenous Cardiac Vein Preformed Body	Polyurethane (55D)	MP35N	Platinized Platinum	IS-1 UNI
4194	Attain	Transvenous Cardiac Vein Preformed Body	Polyurethane (55D)/ Silicone (4719)	MP35N	Platinum Alloy	IS-1 BI

## **Defibrillation Leads**

## 6721, 6921 Epicardial Patch

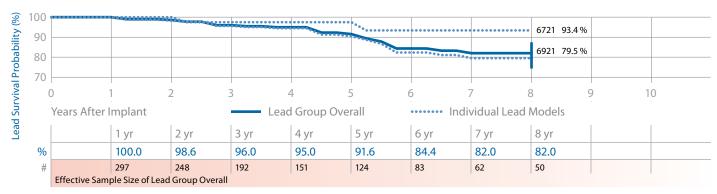
### **Product Characteristics**

US Market Release	Feb-93	Serial Number Prefix	TBH, TBG, TBB, TAD, TAC, or TAB	US Returned Product Ana	alysis
Estimated US Implants	9,200	Type and/or Fixation	Epicardial Defib Patch, Suture	Implant Damage	5
Estimated US Active	2,100	Polarity	Defib Electrode only	Electrical Malfunction	79
Advisories	None	Steroid	No	Other	0

### System Longevity Study Results

### Qualifying Complications 28 Total

Number of Leads Enrolled in Study	407	Conductor Fracture	20	Insulation (not further defined)	3
Cumulative Months of Follow-Up	18,247	Failure to Capture	2		
Number of Leads Active in Study	14	Impedance Out of Range	3		



## **6930 Sprint Fidelis**

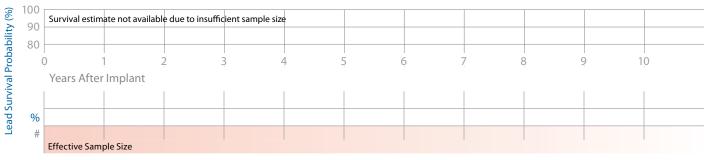
### **Product Characteristics**

US Market Release	Sep-04	Serial Number Prefix	LFK	US Returned Product Ana	alysis
Estimated US Implants	400	Type and/or Fixation	Transvenous, Vent, Defib and Pace/ Sense, Tines	Implant Damage	0
Estimated US Active	300	Polarity	True Bipolar/One Coil	Electrical Malfunction	2
Advisories	1	Steroid	Yes	Other	0
see page 144 – 2007 Pote Conductor Wire Fracture					

### **System Longevity Study Results**

#### **Qualifying Complications** 0 Total

Number of Leads Enrolled in Study	4
Cumulative Months of Follow-Up	59
Number of Leads Active in Study	4



## **6931 Sprint Fidelis**

### **Product Characteristics**

US Market Release	Sep-04	Serial Number Prefix	LFL	US Returned Product An	alvsis
Estimated US Implants	8,300	Type and/or Fixation	Transvenous, Vent, Defib and Pace/ Sense, Screw-in	Implant Damage	27
Estimated US Active	6,800	Polarity	True Bipolar/One Coil	Electrical Malfunction	56
Advisories	1	Steroid	Yes	Other	0
see page 144 – 2007 Pote Conductor Wire Fracture					

### System Longevity Study Results

211

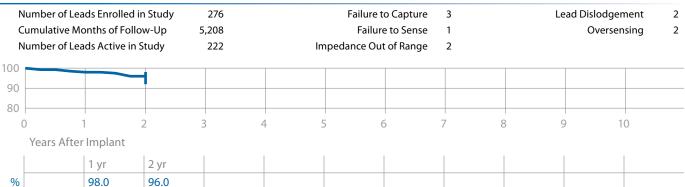
**Effective Sample Size** 

Lead Survival Probability (%)

Lead Survival Probability (%)

#

### Qualifying Complications 10 Total



# 6932 Sprint Product Characteristics

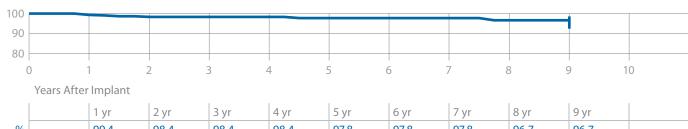
42

US Market Release	Aug-96	Serial Number Prefix	TCA	US Returned Product An	alysis
Estimated US Implants	15,300	Type and/or Fixation	Transvenous, Vent, Defib and Pace/ Sense, Tines	Implant Damage	16
Estimated US Active	5,900	Polarity	True Bipolar/One Coil	Electrical Malfunction	39
Advisories	None	Steroid	Yes	Other	7

### **System Longevity Study Results**

### Qualifying Complications 8 Total

Number of Leads Enrolled in Study	410	Extra Cardiac Stimulation	1
Cumulative Months of Follow-Up	20,548	Failure to Capture	2
Number of Leads Active in Study	75	Failure to Sense	2
		Oversensing	3



### 6933, 6937, 6937A, 6963 SVC/CS

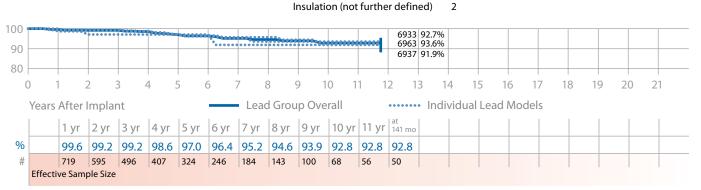
### **Product Characteristics**

US Market Release	Dec-93	Serial Number Prefix	TAT, TBU, or TAF	US Returned Product An	alysis
Estimated US Implants	17,600	Type and/or Fixation	Transvenous CS or SVC Defib	Implant Damage	31
Estimated US Active	5,200	Polarity	One Defib Coil	Electrical Malfunction	197
Advisories	None	Steroid	No	Other	13

### System Longevity Study Results

### Qualifying Complications 24 Total

Number of Leads Enrolled in Study	966	Conductor Fracture	15	Lead Dislodgement	1
Cumulative Months of Follow-Up	47,573	Failure to Capture	1	<b>Unspecified Clinicial Failure</b>	3
Number of Leads Active in Study	39	Impedance Out of Range	2		
			_		



### 6936, 6966 Transvene

Lead Survival Probability (%)

### **Product Characteristics**

US Market Release	Dec-93	Serial Number Prefix	TAV or TAL	US Returned Product An	alysis
Estimated US Implants	24,600	Type and/or Fixation	Transvenous, Vent, Defib and Pace/Sense, Screw-in	Implant Damage	90
Estimated US Active	5,300	Polarity	True Bipolar/One Coil	Electrical Malfunction	465
Advisories	None	Steroid	No	Other	19

### **System Longevity Study Results**

Effective Sample Size

### Qualifying Complications 148 Total

	١	Numbe	er of Lea	ads Enr	olled ir	ո Study	' 1	1,349				Co	nducto	r Fract	ure	18			Impe	dance	Out o	of Rang	је	5
	(	Cumula	ative M	onths c	of Follo	w-Up	67	7,334	Extra Cardiac Stimulation				ion	2		Insula	tion (	not fu	ırther	define	d)	14		
	N	Numbe	er of Lea	ads Act	ive in S	tudy		45				F	ailure t	o Capt	ure	8					Ove	rsensir	ıg	92
													Failur	e to Sei	nse	4		U	nspec	ified	Clinica	al Failu	re	5
(%	100	CHINING EN		-	1000000																			
ead Survival Probability (%)	90					200000																_	+	
pap	80									•••••	6966	61.9%												
I Pro	70									******	0300	61.9%												
viv	60											60.7%	To bearing	-										
Sur	50										0730	00.7 70		•										
Lead	(	0	1 :	2 3	3 4	1 5	5 6	5 7	7 8	3 9	9 1	0 1	1 1	2 1.	3 1	4 1	5 10	5 1	7	18	19	20	21	
		Years	After	Implar	nt				Leac	d Grou	p Ove	rall		•••••	Indi	vidual	Lead I	Node	ls					
			1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	12 yr	at 147 mo									
	%		99.2	98.4	97.0	96.0	92.7	87.3	79.5	75.4	69.5	65.4	63.1	62.2	61.1									
	#		1,042	862	711	582	472	353	251	195	135	95	74	55	51									

## 6939, 6999 Sub-Q Patch

### **Product Characteristics**

	US Market Release	Dec-93		Serial Number	er Prefix	TBA or TA	P		US Ret	urned Product Ai	nalysis
	Estimated US Implants	4,300		Type and/or	Fixation	Subcutan	eous Defil	Patch, Suture		Implant Damage	4
	Estimated US Active	800		Polarity		Defib Elec	trode Onl	у	Electi	rical Malfunction	33
	Advisories	None		Steroid		No				Other	1
Syster	n Longevity Study Res	ults			Qualifyi	ng Compli	cations	20 Total			
	Number of Leads Enroll	ed in Study	384			Conductor I	racture	10	Unspecif	ied Clinical Failure	2
	Cumulative Months of F	ollow-Up	17,670			Failure to	Capture	2			
	Number of Leads Active	in Study	6		Insulation (	not further o	defined)	6			
<b>©</b> 10	00		•••••	•••••••							
9	90		***************************************		Constitution of the last				6939	92.4%	
bility	/0							•	6999	84.6%	



## 6942 Sprint

	US Market Rel	ease	Jul-97		Serial N	umber Prefix	TCB			US R	eturned Prod	uct Ana	alysis
	Estimated US	mplants	18,100		Type an	nd/or Fixation		enous, Vent, I ense, Tines	Defib and	Implant Damage			31
	Estimated US	Active	7,500		Polarity	1	Integra	ated Bipolar/	Two Coils	Ele	ctrical Malfunc	tion	37
	Advisories		None		Steroid		Yes				0	ther	5
Syster	m Longevity St	udy Results				Qual	ifying Com	plications	7 Total				
	Number of Lea	ads Enrolled i	n Study	351			Conduct	or Fracture	1		Oversei	nsing	3
	Cumulative M	onths of Follo	w-Up 1	5,293			Failu	re to Sense	1	Unspe	cified Clinical Fa	ailure	1
	Number of Lea	ads Active in S	Study	58			Lead Disl	odgement	1				
<b>3</b> 10	0												
ty (9	00												
iliqu	30												
roba	0	1	2	3	4	1 4	 	6	7	8	9 1	10	
Lead Survival Probability (%)	Years After								,				
Sur		1 yr	2 yr	3 yr	r	4 yr	5 yr	6 yr	7 yr	8 yr			
-ead	%	98.9	98.9	97.8	3	97.2	96.3	96.3	96.3	96.3			
_	#	248	201	155		128	108	83	70	51			
	Effective Sam	ple Size											

## 6943 Sprint

### **Product Characteristics**

43	Spriiit			Product Cha	racteristic							
U	US Market Release	Oct-97		Serial Number	r Prefix	TCE		US	Returned Produ	uct Ana	alysis	
E	Estimated US Implants	21,300		Type and/or F	ixation	Transvenous, Ver Pace/Sense, Scre		Implant Damage				
E	Estimated US Active	9,000	Polarity			True Bipolar/One	Coil	Electrical Malfunction			68	
,	Advisories	None		Steroid		Yes			Ot	ther	8	
tem	Longevity Study Res	sults			Qualifyir	ng Complications	66 Total					
1	Number of Leads Enrol	lled in Study	1,311		(	Conductor Fracture	e 15	Insulation	n (not further defi	ined)	1	
(	Cumulative Months of Follow-Up Number of Leads Active in Study		63,333			Failure to Capture 7			Lead Dislodgement			
1			405			Failure to Sense	2 5	Oversensing				
					Imped	lance Out of Range	<b>4</b>	Unsp	ecified Clinical Fa	ailure	3	
100												
90									1			
80												
	0 1	2	3	4	5	6	7	8	9 1	0		
	Years After Implan	it										
	1 yr	2 yr	3 yr	4 yr	5 y	r 6 yr	7 yr	8 yr	at 105 mo			
%	98.8	98.0	96.8	95.8	93.	4 91.7	91.0	90.5	90.5			
#		929	794	613	453	318	194	97	59			
	Effective Sample Size											

## **6944** Sprint Quattro

US	Market Release	Dec-00	Seria	al Number Pı	refix TE	C			<b>US Returned</b>	Product An	alysis
Est	timated US Implants	31,300	Type and/or Fixation			Transvenous, Vent, Defib and Pace/Sense, Tines			Implan	t Damage	27
Est	timated US Active	19,600	Pola	rity	Tr	ue Bipolar/Two C	oils		Electrical Ma	alfunction	34
Ad	dvisories	None	Ster	oid	Ye	S				Other	8
stem Lo	ongevity Study Res	ults		(	Qualifying (	Complications	3 Total				
Nu	umber of Leads Enroll	ed in Study	172			Oversensing	2				
Cu	ımulative Months of F	ollow-Up	7,077		Unspecified	Clinical Failure	1				
Nu	umber of Leads Active	in Study	61								
100 =											
90 -											
90											
80			-	-				+	+	10	
0	1	2	3	4	5	6	7	8	9	10	
	Years After Implant										
90 - 80 - 0	1 yr	2 yr	3 yr	4 yr	5 yr	at 66 mo					
%	100.0	100.0	98.9	97.6	95.9	95.9					
#	131	104	83	64	54	47					
	Effective Sample Size										

## 6945 Sprint

### **Product Characteristics**

acteristics						
Prefix TD	DA .		US	Returned Pro	duct An	alysis
	ransvenous, Ver Pace/Sense, Scre			Implant Da	mage	198
In	ntegrated Bipol	ar/Two Coils	E	lectrical Malfur	nction	105
Ye	'es				Other	11
Qualifying (	Complication	s 25 Total				
Con	nductor Fracture	e 2	lmı	pedance Out of	f Range	4
Extra Card	diac Stimulation	n 1		Overs	sensing	12
Fai	ailure to Captur	e 1	Unsp	ecified Clinical	Failure	1
I	Failure to Sense	e 4				
5	6	7	8	9	10	
5 yr	6 yr	7 yr	8 yr	at 102 mo		
97.0	95.9	95.5	94.9	94.9		
377	293	217	121	51		
	377	377 293	377 293 217	377 293 217 121	377 293 217 121 51	377 293 217 121 51

## **6947** Sprint Quattro Secure

	US Market Release	e Nov-	-01	Serial Number	Prefix TD	G		US Re	turned Product An	alysis
	Estimated US Impl	lants 176,7	700	Type and/or Fi		nsvenous, Vent, ce/Sense, Screw			Implant Damage	344
	Estimated US Activ	ve 116,4	.00	Polarity	Tru	ie Bipolar/Two C	oils	Elec	trical Malfunction	117
	Advisories	No	ne	Steroid	Ye	s			Other	13
Syster	m Longevity Study	/ Results			Qualifying C	complications	19 Total			
	Number of Leads I	Enrolled in Stu	dy 1,367		Conc	ductor Fracture	3	I	_ead Dislodgement	3
	Cumulative Month	ns of Follow-U <sub>l</sub>	51,903		F	ailure to Sense	1		Oversensing	7
	Number of Leads A	Active in Study	622		Impedanc	e Out of Range	2	Unspeci	ified Clinical Failure	2
				lı	nsulation (not fu	urther defined)	1			
<b>⊚</b> 10	00									
<b>it</b>	00									
abil	30									
rob	0 1	2	3	4	5	6	7	8	9 10	
/al F	Years After Im	plant								
	rears Arter IIII	1								
Surviv	1)		r 3 y	r 4 yr	5 yr	6 yr	at 75 mo			
ead Surviv		/r 2 y			5 yr	6 yr	at 75 mo			
Lead Survival Probability (%)	1 )	/r 2 y	1 98.	7 98.2						

## **6948** Sprint Fidelis

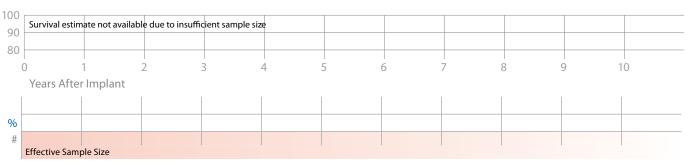
### **Product Characteristics**

US Market Release	Sep-04	Serial Number Prefix	LFH	US Returned Product An	alysis
Estimated US Implants	10,700	Type and/or Fixation	Transvenous, Vent, Defib and Pace/ Sense, Tines	Implant Damage	9
Estimated US Active	8,700	Polarity	True Bipolar/Two Coils	Electrical Malfunction	12
Advisories see page 144 – 2007 Pote		Steroid	Yes	Other	4
Conductor Wire Fracture					

### System Longevity Study Results

#### Qualifying Complications 0 Total

Number of Leads Enrolled in Study 30 Cumulative Months of Follow-Up 658 Number of Leads Active in Study 28



### **6949 Sprint Fidelis**

Lead Survival Probability (%)

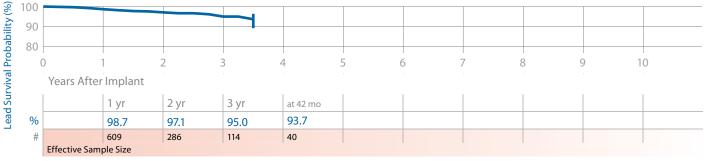
### **Product Characteristics**

US Market Release	Sep-04	Serial Number Prefix	LFJ	US Returned Product Ar	nalysis
Estimated US Implants	188,500	Type and/or Fixation	Transvenous, Vent, Defib and Pace/ Sense, Screw-in	Implant Damage	450
Estimated US Active	150,600	Polarity	True Bipolar/Two Coils	Electrical Malfunction	776
Advisories	1	Steroid	Yes	Other	41
see page 144 – 2007 Pote Conductor Wire Fracture					

### System Longevity Study Results

### Qualifying Complications 22 Total

Number of Leads Enrolled in Study	759	Conductor Fracture	2	Insulation (not further defined)	1
Cumulative Months of Follow-Up	17,601	Failure to Capture	2	Lead Dislodgement	1
Number of Leads Active in Study	596	Failure to Sense	2	Other	2
		Impedance Out of Range	2	Oversensing	10
_					



### 6996 Sub-Q Lead

Lead Survival Probability (%)

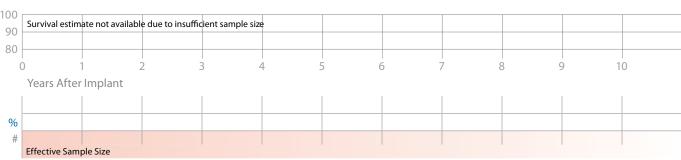
### **Product Characteristics**

US Market Release	Jun-01	Serial Number Prefix	TCR	<b>US Returned Product Analysis</b>	
Estimated US Implants	2,800	Type and/or Fixation	Subcutaneous Defib Coil, Suture	Implant Damage 0	)
Estimated US Active	2,200	Polarity	One Defib Coil	Electrical Malfunction 3	;
Advisories	None	Steroid	No	Other 0	ı

### System Longevity Study Results

**Qualifying Complications** 0 Total

Number of Leads Enrolled in Study 14 Cumulative Months of Follow-Up 359 Number of Leads Active in Study 13



Complement   Complement   Confidence   Con					,		,														
Sprint Facility Special   Special			əseələ	рә	in Study با	su		Device 5	urvival F	Probabilit	(%) <b>K</b> :										
Explane    Explane			ket R	lloau3				Years Af	ter Impla	ınt											
Sprint Holeis Sup-04   4   4     59   Survival elithrate not available due to insignificant see page 1444   2007 Potential Conductor Wine Practure   Sprint Holeis Sup-04   4   4     59   Survival elithrate not available due to insignificant sample size   Survival elithrate not available due to insignificant sample size   Survival elithrate not available due to insignificant sample size   Survival elithrate not available due to insignificant sample size   Survival elithrate not available due to insignificant sample size   Survival elithrate not available due to insignificant sample size   Survival elithrate not available due to insignificant sample size   Survival elithrate not available due to insignificant sample size   Survival elithrate not available due to insignificant sample size   Survival elithrate not available due to insignificant sample size   Survival elithrate not available due to insignificant sample size   Survival elithrate not available due to insignificant sample size   Survival elithrate not available due to insignificant sample size   Survival elithrate not available due to insignificant sample size   Survival elithrate not available due to insignificant sample size   Survival elithrate not available due to insignificant sample size   Survival elithrate not available due to insignificant sample size   Survival elithrate not available due to insignificant sample size   Survival elithrate not available due to insignificant sample size   Survival elithrate not available due to insignificant sample size   Survival elithrate not available due to insignificant sample size   Survival elithrate not available due to insignificant sample size   Survival elithrate not available due to insignificant sample size   Survival elithrate not available due to insignificant sample size   Survival elithrate not available due to insignificant sample size   Survival elithrate not available due to insignificant sample size   Survival elithrate not available due to insignificant sample size   Survival elith		Family	isM 2U	speə7				1 yr							8 yr	10 yr	12 yr	14 yr	16 yr	18 yr	20 yr
Sprint Fidelis Sep 04   4   4   4   59   Survival estimate not available due to inalfficient sample size   Advisories seepage 144 - 2007 Parential Conductor Wire Facture   Sprint Fidelis Sep 04   20   20   20   20   20   20   20		Epicardial Patch	Feb-93	407	41	28									82.0 +5.6/-7.6						
Sprint Fidelis Sep-04   276   222   10   5,208   960		Sprint Fidelis	Sep-04	4	4		59	Survivale	timate not	available	lue to insuf	ficient sam	ple size								
Sprint Fidelis Sep-04   276   222   10   5208   99.04   99.0		Advisories: seep	)age 144 - 20	007 Potenti	ial Conduct	tor Wire Fr	racture														
Sylicide See page 144 - 2007 Potential Conductor Wire Fracture   Sprint   Advisories see page 144 - 2007 Potential Conductor Wire Fracture   Sprint   Advisories see page 144 - 2007 Potential Conductor Wire Fracture   Sprint   Aug-96   410   75   8   20.548   99.4   48.4   48.4   48.4   41.2		Sprint Fidelis	Sep-04	276	222	10			96.0												
Sylvic   Aug. 96   410   75   8   205.48   994,   984,		Advisories: see p	oage 144 - 20	007 Potenti	ial Conduct	tor Wire Fi	racture														
Stock   Dec 93   966   39   24   47573   966   992   982	l	Sprint	Aug-96	410	75											96.7 +1.9/-4.2 at 108 mo					
Sub-Q Patch   Dec-93   1349   45   148   67334   992,   994,   970,   957,   950,   957,	<del>\</del>	_	Dec-93	996	39	24											92.8 +2.8/-4.5 at 141 mo				
Sprint         Jul-97         351         66         63333         980-9         987-29         982-6         981-10-26         981-1	.5.10	Transvene	Dec-93	1,349	45	148												61.1 +5.9/-6.7 at 147 mo			
Sprint         Oct-97         1,311         405         63         98.9         98.9         98.9         98.9         98.9         98.9         98.9         98.9         98.9         98.9         98.9         97.8         4.13/-3.3         4.20/-4.1	~ ~	Sub-Q Patch	Dec-93	384	9	20										86.1 +5.2/-8.0 at 99 mo					
Sprint         Oct-97         1,311         405         66         63,333         98.8         98.0         95.8         93.4         91.7         91.0         90.5         22.8         93.4         91.7         41.0/-1.2         41.1/-1.6         41.0/-1.2         41.1/-1.6         41.0/-2.0         41.0/-2.0         41.0/-2.0         41.0/-2.0         41.0/-1.2         41.1/-1.6         41.0/-2.0	١	Sprint	Jul-97	351	28	7									96.3 +2.0/-4.1						
Sprint         Dec-00         172         61         3         7,077         100.0         100.0         98.9         97.6         42.8/-6.3	l	Sprint	Oct-97	1,311	405	99										90.5 +2.2/-2.8 at 105 mo					
Sprint         Sep-97         1,158         252         25         53,783         99.6         99.1         98.8         98.1         97.0         95.9         94.9         41.47.2.8         41.47.2.2         41.47.2.2         41.64.2.3         41.87.2.8         41.87.2.8         41.87.2.8         41.87.2.8         41.87.2.8         41.87.2.8         41.87.2.8         41.87.2.9         41.87.2.9         41.87.2.3         41.87.2.8         41.87.2.9         42.77.4.5         42.77.4.5         41.87.2.9         41.87.2.9         41.87.2.9         41.87.2.9         41.87.2.9         41.87.2.9         41.87.2.9         41.87.2.9         41.87.2.9         41.87.2.9         41.87.2.9         41.87.2.9         41.87.2.9         41.87.2.9         41.87.2.9         41.8	_	Sprint Quattro	Dec-00	172	61	m							95.9 +2.8/-8.3 at 66 mo								
Sprint Output         Nov-01         1,367         622         19         51,903         99.3         99.1         98.7         98.2         40.7/-1.1         40.9/-1.6         40.9/-1.6           Sprint Fidelis         Sep-04         30         28         0         658         Survival estimate not available due to insufficient sample size           Advisories:         See page 144 - 2007 Potential Conductor Wire Fracture         2007         93.7         40.9/-1.8         40.5/-0.9         98.7         40.9/-1.8         40.9/-1.6		Sprint	Sep-97	1,158	252	25										94.9 +1.8/-2.8 at 108 mo					
Sprint Fidelis         Sep-04         30         28         0         658           Advisories:         See page 144 - 2007 Potential Conductor Wire Fracture           Sprint Fidelis         Sep-04         759         596         22         17,601           Advisories:         See page 144 - 2007 Potential Conductor Wire Fracture           Sub-Q Lead         Jun-01         14         13         0         359		Sprint Quattro Secure	Nov-01	1,367	622	19								97.7 +0.9/-1.6 at 75 mo							
Advisories: see page 144 - 2007 Potential Conductor Wire Fracture  Sprint Fidelis Sep-04 759 596 22 17,601  Advisories: see page 144 - 2007 Potential Conductor Wire Fracture  Sub-Q Lead Jun-01 14 13 0 359	~	Sprint Fidelis	Sep-04	30	28	0	658	Survivale	timate not	available	lue to insuf	ficient sam	ple size								
Sprint Fidelis         Sep-04         759         596         22         17,601           Advisories: See page 144 2007 Potential Conductor Wire Fracture           Sub-Q Lead         Jun-01         14         13         0         359		Advisories: seep	oage 144 - 20	007 Potenti	ial Conduct	tor Wire Fi	racture														
Advisories: see page 144 - 2007 Potential Conductor Wire Fracture Sub-Q Lead Jun-01 14 13 0 359		Sprint Fidelis	Sep-04	759	969	22					93.7										
Sub-Q Lead Jun-01 14 13 0 359			oage 144 - 2	007 Potenti	ial Conduct	tor Wire Fi	racture				at 42 mo										
		Sub-Q Lead	Jun-01	4	13	0	359	Survival e.	timate not	available	lue to insuf	ficient sam	ple size								

## **US Returned Product Analysis Summary**

Model Number	Family	US Market Release	Estimated US Implants	Estimated US Active	Implant Damage	Electrical Malfunction	Other
6721, 6921	<b>Epicardial Patch</b>	Feb-93	9,200	2,100	5	79	0
6930	Sprint Fidelis	Sep-04	400	300	0	2	0
6931	Sprint Fidelis	Sep-04	8,300	6,800	27	56	0
6932	Sprint	Aug-96	15,300	5,900	16	39	7
6933, 6937, 6937A, 6963	SVC/CS	Dec-93	17,600	5,200	31	197	13
6936, 6966	Transvene	Dec-93	24,600	5,300	90	465	19
6939, 6999	Sub-Q Patch	Dec-93	4,300	800	4	33	1
6942	Sprint	Jul-97	18,100	7,500	31	37	5
6943	Sprint	Oct-97	21,300	9,000	50	68	8
6944	Sprint Quattro	Dec-00	31,300	19,600	27	34	8
6945	Sprint	Sep-97	44,000	19,800	198	105	11
6947	Sprint Quattro Secure	Nov-01	176,700	116,400	344	117	13
6948	Sprint Fidelis	Sep-04	10,700	8,700	9	12	4
6949	Sprint Fidelis	Sep-04	188,500	150,600	450	776	41
6996	Sub-Q Lead	Jun-01	2,800	2,200	0	3	0

## **Reference Chart**

			Pin Conf	iguration			
Model Number	Family	Туре	Pace/ Sense	High Voltage	Lead Body Diameter	Insulation, Lead Body	Fixation, Steroid
6721	<b>Epicardial Patch</b>	Epi Patch	_	DF-1	S, M, L	Silicone, Single Lumen	Suture
6921	<b>Epicardial Patch</b>	Epi Patch	_	6.5 mm	S, M, L	Silicone, Single Lumen	Suture
6930	Sprint Fidelis	Endo RV True Bipolar Sensing	IS-1	DF-1	6.6 Fr	Silicone with Polyurethane Overlay, Multilumen	Passive, Steroid
6931	Sprint Fidelis	Endo RV True Bipolar Sensing	IS-1	DF-1	6.6 Fr	Silicone with Polyurethane Overlay, Multilumen	Active, Steroid
6932	Sprint	Endo RV True Bipolar Sensing	IS-1	DF-1	7.8 Fr	Silicone, Multilumen	Passive, Steroid
6933	SVC/CS	Endo SVC/CS Coil	_	DF-1	7 Fr	Silicone, Single Lumen	Passive
69345	Transvene	Endo RV True Bipolar Sensing	IS-1	DF-1	12 Fr	Silicone, Coaxial	Passive, Steroid
6936	Transvene	Endo RV True Bipolar Sensing	IS-1	DF-1	10 Fr	Polyurethane, Coaxial	Active
6937	SVC/CS	Endo SVC Coil	_	DF-1	5.5 Fr	Silicone, Single Lumen	Passive
6937A	SVC/CS	Endo SVC Coil	_	DF-1	7.5 Fr	Silicone with Polyurethane Overlay, Single Lumen	Passive
6939	Sub-Q Patch	SQ Patch	_	DF-1	One Size	Silicone, Single Lumen	Suture
6942	Sprint	Endo RV/SVC Integrated Bipolar Sensing	IS-1	2 DF-1	7.8 Fr	Silicone, Multilumen	Passive, Steroid
6943	Sprint	Endo RV True Bipolar Sensing	IS-1	DF-1	7.8 Fr	Silicone, Multilumen	Active, Steroid
6944	Sprint Quattro	Endo RV/SVC True Bipolar Sensing	IS-1	2 DF-1	8.2 Fr	Silicone with Polyurethane Overlay, Multilumen	Passive, Steroid
6945	Sprint	Endo RV/SVC Integrated Bipolar Sensing	IS-1	2 DF-1	7.8 Fr	Silicone, Multilumen	Active, Steroid
6947	Sprint Quattro Secure	Endo RV/SVC True Bipolar Sensing	IS-1	2 DF-1	8.2 Fr	Silicone with Polyurethane Overlay, Multilumen	Active, Steroid
6948	Sprint Fidelis	Endo RV/SVC True Bipolar Sensing	IS-1	2 DF-1	6.6 Fr	Silicone with Polyurethane Overlay, Multilumen	Passive, Steroid
6949	Sprint Fidelis	Endo RV/SVC True Bipolar Sensing	IS-1	2 DF-1	6.6 Fr	Silicone with Polyurethane Overlay, Multilumen	Active, Steroid
6963	SVC/CS	Endo SVC/CS Coil	_	6.5 mm	7 Fr	Silicone, Single Lumen	Passive
6966	Transvene	Endo RV True Bipolar Sensing	3.2 mm L.P.	6.5 mm	10 Fr	Polyurethane, Coaxial	Active
6996	Sub-Q Lead	SQ Coil	_	DF-1	7.5 Fr	Silicone, Single Lumen	Passive
6999	Sub-Q Patch	SQ Patch	_	6.5 mm	One Size	Silicone, Single Lumen	Suture

# **Pacing Leads**

### 3830 SelectSecure

### **Product Characteristics**

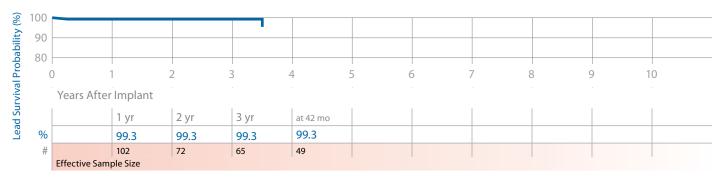
US Market Release	Aug-05	Serial Number Prefix	LFF	US Returned Product Ana	alysis
Estimated US Implants	10,800	Type and/or Fixation	Transvenous, V or A, Screw-in	Implant Damage	18
Estimated US Active	9,200	Polarity	Bipolar	Electrical Malfunction	4
Advisories	None	Steroid	Yes	Other	1

Failure to Sense

### **Atrial Placement**

System Longevity Study Results **Qualifying Complications** 1 Total

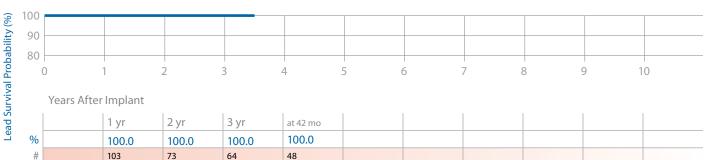
Number of Leads Enrolled in Study 160 Cumulative Months of Follow-Up 4,613 Number of Leads Active in Study 92



### **Ventricular Placement**

**Qualifying Complications System Longevity Study Results** 0 Total

Number of Leads Enrolled in Study 144 Cumulative Months of Follow-Up 4,519 Number of Leads Active in Study 81



### 4003, 4003M CapSure

### **Product Characteristics**

US Market Release	Jul-86	Serial Number Prefix	IH or LAX	US Returned Product Analysis
Estimated US Implants	40,000	Type and/or Fixation	Transvenous, Vent., Tines	Implant Damage 24
Estimated US Active	6,400	Polarity	Unipolar	Electrical Malfunction 59
Advisories	None	Steroid	Yes	Other 2

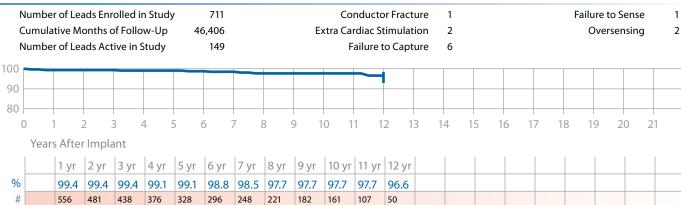
### **Ventricular Placement**

Lead Survival Probability (%)

**System Longevity Study Results** 

**Effective Sample Size** 

### Qualifying Complications 12 Total



### 4004, 4004M CapSure

#### **Product Characteristics**

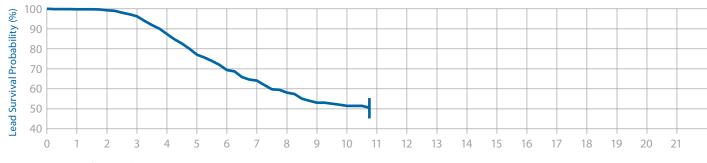
US Market Release	Feb-89	Serial Number Prefix	PS or LAV	US Returned Product Analysis
Estimated US Implants	74,500	Type and/or Fixation	Transvenous, Vent., Tines	Implant Damage 55
Estimated US Active	2,300	Polarity	Bipolar	Electrical Malfunction 684
Advisories	1	Steroid	Yes	Other 19
see page 150 – 1993 Lead Below Expectations	Survival			

#### **Ventricular Placement**

**System Longevity Study Results** 

### Qualifying Complications 277 Total

Number of Leads Enrolled in Study	1,640	Conductor Fracture	7	Insulation (ESC)	4
Cumulative Months of Follow-Up	71,629	Electrical Abandonment	1	Insulation (MIO)	4
Number of Leads Active in Study	4	Extra Cardiac Stimulation	2	Insulation (not further defined)	7
		Failure to Capture	131	Medical Judgment	1
		Failure to Sense	62	Oversensing	25
		Impedance Out of Range	32	Unspecified Clinical Failure	1



### Years After Implant

		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	at 129 mo					
%		99.8	99.3	96.3	87.4	77.1	69.4	64.1	58.1	53.1	51.5	50.6					
#		1,192	1,020	824	630	453	314	231	161	118	78	51					
	Effecti	ve Samı	ole Size														

### 4011 Target Tip

#### **Product Characteristics**

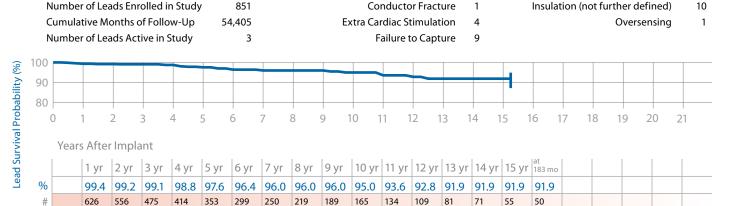
US Market Release	Nov-82	Serial Number Prefix	IB	US Returned Product Ana	alysis
Estimated US Implants	64,000	Type and/or Fixation	Transvenous, Vent., Tines	Implant Damage	29
Estimated US Active	6,500	Polarity	Unipolar	Electrical Malfunction	147
Advisories	None	Steroid	No	Other	5

### **Ventricular Placement**

System Longevity Study Results

**Effective Sample Size** 

#### Qualifying Complications 25 Total



## **4012** Target Tip

### **Product Characteristics**

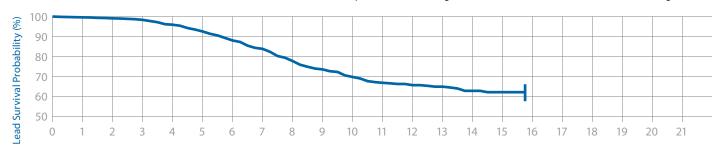
US Market Release	Jul-83	Serial Number Prefix	HQ	US Returned Product Analysis
Estimated US Implants	96,800	Type and/or Fixation	Transvenous, Vent., Tines	Implant Damage 50
Estimated US Active	5,000	Polarity	Bipolar	Electrical Malfunction 825
Advisories	1	Steroid	No	Other 34
see page 151 – 1991 Lead Below Expectations	Survival			

### **Ventricular Placement**

**System Longevity Study Results** 

### Qualifying Complications 316 Total

9	Insulation (ESC)	6	Conductor Fracture	2,543	Number of Leads Enrolled in Study
4	Insulation (MIO)	3	Extra Cardiac Stimulation	151,094	Cumulative Months of Follow-Up
16	Insulation (not further defined)	126	Failure to Capture	12	Number of Leads Active in Study
1	Medical Judgment	77	Failure to Sense		
48	Oversensing	26	Impedance Out of Range		



#### Years After Implant

		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	12 yr	13 yr	14 yr	15 yr	at 189 mo			
%		99.6	99.1	98.4	95.9	92.6	88.1	83.9	77.8	73.6	69.8	66.9	65.7	65.0	62.9	62.2	62.2			
#		1,935	1,714	1,528	1,310	1,084	888	698	522	400	307	243	200	144	98	69	51			
	Effectiv	ve Sami	محنک مام																	

## 4023 CapSure SP

US Market Release	Aug-91	Serial Number Prefix	LAK	US Returned Product Ana	alysis
Estimated US Implants	43,700	Type and/or Fixation	Transvenous, Vent., Tines	Implant Damage	47
Estimated US Active	13,500	Polarity	Unipolar	<b>Electrical Malfunction</b>	21
Advisories	None	Steroid	Yes	Other	6

		<b>ular F</b> Longe		<b>nent</b> :udy R	esults						Qua	lifying	ı Com <sub>l</sub>	olicatio	ns 2	20 T	otal							
	١	lumbe	r of Lea	ads Enr	olled i	ո Study	,	1,158			Ex	ktra Ca	rdiac S	timulati	on	1		Insu	lation	(not fu	ırther	defined	1)	1
	(	Cumula	tive M	onths c	of Follo	w-Up	63	3,970				F	ailure	to Captu	ire 1	15				Lead	Dislod	gemen	t	2
	١	lumbe	r of Lea	ads Act	ive in S	study		363			Ir	npeda	nce Ou	t of Ran	ge	1								
(0)	100																							
ity (9	90																						_	_
jabil	80																							
Prob	(	) 1	1 2	2 3	3 4	4 !	5 6	5 7	7 8	8 9	9 1	0 1	1 1	2 13	14	4	15	16	17	18	19	20	21	
vall		Year	s After	Impla	nt																			
Lead Survival Probability (%)			1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	at 141 mo										
sad	%		99.9	99.3	98.8	98.6	98.6	98.2	97.0	96.7	96.7	96.1	94.7	94.7										
Ľ	#		886	765	681	603	514	422	292	208	153	80	61	49										
		Effecti	ve Samı	ple Size																				

### 4024 CapSure SP

#### **Product Characteristics**

US Market Release	Oct-91	Serial Number Prefix	LAJ	US Returned Product Analysis
Estimated US Implants	229,200	Type and/or Fixation	Transvenous, Vent., Tines	Implant Damage 264
Estimated US Active	76,900	Polarity	Bipolar	Electrical Malfunction 119
Advisories	None	Steroid	Yes	Other 34

Failure to Capture

3

### **Ventricular Placement**

**System Longevity Study Results Qualifying Complications** 3 Total

Number of Leads Enrolled in Study 1,214 Cumulative Months of Follow-Up 52,003 Number of Leads Active in Study 27



### 4033 CapSure Z

### **Product Characteristics**

US Market Release	not US released	Serial Number Prefix	LCA	US Returned Product Analysi	iS
Estimated US Implants	n/a	Type and/or Fixation	Transvenous, Vent., Tines	Implant Damage	2
Estimated US Active	n/a	Polarity	Unipolar	Electrical Malfunction	0
Advisories	None	Steroid	Yes	Other	0

#### **Ventricular Placement**

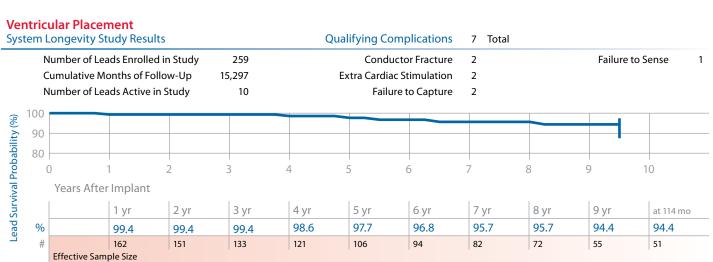
**Effective Sample Size** 

Lead Survival Probability (%)

System Longevity Study Results **Qualifying Complications** 10 Total Number of Leads Enrolled in Study 540 **Conductor Fracture** 1 Cumulative Months of Follow-Up 8 28,426 Failure to Capture Number of Leads Active in Study 43 Impedance Out of Range 1 100 90 80 5 9 3 6 10 Years After Implant 3 yr 4 yr 5 yr 6 yr 7 yr 8 yr 2 yr at 105 mo 95.3 98.5 98.1 97.5 97.5 96.5 % 99.4 99.4 98.8 431 384 322 252 201 160 111 77 51

## 4057, 4057M Screw-In

US Market Release	Aug-88	Serial Number Prefix	XQ or LAN	US Returned Product Ana	alysis
Estimated US Implants	12,100	Type and/or Fixation	Transvenous, V or A, Screw-in	Implant Damage	39
Estimated US Active	2,500	Polarity	Unipolar	Electrical Malfunction	6
Advisories	None	Steroid	No	Other	4



### 4058, 4058M Screw-In

### **Product Characteristics**

US Market Release	Jan-89	Serial Number Prefix	ZY or LAW	US Returned Product An	alysis
Estimated US Implants	111,100	Type and/or Fixation	Transvenous, V or A, Screw-in	Implant Damage	388
Estimated US Active	23,400	Polarity	Bipolar	Electrical Malfunction	243
Advisories	None	Steroid	No	Other	23

### **Atrial Placement**

System Longevity Study Results

### Qualifying Complications 32 Total

Number of Leads Enrolled in Study	2,364	Extra Cardiac Stimulation	1	Insulation (not further defined)	1
Cumulative Months of Follow-Up	131,206	Failure to Capture	15	Lead Dislodgement	3
Number of Leads Active in Study	53	Failure to Sense	7	Oversensing	1
		Impedance Out of Range	4		



	i cai.	3 / ([(C]	ППРІС	1110															
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	12 yr	13 yr	14 yr	at 174 mo			
%		99.9	99.6	99.5	99.1	98.7	98.3	98.2	97.5	97.5	96.1	96.1	96.1	95.0	95.0	95.0			
#		1,756	1,547	1,336	1,156	993	790	609	455	334	219	153	116	85	65	52			
	Effecti	ve Samp	ole Size																

### **Ventricular Placement**

System Longevity Study Results

### Qualifying Complications 52 Total

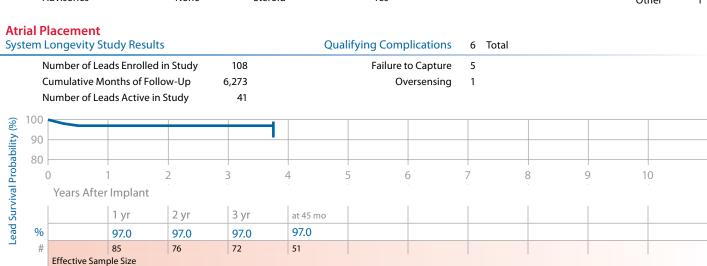
	Number of Leads Enrolled in Study	1,690	Conductor Fracture	4	Impedance Out of Range	7
	Cumulative Months of Follow-Up	77,187	Extra Cardiac Stimulation	3	Insulation (not further defined)	4
	Number of Leads Active in Study	55	Failure to Capture	22	Lead Dislodgement	1
			Failure to Sense	10	Oversensing	1
_						



	rear	s Arter	шріс	1111														
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	12 yr	13 yr				
%		99.4	99.2	99.1	98.7	97.9	96.9	94.6	93.6	91.5	89.2	87.6	85.4	84.2				
#		1,123	943	789	663	533	423	318	233	177	121	91	68	49				
	Effecti	ve Samı	ole Size															

## 4067 CapSureFix

US Market Release	Jan-97	Serial Number Prefix	LCV	US Returned Product Analysi	is
Estimated US Implants	1,300	Type and/or Fixation	Transvenous, V or A, Screw-in	Implant Damage	3
Estimated US Active	400	Polarity	Unipolar	Electrical Malfunction	1
Advisories	None	Steroid	Yes	Other	1



2

8

7

**Unspecified Clinical Failure** 

## Pacing Leads continued

### 4068 CapSureFix

#### **Product Characteristics**

US Market Release	Mar-96	Serial Number Prefix	LCE	US Returned Product Ar	nalysis
Estimated US Implants	131,700	Type and/or Fixation	Transvenous, V or A, Screw-in	Implant Damage	406
Estimated US Active	52,100	Polarity	Bipolar	Electrical Malfunction	98
Advisories	None	Steroid	Yes	Other	11

#### **Atrial Placement**

**System Longevity Study Results Qualifying Complications** 54 Total Number of Leads Enrolled in Study 2,401 Conductor Fracture 1 Insulation (ESC) Lead Dislodgement Cumulative Months of Follow-Up 120,334 Extra Cardiac Stimulation 1 Number of Leads Active in Study 581 Failure to Capture 19 Oversensing

Impedance Out of Range

Failure to Sense

100 Lead Survival Probability (%) 90 80 8 19 9 10 12 13 14 15 16 20 21

	Year:	s Artei	ımpıa	ant														
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	at 135 mo					
%		99.0	98.8	98.3	98.1	97.6	97.4	97.3	96.3	95.4	94.9	93.4	93.4					
#		1,896	1,620	1,357	1,101	854	646	448	326	228	140	59	44					
	Effecti	ve Samı	ole Size															

### **Ventricular Placement**

Lead Survival Probability (%)

**System Longevity Study Results** 

#### **Qualifying Complications** 33 Total Number of Leads Enrolled in Study 1,799 **Conductor Fracture** 2 Failure to Sense 3 Cumulative Months of Follow-Up 2 87,084 Extra Cardiac Stimulation Impedance Out of Range 4 Number of Leads Active in Study 503 Failure to Capture 19 Oversensing 3 100 90 80 10 12 13 16 11 15 Years After Implant

10 yr | at 126 mo 1 yr | 2 yr | 3 yr | 4 yr | 5 yr | 6 yr | 7 yr | 8 yr | 9 yr % 96.6 99.3 98.8 98.8 98.4 98.1 97.7 97.0 94.4 94.4 94.4 1,427 1,214 1,031 839 638 457 288 170 94 46 **Effective Sample Size** 

## **4073** CapSure Sense

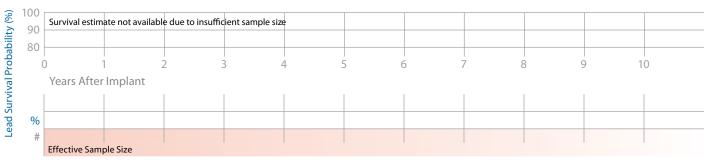
### **Product Characteristics**

US Market Release	Jun-02	Serial Number Prefix	BBF	<b>US Returned Product Analysis</b>
Estimated US Implants	600	Type and/or Fixation	Transvenous, Vent., Tines	Implant Damage 1
Estimated US Active	400	Polarity	Unipolar	Electrical Malfunction 0
Advisories	None	Steroid	Yes	Other 0

### **Atrial Placement**

System Longevity Study Results	Qualifying Complications	0 Total

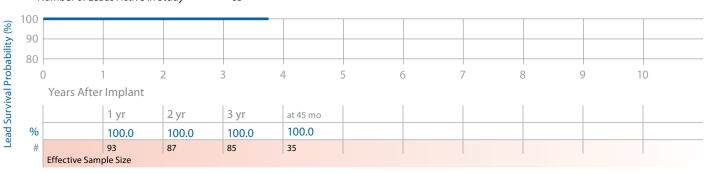
Number of Leads Enrolled in Study 1 Cumulative Months of Follow-Up 46 Number of Leads Active in Study 1



### **Ventricular Placement**

System Longevity Study Results **Qualifying Complications** 0 Total

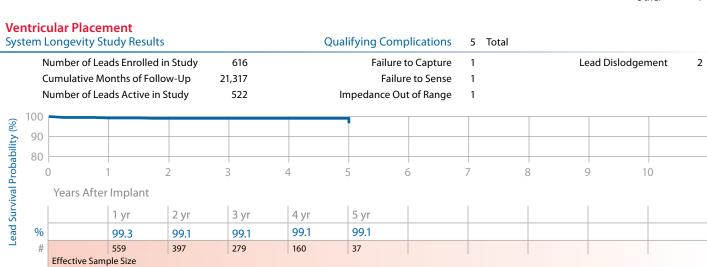
Number of Leads Enrolled in Study 100 Cumulative Months of Follow-Up 4,266 Number of Leads Active in Study 83



Data as of July 31, 2008

## **4074** CapSure Sense

US Market Release	Jun-02	Serial Number Prefix	BBD	US Returned Product Analysis
Estimated US Implants	57,800	Type and/or Fixation	Transvenous, Vent., Tines	Implant Damage 13
Estimated US Active	43,200	Polarity	Bipolar	Electrical Malfunction 7
Advisories	None	Steroid	Yes	Other 1



## **4076** CapSureFix Novus

### **Product Characteristics**

US Market Release	Feb-04	Serial Number Prefix	BBL	US Returned Product Ana	alysis
Estimated US Implants	170,300	Type and/or Fixation	Transvenous, V or A, Screw-in	Implant Damage	75
Estimated US Active	131,900	Polarity	Bipolar	<b>Electrical Malfunction</b>	8
Advisories	None	Steroid	Yes	Other	7

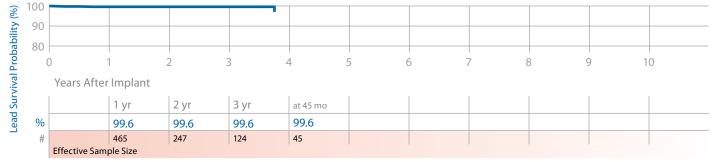
Number of	Leads Enrolled in S	Studv	637		Failure to Captu	re 1			
	e Months of Follow		13,730		Lead Dislodgeme				
Number of	Leads Active in Stu	udy	541		J				
00									
10									
00									
	1 2		3	4	5 6	7	8	9	10
0	_		3	4	5 6	7	8	9	10
0	1 2		3	4	5 6	7	8	9	10
0	fter Implant	2 yr	3   3 yr	4 at 42 mo	5 6	7	8	9	10
_	fter Implant	2 yr 99.6		ı	5 6	7	8	9	10

### **Ventricular Placement**

**System Longevity Study Results** 

**Qualifying Complications** 2 Total

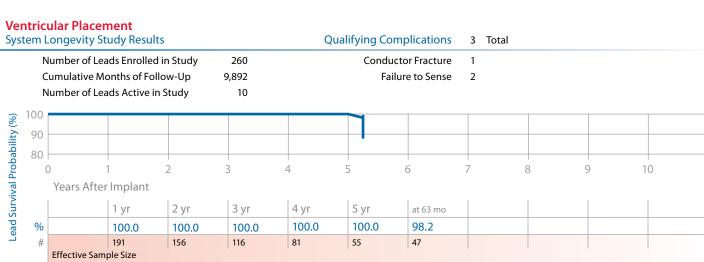
Number of Leads Enrolled in Study 599 Cumulative Months of Follow-Up 14,423 Number of Leads Active in Study 512 Failure to Capture 2



### 4081 Target Tip

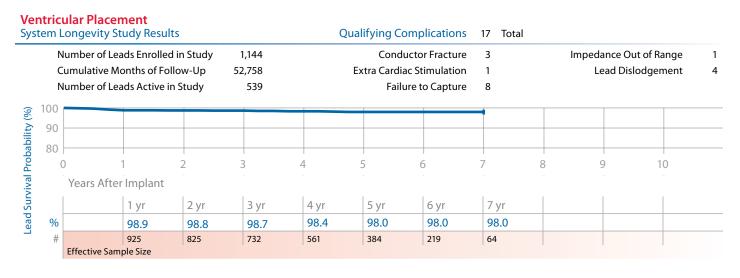
#### **Product Characteristics**

US Market Release	Jul-89	Serial Number Prefix	LAC	US Returned Product Analysis
Estimated US Implants	4,100	Type and/or Fixation	Transvenous, Vent., Tines	Implant Damage 4
Estimated US Active	800	Polarity	Unipolar	Electrical Malfunction 5
Advisories	None	Steroid	No	Other 0



### **4092** CapSure SP Novus

US Market Release	Sep-98	Serial Number Prefix	LEP	<b>US Returned Product Ana</b>	lysis
Estimated US Implants	149,500	Type and/or Fixation	Transvenous, Vent., Tines	Implant Damage	37
Estimated US Active	90,500	Polarity	Bipolar	Electrical Malfunction	16
Advisories	None	Steroid	Yes	Other	5



## 4503, 4503M CapSure

### **Product Characteristics**

US Market Release	Jul-86	Serial Number Prefix	MQ, LAY	US Returned Product Analysis
Estimated US Implants	9,000	Type and/or Fixation	Transvenous, Atrial-J, Tines	Implant Damage 2
Estimated US Active	1,300	Polarity	Unipolar	Electrical Malfunction 12
Advisories	None	Steroid	Yes	Other 0

	estimated US P	ctive	1,300	Polarity	/	Unipol	ar		Ele	ectrical Malfuncti	on 12
Α	Advisories		None	Steroid		Yes				Oth	ner
	lacement										
stem L	Longevity St	udy Results			Qua	lifying Com	olications	1 Total			
N	Number of Lea	ds Enrolled ir	n Study	59		Failur	e to Sense	1			
C	Cumulative Mo	nths of Follo	w-Up	3,242							
N	Number of Lea	ds Active in S	itudy	6							
100											
90	Survival estima	ate not availabl	e due to insuf	ficient sample siz	e						
80											
00	0 1			2	4		-	7	0	0 10	
	0 1		_	3	4	0	0	/	8	9 10	)
5	Years After	Implant									
5											
80 (90 % # % # % # % # % # % # % # # % #											
ا							1				

### 4504, 4504M CapSure

Number of Leads Enrolled in Study

Effective Sample Size

### **Product Characteristics**

US Market Release	Mar-90	Serial Number Prefix	QM or LBA	US Returned Product Analysis
Estimated US Implants	16,600	Type and/or Fixation	Transvenous, Atrial-J, Tines	Implant Damage 5
Estimated US Active	1,400	Polarity	Bipolar	Electrical Malfunction 171
Advisories	1	Steroid	Yes	Other 4
see page 149 – 1996 Lead Survival Below Expectations				

**Electrical Abandonment** 

3

### **Atrial Placement**

System Longevity Study Results Qualifying Complications 48 Total

368

				oths of Follow-Up 19,873 Extra Cardiac Stimulation is Active in Study 1 Failure to Capture Failure to Sense				e 14 Lead Dislodgement				1 1 3	
(%)	100												
ility	90												
Survival Probability	80												
al Pro	70										<del></del>		
rviv	60												
	(	0	1	2	3	4	5	6	7	8	9	10	
Lead		Years Aft	er Implant										
			1 vr	2 vr	3 vr	4 vr	5 vr	6 vr	7 vr	8 vr	at 105	mo	

Impedance Out of Range

9

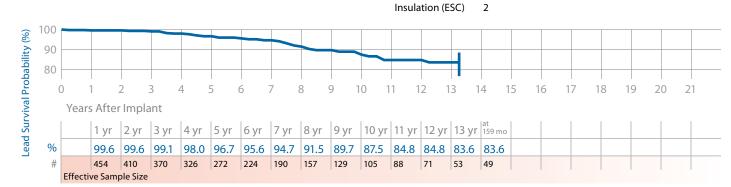
### 4512 Target Tip

#### **Product Characteristics**

US Market Release	Jul-83	Serial Number Prefix	PF	US Returned Product Analys	sis
Estimated US Implants	11,600	Type and/or Fixation	Transvenous, Atrial-J, Tines	Implant Damage	4
Estimated US Active	1,000	Polarity	Bipolar	Electrical Malfunction	84
Advisories	None	Steroid	No	Other	8

#### **Atrial Placement**

**System Longevity Study Results Qualifying Complications** 35 Total Number of Leads Enrolled in Study 600 **Electrical Abandonment** 1 Insulation (MIO) 4 2 Cumulative Months of Follow-Up 39,801 Failure to Capture 6 Insulation (not further defined) Number of Leads Active in Study Failure to Sense Lead Dislodgement 6 14 1 Impedance Out of Range 3 Oversensing



### 4523 CapSure SP

### **Product Characteristics**

US Market Release	Aug-91	Serial Number Prefix	ZE	<b>US Returned Product Analys</b>	is
Estimated US Implants	12,000	Type and/or Fixation	Transvenous, Atrial-J, Tines	Implant Damage	5
Estimated US Active	3,100	Polarity	Unipolar	Electrical Malfunction	2
Advisories	None	Steroid	Yes	Other	1

#### **Atrial Placement**

System Longevity Study Results **Qualifying Complications** Total Number of Leads Enrolled in Study 121 Impedance Out of Range 1 Cumulative Months of Follow-Up 7,160 Lead Dislodgement 2 Number of Leads Active in Study 18 Oversensing 100 Lead Survival Probability (%) 90 80 10 Years After Implant 1 yr 2 yr 3 yr 4 yr at 57 mo 98.1 % 98.1 98.1 98.1 98.1 50 81 71 58 **Effective Sample Size** 

## 4524 CapSure SP

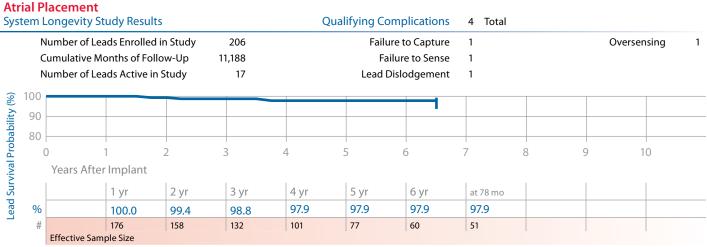
### **Product Characteristics**

US Market Release	Oct-91	Serial Number Prefix	LAR	US Returned Product Analysis
Estimated US Implants	106,900	Type and/or Fixation	Transvenous, Atrial-J, Tines	Implant Damage 47
Estimated US Active	34,600	Polarity	Bipolar	Electrical Malfunction 28
Advisories	None	Steroid	Yes	Other 8

	lumber of Lea	ds Enrolled	in Study	911		Failu	re to Capture	3			
	umulative Mo		•	40,011			lure to Sense	2			
	lumber of Lea		•	58			islodgement	1			
00											
90											
80											
00			2	2	4	5	6	7	8	9	10
(	) 1		2	3	4	5	0	/	O	7	10
	) 1 Years After	mplant	2	5	4	,					
		Implant 1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	
	Years After	'	2 yr 99.3					7 yr 99.0			at 117 m

## 4533 CapSure Z

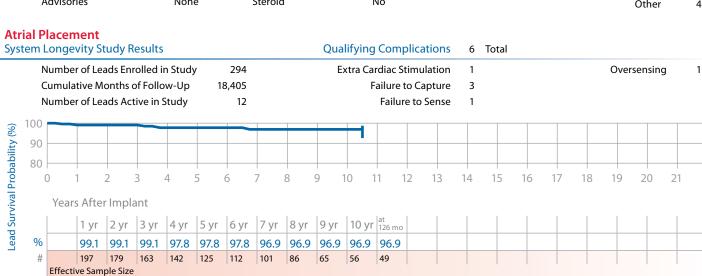
	US Market Release	not US released	Serial Number Prefix	LCB	US Returned Product Analysis		
	Estimated US Implants	n/a	Type and/or Fixation	Transvenous, Atrial-J, Tines	Implant Damage	0	
	Estimated US Active	n/a	Polarity	Unipolar	Electrical Malfunction	0	
	Advisories	None	Steroid	Yes	Other	0	
ria	Placement						



### 4557, 4557M Screw-In

#### **Product Characteristics**

US Market Release	Aug-88	Serial Number Prefix	VQ or LAM	US Returned Product Ana	alysis
Estimated US Implants	22,500	Type and/or Fixation	Transvenous, Atrial-J, Screw-in	Implant Damage	53
Estimated US Active	4,600	Polarity	Unipolar	Electrical Malfunction	14
Advisories	None	Steroid	No	Other	4

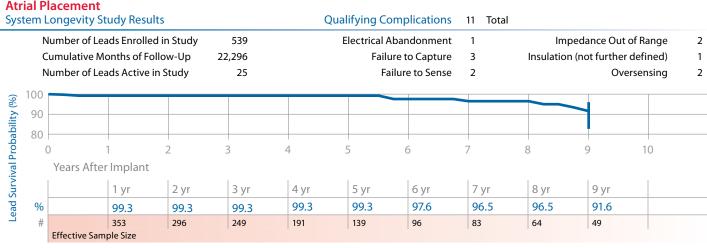


### 4558M Screw-In

### **Product Characteristics**

US Market Release	Nov-94	Serial Number Prefix	LDC	<b>US Returned Product Analysis</b>	
Estimated US Implants	21,000	Type and/or Fixation	Transvenous, Atrial-J, Screw-in	Implant Damage	111
Estimated US Active	5,400	Polarity	Bipolar	Electrical Malfunction	11
Advisories	None	Steroid	No	Other	1

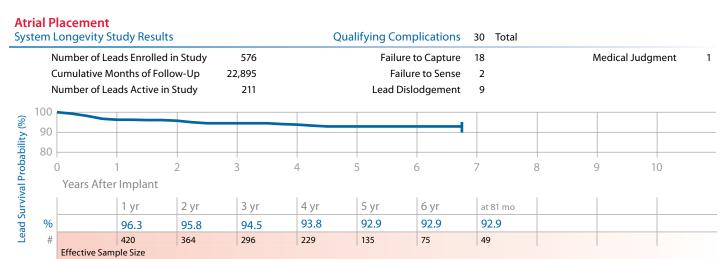
#### **Atrial Placement**



## 4568 CapSureFix

#### **Product Characteristics**

US Market Release	Jan-97	Serial Number Prefix	LDD	US Returned Product An	nalysis
Estimated US Implants	72,800	Type and/or Fixation	Transvenous, Atrial-J, Screw-in	Implant Damage	198
Estimated US Active	33,800	Polarity	Bipolar	Electrical Malfunction	12
Advisories	None	Steroid	Yes	Other	4



## 4574 CapSure Sense

#### **Product Characteristics**

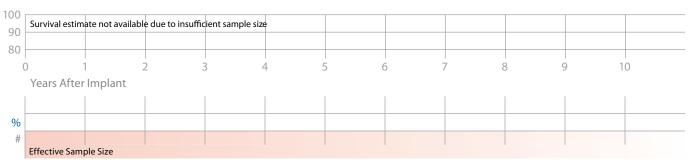
US Market Release	Jun-02	Serial Number Prefix	BBE	US Returned Product Anal	ysis
Estimated US Implants	37,600	Type and/or Fixation	Transvenous, Atrial-J, Tines	Implant Damage	7
Estimated US Active	28,000	Polarity	Bipolar	Electrical Malfunction	2
Advisories	None	Steroid	Yes	Other	0

#### **Atrial Placement**

Lead Survival Probability (%)

System Longevity Study Results Qualifying Complications 0 Total

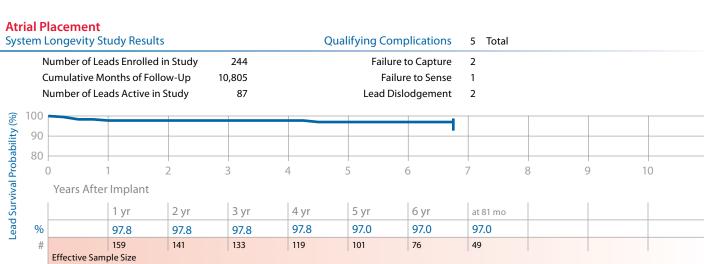
Number of Leads Enrolled in Study 8
Cumulative Months of Follow-Up 193
Number of Leads Active in Study 6



## **4592** CapSure SP Novus

#### **Product Characteristics**

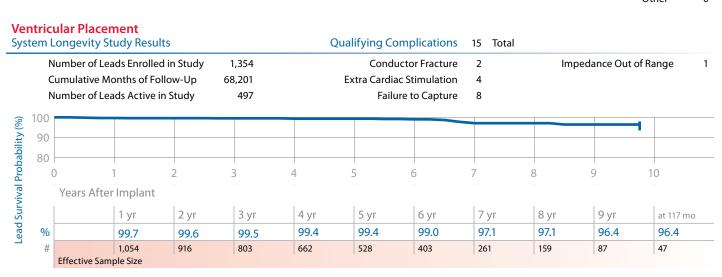
US Market Release	Oct-98	Serial Number Prefix	LER	US Returned Product Analysis
Estimated US Implants	75,100	Type and/or Fixation	Transvenous, Atrial-J, Tines	Implant Damage 12
Estimated US Active	44,200	Polarity	Bipolar	Electrical Malfunction 3
Advisories	None	Steroid	Yes	Other 0



## **5023, 5023M CapSure SP**

#### **Product Characteristics**

US Market Release	Nov-88	Serial Number Prefix	SX or LAS	US Returned Product Ana	alysis
Estimated US Implants	10,600	Type and/or Fixation	Transvenous, Vent., Tines	Implant Damage	15
Estimated US Active	2,600	Polarity	Unipolar	Electrical Malfunction	7
Advisories	None	Steroid	Yes	Other	0



### 5024, 5024M CapSure SP

#### **Product Characteristics**

US Market Release	Mar-90	Serial Number Prefix	SY or LAT	US Returned Product Analysis
Estimated US Implants	211,400	Type and/or Fixation	Transvenous, Vent., Tines	Implant Damage 723
Estimated US Active	65,900	Polarity	Bipolar	Electrical Malfunction 109
Advisories	None	Steroid	Yes	Other 29

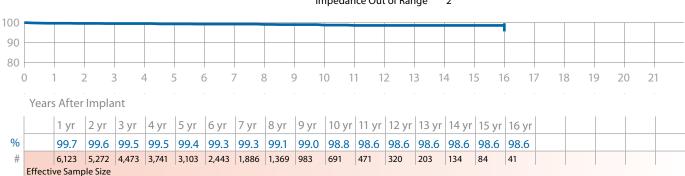
#### **Ventricular Placement**

**System Longevity Study Results** 

#### **Qualifying Complications** 45 Total

Number of Leads Enrolled in Study	8,142	Conductor Fracture	3	Insulation (ESC)	1
Cumulative Months of Follow-Up	428,956	Extra Cardiac Stimulation	2	Insulation (not further defined)	5
Number of Leads Active in Study	672	Failure to Capture	24	Lead Dislodgement	5
		Failure to Sense	2	Oversensing	1

Impedance Out of Range



#### 5026 CapSure

Lead Survival Probability (%)

#### **Product Characteristics**

US Market Release	Feb-88	Serial Number Prefix	RZ	<b>US Returned Product Ana</b>	lysis
Estimated US Implants	7,800	Type and/or Fixation	Transvenous, Vent., Tines	Implant Damage	60
Estimated US Active	1,200	Polarity	Bipolar	<b>Electrical Malfunction</b>	7
Advisories	None	Steroid	Yes	Other	1

#### **Ventricular Placement**

**System Longevity Study Results Qualifying Complications** 4 Total

Number of Leads Enrolled in Study	168	<b>Electrical Abandonment</b>	1
Cumulative Months of Follow-Up	9,581	Failure to Capture	3
Number of Leads Active in Study	5		



10

## 5033 CapSure Z

#### **Product Characteristics**

US Market Release	Feb-96	Serial Number Prefix	LDK	US Returned Product Analys	is
Estimated US Implants	2,500	Type and/or Fixation	Transvenous, Vent., Tines	Implant Damage	6
Estimated US Active	900	Polarity	Unipolar	Electrical Malfunction	1
Advisories	None	Steroid	Yes	Other	3

**Ventricular Placement System Longevity Study Results Qualifying Complications** 26 Total Number of Leads Enrolled in Study 1,901 Cardiac Perforation 1 Impedance Out of Range 4 Cumulative Months of Follow-Up 94,411 **Conductor Fracture** 7 Insulation (not further defined) 1 Number of Leads Active in Study Failure to Capture Lead Dislodgement 2 283 11 100 Lead Survival Probability (%) 90 80 2 10 11 12 13 14 15 16 17 18 19 20 21 Years After Implant 1 yr 2 yr | 3 yr | 4 yr | 5 yr | 6 yr | 7 yr | 8 yr | 9 yr | 10 yr | 11 yr | 135 mo

## 5034 CapSure Z

%

99.6

**Effective Sample Size** 

99.1

99.0

784

98.7

98.3 97.7

455

#### **Product Characteristics**

97.2

362

96.3

181

266

96.3 95.4

78

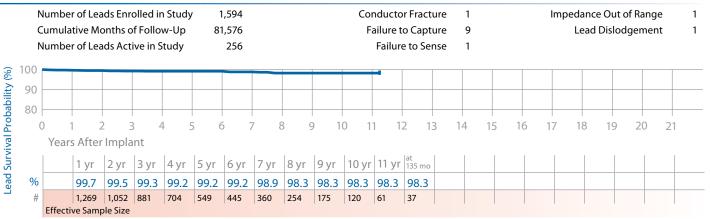
95.4

56

US Market Release	Feb-96	Serial Number Prefix	LDF	US Returned Product Ana	alysis
Estimated US Implants	58,700	Type and/or Fixation	Transvenous, Vent., Tines	Implant Damage	85
Estimated US Active	20,800	Polarity	Bipolar	Electrical Malfunction	29
Advisories	None	Steroid	Yes	Other	11

#### **Ventricular Placement**

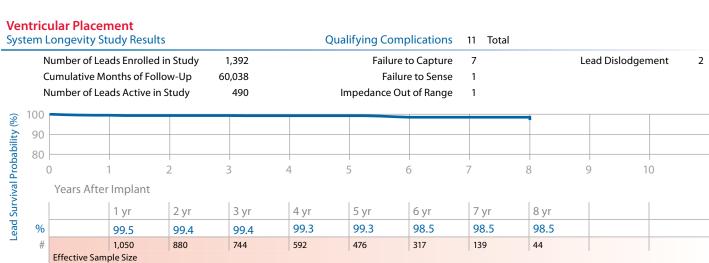
System Longevity Study Results **Qualifying Complications** 13 Total



## **5054** CapSure Z Novus

#### **Product Characteristics**

US Market Release	Jun-98	Serial Number Prefix	LEH	<b>US Returned Product Anal</b>	lysis
Estimated US Implants	86,600	Type and/or Fixation	Transvenous, Vent., Tines	Implant Damage	41
Estimated US Active	49,200	Polarity	Bipolar	<b>Electrical Malfunction</b>	15
Advisories	None	Steroid	Yes	Other	6

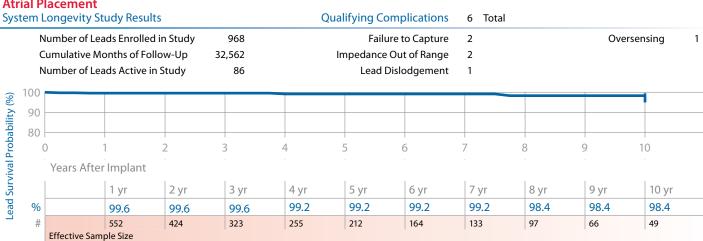


## 5068 CapSureFix

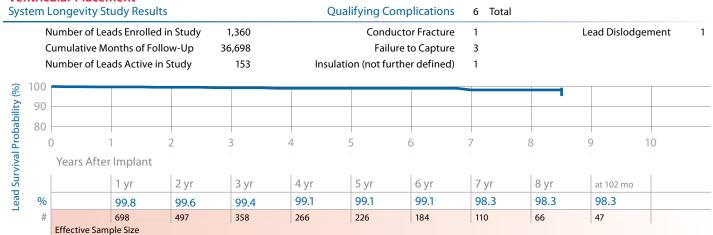
#### **Product Characteristics**

US Market Release	Jan-97	Serial Number Prefix	LDJ	US Returned Product An	alysis
Estimated US Implants	108,000	Type and/or Fixation	Transvenous, V or A, Screw-in	Implant Damage	455
Estimated US Active	47,400	Polarity	Bipolar	<b>Electrical Malfunction</b>	66
Advisories	None	Steroid	Yes	Other	15

#### **Atrial Placement**



#### **Ventricular Placement**



## 5072 SureFix

#### **Product Characteristics**

US Market Release	Jun-98	Serial Number Prefix	LEM	US Returned Product Ana	alysis
Estimated US Implants	9,200	Type and/or Fixation	Transvenous, V or A, Screw-in	Implant Damage	28
Estimated US Active	4,900	Polarity	Bipolar	Electrical Malfunction	4
Advisories	None	Steroid	Yes	Other	1

	jevity Study Resu					mplications	2 Total			
	per of Leads Enrolle	•	451			c Perforation	1			
	lative Months of Fo	•	21,491		Failu	re to Capture	1			
Numb	er of Leads Active	in Study	126							
00								_		
90										
20									ı	
- 1	1	2	3	/	5	6	7	8	9	10
0	1	2	3	4	5	6	7	8	9	10
0	1 ars After Implant	2	3	4	5	6	7	8	9	10
0	1 ars After Implant 1 yr	2 2 yr	3   3 yr	4   4 yr	5   5 yr	6 6 yr	7   7 yr	8 8 yr	9	10
_						ı	7	1	9	10

## **5076** CapSureFix Novus

#### **Product Characteristics**

US Market Release	Aug-00	Serial Number Prefix	PJN	US Returned Product An	alysis
Estimated US Implants	983,700	Type and/or Fixation	Transvenous, V or A, Screw-in	Implant Damage	874
Estimated US Active	676,500	Polarity	Bipolar	Electrical Malfunction	205
Advisories	None	Steroid	Yes	Other	80

I	Advisories		None		Steroid		Yes					Other	80
	<b>Placement</b> Longevity St	udy Results				Qual	ifying Coı	mplications	16 Total				
1	Number of Lea	ads Enrolled in	Study	2,514			Cardia	Perforation	1	In	npedanc	e Out of Range	2
(	Cumulative M	onths of Follov	w-Up	88,410			Condu	ctor Fracture	1	Insulatio	on (not f	urther defined)	1
1	Number of Lea	ads Active in S	tudy	1,169		Ex	tra Cardia	Stimulation	2		Lead	l Dislodgement	4
							Failur	e to Capture	4			Oversensing	1
<b>a</b> 100													
% 90 % 90													
bilit o													
obak 08		1 2		3	1			6	7	8	9	10	
l Pro	0		_	3	4	3	)	6	/	ŏ	9	10	
viv	Years After	r Implant											
Lead Survival Probability (%) % %		1 yr	2 yr	3 yr	4 y	r	5 yr	6 yr	7 yr				
ead %		99.6	99.6	99.4	99.	1	99.1	98.9	98.9				
<b>-</b> #		1,804	1,509	1,136	750		488	266	53				
	Effective Sam	ple Size											

# Ventricular Placement System Longevity Study Re

	Longevity Stud	ay resures				Qualifying Co	присастотть	9 Total			
1	Number of Leads	s Enrolled in	Study	1,509		Cardia	ac Perforation	1		Failure to Sense	
(	Cumulative Mon	ths of Follov	w-Up	51,691		Conductor Fracture			Impedance Out of Range		
1	Number of Leads Active in Study		tudy	625		Failure to Capture		3		Lead Dislodgement	
100							-				
90											
80											
	0 1	2	2	3	4	5	6	7	8	9 10	
	Years After Ir	mplant									
	1	yr	2 yr	3 yr	4 yr	5 yr	6 yr	at 81 mo			
%	9	99.6	99.4	99.3	99.1	99.1	99.1	99.1			
#	1,	,028	839	681	472	309	159	48			
	Effective Sample	e Size									

## **5092** CapSure SP Novus

#### **Product Characteristics**

US Market Release	Jun-98	Serial Number Prefix	LET	US Returned Product Ana	alysis
Estimated US Implants	113,500	Type and/or Fixation	Transvenous, Vent., Tines	Implant Damage	48
Estimated US Active	69,300	Polarity	Bipolar	<b>Electrical Malfunction</b>	25
Advisories	None	Steroid	Yes	Other	11

#### Ventricular Placement

	Number of I	eads Enrolle	d in Study	1,171		Extra Cardia	c Stimulation	1			
	Cumulative	Cumulative Months of Follow-Up		40,309	Failure to Capture			2			
	Number of I	eads Active	in Study	242		Lead [	Dislodgement	5			
00	)										
90	)										
80	)										
	0	1	2	3	4	5	6	7	8	9	10
	Years Af	ter Implant									
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	at 87 mo		
%	, D	99.6	99.5	99.3	99.0	99.0	99.0	99.0	99.0		
									50		

## 5524, 5524M CapSure SP

**Effective Sample Size** 

#### **Product Characteristics**

US Market Release	Mar-90	Serial Number Prefix	XV or LAV	US Returned Product Ana	alysis
Estimated US Implants	63,800	Type and/or Fixation	Transvenous, Atrial-J, Tines	Implant Damage	67
Estimated US Active	21,300	Polarity	Bipolar	Electrical Malfunction	23
Advisories	None	Steroid	Yes	Other	7

#### **Atrial Placement**

Lead Survival Probability (%)

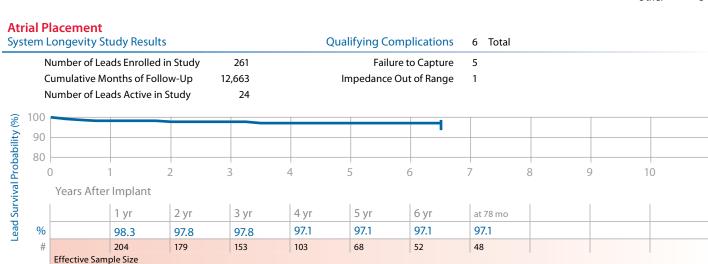
System Longevity Study Results Qualifying Complications 38 Total

C	iumula	tive Mo	onths o	olled in of Follo ive in S	w-Up		1,442 3,627 526			lr	F	ailure Failur	or Fract to Capt e to Se t of Rai	ure :	1 22 4 1		Insulat	•		Dislod	lefined gemen sensing	t	2 4 4
100															•								
90																							
80				-	-					-	-									-			
	)	1 :	2	3	4	5	6	7	8	9 1	0	11 1	12 1	3 1	4 1	5 1	6 1	7	18	19	20	21	
	Years	After	Impla	ant																			
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	12 yr	13 yr	14 yr								
%		99.8	99.8	99.5	99.4	99.3	99.2	98.9	98.4	98.0	97.6	97.0	97.0	97.0	97.0								
#		3,393	2,931	2,513	2,114	1,757	1,387	1,052	751	544	403	265	166	101	51								

## 5534 CapSure Z

#### **Product Characteristics**

US Market Release	Feb-96	Serial Number Prefix	LDG	US Returned Product Ana	alysis
Estimated US Implants	27,700	Type and/or Fixation	Transvenous, Atrial-J, Tines	Implant Damage	29
Estimated US Active	8,200	Polarity	Bipolar	Electrical Malfunction	6
Advisories	None	Steroid	Yes	Other	5

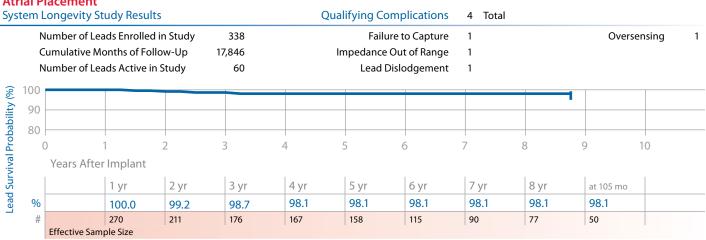


## 5554 CapSure Z Novus

#### **Product Characteristics**

US Market Release	Jun-98	Serial Number Prefix	LEJ	<b>US Returned Product Analy</b>	/sis
Estimated US Implants	55,800	Type and/or Fixation	Transvenous, Atrial-J, Tines	Implant Damage	8
Estimated US Active	32,000	Polarity	Bipolar	Electrical Malfunction	9
Advisories	None	Steroid	Yes	Other	4

#### **Atrial Placement**

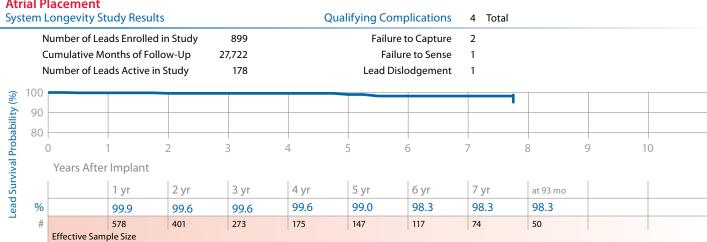


## 5568 CapSureFix

#### **Product Characteristics**

US Market Release	Jan-97	Serial Number Prefix	LDN	US Returned Product An	ialysis
Estimated US Implants	70,400	Type and/or Fixation	Transvenous, Atrial-J, Screw-in	Implant Damage	246
Estimated US Active	46,400	Polarity	Bipolar	<b>Electrical Malfunction</b>	11
Advisories	None	Steroid	Yes	Other	11

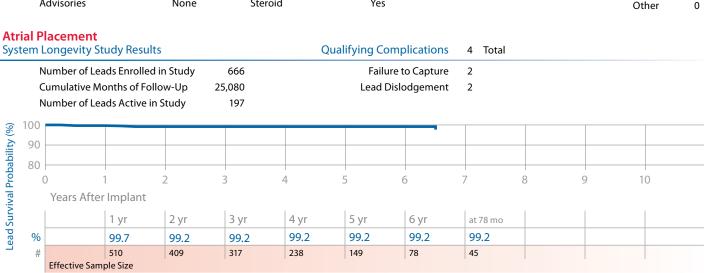
#### **Atrial Placement**



## **5592** CapSure SP Novus

#### **Product Characteristics**

US Market Release	Jun-98	Serial Number Prefix	LEU	US Returned Product Analysis
Estimated US Implants	27,900	Type and/or Fixation	Transvenous, Atrial-J, Tines	Implant Damage 6
Estimated US Active	18,500	Polarity	Bipolar	Electrical Malfunction 3
Advisories	None	Steroid	Yes	Other 0



## **5594** CapSure SP Novus

#### **Product Characteristics**

US Market Release	Jun-01	Serial Number Prefix	LFD	US Returned Product Analysis
Estimated US Implants	10,600	Type and/or Fixation	Transvenous, Atrial-J, Tines	Implant Damage 0
Estimated US Active	7,700	Polarity	Bipolar	Electrical Malfunction 3
Advisories	None	Steroid	Yes	Other 0

#### **Atrial Placement**

**System Longevity Study Results Qualifying Complications** 0 Total

Number of Leads Enrolled in Study 18 Cumulative Months of Follow-Up 995 Number of Leads Active in Study 12

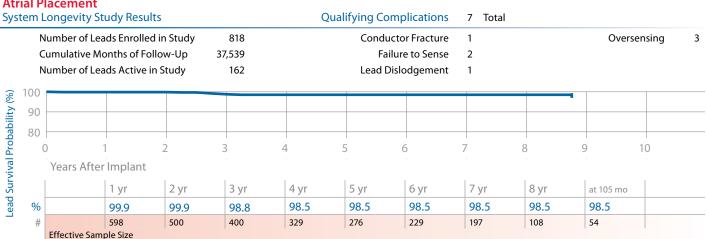


## 6940 CapSureFix

#### **Product Characteristics**

US Market Release	Oct-98	Serial Number Prefix	TCP	US Returned Product An	alysis
Estimated US Implants	26,600	Type and/or Fixation	Transvenous, A or V, Screw-in	Implant Damage	114
Estimated US Active	11,700	Polarity	Bipolar	Electrical Malfunction	20
Advisories	None	Steroid	Yes	Other	3

#### **Atrial Placement**



## **6957** Spectraflex

#### **Product Characteristics**

US Market Release	Jul-79	Serial Number Prefix	VC	US Returned Product Ana	alysis
<b>Estimated US Implants</b>	29,100	Type and/or Fixation	Transvenous, V or A, Screw-in	Implant Damage	85
Estimated US Active	2,400	Polarity	Unipolar	Electrical Malfunction	39
Advisories	None	Steroid	No	Other	25

	ongevity Study	Results			ualifying Co	mplications	10 Total			
Ν	lumber of Leads E	nrolled in Study	673		Extra Cardia	c Stimulation	1		Over	sensing
C	Cumulative Month	of Follow-Up	24,255		Failu	re to Capture	3			
Ν	lumber of Leads A	ctive in Study	1		Fa	ilure to Sense	5			
00										
90										
80										
(	) 1	2	3	4	5	6	7	8	9	10
	Years After Imp	lant								
	1 y	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	at 99 mo	
	' /			00.5	98.0	98.0	95.6	93.5	93.5	
%	100	0.0 99.7	99.4	98.5	90.0	70.0	75.0	75.5	70.0	

#### **Ventricular Placement**

Lead Survival Probability (%)

System Longevity Study Results

Effective Sample Size

#### Qualifying Complications 42 Total

(	lumbei Iumula Iumbei	tive Mo	onths c	f Follo	w-Up		1,853 6,243 18			Ex	ktra Ca	nducto rdiac St ailure t Failur	timulat	ion ure	14 2 18 2			mpeda ion (no	t furth		ined)		1 1 4
100																							
90																		-				_	
80																		•					
	0 ′	1 :	2 :	3 4	4	5	6	7	8	9 1	0 1	11 1	2 1	3 1	14 1	5 1	6 1	7 1	8 1	9 2	20	21	
	Years	After	Impla	nt																			
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	12 yr	13 yr	14 yr	15 yr	16 yr	17 yr	at 207 mo				
%		99.6	99.3	98.9	98.3	97.8	97.1	96.9	96.2	96.2	95.4	95.0	94.4	94.4	93.7	93.7	92.6	91.2	91.2				
#		1,224	998	834	709	623	515	430	341	279	227	192	159	132	108	86	67	53	50				

## **6957J Spectraflex**

#### **Product Characteristics**

US Market Release	Sep-80	Serial Number Prefix	GG	US Returned Product Ana	alysis
Estimated US Implants	30,000	Type and/or Fixation	Transvenous, Atrial-J, Screw-in	Implant Damage	74
Estimated US Active	1,900	Polarity	Unipolar	Electrical Malfunction	29
Advisories	None	Steroid	No	Other	30

#### **Atrial Placement**

**System Longevity Study Results** 

#### Qualifying Complications 88 Total

1	Insulation (ESC)	13	Conductor Fracture	2,348	Number of Leads Enrolled in Study
3	Insulation (not further defined)	3	Extra Cardiac Stimulation	160,441	Cumulative Months of Follow-Up
2	Lead Dislodgement	48	Failure to Capture	23	Number of Leads Active in Study
3	Oversensing	14	Failure to Sense		
		1	Impodance Out of Dance		

Impedance Out of Range



#### Years After Implant

		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	12 yr	13 yr	14 yr	15 yr	16 yr	17 yr	18 yr	19 yr	at 231 mo	
%		99.5	99.0	98.6	97.8	97.5	96.8	96.2	95.7	94.0	93.3	92.5	92.0	92.0	91.2	91.2	90.7	88.4	87.5	86.2	86.2	
#		1,775	1,556	1,359	1,205	1,076	915	766	652	554	465	393	320	257	207	160	125	99	70	53	48	
	Effecti	ve Samı	ole Size																			

#### **6961 Tenax**

#### **Product Characteristics**

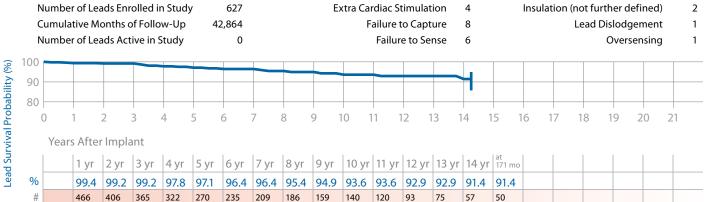
US Market Release	Jan-78	Serial Number Prefix	ТВ	US Returned Product Analysis
Estimated US Implants	44,700	Type and/or Fixation	Transvenous, Vent., Tines	Implant Damage 103
Estimated US Active	800	Polarity	Unipolar	Electrical Malfunction 27
Advisories	None	Steroid	No	Other 0

#### **Ventricular Placement**

**System Longevity Study Results** 

**Effective Sample Size** 

#### **Qualifying Complications** 22 Total



## **6962 Tenax**

Lead Survival Probability (%)

#### **Product Characteristics**

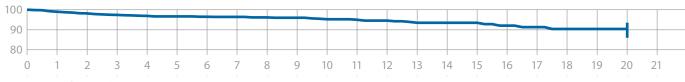
US Market Release	Jan-78	Serial Number Prefix	UB	US Returned Product Analysis
Estimated US Implants	70,600	Type and/or Fixation	Transvenous, Vent., Tines	Implant Damage 170
Estimated US Active	1,700	Polarity	Bipolar	Electrical Malfunction 84
Advisories	None	Steroid	No	Other 0

#### **Ventricular Placement**

**System Longevity Study Results** 

#### Qualifying Complications 52 Total

1,483	Conductor Fracture	5	Impedance Out of Range	3
109,930	Extra Cardiac Stimulation	1	Insulation (not further defined)	2
2	Failure to Capture	27	Lead Dislodgement	1
	Failure to Sense	10	Oversensing	3
	,	109,930 Extra Cardiac Stimulation 2 Failure to Capture	109,930 Extra Cardiac Stimulation 1 2 Failure to Capture 27	109,930 Extra Cardiac Stimulation 1 Insulation (not further defined) 2 Failure to Capture 27 Lead Dislodgement



## Years After Implant

		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	12 yr	13 yr	14 yr	15 yr	16 yr	17 yr	18 yr	19 yr	20 yr	
%		99.0	98.2	97.4	96.9	96.7	96.5	96.4	96.2	96.0	95.3	95.0	94.6	93.5	93.5	93.5	92.1	91.3	90.4	90.4	90.4	
#		1,082	968	857	757	676	611	559	489	420	364	306	260	213	177	147	122	103	83	65	51	
	Effecti	ve Samı	ole Size																			

Pa	cing	J L	ead	ds	contin	ued	I	ı	I	I	I	ı			I	I	I	I
			20 yr															
			18 yr															
		-	16 yr					91.9 +3.1/-4.7 at 183 mo	62.2 +4.1/-4.4 at 189 mo					95.0 +2.1/-3.5 at 174 mo				
		-	14 yr					91.9	62.9 +4.0/-4.2					95.0 +2.1/-3.5	84.2 +4.7/-6.5 at 156 mo			
		-	12 yr			96.6	50.6 +5.0/-5.2 at 129 mo	92.8 +2.7/-4.2	65.7 +3.5/-3.7	94.7 +2.5/-4.7 at 141 mo				96.1	85.4 +4.3/-5.9		93.4 +2.3/-3.4 at 135 mo	94.4 +2.2/-3.7 at 126 mo
			10 yr			97.7	51.5 +4.8/-5.0	95.0 +1.9/-3.0	69.8 +3.1/-3.4	96.1 +1.6/-2.7	99.8 +0.1/-0.7	95.3 +2.5/-5.2 at 105 mo	94.4 +3.1/-6.8 at 114 mo	96.1 +1.4/-2.1	89.2 +3.1/-4.1		94.9 +1.6/-2.4	94.4 +2.2/-3.7
			8 yr			97.7 +1.1/-2.4	58.1 +4.2/-4.5	96.0 +1.6/-2.4	77.8 +2.5/-2.7	96.7 +1.3/-2.1	99.8 +0.1/-0.7	96.5 +1.9/-3.8	95.7 +2.5/-5.9	97.5 +0.8/-1.3	93.6 +1.9/-2.6		96.3 +1.1/-1.5	96.6
			7 yr			98.5 +0.8/-1.8	64.1 +3.7/-4.1	96.0	83.9 +2.0/-2.2	97.0	99.8 +0.1/-0.7	97.5	95.7 +2.5/-5.9	98.2 +0.6/-1.0	94.6		97.3 +0.7/-1.0	97.0
			6 yr			98.8 +0.7/-1.5	69.4 +3.4/-3.7	96.4 +1.4/-2.3	88.1	98.2 +0.8/-1.3	99.8	97.5	96.8 +2.0/-5.3	98.3 +0.6/-0.9	96.9 +1.1/-1.6		97.4	97.7
		_	5 yr			99.1	77.1	97.6	92.6	98.6 +0.6/-1.1	99.8 +0.1/-0.7	98.1 +1.0/-2.2	97.7	98.7 +0.5/-0.7	97.9		97.6 +0.6/-0.9	98.1 +0.6/-1.0
	lity (%)	_	4 yr	99.3 +0.6/-3.9 at 42 mo	100.0 at 42 mo	99.1	87.4 +2.1/-2.4	98.8 +0.7/-1.2	95.9 +0.8/-1.1	98.6 +0.6/-1.1	99.8	98.5	98.6 +1.1/-4.1	99.1	98.7	97.0 +2.0/-5.9 at 45 mo	98.1	98.4 +0.6/-0.8
	Device Survival Probability (%)	lant	3 yr	99.3 +0.6/-3.9	100.0	99.4	96.3	99.1	98.4 +0.5/-0.7	98.8 +0.5/-1.1	99.8	98.8	99.4 +0.5/-3.5	99.5	99.1	97.0	98.3 +0.5/-0.7	98.8 +0.4/-0.7
	Survival	Years After Implant	2 yr	99.3 +0.6/-3.9	100.0	99.4 +0.4/-1.1	99.3 +0.4/-0.7	99.2 +0.5/-1.0	99.1	99.3 +0.4/-0.9	99.8	99.4	99.4 +0.5/-3.5	99.6	99.2	97.0	98.8 +0.4/-0.6	98.8 +0.4/-0.7
val)	Device	Years A	1 yr	99.3 +0.6/-3.9	100.0	99.4	99.8 +0.1/-0.5	99.4 +0.4/-1.0	99.6 +0.2/-0.3	99.9 +0.1/-0.6	99.9 +0.1/-0.5	99.4	99.4 +0.5/-3.5	99.9 +0.1/-0.4	99.4	97.0 +2.0/-5.9	99.0	99.3
ce Inter	Months o in Study			4,613	4,519	46,406	71,629 tations	54,405	151,094 tations	63,970	52,003	28,426	15,297	131,206	77,187	6,273	120,334	87,084
ntiden	su	ying licatio	Qualif dmoD	-	0	12	277 w Expec	25	316 N Expec	70	m	10	7	32	52	9	52	33
5% Co	γbu32 ni s	əvitəA	speə7	92	18	149	4 val Belov	m	12 val Belov	363	27	43	10	53	55	41	581	503
<u>5</u>	pə	Enroll	speə7	160	144	711	1,640 ad Surviv	851	2,543 ad Surviv	1,158	1,214	540	259	2,364	1,690	108	2,401	1,799
umma	əseələ	ırket R	<sub>B</sub> M 2U	Aug-05	Aug-05	Jul-86	Vent Feb-89 1,640 4 277 71,62 see page 150 - 1993 Lead Survival Below Expectations	Nov-82	Jul-83 1 - 1991 Lea	Aug-91	Oct-91	not US released	Aug-88	Jan-89	Jan-89	Jan-97	Mar-96	Mar-96
val s		þer	Сһат	Atrial	Vent	Vent	Vent	Vent	Vent	Vent	Vent	Vent	Vent	Atrial	Vent	Atrial	Atrial	Vent
Lead Survival Summary (95% Confidence Interval)		,	(lime7	SelectSecure	SelectSecure	CapSure	CapSure Advisories: see p	Target Tip	Target Tip Vent Jul-83 2,543 12 316 151,09 Advisories: see page 151-1991 Lead Survival Below Expectations	CapSure SP	CapSure SP	CapSure Z	Screw-In	Screw-In	Screw-In	CapSureFix	CapSureFix	CapSureFix
-		er I	qwnN apoM	3830	3830	4003, 4003M	4004, 4004M	4011	4012	4023	4024	4033	4057, 4057M	4058, 4058M	4058, 4058M	4067	4068	4068

	_	7															
	_	18 yr															
		16 yr															
	_	14 yr										83.6 +5.0/-6.8 at 159 mo					
	-	12 yr										84.8 +4.6/-6.3				96.9 +1.8/-4.4 at 126 mo	
	_	10 yr									66.1 +7.7/-9.2 at 105 mo	87.5 +3.9/-5.5 +		99.0 +0.6/-1.2 at 117 mo		96.9	91.6 +4.5/-8.9 at 108 mo
	_	8 yr									69.9	91.5 +2.9/-4.3		99.0		96.9 +1.8/-4.4	96.5
	_	7 yr							98.0 +0.8/-1.3		73.0 +6.5/-8.2	94.7 +2.0/-3.2		99.0	97.9 +1.4/-4.2 at 78 mo	96.9 +1.8/-4.4	96.5 +2.1/-5.2
	_	6 yr	mple size					98.2 +1.5/-10.5 at 63 mo	98.0 +0.8/-1.3	mple size	82.2 +5.1/-6.8	95.6 +1.8/-2.8		99.0	97.9 +1.4/-4.2	97.8 +1.4/-3.6	97.6
		5 yr	Survival estimate not available due to insufficient sample size		99.1 +0.5/-1.2			100.0	98.0 +0.8/-1.3	Survival estimate not available due to insufficient sample size	90.3	96.7	98.1 +1.4/-5.3 at 57 mo	99.0	97.9 +1.4/-4.2	97.8 +1.4/-3.6	99.3
ity (%)	_	4 yr	due to insu	100.0 at 45 mo	99.1 +0.5/-1.2	99.6 +0.3/-1.2 at 42 mo	99.6 +0.3/-1.1 at 45 mo	100.0	98.4 +0.6/-1.1	due to insu	98.2 +1.1/-3.0	98.0	98.1 +1.4/-5.3	99.0	97.9 +1.4/-4.2	97.8 +1.4/-3.6	99.3
Probabil	ant	3 yr	x available	100.0	99.1 +0.5/-1.2	99.6 +0.3/-1.2	99.6 +0.3/-1.1	100.0	98.7 +0.5/-1.0	x available	99.1	99.1 +0.6/-1.5	98.1 +1.4/-5.3	99.3 +0.4/-1.0	98.8 +0.9/-3.6	99.1 +0.7/-2.8	99.3
Device Survival Probability (%)	Years After Implant	2 yr	stimate no	100.0	99.1 +0.5/-1.2	99.6 +0.3/-1.2	99.6 +0.3/-1.1	100.0	98.8	stimate no	100.0	99.6 +0.3/-1.2	98.1 +1.4/-5.3	99.3 +0.4/-1.0	99.4 +0.5/-3.5	99.1 +0.7/-2.8	99.3
Device	Years A	1 yr	Survival	100.0	99.3 +0.4/-1.1	99.8 +0.2/-1.0	99.6 +0.3/-1.1	100.0	98.9	Survival	100.0	99.6 +0.3/-1.2	98.1 +1.4/-5.3	99.6 +0.3/-0.7	100.0	99.1 +0.7/-2.8	99.3
Months o in Study			46	4,266	21,317	13,730	14,423	9,892	52,758	3,242	19,873 tations	39,801	7,160	40,011	11,188	18,405	22,296
suc	γing Jicatio	Quality Comp	0	0	5	2	2	ю	17	-	48 v Expec	35	4	9	4	9	=
γpn1S ni e			-	83	522	541	512	10	539	9	1 al Belov	9	18	28	17	12	25
pə	Iloau3 :	reads	-	100	616	637	599	260	1,144	59	368 Id Surviv	009	121	911	206	294	539
əseələ	arket R	?W S∩	Jun-02	Jun-02	Jun-02	Feb-04	Feb-04	Jul-89	Sep-98	Jul-86	Mar-90	Jul-83	Aug-91	Oct-91	not US released	Aug-88	Nov-94
	per	Сһат	Atrial	Vent	Vent	Atrial	Vent	Vent	Vent	Atrial	Atrial page 149	Atrial	Atrial	Atrial	Atrial	Atrial	Atrial
	٨	lime4	CapSure Sense	CapSure Sense	CapSure Sense	CapSureFix Novus	CapSureFix Novus	Target Tip	CapSure SP Novus	CapSure	CapSure Atrial Mar-90 368 1 48 Advisories: see page 149 - 1996 Lead Survival Below Expect	Target Tip	CapSure SP	CapSure SP	CapSure Z	Screw-In	Screw-In
	oer il	apoM Mode	4073	4073	4074	4076	4076	4081	4092	4503, 4503M	4504, 4504M	4512	4523	4524	4533	4557, 4557M	4558M

# Lead Survival Summary continued

		_																
	_	20 yr																
		18 yr																
		16 yr					98.6 +0.5/-0.7											
	-	14 yr					98.6 +0.5/-0.7											97.0
	-	12 yr					98.6		95.4 +1.9/-3.2 at 135 mo	98.3 +0.8/-1.4 at 135 mo								97.0
	-	10 yr				96.4 +1.6/-2.9 at 117 mo	98.8 +0.4/-0.6 +		96.3 +1.3/-2.0 +	98.3 +0.8/-1.4 +		98.4 +1.1/-3.4	98.3 +1.1/-3.1 at 102 mo					97.6 +0.8/-1.3 +
	-					97.1 96 +1.3/-2.3 +1	99.1 96.1 +0.3/-0.4		97.2 96 +1.0/-1.6	98.3 +0.8/-1.4 +C	98.5 +0.7/-1.4	98.4 98.1+11/-3.4 +1	98.3 98 +1.1/-3.1 +1	99.4 +0.4/-1.9			99.0 +0.6/-1.2 at 87 mo	98.4 +0.5/-0.8 +0.5/-0.8
	-	r 8 yr	92.9 +2.2/-3.1 at 81 mo		97.0 +1.8/-4.3 at 81 mo	97.1 97	99.3 99.40.2/-0.3 +0	95.7 +2.7/-7.2 at 75 mo	97.7 97 +1.14 +1.1	98.9 +0.5/-0.9	98.5 98.1+0.7/-1.4	99.2 98 +0.5/-1.5 +1.	98.3 98.1 +1.1/-3.1	99.4 +0.4/-1.9	98.9 +0.5/-1.0	99.1 +0.5/-0.8 at 81 mo	99.0 +0.6/-1.2 +0 at i	98.9 98.9 +0.4/-0.5
	-	7 yr		size														
	-	6 yr	92.9 +2.2/-3.1	samples	97.0 +1.8/-4.3	99.0	99.3	95.7	98.3 +0.6/-1.2	99.2 +0.4/-0.8	98.5	99.2	99.1	99.4	98.9 +0.5/-1.0	99.1	99.0	99.2 +0.3/-0.4
	_	5 yr	92.9 +2.2/-3.1	ufficient	97.0	99.4 +0.3/-0.8	99.4	97.1	98.7 +0.6/-0.9	99.2	99.3	99.2 +0.5/-1.5	99.1 +0.5/-1.5	99.4 +0.4/-1.9	99.1	99.1 +0.5/-0.8	99.0	99.3
ty (%)		4 yr	93.8 +1.9/-2.9	due to insi	97.8 +1.4/-3.5	99.4 +0.3/-0.8	99.5 +0.1/-0.2	97.1 +2.0/-5.9	99.0 +0.5/-0.7	99.2 +0.4/-0.8	99.3 +0.3/-0.8	99.2 +0.5/-1.5	99.1 +0.5/-1.5	99.4 +0.4/-1.9	99.1	99.1 +0.5/-0.8	99.0 +0.6/-1.2	99.4 +0.2/-0.4
Probabili	int	3 yr	94.5 +1.7/-2.6	available	97.8 +1.4/-3.5	99.5 +0.3/-0.6	99.5 +0.2/-0.2	98.2 +1.4/-5.2	99.1	99.3 +0.3/-0.7	99.4 +0.3/-0.6	99.6 +0.3/-0.9	99.4 +0.4/-1.1	99.4 +0.4/-1.9	99.4 +0.3/-0.4	99.3 +0.3/-0.8	99.3 +0.4/-0.9	99.5 +0.2/-0.3
Device Survival Probability (%)	Years After Implant	2 yr	95.8 +1.5/-2.2	timate not	97.8 +1.4/-3.5	99.6 +0.3/-0.6	99.6 +0.1/-0.2	99.2 +0.7/-4.8	99.6 +0.2/-0.4	99.5 +0.3/-0.6	99.4 +0.3/-0.6	99.6 +0.3/-0.9	99.6 +0.3/-0.8	99.7 +0.3/-1.5	99.6 +0.2/-0.4	99.4 +0.3/-0.6	99.5 +0.3/-0.8	99.8
Device S	Years Af	1 yr	96.3 +1.4/-2.1	Survival estimate not available due to insufficient sample size	97.8 +1.4/-3.5	99.7 +0.2/-0.5	99.7 +0.1/-0.2	100.0	99.7 +0.2/-0.4	99.7 +0.2/-0.5	99.5 +0.3/-0.6	99.6 +0.3/-0.9	99.8 +0.1/-0.6	99.7 +0.3/-1.5	99.6 +0.2/-0.3	99.6 +0.2/-0.5	99.6 +0.2/-0.7	99.8 +0.1/-0.2
Months o in Study			22,895	193	10,805	68,201	428,956	9,581	94,411	81,576	60,038	32,562	36,698	21,491	88,410	51,691	40,309	238,627
	oitsaile		30	0	5	15	45 4	4	26	55	Ξ	9	9	7	16	6	∞	38 2
pn12 ni			211	9	87	497	672	20	283	256	490	86	153	126	1,169	625	242	526
рə	Enrolle	speə7	576	∞	244	1,354	8,142	168	1,901	1,594	1,392	896	1,360	451	2,514	1,509	1,171	4,442
əseələ	arket Re	₽W SN	Jan-97	Jun-02	Oct-98	Nov-88	Mar-90	Feb-88	Feb-96	Feb-96	Jun-98	Jan-97	Jan-97	Jun-98	Aug-00	Aug-00	Jun-98	Mar-90
	per	Сһат	Atrial	Atrial	Atrial	Vent	Vent	Vent	Vent	Vent	Vent	Atrial	Vent	Atrial	Atrial	Vent	Vent	Atrial
	Á	lime3	CapSureFix	CapSure Sense	CapSure SP Novus	CapSure SP	CapSure SP	CapSure	CapSure Z	CapSure Z	CapSure Z Novus	CapSureFix	CapSureFix	SureFix	CapSureFix Novus	CapSureFix Novus	CapSure SP Novus	CapSure SP
		Mode Mumb	4568	4574	4592	5023, 5023M	5024, 5024M	5026	5033	5034	5054	5068	5068	5072	5076	5076	5092	5524, 5524M

000000

		20 yr									86.2 +3.9/-5.4 at 231 mo		90.4
		18 yr								91.2 +3.4/-5.4 at 207 mo	87.5 +3.4/-4.5		90.4
		16 yr								92.6 +2.7/-4.2	90.7	91.4 +3.5/-5.7 at 171 mo	92.1 +2.4/-3.3
		14 yr								93.7 +2.2/-3.2	91.2 +2.0/-2.4	91.4 +3.5/-5.7	93.5 +1.8/-2.6
		12 yr								94.4 +1.9/-2.7	92.0	92.9 +2.7/-4.3	94.6 +1.5/-2.0
		10 yr		98.1 +1.2/-3.1 at 105 mo				98.5 +0.8/-1.6 at 105 mo	93.5 +3.1/-5.9 at 99 mo	95.4 +1.5/-2.2	93.3 +1.5/-1.8	93.6 +2.5/-3.8	95.3 +1.3/-1.8
		8 yr		98.1 +1.2/-3.1	98.3 +1.1/-3.6 at 93 mo			98.5 +0.8/-1.6	93.5 +3.1/-5.9	96.2	95.7 +1.0/-1.3	95.4 +1.9/-3.1	96.2 +1.0/-1.5
		7 yr	97.1 +1.6/-3.5 at 78 mo	98.1	98.3 +1.1/-3.6	99.2 +0.5/-1.2 at 78 mo		98.5 +0.8/-1.6	95.6 +2.3/-4.6	96.9 +1.0/-1.5	96.2 +1.0/-1.2	96.4 +1.5/-2.7	96.4 +1.0/-1.4
		6 yr	97.1 +1.6/-3.5	98.1 +1.2/-3.1	98.3 +1.1/-3.6	99.2 +0.5/-1.2	mple size	98.5 +0.8/-1.6	98.0	97.1 +1.0/-1.4	96.8 +0.8/-1.1	96.4	96.5
Device Survival Probability (%)		5 yr	97.1	98.1	99.0	99.2 +0.5/-1.2	Survival estimate not available due to insufficient sample size	98.5 +0.8/-1.6	98.0 +1.2/-2.9	97.8 +0.8/-1.2	97.5 +0.7/-1.0	97.1	96.7 +0.9/-1.4
		4 yr	97.1 +1.6/-3.5	98.1 +1.2/-3.1	99.6 +0.3/-1.1	99.2 +0.5/-1.2	due to insi	98.5 +0.8/-1.6	98.5 +0.9/-2.5	98.3 +0.7/-1.0	97.8 +0.6/-0.8	97.8 +1.1/-2.0	96.9 +0.9/-1.2
	ant	3 yr	97.8 +1.3/-3.1	98.7 +0.9/-2.8	99.6 +0.3/-1.1	99.2 +0.5/-1.2	t available	98.8 +0.6/-1.6	99.4 +0.4/-2.0	98.9 +0.4/-0.9	98.6 +0.4/-0.7	99.2 +0.5/-1.3	97.4 +0.8/-1.2
	Years After Implant	2 yr	97.8 +1.3/-3.1	99.2 +0.6/-2.5	99.6 +0.3/-1.1	99.2 +0.5/-1.2	stimate no	99.9 +0.1/-0.8	99.7 +0.3/-1.6	99.3 +0.3/-0.6	99.0 +0.4/-0.6	99.2 +0.5/-1.3	98.2 +0.7/-0.9
Device	Years A	1 yr	98.3 +1.1/-2.8	100.0	99.9 +0.1/-0.9	99.7 +0.2/-1.1	Survivale	99.9 +0.1/-0.8	100.0	99.6 +0.2/-0.5	99.5 +0.2/-0.5	99.4 +0.4/-1.1	99.0
Months on Study			12,663	17,846	27,722	25,080	995	37,539	24,255	96,243	160,441	42,864	109,930
su		Qualif Gomp	9	4	4	4	0	7	10	42	88	22	52
به انه کژسطک	evitoA	reads	24	09	178	197	12	162	-	18	23	0	2
	Iloau3	reads	261	338	868	999	18	818	673	1,853	2,348	627	1,483
	rket R	eM 2U	Feb-96	Jun-98	Jan-97	Jun-98	Jun-01	Oct-98	97-Inr	97-Inr	Sep-80	Jan-78	Jan-78
	per	Chaml	Atrial	Atrial	Atrial	Atrial	Atrial	Atrial	Atrial	Vent	Atrial	Vent	Vent
	,	(lime7	CapSure Z	CapSure Z Novus	CapSureFix	CapSure SP Novus	CapSure SP Novus	CapSureFix	Spectraflex	Spectraflex	Spectraflex	Tenax	Tenax
		qwnN ləpoM	5534	5554	5568	5592	5594	6940	6957	6957	6957J	6961	6962

# **US Returned Product Analysis Summary**

Model Number	Family	US Market Release	Estimated US Implants	Estimated US Active	Implant Damage	Electrical Malfunction	Other
3830	SelectSecure	Aug-05	10,800	9,200	18	4	1
4003, 4003M	CapSure	Jul-86	40,000	6,400	24	59	2
4004, 4004M	CapSure	Feb-89	74,500	2,300	55	684	19
4011	Target Tip	Nov-82	64,000	6,500	29	147	5
4012	Target Tip	Jul-83	96,800	5,000	50	825	34
4023	CapSure SP	Aug-91	43,700	13,500	47	21	6
4024	CapSure SP	Oct-91	229,200	76,900	264	119	34
4033	CapSure Z	not US released	N/A	N/A	2	0	0
4057, 4057M	Screw-in	Aug-88	12,100	2,500	39	6	4
4058, 4058M	Screw-in	Jan-89	111,100	23,400	388	243	23
4067	CapSureFix	Jan-97	1,300	400	3	1	1
4068	CapSureFix	Mar-96	131,700	52,100	406	98	11
4073	CapSure Sense	Jun-02	600	400	1	0	0
4074	CapSure Sense	Jun-02	57,800	43,200	13	7	1
4076	CapSureFix Novus	Feb-04	170,300	131,900	75	8	7
4081	Target Tip	Jul-89	4,100	800	4	5	0
4092	CapSure SP Novus	Sep-98	149,500	90,500	37	16	5
4503, 4503M	CapSure	Jul-86	9,000	1,300	2	12	0
4504, 4504M	CapSure	Mar-90	16,600	1,400	5	171	4
4512	Target Tip	Jul-83	11,600	1,000	4	84	8
4523	CapSure SP	Aug-91	12,000	3,100	5	2	1
4524	CapSure SP	Oct-91	106,900	34,600	47	28	8
4533	CapSure Z	not US released	N/A	N/A	0	0	0
4557, 4557M	Screw-in	Aug-88	22,500	4,600	53	14	4
4558M	Screw-in	Nov-94	21,000	5,400	111	11	1
4568	CapSureFix	Jan-97	72,800	33,800	198	12	4
4574	CapSure Sense	Jun-02	37,600	28,00	7	2	0
4592	CapSure SP Novus	Oct-98	75,100	44,200	12	3	0
5023, 5023M	CapSure SP	Nov-88	10,600	2,600	15	7	0
5024, 5024M	CapSure SP	Mar-90	211,400	65,900	723	109	29
5026	CapSure	Feb-88	7,800	1,200	60	7	1
5033	CapSure Z	Feb-96	2,500	900	6	1	3
5034	CapSure Z	Feb-96	58,700	20,800	85	29	11
5054	CapSure Z Novus	Jun-98	86,600	49,200	41	15	6
5068	CapSureFix	Jan-97	108,000	47,400	455	66	15
5072	SureFix	Jun-98	9,200	4,900	28	4	1
5076	CapSureFix Novus	Aug-00	983,700	676,500	874	205	80
5092	CapSure SP Novus	Jun-98	113,500	69,300	48	25	11
5524, 5524M	CapSure SP	Mar-90	63,800	21,300	67	23	7
5534	CapSure Z	Feb-96	27,700	8,200	29	6	5
5554	CapSure Z Novus	Jun-98	55,800	32,000	8	9	4
	•						
5568	CapSureFix	Jan-97	70,400	46,400	246	11	11

continued

# **US Returned Product Analysis Summary** continued

Model Number	Family	US Market Release	Estimated US Implants	Estimated US Active	Implant Damage	Electrical Malfunction	Other
5592	CapSure SP Novus	Jun-98	27,900	18,500	6	3	0
5594	CapSure SP Novus	Jun-01	10,600	7,700	0	3	0
6940	CapSureFix	Oct-98	26,600	11,700	114	20	3
6957	Spectraflex	Jul-79	29,100	2,400	85	39	25
6957J	Spectraflex	Sep-80	30,000	1,900	74	29	30
6961	Tenax	Jan-78	44,700	800	103	27	0
6962	Tenax	Jan-78	70,600	1,700	170	84	0

## **Reference Chart**

Model Number	Family	Туре	Insulation	Conductor Material	Tip Electrode	Connector Type
3830	SelectSecure	Transvenous V or A Screw-In	Polyurethane/Silicone (55D,4719)	MP35N 5 Filars/ Cable	1.8 mm Helix/Steroid	IS-1 BI
4003, 4003M	CapSure	Transvenous Ventricular Tines	Polyurethane (80A)	MP35N 4 Filars	Porous/Steroid	5 mm (4003) IS-1 UNI (4003M)
4004, 4004M	CapSure	Transvenous Ventricular Tines	Polyurethane (80A)	MP35N 6/4 Filars	Porous/Steroid	3.2 mm Low Profile (4004) IS-1 BI (4004M)
4011	Target Tip	Transvenous Ventricular Tines	Polyurethane (80A)	MP35N 4 Filars	Target Tip Concentric Grooves	5 mm
4012	Target Tip	Transvenous Ventricular Tines	Polyurethane (80A)	MP35N 6/4 Filars	Target Tip Concentric Grooves	3.2 mm Low Profile
4023	CapSure SP	Transvenous Ventricular Tines	Polyurethane (55D)	MP35N 4 Filars	Porous Platinized/ Steroid	IS-1 UNI
4024	CapSure SP	Transvenous Ventricular Tines	Polyurethane (55D)	MP35N 4/5 Filars	Porous Platinized/ Steroid	IS-1 BI
4033	CapSure Z	Transvenous Ventricular Tines	Polyurethane (55D)	MP35N 2 Filars	CapSure Z Platinized/Steroid	IS-1 UNI
4057, 4057M	Screw-In	Transvenous V or A Screw-In	Polyurethane (80A)	MP35N 1 Filar	2.0 mm Helix	5 mm (4057) IS-1 UNI (4057M)
4058, 4058M	Screw-In	Transvenous V or A Screw-In	Polyurethane (80A/55D)	MP35N 4/1 Filars	2.0 mm Helix	3.2 mm Low Profile (4058) IS-1 BI (4058M)
4067	CapSureFix	Transvenous V or A Screw-In	Polyurethane (80A)	MP35N 3 Filars	1.8 mm Helix/Steroid	IS-1 UNI
4068	CapSureFix	Transvenous V or A Screw-In	Polyurethane (80A/55D)	MP35N 4/3 Filars	1.8 mm Helix/Steroid	IS-1 BI
4073	CapSure Sense	Transvenous Ventricular Tines	Polyurethane (55D)	MP35N 5 Filars	TiN Coated Platinum Iridium/Steroid	IS-1 UNI
4074	CapSure Sense	Transvenous Ventricular Tines	Polyurethane/Silicone (55D, 4719)	MP35N 5/5 Filars	TiN Coated Platinum Iridium/ Steroid	IS-1 BI
4076	CapSureFix Novus	Transvenous V or A Screw-In	Polyurethane/Silicone (55D, 4719)	MP35N 4/6 Filars	TiN Coated Platinum Alloy/Steroid	IS-1 BI
4081	Target Tip	Transvenous Ventricular Tines	Polyurethane (80A)	MP35N 4 Filars	Target Tip Concentric Grooves	IS-1 UNI w/Removable 5 mm Sleeve
4092	CapSure SP Novus	Transvenous Ventricular Tines	Polyurethane/Silicone (55D/4719)	MP35N 6/4 Filars	Porous Platinized/ Steroid	IS-1 BI
4503, 4503M	CapSure	Transvenous Atrial-J Tines	Polyurethane (80A)	MP35N 4 Filars	Porous/Steroid	5 mm (4503) IS-1 UNI (4503M)
4504, 4504M	CapSure	Transvenous Atrial-J Tines	Polyurethane (80A)	MP35N 3/4 Filars	Porous/Steroid	3.2 mm Low Profile (4504) IS-1 BI (4504M)
4512	Target Tip	Transvenous Atrial-J Tines	Polyurethane (80A)	MP35N 2/4 Filars	Target Tip Concentric Grooves	3.2 mm Low Profile
4523	CapSure SP	Transvenous Atrial-J Tines	Polyurethane (55D)	MP35N 2 Filars	Porous Platinized/ Steroid	IS-1 UNI
4524	CapSure SP	Transvenous Atrial-J Tines	Polyurethane (55D)	MP35N 4/5 Filars	Porous Platinized/ Steroid	IS-1 BI
4533	CapSure Z	Transvenous Atrial-J Tines	Polyurethane (55D)	MP35N 2 Filars	CapSure Z Platinized/Steroid	IS-1 UNI
4557, 4557M	Screw-In	Transvenous Atrial-J Screw-In	Polyurethane (80A)	MP35N 1 Filar	1.5 mm Helix	5 mm (4557) IS-1 UNI (4557M)
4558M	Screw-In	Transvenous Atrial-J Screw-In	Polyurethane (80A/55D)	MP35N 6/3 Filars	1.8 mm Helix/Steroid	IS-1 BI
4568	CapSureFix	Transvenous Atrial-J Screw-In	Polyurethane (80A/55D)	MP35N 6/3 Filars	1.8 mm Helix/Steroid	IS-1 BI
4574	CapSure Sense	Transvenous Atrial -J Tines	Polyurethane/Silicone (55D,4719)	MP35N 5/5 Filars	TiN Coated Platinum Iridium	IS-1 BI
4592	CapSure SP Novus	Transvenous Atrial-J Tines	Polyurethane/Silicone (55D/4719)	MP35N 6/3 Filars	Porous Platinized/ Steroid	IS-1 BI
5023, 5023M	CapSure SP	Transvenous Ventricular Tines	Silicone	MP35N 4 Filars	Porous Platinized/ Steroid	5 mm (5023) IS-1 UNI (5023M)

continued

## Reference Chart continued

Model Number	Family	Туре	Insulation	Conductor Material	Tip Electrode	Connector Type
5024, 5024M	CapSure SP	Transvenous Ventricular Tines	Silicone	MP35N 4/5 Filars	Porous Platinized/ Steroid	3.2 mm Low Profile (5024) IS-1 BI (5024M)
5026	CapSure	Transvenous Ventricular Tines	Silicone	MP35N 6/4 Filars	Porous Platinized/ Steroid	3.2 mm Low Profile
5033	CapSure Z	Transvenous Ventricular Tines	Silicone	MP35N 4 Filars	CapSure Z Platinized/Steroid	IS-1 UNI
5034	CapSure Z	Transvenous Ventricular Tines	Silicone	MP35N 4/5 Filars	CapSure Z Platinized/Steroid	IS-1 BI
5054	CapSure Z Novus	Transvenous Ventricular Tines	Silicone (4719)	MP35N 5/5 Filars	CapSure Z Porous/Platinized/ Steroid	IS-1 BI
5068	CapSureFix	Transvenous V or A Screw-In	Silicone	MP35N 4/3 Filars	1.8 mm Helix/Steroid	IS-1 BI
5072	SureFix	Transvenous V or A Screw-In	Silicone	MP35N 4/5 Filars	1.8 mm Helix/Steroid	IS-1 BI
5076	CapSureFix Novus	Transvenous V or A Screw-In	Silicone (4719)	MP35N 4/6 Filars	Porous Platinized/ Steroid	IS-1 BI
5092	CapSure SP Novus	Transvenous Ventricular Tines	Silicone (4719)	MP35N 5/5 Filars	Porous Platinized/ Steroid	IS-1 BI
5524, 5524M	CapSure SP	Transvenous Atrial-J Tines	Silicone	MP35N 6/5 Filars	Porous Platinized/ Steroid	3.2 mm Low Profile (5524) IS-1 BI (5524M)
5534	CapSure Z	Transvenous Atrial-J Tines	Silicone	MP35N 4/5 Filars	CapSure Z Platinized/Steroid	IS-1 BI
5554	CapSure Z Novus	Transvenous Atrial-J Tines	Silicone (4719)	MP35N 6/5 Filars	CapSure Z Porous Platinized/ Steroid	IS-1 BI
5568	CapSureFix	Transvenous Atrial-J Screw-In	Silicone	MP35N 6/3 Filars	1.8 mm Helix/Steroid	IS-1 BI
5592	CapSure SP Novus	Transvenous Atrial-J Tines	Silicone (4719)	MP35N 6/5 Filars	Porous Platinized/ Steroid	IS-1 BI
5594	CapSure SP Novus	Transvenous Atrial-J Tines	Silicone (4719)	MP35N 6/5 Filars	Platinized Platinum/ Steroid	IS-1 BI
6940	CapSureFix	Transvenous A or V Screw-In	Silicone	MP35N 3/6 Filars	Platinum Alloy	IS-1 BI
6957	Spectraflex	Transvenous V or A Screw-In	Polyurethane (80A)	MP35N 1 Filar	2.0 mm Helix	5 mm
6957J	Spectraflex	Transvenous Atrial-J Screw-In	Polyurethane (80A)	MP35N 1 Filar	1.5 mm Helix	5 mm
6961	Tenax	Transvenous Ventricular Tines	Silicone	MP35N 3 Filars	Ring Tip	5 mm
6962	Tenax	Transvenous Ventricular Tines	Silicone	MP35N 4 Filars	Ring Tip	5 mm Bifurcated

# **Epi/Myocardial Pacing Leads**

## 4951, 4951M Spectraflex Product Characteristics

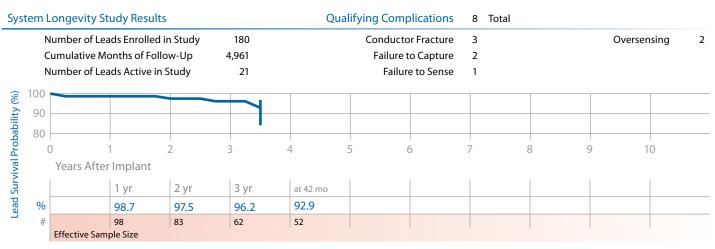
US Market Release	Oct-81	Serial Number Prefix	TF or LBJ	US Returned Product Ana	alysis
Estimated US Implants	25,400	Type and/or Fixation	Myocardial Stab-in, V or A, Peds	Implant Damage	15
Estimated US Active	3,300	Polarity	Unipolar	Electrical Malfunction	97
Advisories	None	Steroid	No	Other	28

#### System Longevity Study Results **Qualifying Complications** 10 Total Number of Leads Enrolled in Study 179 Failure to Capture Insulation (ESC) 1 3 Cumulative Months of Follow-Up 6,409 Failure to Sense Insulation (not further defined) 1 Number of Leads Active in Study 4 Impedance Out of Range 1 100 Lead Survival Probability (%) 90 80 8 6 9 10 Years After Implant 2 yr 1 yr 3 yr 4 yr at 57 mo 93.4 93.4 % 97.7 96.5 96.5 89 74 65 55 48 **Effective Sample Size**

## 4965 CapSure Epi

#### **Product Characteristics**

US Market Release	Sep-96	Serial Number Prefix	LBT	US Returned Product Analysis
Estimated US Implants	19,900	Type and/or Fixation	Epicardial Suture-On V or A	Implant Damage 8
Estimated US Active	10,600	Polarity	Unipolar	Electrical Malfunction 101
Advisories	None	Steroid	Yes	Other 2



# **Epi/Myocardial Pacing Leads** continued

## 4968 CapSure Epi

#### **Product Characteristics**

US Market Release	Sep-99	Serial Number Prefix	LEN	US Returned Product Ana	alysis
Estimated US Implants	16,900	Type and/or Fixation	Epicardial Suture-On V or A	Implant Damage	2
Estimated US Active	11,700	Polarity	Bipolar	Electrical Malfunction	10
Advisories	None	Steroid	Yes	Other	0

## System Longevity Study Results

100

#### **Qualifying Complications** 33 Total

Number of Leads Enrolled in Study	515	Conductor Fracture	7	Impedance Out of Range	4
Cumulative Months of Follow-Up	20,193	Failure to Capture	13	Insulation (not further defined)	2
Number of Leads Active in Study	321	Failure to Sense	3	Oversensing	4



#### 5071

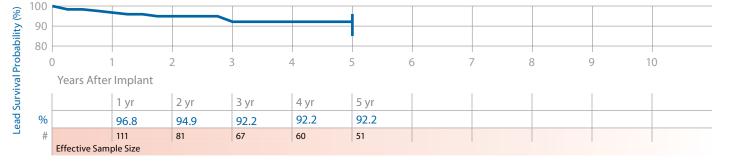
#### **Product Characteristics**

US Market Release	Dec-92	Serial Number Prefix	LAQ	US Returned Product Analysis
Estimated US Implants	38,200	Type and/or Fixation	Myocardial Screw-in Vent.	Implant Damage 28
Estimated US Active	22,300	Polarity	Unipolar	Electrical Malfunction 7
Advisories	None	Steroid	No	Other 2

#### System Longevity Study Results

#### **Qualifying Complications** 10 Total

Number of Leads Enrolled in Study	218	Failure to Capture	8
Cumulative Months of Follow-Up	6,841	Oversensing	2
Number of Leads Active in Study	30		



# **Epi/Myocardial Pacing Leads** continued

## 6917, 6917A Tenax

#### **Product Characteristics**

US Market Release	Jun-73		Serial Num	ber Prefi	х	WV oı	WC				US F	Return	ed Pro	oduct A	Analy
Estimated US Implan	ts 180,100		Type and/o	or Fixatio	n	Муос	ardial S	crew-i	in Ven	t.		Imp	lant D	amage	1
<b>Estimated US Active</b>	4,600		Polarity			Unipo	lar				Ele	ectrica	l Malfu	nction	
Advisories	None		Steroid			No								Other	
system Longevity Study R	esults			Qu	alifying	g Con	nplicat	ions	69	Total					
Number of Leads Enr	olled in Study	985			Co	onduc	tor Frac	cture	6		lmp	edance	e Out o	f Range	2
Cumulative Months of	of Follow-Up	47,506		ı	Extra Ca	ardiac	Stimula	ation	1			Ir	sulatio	n (MIO	)
Number of Leads Act	tive in Study	6				Failure	to Cap	oture	30				Over	sensing	3
						Failu	ire to S	ense	11						
§ 100															
90															
90 80 70 70 1 2 2							74								
70															
C .															

Vacus After Incolon

	Years	s After	Impla	nt														
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	12 yr	at 150 mo				
%		99.0	97.6	95.9	93.6	92.8	91.1	89.5	87.2	85.0	84.2	84.2	83.2	80.4				
#		638	546	463	371	319	248	197	167	137	93	84	58	50				
	Effecti	ve Sami	ole Size															

Device Survival Probability (%)	rImplant	2 yr 3 yr 4 yr 5 yr 6 yr 7 yr 8 yr 10 yr 12 yr 16 yr	96.5 96.5 93.4 93.4 +2.2/-5.8 +3.7/-8.1 = 57 mo	97.5 96.2 92.9 +1.7/-5.3 +2.4/-6.5 +4.0/-8.7 at 42 mo	97.0 95.5 93.9 92.4 90.7 90.7 90.7 90.7 41.4/-2.5 +1.8/-3.1 +2.3/-3.8 +2.8/-4.4 +3.4/-5.3 +3.4/-5.3 43.4/-5.3 at 87 mo	94.9 92.2 92.2 92.2 43.8/7.2 +3.8/7.2 +3.8/7.2	976 95.9 93.6 92.8 91.1 89.5 87.2 84.2 83.2 80.4 90.4 97.1 89.5 87.2 84.2 83.2 80.4 90.4 97.1 97.2 97.3 97.4 91.3 97.4 91.3 97.4 91.3 97.4 91.3 97.4 91.3 97.4 91.3 97.4 91.3 97.4 91.3 97.4 91.3 97.4 91.3 97.4 91.3 97.4 91.3 97.4 91.3 97.4 91.3 97.4 91.3 97.3 97.3 97.3 97.3 97.3 97.3 97.3 97	
evice Sur	Years After Implant	yr 2 y	97.7 96.	98.7 97.+1.0/-3.8	99.5 97.	96.8 94.+1.9/-4.5 +2.	99.0 97.	
tanoM Italia Italia	licatic lative U-wol	umu⊃ llo∃ ło	10 6,409 97.	8 4,961 98	33 20,193 99	10 6,841 96	69 47,506   99   +0	
pəl n₁Ş uị ə		speə7	179 4	180 21	515 321	218 30	985 6	
əseələ	US Market Rel		Oct-81	Sep-96	Sep-99	Dec-92	Jun-73	
	٨	(lime7	Spectraflex	CapSure Epi	CapSure Epi	(no brand name)	Tenax	
		əpoW	4951, 4951M	4965	4968	5071	6917, 6917A	

# **Epi/Myocardial Pacing Leads** continued

# **US Returned Product Analysis Summary**

Model Number	Family	US Market Release	Estimated US Implants	Estimated US Active	Implant Damage	Electrical Malfunction	Other
4951, 4951M	Spectraflex	Oct-81	25,400	3,300	15	97	28
4965	CapSure Epi	Sep-96	19,900	10,600	8	101	2
4968	CapSure Epi	Sep-99	16,900	11,700	2	10	0
5071	(no brand name)	Dec-92	38,200	22,300	28	7	2
6917, 6917A	Tenax	Jun-73	180,100	4,600	115	42	1

Source: Returned Product Analysis Data as of July 31, 2008

## **Reference Chart**

Model Number	Family	Туре	Insulation	Conductor Material	Tip Electrode	Connector Type
4951, 4951M	Spectraflex	Myocardial Stab-In V or A/Peds	Polyurethane (80A)	MP35N 4 Filars	Barb	5 mm (4951) IS-1 UNI (4951M)
4965	CapSure Epi	Epicardial Suture-On V or A	Silicone	MP35N 5 Filars	Porous Platinized/ Steroid	IS-1 UNI
4968	CapSure Epi	Epicardial Suture V or A	Silicone	MP35N 5 Filars	Porous Platinized/ Steroid	IS-1 B1
5069	(no brand name)	Myocardial Screw-In	Silicone	MP35N Multifilars	3-Turn Helix	IS-1 UNI
5071	(no brand name)	Myocardial Screw-In Ventricular	Silicone	MP35N Multifilars	2-Turn Helix	IS-1 UNI
6917	Tenax	Myocardial Screw-In Ventricular	Silicone	Pt Ir Tinsel Wire	3-Turn Helix	5 mm
6917A	Tenax	Myocardial Screw-In Ventricular	Silicone	Pt Ir Tinsel Wire	2-Turn Helix	5 mm

# **VDD Single Pass Pacing Leads**

## 5032 CapSure VDD

#### **Product Characteristics**

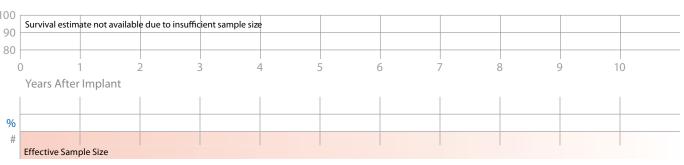
US Market Release	Mar-96	Serial Number Prefix	LCL, LCN, LCM	US Returned Product Ana	alysis
Estimated US Implants	5,400	Type and/or Fixation	Transvenous, Atr-Vent., Tines	Implant Damage	24
Estimated US Active	1,900	Polarity	Quadripolar	Electrical Malfunction	12
Advisories	None	Steroid	Yes	Other	0

#### System Longevity Study Results

Lead Survival Probability (%)

#### Qualifying Complications 1 Total

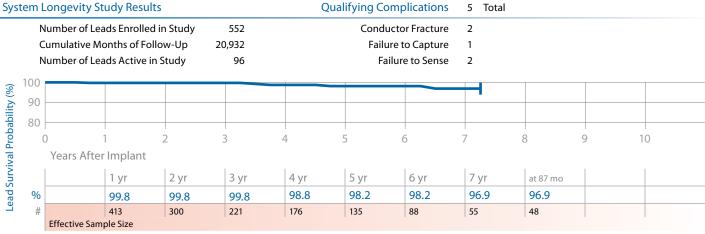
Number of Leads Enrolled in Study 38 Cumulative Months of Follow-Up 1,962 Number of Leads Active in Study 0 Failure to Sense 1



## 5038 CapSure VDD-2

#### **Product Characteristics**

US Market Release	Sep-98	Serial Number Prefix	LEE, LEG, or LEF	US Returned Product Ana	lysis
Estimated US Implants	7,800	Type and/or Fixation	Transvenous, Atr-Vent., Tines	Implant Damage	6
Estimated US Active	4,200	Polarity	Quadripolar	Electrical Malfunction	4
Advisories	None	Steroid	Yes	Other	1



# **VDD Single Pass Pacing Leads** continued

## **Lead Survival Summary** (95% Confidence Interval)

ā		US Market Release	Enrolled	Active in Study	•	Cumulative Months of Follow-Up in Study		Device Survival Probability (%)  Years After Implant											
Model Numbe	Family	US Mai	Leads En	Leads ,	Qualify Compl	Cumul	1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr			
5032	CapSure VDD	Mar-96	38	0	1	1,962	Survival e	stimate no	t available (	due to insu	fficient san	ple size							
5038	CapSure VDD-2	Sep-98	552	96	5	20,932	99.8 +0.2/-1.4	99.8 +0.2/-1.4	99.8 +0.2/-1.4	98.8 +0.8/-2.7	98.2 +1.1/-3.2	98.2 +1.1/-3.2	96.9 +2.0/-5.4	96.9 +2.0/-5.4 at 87 mo					

Source: System Longevity Study Data as of July 31, 2008

## **US Returned Product Analysis Summary**

Model Number	Family	US Market Release	Estimated US Implants	Estimated US Active	Implant Damage	Electrical Malfunction	Other
5032	CapSure VDD	Mar-96	5,400	1,900	24	12	0
5038	CapSure VDD-2	Sep-98	7,800	4,200	6	4	1

Source: Returned Product Analysis Data as of July 31, 2008

#### **Reference Chart**

Model Number	Family	Туре	Insulation	Conductor Material	Tip Electrode	Connector Type
5032	CapSure VDD	Transvenous V and A Tines	Silicone	MP35N 5/6/1 Filars	Porous Platinized/ Steroid	Atr. IS-1 BI, Vent. IS-1 BI
5038	CapSure VDD-2	Transvenous Ventricular Tines	Silicone	MP35N	Porous Platinized/ Steroid	Atr. IS-1 BI, Vent. IS-1 BI

# **ICD and CRT-D Charge Time Performance**

Medtronic continues its commitment to providing updated information on charge time performance.

#### Introduction

Information on charge time performance of Medtronic is presented in this section of the CRDM Product Performance Report. Medtronic implemented the collection of charge time data on July 1, 1999. The data are collected via our ongoing active clinical study of long-term system performance called the System Longevity Study. The study protocol requests device data be routinely taken and sent to Medtronic at no more than six-month intervals.

In our analysis performed for this report, only charge times resulting from full energy charges are considered. To ensure consistent reporting across devices, the charge time reported at implant represents the last charge time available from date of implant. When more than one charge time is available in a six-month interval, a conservative approach has been adopted whereby only the maximum charge in each 6-month interval is reported. As charge time is directly proportional to the time elapsed since the last capacitor reformation, charges occurring within 15 days of a previous charge are excluded. This precludes the reporting of overly optimistic results.

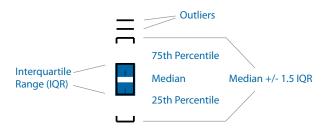
Data from over 20,000 devices contribute to the charge time data in this report. By tracking and reporting this charge time data, Medtronic is able to ascertain the actual performance of its charging circuitry. The insight gained through this information is applied to Medtronic's ongoing efforts to provide charge times that are short and consistent over the life of the product.

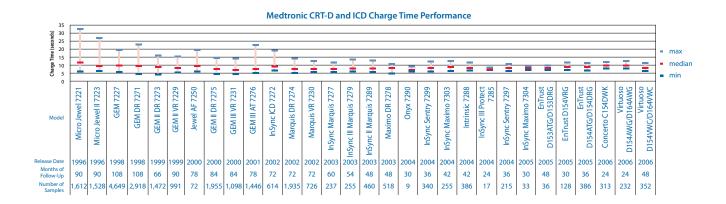
#### **Data Presentation**

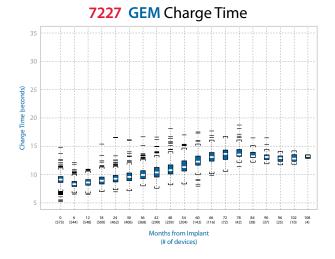
Charge time data for ICD and CRT-D models are presented using boxplots at 6-month intervals. The shaded box on the plots represents the middle half of the data - the Interquartile Range (IQR). The white line in the middle of each box is the median charge time. The top of the box representing the IQR is the 75th percentile (i.e., 75% of all charge times fall below this line), whereas the bottom of the box represents the 25th percentile. The brackets around the box represent the variance in charge times (analogous to a confidence interval), and are calculated as a function of the median and IQR. Individual values falling outside the brackets are labeled as outliers.

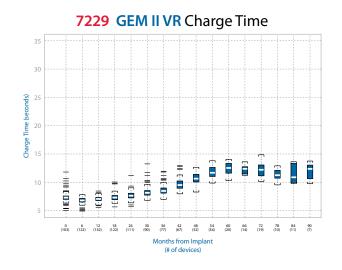
#### Results

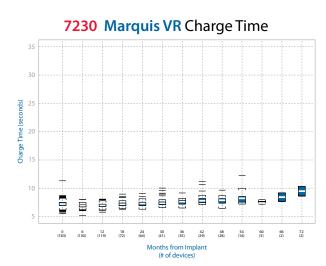
As shown in the graph below, the performance of Medtronic ICD and CRT-D devices has improved. This graph shows the overall maximums, minimums, and medians for Medtronic ICD and CRT-D products, beginning with the 7221 Micro Jewel. A progression toward shorter mean charge times and less variation has occurred between 1996 and 2002. Models released after 2002 have limited experience, but appear to be continuing this performance.

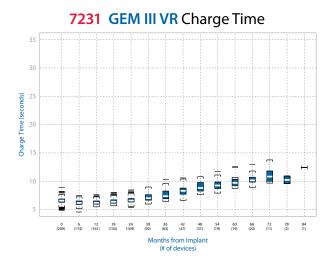


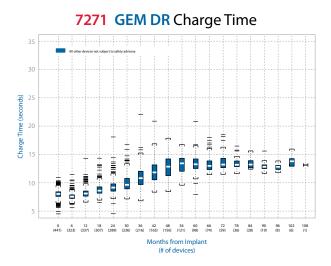


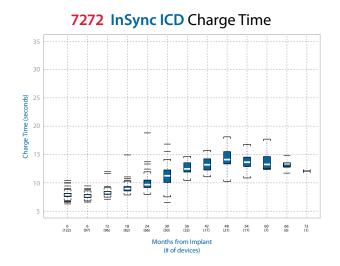


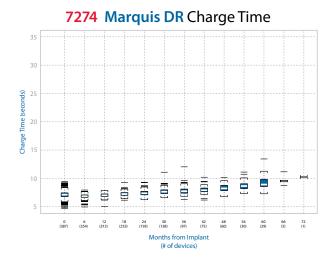


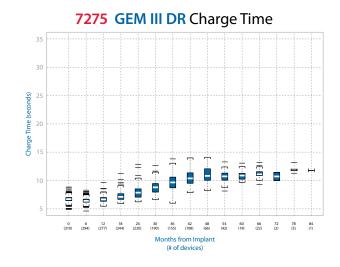


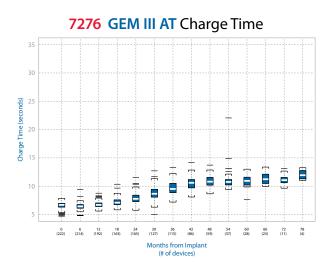


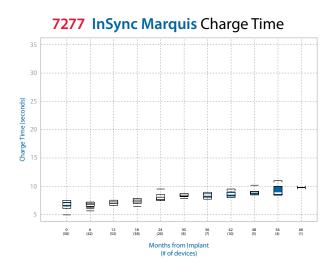


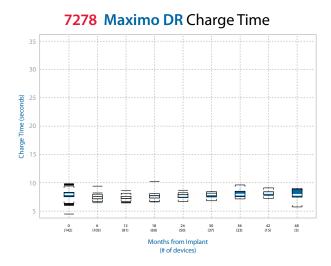


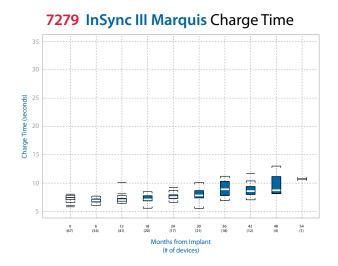


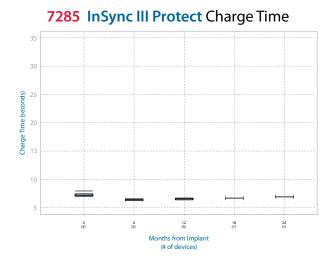


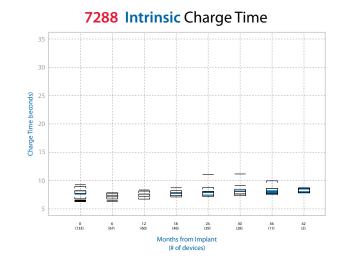


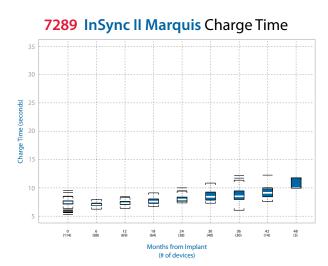


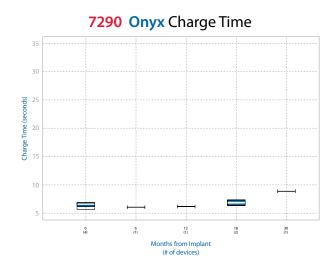


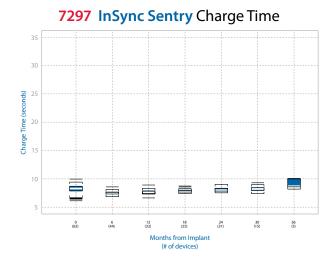


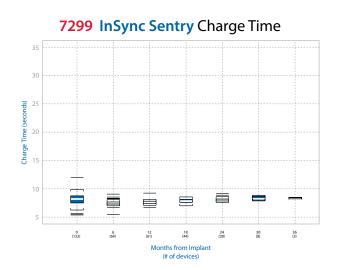




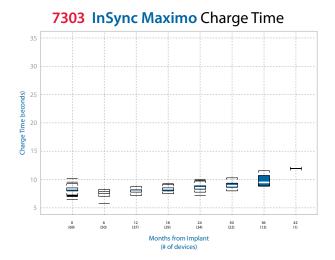


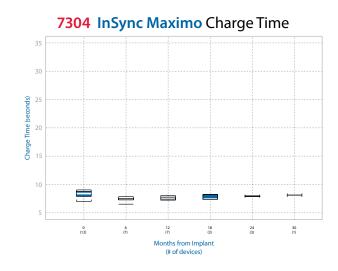


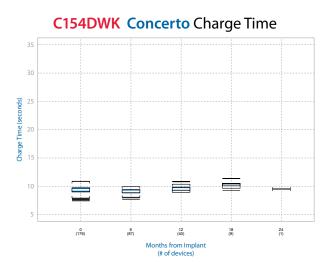


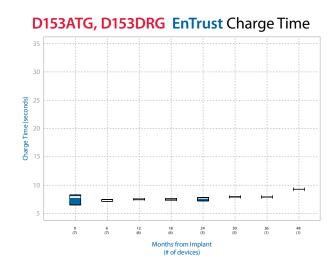


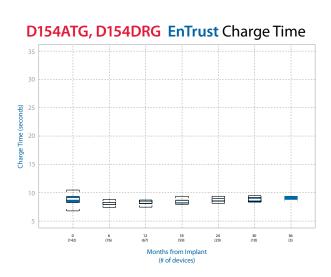
Data as of July 31, 2008

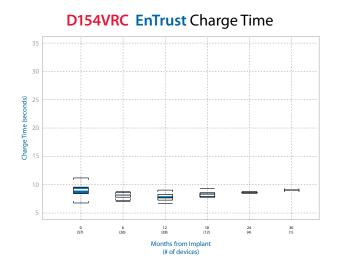


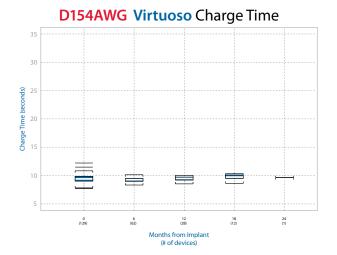


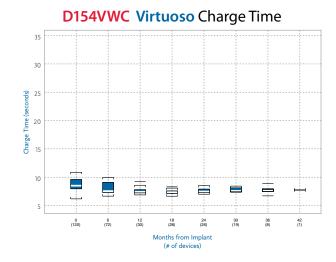












## **Advisories**

## 6930, 6931, 6948, 6949 Sprint Fidelis Defibrillation Leads

Original Date of Advisory: October 2007

### **Potential Conductor Wire Fracture**

#### Product

All Model 6930, 6931, 6948, and 6949 Implantable Defibrillation Leads.

### Advisory

There are two primary locations where chronic conductor fractures have occurred on Sprint Fidelis leads: 1) the distal portion of the lead, affecting the anode (ring electrode) and 2) near the anchoring sleeve tie-down, predominantly affecting the cathode (helix tip electrode), and occasionally the high voltage conductor. These two locations account for 90% of the chronic fractures identified in Returned Product Analysis (RPA). The remaining 10% of chronic fractures occurred in the DF-1 connector leg and the proximal portion of the RV coil. High voltage conductor fractures could result in the inability to deliver defibrillation therapy. Anode or cathode conductor fractures (at either location) may present clinically as increased impedance, oversensing, increased interval counts, multiple inappropriate shocks, and/or loss of pacing output.

### **Patient Management Recommendations**

Medtronic recommends you consider the following as part of routine follow-up for each patient.

- To reduce the risk of inappropriate detection and therapy due to oversensing, program VF detection for initial Number of Intervals to Detect (NID) to nominal settings (18/24) or longer at physician discretion and Redetect NID to nominal settings (12/16)
- Turn ON Patient Alert for RV Pacing, RV Defibrillation, and SVC Defibrillation impedance. For Concerto and Virtuoso devices enrolled on the Medtronic CareLink Network, turn ON the Medtronic CareAlert Notifications for these same parameters.
- To optimize effectiveness of the lead impedance alert:
  - Review V Pacing Lead Performance Trend to determine typical chronic impedance value for the patient (typical values for Fidelis leads should be 350-1,000 ohms)
  - Program lead impedance alert threshold for RV Pacing to 1,000 ohms, if the typical chronic impedance for the patient is ≤ 700 ohms, or
  - Program lead impedance alert threshold for RV Pacing to 1,500 ohms, if the typical chronic impedance for the patient is > 700 ohms
  - Program lead impedance alert threshold for RV Defibrillation and SVC Defibrillation to 100 ohms

### Status Update

Sprint Fidelis lead performance continues to be in line with the information provided in the October 2007 and May 2008 advisory communications. After consideration of updated

performance information, as well as ongoing reviews by our Independent Physician Quality Panel, **patient management recommendations remain unchanged.** 

- The risk of prophylactic intervention appears to be greater than the risk of serious injury resulting from lead fracture even for pacemaker dependent patients, except in select individual patient circumstances as determined by the physician
- When a lead fracture is suspected or confirmed, we strongly recommend urgent patient attention. Patients should contact their physician without delay if they experience unexpected shocks.
- Without Lead Integrity Alert described below, implementation of our patient management recommendations is expected to provide two days advance notice prior to inappropriate therapy to 49% of the patients with lead fractures. The remainder will receive less than two days advance notice or no notice. This percentage may vary by implanted device.

Out of the initial implant population of 204,000 in the United States, approximately 166,500 remain implanted. According to System Longevity Study results, lead survival is estimated to be 93.7% ( $\pm$ 2.7/-4.5) at 42 months. As the implanted population ages and the sample size increases for each time interval, the accuracy of the estimated survival probability will increase as shown by tighter confidence intervals.

As part of our commitment to keep you informed about Sprint Fidelis lead performance, Medtronic publishes the quarterly System Longevity Study's all-cause lead survival curve for the 6949 lead model at <a href="https://www.medtronic.com/fidelis">www.medtronic.com/fidelis</a>. Semi-annual updates will also continue to be provided in the Product Performance Report. Additional information about the Sprint Fidelis lead is available at <a href="https://www.medtronic.com/fidelis">www.medtronic.com/fidelis</a>.

### Lead Integrity Alert<sup>†</sup>

Medtronic has released Lead Integrity Alert (LIA) software. LIA was designed to provide patients more advance notice via an audible sound of a potential lead fracture that could result in an unnecessary shock.

Data shows that with LIA, approximately 76% of the patients with Sprint Fidelis leads are expected to receive three or more days advance warning of a potential lead fracture which could result in an unnecessary shock.

Upon hearing the alert, patients should contact their physician without delay.

LIA can be downloaded into nearly all Medtronic implantable cardioverter defibrillators (ICDs) and cardiac resynchronization therapy defibrillators (CRT-Ds) implanted worldwide.

## Advisories continued

### **Sigma Implantable Pulse Generators**

Original Date of Advisory: November 2005

## **Potential Separation of Interconnect Wires**

#### **Product**

A specific subset of Sigma series pacemakers may fail due to separation of interconnect wires from the hybrid circuit. Specific model and serial numbers of affected devices are available online at <a href="http://SigmaSNList.medtronic.com">http://SigmaSNList.medtronic.com</a>.

### Advisory

This subset of Sigma series pacemakers that may fail due to separation of interconnect wires from the hybrid circuit may present clinically as loss of rate response, premature battery depletion, intermittent or total loss of telemetry, or no output.

Separation of redundant interconnect wires has been observed on hybrid terminal blocks. Device failure occurs only where both interconnect wires separate from a hybrid terminal block. In October 2005, testing and analysis identified the root cause of these failures and the affected population. Hybrid circuits used in this subset of devices were cleaned during manufacturing with a particular cleaning solvent that could potentially reduce the strength of the interconnect wire bond over time.

Our modeling predicts a failure rate from 0.17% to 0.30% over the remaining lifetime of these pacemakers. No provocative testing can predict which devices may fail.

### **Patient Management Recommendations**

To assist physicians in their patient care and after discussion with physician consultants, Medtronic offers the following recommendations:

- Medtronic does not recommend replacement of these devices prior to normal elective replacement (ERI), based on the low probability of occurrence of a serious event in this population.
- Continue routine follow-up in accordance with standard practice.
- Advise patients to seek attention immediately if they experience return of symptoms (e.g., syncope or light-headedness).
- Determine whether device replacement is warranted on a case-by-case basis based upon consultation with patients, review of the individual

patient's medical history, and consideration of the relative risks of an invasive procedure.

### Status Update

The Sigma Family device performance related to the interconnect wires separation mechanism continues to be within Medtronic's engineering projections. As of July 31, 2008, 131 devices out of approximately 40,000 devices worldwide have been confirmed as having experienced interconnect wire separation. Twenty-three (23) of these devices were returned from the United States.

One hundred nineteen (119) of the 131 devices (0.30%) were returned with information indicating a problem with the patient's pacing system prior to explant. The remaining 12 devices (0.03%) were returned with no information indicating a potential malfunction while implanted or with insufficient information to determine the state of the device at explant. Lacking definite information indicating proper operation until explant, these devices are conservatively categorized as having experienced interconnect wire separation while implanted.

Implant duration for the 131 devices confirmed as having experienced interconnect wire separation has ranged between 17 and 72 months, with an average of 55.7 months.

Out of the initial advisory population of 40,000 worldwide, approximately 17,900 remain implanted. Approximately 4,200 of these are in the United States.

The Patient Management Recommendations set forth in the advisory remain unchanged.

7274 Marquis DR 7230 Marquis VR 7278 Maximo DR 7232 Maximo VR 7277 InSync Marquis7289 InSync II Marquis

7279 InSync III Marquis 7285 InSync III Protect

Original Date of Advisory: February 2005

## Potential Premature Battery Depletion Due to Battery Short

### **Product**

The specific subset of Marquis family ICD and CRT-D devices having batteries manufactured prior to December 2003 is affected. Devices manufactured with batteries produced after December 2003 are not affected. Specific model and serial numbers of affected devices are available online at <a href="http://MarquisSNList.medtronic.com">http://MarquisSNList.medtronic.com</a>.

## Advisory

Medtronic Marquis family of ICD and CRT-D devices having batteries manufactured prior to December 2003 may experience rapid battery depletion due to a specific internal battery short mechanism. Battery design changes were implemented in December 2003 that eliminate the possibility of this internal shorting mechanism.

Highly accelerated bench testing indicated the rate of this shorting mechanism may increase as the battery is depleted. As of February 2005, the rate of shorting was approximately 1 in 10,000 (0.01%); bench test data indicated the rate may increase to between 0.2% and 1.5% over the second half of device life.

No provocative testing can predict which of these devices will experience this issue. Once a short occurs, battery depletion can take place within a few hours to a few days. After depletion the device ceases to function. It is also possible that as the battery depletes quickly, patients may experience temporary warmth in the area surrounding the ICD.

## **Patient Management Recommendations**

We recommend you consider the following patient management options:

- Conduct quarterly (i.e., every three months) follow-up procedures.
- Inform patients that should they experience warmth in the area surrounding the ICD to seek follow-up care promptly.
- Program Low Battery Voltage ERI Patient Alert to "On-High." This will result in an audible, alternating tone in the limited circumstances where a battery depletes slowly over a number of days. Data indicates most shorts will occur rapidly and will not be detected by this feature.

Provide a hand-held magnet to patients to check device status and program the Low Battery Voltage ERI Patient Alert to "On-High." Device operation may be monitored periodically (e.g., daily) by patients placing the magnet over the device for 1-2 seconds. If the device is functional, a steady tone will sound for approximately 20 seconds. If no tone is heard, follow-up care should be sought promptly.

### Status Update

The Marquis Family device performance related to the battery shorting mechanism continues to be within Medtronic's engineering projections. As of July 31, 2008, 113 Marquis Family devices have been confirmed as having this internal battery shorting mechanism. Fifty-eight (58) of these devices were returned from the United States.

Of the 113 returns, 34 have been identified by patients reporting warmth in the ICD pocket, 41 by a regularly scheduled follow-up or during a nondevice related hospital visit, 15 by hand-held magnet test or CareLink attempt, 9 by return of bradycardia symptoms, 4 by the Patient Alert sounding, and 10 unknown.

Implant duration for the 113 devices ranged between 11 to 63 months, with an average of 37 months.

Consistent with Medtronic projections, the observed rate of shorting is higher in the second half of device life than in the first half of device life. Of the devices that have exhibited shorting in the last half of device life, 43% occurred in the last quarter of device life and 26% in the last 10% of device life.

Out of the initial advisory population of 87,000 worldwide, approximately 26,600 remain implanted. Approximately 23,400 of these are in the United States.

The Patient Management Recommendations set forth in the advisory remain unchanged.

### Warranty

All Marquis devices are subject to a Limited Warranty. Devices returned to Medtronic and determined to be malfunctioning will be replaced or credited in accordance with the warranty terms. In addition, for devices subject to the Marquis advisory, should a physician decide to replace a device for a patient who is pacemaker dependent or who receives frequent VT/VF therapy, Medtronic will, upon receipt of a written statement from the physician setting forth the basis for early replacement of the device, provide a replacement device at no cost.

## Advisories continued

## Kappa 600, 700 Dual Chamber (D, DR, and VDD) IPGs

Original Date of Advisory: March 15, 2002

## **Potential Fractured Power Supply Wires**

#### Product

A specific subset of Kappa 700/600 Dual Chamber (D, DR, and VDD) Implantable Pulse Generators have been identified by serial numbers. Hospitals and Physicians were notified. Specific model and serial numbers of affected devices are available by calling US Technical Services at 1 (800) 505-4636.

### Advisory

As of March 15, 2002, Medtronic observed 53 related failures (0.02%) in over 255,000 Kappa 700/600 Dual Chamber (D, DR, and VDD) Series devices sold worldwide. Medtronic voluntarily communicated this information to physicians because these failures had been observed in patients having submuscular implants.

These devices have presented with an electrical reset, intermittent output, or no output. Our investigation identified the root cause as fractured wires supplying power to the pacemaker. This has been directly correlated to submuscular placement of these devices. Submuscular implant locations (e.g., subpectoral, abdominal, etc.) can result in additional stress and repetitive flexing on the implanted device causing excessive fatigue on these wires. Of the estimated 4,000 devices implanted submuscular, approximately 200 (5%) may experience this failure. These stresses on the implanted device are unique to submuscular implant sites and do not exist with subcutaneous implants.

### Patient Management Recommendations

While there is no provocative testing or time dependency that will predict which submuscular placed device will fail, certain electrical resets may be an indicator that a wire fracture has occurred. Normal electrical resets can occur as a result of electrosurgical procedures such as cautery and ablation or from defibrillation therapy. If none of the normal causes of electrical reset can be confirmed, or if a device serial number presents as "000000" following an electrical reset, this may be an indicator of a wire fracture.

For patients who have submuscular implants of devices within the designated serial number range and who are pacemaker dependent with no underlying rhythm, replacement of the device should be considered. Medtronic will provide the replacement device free-of-charge under the terms of its warranty program if a device is replaced in these patients.

For patients having subcutaneous implants, no change to your current patient care and follow-up is advised.

### Status

Device performance related to this advisory continues to be within Medtronic's engineering projections. Patient management recommendations remain unchanged. As of July 31, 2008, 291 out of approximately 180,000 (0.16% incidence) Kappa family devices worldwide have been confirmed as having fractured power supply wires. One hundred forty-seven (147) of these devices were returned from the United States. Out of the initial implant population of 121,000 in the United States, approximately 32,600 remain implanted.



## **7227Cx GEM** 7229Cx GEM II VR

Original Date of Advisory: October 15, 1999

### Potential Circuit Overload

#### Product

Model 7227Cx and Model 7229Cx Implantable Cardioverter Defibrillators supplied before October 15, 1999, with serial numbers ending in an "H." For example, PIPxxxxxxH or PJJxxxxxxH, where x is a variable numeric, may be affected. Specific model and serial numbers of affected devices are available by calling US Technical Services at 1 (800) 723-4636.

### IMPORTANT REMINDER:

Medtronic strongly advises physicians who have patients under their care affected by this issue to reprogram the Patient Alert feature "ON" without delay.

### Advisory

Manufacturing error in a small percentage of devices may cause circuit overload when AX ≥ B High Voltage energy is delivered via an integrated bipolar lead. GEM Model 7227Cx and GEM II VR Model 7229Cx devices with dedicated bipolar sensing leads are not affected by this issue. Devices affected may not be able to subsequently charge to full energy and experience "charge circuit timeout."

### Patient Management Recommendations

- Assessment of all patients with the potentially affected devices implanted AND an integrated bipolar ICD lead such as the 6942 and 6945 should take place without delay.
- Reprogram polarity pathway to B ≥ AX for all cardioversion and defibrillation therapies.
- Confirm correct device function:
  - Perform a full energy charging sequence.
  - If "charge circuit timeout" is observed, contact your Medtronic representative.
  - If device charges normally, it has not been damaged and will function appropriately with polarity programmed  $B \ge AX$ .

Recent studies have demonstrated that DFTs are similar or lower in a B ≥ AX polarity pathway when compared to  $AX \ge B$ .

Devices implanted with functional dedicated bipolar leads such as the 6932, 6934S, 6936, 6943, and 6966 are not affected.

### Status

Device performance related to this advisory continues to be within Medtronic's engineering projections. Patient management recommendations remain unchanged. Out of the initial implant population of 10,000 in the United States, approximately 1,600 remain implanted. The devices affected by this advisory are nearing the end of their expected battery longevity.



4504, 4504M CapSure Atrial Lead 4582 Target Tip Atrial Lead

Original Date of Advisory: October 4, 1996

## **Lead Survival Below Expectations**

### **Product**

All Models 4504, 4504M, and 4582 Implantable Pacing Leads

### Advisory

Lead survival probability is below expectations and is primarily associated with insulation degradation due to Metal Ion Oxidation (MIO).

### Patient Management Recommendations

- Follow patients in accordance with Medicare Guidelines.
- Avoid the use of the AAI or AOO mode.
- During patient evaluation, give careful attention to lead performance such as:
  - Review patient ECG for indications of transient sensing and/or capture abnormalities.
  - Monitor in clinic for impedance less than 250 ohms or a decrease of more than 30% from implant values (or an established baseline using telemetry) which would suggest lead failure.
- Consider the use of unipolar if the pulse generator has this capability.
- At the time of pacemaker system revision (e.g., normal pulse generator or ventricular lead revision), carefully evaluate lead integrity and patient status before choosing to reuse.

### Status

Patient management recommendations remain unchanged. Laboratory analysis trends and engineering conclusions remain unchanged. Out of the initial implant population of 16,600 in the United States, approximately 1,400 remain implanted. According to System Longevity Study results, lead survival is estimated to be 66.1% at 8 years, 9 months.



## 4004, 4004M CapSure Ventricular Lead **4082** Target Tip Ventricular Lead

Original Date of Advisory: October 8, 1993

## **Lead Survival Below Expectations**

### **Product**

All Models 4004/4004M and 4082 Implantable Pacing Leads

### Advisory

Lead survival probability is below expectations due primarily to polyurethane insulation failure (MIO) and conductor fracture (associated with "subclavian crush").

### **Patient Management Recommendations**

- Increase, as appropriate, the frequency of patient evaluation through in-clinic visits supplemented with transtelephonic and/or ambulatory monitoring; for example, consistent with Guideline I under Medicare Pacemaker Monitoring Guidelines (50-1 Cardiac Pacemaker Evaluation Services).
- During patient evaluations, give careful attention to lead performance such as:
  - Reviewing patient ECGs carefully for indications of transient sensing and/or capture abnormalities.
  - Monitoring in-clinic for impedances less than 300 ohms or a decrease of more than 30% from implant values (or an established baseline using telemetry) which would suggest lead failure.
  - Eliciting and thoroughly investigating any patient complaints suggestive of lead failure.

- Consider whether prophylactic replacement would be appropriate, especially in patients at high risk, such as pacemaker dependent patients.
- Carefully evaluate lead integrity when performing routine pulse generator replacements. Replace lead if
  - insulation breaches are observed.
  - lead impedance is less than 300 ohms or has decreased by more than 30% from implant values.
  - impedance or voltage threshold measurements vary significantly when multiple readings are taken.
  - if the risk of continued use outweighs the risk associated with implanting a new lead.
- As always, individual circumstances and medical judgment dictate patient care and frequency of follow-up.
- Consider lead replacement during normal pulse generator change-out. Carefully evaluate lead integrity and patient status before choosing to reuse.

### Status

Patient management recommendations remain unchanged. Laboratory analysis trends and engineering conclusions remain unchanged. Out of the initial implant population of 77,000 in the United States, approximately 2,700 remain implanted. According to System Longevity Study results, lead survival is 50.6% at 10 years, 9 months.

## Advisories continued

## **4012** Target Tip Ventricular Lead

Original Date of Advisory: September 26, 1991

## **Lead Survival Below Expectations**

#### Product

All Model 4012 Implantable Pacing Leads

### Advisory

Lead survival probability beyond 5 years is below expectations due primarily to polyurethane insulation failure (due to ESC and/or MIO) and conductor fracture (associated with "subclavian crush").

### **Patient Management Recommendations**

Consider increasing frequency of monitoring (e.g., from quarterly to bimonthly or monthly). Consider the following activities as part of normal follow-up procedures:

- Monitor for significant changes in impedance which could be an indication of impending failure (pulse generator must have impedance telemetry capabilities).
- Review patient ECGs carefully for indications of transient sensing and/or capture abnormalities. This can be done using transtelephonic or in-clinic monitoring and/or using ambulatory monitoring.
- Elicit any patient complaints suggestive of lead failure and investigate thoroughly lead integrity/ performance characteristics following reports of patient complaints or symptoms using the above techniques.

- Consider whether prophylactic replacement would be appropriate in patients at high risk, such as pacemaker dependent patients.
- Evaluate carefully the integrity of the lead during routine pulse generator replacement before choosing to reuse. Specifically, Medtronic recommends placement of a new lead if:
  - insulation breaches are observed.
  - lead impedance is less than 300 ohms or has decreased by more than 30% from implant values.
  - electrical properties such as impedance and threshold vary significantly when multiple readings are taken.

As always, medical judgment must be used to establish the appropriate schedule and course of care for every individual, particularly pacemaker dependent or other patients at higher risk.

### Status

Patient management recommendations remain unchanged. Laboratory analysis trends and engineering conclusions remain unchanged. Out of the initial implant population of 96,800 in the United States, approximately 5,000 remain implanted. The System Longevity Study results show 62.2% lead survival at 15 years, 9 months.



## Minix, Minix ST, Micro Minix IPGs

Original Date of Advisory: May 6, 1991

## Potential Delayed Restoration of Permanent Settings

#### Product

All Models of the Minix, Minix ST, and Micro Minix families of Implantable Pulse Generators

## Advisory

Possibility of delayed restoration of permanent pacing mode and parameters, after the magnet or programming head is removed under certain conditions.

### Patient Management Recommendations

To eliminate any potential risk associated with temporary programming, depress the INTERROGATE KEY and verify successful interrogation before moving the programming head away from the pulse generator. The delay condition can also be terminated by repositioning the programming head and depressing the EMERGENCY VVI key.

#### Status

Device performance related to this advisory continues to be within Medtronic's engineering projections. Patient management recommendations remain unchanged. Out of the initial implant population of 65,000 in the United States, approximately 4,000 remain implanted. The devices affected by this advisory are nearing the end of their expected longevity.

## **Performance Notes**

## **Clinical Management of VCM near Elective Replacement**

## Background

Medtronic Technical Services has received reports of devices going to ERI or End-of-Life (EOL) sooner than expected after a normal follow-up in which the device longevity was projected to be approximately 18 months. It has been noted that these cases typically involve Kappa 700 devices where Ventricular Capture Management set the ventricular lead to high output (5 V, 1 ms), which occurs by device design when a high threshold is measured. It is important for physicians and allied professionals to understand VCM behavior as it relates to longevity so that they can, in turn, understand how this affects management of the device and follow-up visits as VCM equipped IPGs near the end of their expected longevity.

## Device Longevity and VCM Behavior

Ventricular Capture Management is a feature that uses evoked response sensing to determine the stimulation threshold needed to capture the ventricular chamber. Proper detection of the evoked response is crucial to the VCM algorithm determining an accurate capture threshold. There are rare conditions, however, during which the VCM algorithm will not be able to measure the evoked response accurately. When this occurs, for safety reasons the VCM algorithm will reprogram the output to 5 V, 1 ms until the subsequent VCM measurement.

If the device has considerable remaining longevity, these occasional excursions to high output do not substantially affect remaining longevity. However, if the device has less than approximately 18 months remaining longevity, there is the possibility that the high output condition caused by the 5 V, 1 ms output will drain the battery and trigger ERI.

When ERI is declared by the device, VCM is disabled and the outputs are left at 5 V, 1 ms until the device is reprogrammed at an in-office follow-up. This increased current drain of a high output condition will speed depletion of the device, possibly resulting in the device getting to the EOL (battery voltage  $\leq 2.15$  V).

Please note that the following parameter changes occur when the device goes to ERI:

Table: IPG Therapy Parameter Changes at ERI

Parameter	Value
Pacing Mode	VVI
Lower Rate	65 bpm
Single Chamber Hysteresis	OFF
Sleep Function	OFF
Ventricular Capture Management	OFF
Atrial Sensing Assurance	OFF
Ventricular Sensing Assurance	OFF

Kappa 700 is Medtronic's first-generation VCM algorithm, which has a relatively higher incidence of evoked response undersensing compared to subsequent algorithms, resulting in more frequent high output conditions. Therefore, Kappa 700 products are the primary focus of this note. It should be noted that IPGs equipped with the second-generation VCM algorithm (Kappa 900, EnPulse, Adapta/Versa/Sensia, and Relia) have not been observed with evoked response undersensing in the general population, though the items listed in "Follow-up Considerations" may also be used on these devices.

## Follow-Up Considerations

- Estimated longevity in the event the device goes to high output can be determined by the following steps. This allows the clinician to determine follow-up frequency if he or she is concerned the device may go to ERI due to high output.
  - Program the ventricular channel to 5 V, 1 ms
  - Navigate to Data/Battery and Lead Measurements
  - When the message stating "Warning Old Data" is displayed, select "Yes" to measure battery voltage and lead impedance at the new ventricular outputs
  - An updated remaining longevity estimate will be calculated on the elevated outputs. Note the "Minimum Remaining Longevity." Clinical decisions can be based on this value.
  - Program the Amplitude and Pulse Widths back to their original values before leaving the session
- If the capture trends and lead impedance trends are stable, VCM can be programmed to "Monitor Only" for the remaining device life. This should be considered only if remaining longevity is 18 months or less.
- Follow-up frequency can be increased for those patients who do not have stable capture or lead impedance trends. This can be done via a CareLink Home Monitor, or in-office.

 $<sup>^1</sup>$  Medtronic, Inc. (2001). Medtronic Kappa 700/600 Series Pacemaker Reference Guide (Chapter 4, p. 27). Can be retrieved from http://manuals.medtronic.com.

## **Ensuring the Accuracy of Battery Longevity Estimates**

### Purpose of this Information

This article is intended to help the clinician understand how Medtronic estimates CRT-D, ICD, and IPG device longevity and Medtronic's performance against these estimates.

### **Device Longevity and Battery Depletion**

The device service life ends when the usable battery capacity is depleted. The time to battery depletion depends on three factors:

- the amount of electrical energy expended in providing therapy to the patient
- the amount of energy consumed by the electronic circuitry to perform the functions of the device (e.g., operating the microprocessor, telemetry, memory, and charging component)
- the energy capacity of the battery

Medtronic has developed a statistical model for device longevity that accounts for each of these factors, and has validated the model with real time clinical performance. During the development of its products, Medtronic engineers characterize device longevity using this model. Testing begins during development and continues after market release to ensure the accuracy of device longevity estimates.

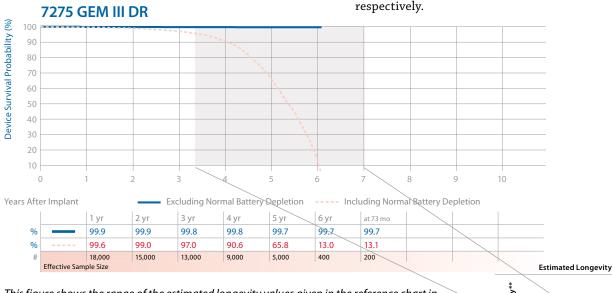
### Using Survival Curves to Assess Longevity

The survival curves in the Product Performance Report represent the composite experience of thousands of devices over a wide range of programming options and patient use conditions. While the curves are useful for understanding the overall performance of a population of devices, they cannot be used to accurately predict the longevity of a specific device in a specific patient. To get a longevity prediction for a specific device, the longevity model must be used. The model is available by contacting Medtronic's Technical Services Department.

Because the survival curves are an aggregate result, the Reference pages in the Product Performance Report include several longevity estimates for a range of use conditions. These longevity estimates, originally published in the device Technical Manual, are mean values calculated for the parameters given. This range of longevity estimates can be compared to the survival curve including normal battery depletion to assess the overall clinical performance of a device model against the original longevity estimates.

If most of a device model's population is being used at nominal parameters and conditions, the time at which the survival curve including normal battery depletion equals 50% should approximate the midpoint in the range of longevity estimates.

If devices tend to be used at conditions that consume more or less energy than nominal, then the time at which the survival curve equals 50% should tend toward the lower or higher end of the range of longevity estimates, respectively.



This figure shows the range of the estimated longevity values given in the reference chart in relation to the survival curve for the Model 7275 ICD. The range of longevity is representative of a typical range of use values, not the absolute minimum or maximum longevities possible. In this example, the survival curve including normal battery depletion is approaching 50% at approximately the mid-point of the range of longevity values.

## Interactions between Cardiac Pacing and Ventricular Arrhythmia Initiation

### Purpose of this Information

This article is intended to provide information for consideration when programming pacemaker operation in ICDs and pacemakers.

### Background

Right ventricular pacing has been associated with increased risk of appropriate therapy for ventricular tachycardia (VT) and ventricular fibrillation (VF) in ICD patients. Abrupt changes in ventricular cycle lengths (short-long-short, S-L-S) may precede initiation of VT/VF in some instances. S-L-S sequences may be permitted in all forms of cardiac pacing. The pause lengths depend upon pacing mode and lower rate programming.<sup>2-4</sup> Because pauses may be associated with VT/VF initiation, pause suppression algorithms have been developed in ICDs. Although pause suppression may have utility in specific patients with repolarization abnormalities and pause dependent VT, it has not been shown to reduce arrhythmia incidence in the general ICD population.5 Conversely, S-L-S sequences may occur with ventricular pacing in a variety of ways, including atrial tracking of premature atrial contractions (PACs) or by terminating pauses with ventricular paced beats. 6 In some patients, the ectopic depolarization pattern of a ventricular paced beat may be pro-arrhythmic, independent of pause timing. These observations have further enforced the desire to reduce unnecessary ventricular pacing.

### **Clinical Trial Observations**

Medtronic-sponsored clinical trials were retrospectively analyzed to further understand pause-mediated (i.e., S-L-S) scenarios prior to VT/VF. S-L-S onset scenarios were observed in a minority of patients in all pacing modes. Pacemaker interactions prior to VT/VF are dependent on patient conditions, as well as the technical aspects of pacing operation (i.e., pacing mode, lower rate and AV interval). Because a very low frequency of ventricular pacing is observed during Managed Ventricular Pacing (MVP)<sup>7-9</sup> or VVI 40 pacing modes, <sup>10</sup> the long interval tended to terminate with a ventricular sense. In DDD mode, the long interval tended to be terminated by a ventricular pace. Long intervals of > 1000 ms prior to VT/VF were rare in MVP mode. In these analyses, only an association between cardiac pacing and VT/VF initiation can be observed, causality cannot be established. The ongoing MVP (Managed Ventricular Pacing vs. VVI 40 Pacing) Trial, a 2-year, 1000-patient prospective, randomized trial in ICD patients may offer more insight into the frequency of VT/VF across pacing modes.11

### **Pacemaker Patients**

In pacemaker patients, ventricular pacing has been associated with higher incidence of AT/AF and heart failure hospitalization. 12,13 MVP provides atrial rate support while dramatically reducing ventricular pacing in patients with sinus node dysfunction and transient AV block.9 However, as stated in Medtronic reference manuals, depending upon the patient's intrinsic rhythm and conduction, MVP may allow ventricular cycle variation and occasional pauses of up to twice the lower rate.

DDD pacing with long AV intervals may reduce ventricular pacing and may decrease the potential length of pauses compared to MVP. However, DDD with long AV interval programming does not appear to be as effective as AAI-based pacing modes at reducing ventricular pacing,  $^{13,14}\,\mathrm{may}$  lead to endless loop tachycardia,  $^{14,15}\,$ and does not completely eliminate pauses. Also, in DDD mode, a higher programmed lower rate or activation of rate response can lead to an increase in AV conduction times and a higher percentage of ventricular pacing. The potential benefits of reducing ventricular pacing must be weighed against the potential for longer ventricular pauses. Therefore, careful consideration should be given to pacemaker mode and lower rate programming, particularly in the setting of frequent AV block and repolarization abnormalities due to congenital Long QT, electrolyte imbalances, and some medications which prolong QT.

#### Conclusion

Pacemaker operation may interact with VT/VF initiation in a variety of ways. The patient's heart failure status, arrhythmia substrate, medications, and the relative importance of maintaining ventricular synchrony vs. ensuring ventricular rate support must be weighed when choosing optimal hardware (ICD vs. pacemaker) and pacemaker programming (pacing mode, lower rate, etc.).

### References

- <sup>1</sup> Steinberg JS, Fischer A, Wang P, et al. The clinical implications of cumulative right  $ventricular\ pacing\ in\ the\ Multicenter\ Automatic\ Defibrillator\ Trial\ II.\ \textit{J Cardiovasc}$ Electrophysiol. April 2005;16(4):359-365.
- <sup>2</sup> Pinski SL, Eguia LE, Trohman RG. What is the minimal pacing rate that prevents Torsades de Pointes? Insights from patients with permanent pacemakers. PACE. November 2002; 25(11):1612-1615.
- <sup>3</sup> Goldman DS, Levine PA. Pacemaker-mediated polymorphic ventricular tachycardia. PACE. October 1998; 21(10):1993-1995.
- <sup>4</sup> Gray CJ, Basta M, Sapp JL, Parkash R, Gardner MJ. Inappropriate application of managed ventricular pacing in a patient with Brugada syndrome leading to polymorphic ventricular tachycardia, ventricular fibrillation and implantable cardioverter debrillator shocks. *Heart Rhythm*. 2006, Abstract P1-89.
- <sup>5</sup> Friedman PA, Jalal S, Kaufman S, et al. Effects of a rate smoothing algorithm for prevention of ventricular arrhythmias: results of the Ventricular Arrhythmia Suppression Trial (VAST). Heart Rhythm. May 2006;3(5):573-580.
- <sup>6</sup> Himmrich E, Przibille O, Zellerhoff C, et al. Proarrhythmic effect of pacemaker stimulation in patients with implanted cardioverter-defibrillators. Circulation July 15, 2003;108(2):192-197.
- $^7$  Sweeney MO, Ellenbogen KA, Casavant D, et al. Multicenter, prospective, randomized trial of a new atrial-based Managed Ventricular Pacing Mode (MVP) in dual chamber ICDs. Cardiovasc Electrophysiol. 2005:16:1-7.
- 8 Sweeney MO, Shea JB, Fox V, et al. Randomized pilot study of a new atrial-based minimal ventricular pacing mode in dual-chamber implantable cardioverter-defibrillators. Heart Rhythm, July 2004;1(2):160-167.
- Gillis AM, Purerfellner H, Israel CW, et al. Reducing unnecessary right ventricular pacing with the managed ventricular pacing mode in patients with sinus node disease and AV block. PACE. July 2006; 29(7):697-705.
- $^{\rm 10}$  The DAVID Trial Investigators. Dual-chamber pacing or ventricular backup pacing in patients with an implantable defibrillator: the Dual Chamber and VVI Implantable Defibrillator (DAVID) Trial. JAMA. December 25, 2002;288(24):3115-3123.
- 11 Sweeney MO, Ellenbogen KA, Whellan D, et al. The Managed Ventricular Pacing vs. VVI 40 Pacing (MVP) Trial: Clinical Background, Rationale, Design and Implementation. J Cardiovasc Electrophysiol. 2006 (In Press).
- 12 Sweeney MO, Hellkamp AS, Ellenbogen KA, et al. Adverse effect of ventricular pacing on heart failure and atrial fibrillation among patients with normal baseline QRS duration in a clinical trial of pacemaker therapy for sinus node dysfunction. Circulation. June 17, 2003;107(23):2932-2937.
- <sup>13</sup> Nielsen JC, Kristensen L, Andersen HR, et al. A randomized comparison of atrial and dual-chamber pacing in 177 consecutive patients with sick sinus syndrome: echocardiographic and clinical outcome. J Am Coll Cardiol. August 20, 2003;42(4):614-623.
- 14 Nielsen JC, Pedersen AK, Mortensen PT, Andersen HR. Programming a fixed long atrioventricular delay is not effective in preventing ventricular pacing in patients with sick sinus syndrome. *Europace*. April 1999; 1(2):113–120.
- 15 Dennis MJ, Sparks PB. Pacemaker mediated tachycardia as a complication of the autointrinsic conduction search function. PACE. June 2004;27(6 Pt 1):824-826.

## AT500 Pacing System Follow-Up Protocol

### Purpose of this Information

This article is intended to provide clinical guidance regarding follow-up practice and patient management when the AT500 battery voltage approaches the Elective Replacement Indicator (ERI) level of 2.6 volts.

### Background

Many AT500 pacing systems are now reaching their ERI voltage level (2.6 volts). This is expected since the battery used has an approximate longevity of 5-6 years under normal conditions (100% DDD pacing, 3 volts, 0.4 ms).

Technical Services has received reports of battery voltage levels below End-of-Life (EOL of 2.2 volts) where EGM prestorage is programmed ON, or higher outputs and/or pacing rates are necessary. It is important for physicians and allied professionals to understand battery depletion characteristics between ERI and EOL so that they, in turn, can understand how this affects management of follow-up visits for the AT500 as this device nears the end of its expected longevity.

### AT500 Battery and Longevity Information

In contrast to other IPGs, the AT500 does not change its mode, stimulation rate, or any other parameter when the battery voltage drops below the ERI level of 2.6 volts (with or without magnet applied). The Threshold Margin Test (TMT) is also not available.

Therefore, it is not possible to perform trans-telephonic assessment of AT500 battery status. This must be done during an in-clinic follow-up session. A warning will be displayed on the Quick Look screen at the beginning of a programmer (follow-up) session when the ERI battery level occurs. The measured battery voltage will also appear on the programmer display and on printouts.

Battery depletion curves at are shown in Figure 1, with special focus on device longevity when programming EGM pre-storage ON or OFF.

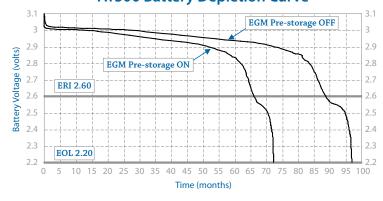
Medtronic's review of ongoing AT500 battery life test data matches our original longevity modeling and so meets our expectations. However, when using longer durations between follow-up periods (> 3 months), clinicians should consider the following in setting their remaining longevity expectations.

- Enabling the "EGM Pre-storage On" capability will increase current and reduce device longevity by approximately 9 days for each month pre-storage is ON.
- Longevity decreases with an increase in pacing rate, an increase in pacing amplitude or pulse width, a decrease in pacing impedance, a higher ratio of paced to sensed events, or extended use of the Atrial Preference Pacing, EGM prestorage, or Holter Telemetry features.

### Recommendations

Follow-up frequency should always be accelerated as devices reach ERI voltage levels to ensure device explant/ replacement occurs prior to End-of-Life voltage levels. With the wide variety of follow-up schedules being used, Medtronic recommends a 3-month follow-up frequency for the AT500 pacing systems. This is particularly important for patients in whom EGM pre-storage is programmed ON, or higher outputs and/or pacing rates are necessary.





### Figure 1

AT500 battery depletion curve for common parameter settings of DDDR, LR 70 ppm, UR 120 ppm, 100% pacing, Atrial - 2 V, 0.4 ms, 600 ohms, Ventricle - 2 V, 0.6 ms, 900 ohms, and EGM Pre-storage ON versus OFF.

### Insertion of the Lead into the Device

The implantable system consists of a pulse generator and at least 1 lead. The system operation depends on proper electrical and mechanical operation. With the advent of internationally recognized connector standards the challenge of ensuring proper mechanical fit between the lead and device connectors has been simplified, although the international connector standard does not address all aspects of the procedure for connecting a lead to the device.

If the lead connector is not fully installed, oversensing may result as described in the connector problems section of the technical article, "Clinical Management of High Voltage Lead System Oversensing."

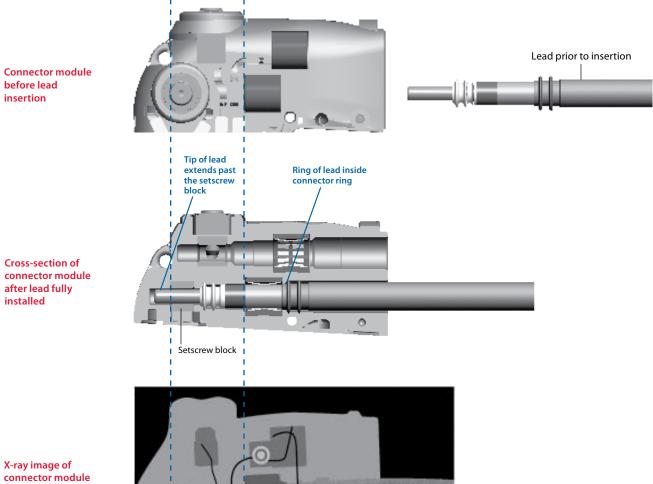
Performing the following steps can be used for each lead connection during the implant procedure.

1 Insert the torque wrench into the appropriate setscrew. For easier lead insertion, insert the lead closest to the device first.

- 2 Look down the connector port to verify that the port is not obstructed. If the port is obstructed, retract the setscrew to clear the bore. Take care not to disengage the setscrew from the connector block.
- 3 Push the lead into the connector port until the lead pin is clearly visible beyond the setscrew block.
- 4 Hold the lead in position while tightening the setscrew until the torque wrench clicks.
- 5 Tug gently on the lead to confirm a secure fit.

Current publications may provide additional information on implant procedures used by others, e.g., radiographic evaluation of the terminal pin beyond the terminal post.1

<sup>1</sup> Pickett RA III, Saavedra P, Ali MF, Darbar D, Rottman JN. Implantable cardioverter-defibrillator malfunction due to mechanical failure of the header connection. J Cardiovasc Electrophysiol. September 2004;15(9):1095-1099.



after lead fully installed

## GEM II DR/VR and GEM III DR/VR/AT ICD Battery Discharge Behavior

Medtronic manufactures and utilizes a unique Lithium/ Silver Vanadium Oxide battery in the GEM II/III family of ICDs. This battery has a distinctive voltage discharge with two regions of constant voltage at 3.2 volts and 2.6 volts.

The battery discharge curve (see curve below) is characterized by a significant decrease in the battery voltage approaching Middle-of-Life (MOL), followed by a plateau (MOL to ERI) where the battery voltage remains around 2.6 volts. The transition to the plateau could be easily misinterpreted as the battery rapidly approaches ERI, which occurs at 2.55 volts, when the battery may in fact have several years remaining until ERI.

It is important to understand that this battery voltage decrease in the GEM II/III family of ICDs is a normal

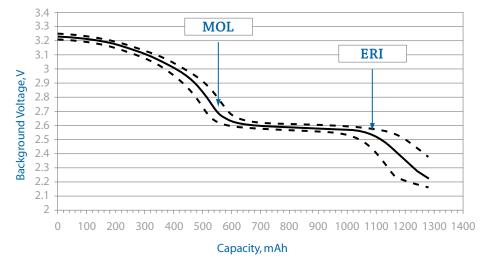
characteristic of the battery function in these devices and should not create a need for additional follow-up or monitoring.

As a general rule of thumb, the longevity from implant to MOL = MOL to ERI.

The design of the battery in subsequently released models has been modified to present a more linear battery discharge curve.

If you are concerned about early ERI in your patient's device, you can utilize the battery trend measurements stored in the save-to-disk file, which can be accessed and interpreted through the Medtronic Technical Services at 1 (800) 723-4636.

## **GEM II/III Battery Discharge Curve**



## **General Follow-Up and Replacement of ICD Leads**

Implanted leads operate in the challenging biochemical environment of the human body and the body's response to foreign objects. Implanted leads are also subject to mechanical stresses associated with heart motion, body motion, and patient anatomy.

In this environment, pacemaker and defibrillation leads cannot be expected to last forever. Unlike implantable cardioverter defibrillators (ICDs), a lead's longevity cannot be predicted nor are there simple indicators that a lead is approaching the end of its service life. The determination that a lead may be approaching end of service life requires follow-up of the chronically implanted lead and thorough evaluation of lead integrity at ICD replacement.

### Follow-Up of Chronically Implanted Leads

The frequency of follow-up for ICD patients will depend on a number of factors including the patient's medical condition, ICD system implant time, hospital/clinic follow-up practice, and Medicare guidelines. In all cases, it is important to assess the functionality of the ICD system and the integrity. For newly implanted leads, it is beneficial to establish a baseline of chronic performance parameters once the lead has stabilized, generally within 6 to 12 months after implant. These performance parameters should include pacing and sensing thresholds and impedance. During routine patient follow-up, these procedures can be used to evaluate lead integrity.

- Measure pacing and sensing threshold and compare to the chronic baseline. Significant increases or decreases may be indicative of lead failure, dislodgement, perforation, exit block, etc.
- Measure pacing impedance where possible and compare to the chronic baseline. Decreases of 30% or more or pacing impedances below 200-250 ohms may be indicative of insulation failure. Sudden and significant increases in pacing impedance may be indicative of conductor fracture.
- High voltage lead circuit impedance should be between 10-75 ohms at system implant. Chronic measurements below 10 and above 200 ohms may be indicative of high voltage lead circuit failure.
- Carefully review ECGs or the non-sustained detection log on Medtronic ICDs for indications of pacing and/or sensing abnormalities such as oversensing, undersensing, and loss of capture.
- Elicit and investigate any patient complaints/symptoms which may be suggestive of potential lead failure.

Where routine follow-up indicates, additional tools should be used to further evaluate performance. Tools include radiographic data, ICD electrograms, ICD Patient Alert and performance information from the System Longevity Study (SLS).

The final decision on the functional integrity and continued use of an implanted lead must be a matter of medical judgment based on these factors as well as specific patient conditions.

### General Criteria for Lead Replacement

The evaluation of a chronically implanted lead is an important part of the decision to continue to use the lead with a new ICD. However, these results alone do not necessarily predict the future integrity of that lead. With the expected longevity of today's ICDs varying between approximately 5 and 10 years, a physician replacing a device should consider a number of factors, including those listed below.

Factors which should be considered in a decision to replace or continue to use include:

- Pacing and sensing thresholds should be evaluated for the potential to maintain acceptable levels.
- Pacing impedance should be measured. Bear in mind that pacing impedance below 250 ohms results in excessive battery current drain, which may seriously compromise ICD longevity, regardless of lead integrity.
- The physical appearance of the lead should be examined for insulation cracks, breaches, or other indications of lead wear or degradation.
- Medtronic System Longevity Study data should be referenced. Actuarial survival of the lead and the observed lead failure mechanisms are specific factors to consider. Use of a new lead should be considered if failure mechanisms suggest an increased time dependency as suggested in the shape of performance curve for the specific lead model.
- Current publications may provide additional information on the clinical management of leads.<sup>1-3</sup> Ultimately, the decision to replace an implanted lead involves medical judgment.
- <sup>1</sup> Hauser RG, Cannom D, Hayes DL, et al. Long-term structural failure of coaxial polyurethane implantable cardioverter defibrillator leads. *PACE*. June 2002;25(6):879-882.
- <sup>2</sup> Ellenbogen KA, Wood MA, Shepard RK, et al. Detection and management of an implantable cardioverter defibrillator lead failure: incidence and clinical implications. *J Am Coll Cardiol*. January 1, 2003;41(1):73-80.
- <sup>3</sup> Hauser RG, Kallinen LM, Almquist AK, Gornick CC, Katsiyiannis WT. Early Failure of a Small Diameter High Voltage Implantable Cardioverter Defibrillator Lead, Heart Rhythm (2007), doi:10.1016/j.hrthm.2007.03.041

## Clinical Management of High Voltage Lead System Oversensing

Appropriate sensing by an ICD system refers to the sensing of cardiac events that may or may not require therapy delivery. ICD systems must sense relatively large QRS complexes while avoiding sensing of smaller T-waves, yet continue to sense often small variable amplitude ventricular fibrillation. Thus, ICD systems attempt to dynamically adjust sensing of electrical events, and discriminate between them based on detection algorithms and programmed settings.

Inappropriate sensing can occur when an ICD system classifies events of non-cardiac origin as QRS/VF events, or senses and counts T- and far field P-waves as ventricular depolarizations. This is often referred to as "oversensing," and may result in delivery of inappropriate high voltage therapies. This is due, in part, to the desire to err on the side of delivering lifesaving high voltage therapy rather than withholding it. Thus, an ICD system which is experiencing oversensing issues will continue to deliver therapeutic shocks as required, but may also subject the patient to unnecessary shocks.

Oversensing can be difficult to manage, in that the precipitating cause of the oversensing can be problematic to isolate. Oversensing can be caused by many factors, including myopotentials/far field sensing, electromagnetic interference, T-wave sensing, connector issues, incomplete or complete conductor fractures, and insulation breaches. While the individual physician must exercise medical judgment in determination of appropriate clinical management of ICD systems, the chart below may assist in the process of causal factor differentiation and possible intervention.

Phenomenon	<b>Causal Factors</b>	Characteristics	Management/Comments
Myopotentials/ Far Field Sensing	Diaphragmatic muscle potentials in breathing, wide tip-ring (coil on integrated bipolar leads) spacing.	Nonphysiological sensed event on EGM, which may confuse detection potentially resulting in false positive shocks.	Check R-waves for deterioration. Reprogram sensitivity. Try repositioning lead. Consider change-out to true bipolar lead, or if true bipolar lead in use, one with closer tip-ring spacing than current lead.
EMI (Electro-Magnetic Interference)	Arc welders, electrical generators, store walk-through security scanners, poorly insulated electrical equipment.	Multiple and consecutive short intervals (< 140 ms) independent of underlying sinus beats. Associated with proximity to the EMI source.	Avoid EMI areas. True bipolar leads less susceptible.
T-wave Sensing	Drugs, ischemic tissue, exercise, long QT syndrome, electrolyte imbalance.	Sense markers seen on EGM related to T-wave. False positive detection.	Check for R-wave deterioration and characteristics. If R-wave > 3.0 mV, reprogram sensitivity. If R-wave < 3.0 mV, reposition/replace lead. Address causal factor (e.g., drugs [if appropriate/medically viable]).
Connector Problems	Loose setscrew, cross-threaded setscrew, incomplete lead insertion into header.	This is an acute phenomenon seen within 6 months of implant (usually sooner).	Requires invasive check of connections.  May be reproducible with pocket manipulation.
Incomplete Conductor Fracture	One or more filars of a multifilar conductor fracturing while leaving enough filars intact to provide a conduction circuit.	Characterized by chaotic oversensing related to motion of the fracture site.	Check EGMs and x-rays. Manipulate lead at suspected fracture site if possible as a provocative test. If confirmed, replace lead.
Lead Insulation Breach	Cuts, tears, metal ion oxidization, abrasion, cold flow, environmental stress cracking.	Characterized by cyclical and/or erratic, intermittent, spontaneous oversensing; often post-pace or post-shock can cause false positives.	Replace lead. If acute, usually secondary to implant damage/replacement damage. If late, material characteristic.
Oversensing during interrogation with programming head (not wireless telemetry) with complete lead fracture	Interrogation with a programming head in combination with complete lead fracture that creates an open circuit can induce noise on the sensing circuitry inside the ICD can.	Nonphysiologic sensed event on EGM. If detection is enabled during interrogation, oversensing may result in inappropriate therapy.	Quickly remove the programming head. CANCEL the interrupted interrogation and manually load the software for the specific device model. Reposition the programmer head over the device and immediately select SUSPEND. Device will resume detection when programming head is removed, or when RESUME is selected. Replace lead.

Technical Services is available at all times to advise clinicians in the troubleshooting and management of Medtronic products. For assistance in the United States, please call 1 (800) 723-4636. In other countries, please contact your local Medtronic representative.

## **Tests and Observations for Clinical Assessment of Chronic Pacing Leads**

Test/Observation	Possible Insulation Failure	Possible Conductor Failure	Possible Other System Failure	Effect on Test/ Observation
Pacing Impedance (Telemetered or Measured Invasively)	Sudden and Significant Decrease	Sudden and Significant Increase	Dislodgement Perforation Electrolyte Imbalance Improper IPG/Lead Connection	. Increase or Decrease .Increase or Decrease
Pacing Thresholds (Telemetered/Programmed or Measured Invasively)	Sudden and Significant Increase Especially in Bipolar System	Sudden and Significant Increase	Dislodgement	. Increase . Increase . Increase
Electrograms (Telemetered or Measured Invasively)	Sudden and Significant Decrease in Amplitudes and/or Slew Rates for P- and/or R-Waves	Sudden and Significant Decrease or Disappearance of Amplitudes and/or Slew Rates for P- and/or R-Waves	Dislodgement	Decrease Decrease .Decrease
Waveform Analysis (Oscillographs of Pacer Artifact from ECG Electrodes)	Sudden Increase in Ratios of Leading-Edge Voltages to Trailing-Edge Voltages (i.e., over 25% increase)	Intermittent or No Pacer Artifacts (Even in Asynchronous Mode)	Improper IPG/Lead Connection	Intermittent or No Pacer Artifacts (Even in Asynchronous Mode)
Radiographs (Post-Implant, Recent, Current)	Not Discernible	Visual Observation of Conductor/Connector/ Electrode Fracture (Sometimes Discernible)	Dislodgement or Perforation. Improper IPG/Lead Connection.	Sometimes Discernible
Visual Inspection (Invasive)	Insulation Breach and/or Degradation, or Ligature Cut-Through	Not Easily Discernible	Connector Defect or Connector Pulled Apart. Improper IPG/ Lead Connection.	Sometimes Discernible
Pectoral Muscle Stimulation	Sudden Onset Especially in Bipolar System		Connector Defect in Bipolar or Unipolar. Hypersensitivity to Unipolar Pulse Generator Can. Anti-Stim Coating or Protection Deficient.	
Phrenic Nerve/ Diaphragmatic Stimulation	Sudden Onset in Bipolar or Unipolar Systems		Perforation or Displacement of Atrial Lead (Phrenic Nerve)	
Pacemaker ECG Stimulus Artifact Size and Morphology Change (May Not Be Possible with Digital ECG)	Sudden Onset and Significant Change, Especially in Bipolar System (Increase in Size)	Sudden Changes, Usually a Decrease in Size	Perforation or Dislodgement. Connector Defect. Improper IPG/ Lead Connection.	Sometimes Discernible
Oversensing (Intermittent or Continuous)	Sudden Onset, Especially in Bipolar Systems		Physical Contact between the Electrode(s) on the Lead and that of Another Lead. Inappropriate IPG Parameter Setting. Improper IPG/Lead Connection.	Sometimes Discernible
Undersensing (Intermittent or Continuous)	Sudden Onset in Either Unipolar or Bipolar Systems	Sudden Onset in Either Unipolar or Bipolar Systems	Dislodgement or Perforation. Infarct at Electrode Site. Electrolyte Imbalance. Inappropriate IPG Parameter Setting. Improper IPG/Lead Connection.	Sometimes Discernible
Loss of Capture	See "Pacing Thresholds" Above	See "Pacing Thresholds" Above	See "Pacing Thresholds" Above	

## Index

### By Model Number

by model italiaei
2187 77, 79
2188 77, 79
3830 91, 123, 127, 129
4003 92, 123, 127, 129
4003M 92, 123, 127, 129
4004 93, 123, 127, 129, 150
4004M 93, 123, 127, 129, 150
4011 93, 123, 127, 129
4012 94, 123, 127, 129, 151 4023 94, 123, 127, 129
4024 95, 123, 127, 129
4033 95, 123, 127, 129 4057 96, 123, 127, 129
4057 96, 123, 127, 129
4057M 96, 123, 127, 129
4058 97, 123, 127, 129
4058M 97, 123, 127, 129 4067 98, 123, 127, 129
4068 99, 123, 127, 129
4073 100, 124, 127, 129
4074 101, 124, 127, 129 4076 102, 124, 127, 129
4076 102, 124, 127, 129
4081 103, 124, 127, 129 4082 150
4092 103, 124, 127, 129
4193 78, 79
4194 78, 79
4503 104, 124, 127, 129
4503M 104, 124, 127, 129
4504 104, 124, 127, 129, 149
4504M 104, 124, 127, 129, 149 4512 105, 124, 127, 129
4523 105, 124, 127, 129
4524 106, 124, 127, 129
4533 106, 124, 127, 129 4557 107, 124, 127, 129
4557 107, 124, 127, 129
4557M 107, 124, 127, 129 4558M 107, 124, 127, 129
4568 108, 125, 127, 129
4574 108, 125, 127, 129
4582 149
4592 109, 125, 127, 129
4951 131, 134, 135
4951M 131, 134, 135 4965 131, 134, 135
4968 132, 134, 135
5023 109, 125, 127, 129
5023M 109, 125, 127, 129
5024 110, 125, 127, 130
5024M 110, 125, 127, 130
5026 110, 125, 127, 130 5032 136, 137
5032 136, 137 5033 111, 125, 127, 130
5034 111, 125, 127, 130
5038 136, 137
5054 112, 125, 127, 130
5068 113, 125, 127, 130
5069 135 5071 132, 134, 135
5072 114, 125, 127, 130
5076 115, 125, 127, 130
5092 116, 125, 127, 130
5524 116, 125, 127, 130
5524M 116, 125, 127, 130
5534 117, 126, 127, 130 5554 117, 126, 127, 130
5554 117, 126, 127, 130 5568 118, 126, 127, 130
5592 118, 126, 128, 130
5594 119, 126, 128, 130
6721 80, 88, 89, 90
6917 133, 134, 135
6917A 133, 134, 135 6921 80, 88, 89, 90
0021 00,00,00,00

```
6930 80, 88, 89, 90, 144
6931 81, 88, 89, 90, 144
6932 81, 88, 89, 90, 148
6933 82, 88, 89, 90
6934S 90, 148
6936 82, 88, 89, 90, 148
6937 82, 88, 89, 90
6937A 82, 88, 89, 90
6939 83, 88, 89, 90
6940 119, 126, 128, 130
6942 83, 88, 89, 90, 148
6943 84, 88, 89, 90, 148
6944 84, 88, 89, 90
6945 85, 88, 89, 90, 148
6947 85, 88, 89, 90
6948 86, 88, 89, 90, 144
6949 86, 88, 89, 90, 144
6957 120, 126, 128, 130
6957J 121, 126, 128, 130
6961 121, 126, 128, 130
6962 122, 126, 128, 130
6963 82, 88, 89, 90
6966 82, 88, 89, 90, 148
6996 87, 88, 89, 90
6999 83, 88, 89, 90
7088 52, 67, 72
7089 52, 67, 72
7107 51, 67, 72
7108 51, 67, 72
7223 33
7227 21, 30, 33, 139, 148
7229 21, 30, 33, 139, 148, 158
7230 22, 30, 33, 139, 146
7231 22, 30, 33, 139, 158
7232 23, 30, 33, 146
7253 38, 63, 71, 156
7271 23, 30, 33, 139
7272 13, 18, 20, 33, 139
7274 24, 30, 33, 140, 146
7275 24, 31, 33, 140, 154, 158
7276 25, 31, 33, 140, 158
7277 13, 18, 20, 33, 140, 146
7278 25, 31, 33, 140, 146
7279 140, 146
7285 141, 146
7287 33
7288 26, 31, 33, 141
7289 14, 18, 20, 141, 146
7290 26, 31, 33, 141
7295 20
7297 14, 18, 20, 141
7299 15, 18, 20, 141
7303 15, 18, 20, 142
7304 16, 18, 20, 142
7860 54, 67, 73
7861 54, 67, 73
7862 54, 67, 73
7864 53, 67, 73
7865 53, 67, 73
7866 53, 67, 73
7960i 60, 69, 73
7961i 60, 69, 73
7962i 60, 69, 73
7964i 59, 69, 73
7965i 59, 69, 73
7966i 59, 69, 73
7968i 60, 69, 73
8040 16, 19, 20
8042 17, 19, 20
```

```
8089 52, 67, 72
8158 55, 68, 73
8160 55, 68, 73
8161 55, 68, 73
8162 55, 68, 73
8164 54, 68, 73
8165 54, 68, 73
8166 54, 68, 73
8330 51, 67, 72, 152
8331 51, 67, 72, 152
8331M 51, 67, 72, 152
8340 51, 67, 72, 152
8341 51, 67, 72, 152
8341M 51, 67, 72, 152
8342 51, 67, 72, 152
8416 50, 66, 72
8417 50, 66, 72
8417M 50, 66, 72
8418 50, 66, 72
8419 50, 66, 72
8424 50, 66, 72
8426 50, 66, 72
8427 50, 66, 72
8960i 61, 70, 73
8961i 61, 70, 73
8962i 61, 70, 73
8964i 61, 69, 73
8965i 61, 69, 73
8966i 61, 69, 73
8968i 62, 70, 73
ADD01 36, 63, 71
ADDR01 36, 63, 71
ADDR03 36, 63, 71
ADDR06 36, 63, 71
ADDRL1 36, 63, 71
ADDRS1 37, 63, 71
ADSR01 37, 63, 71
ADSR03 37, 63, 71
ADSR06 37, 63, 71
ADVDD01 71
AT501 38, 63, 71, 156
C154DWK 17, 19, 20, 142
C164AWK 17, 19, 20
C174AWK 17, 19, 20
D153ATG 27, 31, 34, 142
D153DRG 27, 31, 34, 142
D153VRC 34
D154ATG 27, 31, 34, 142
D154AWG 28, 32, 34, 143
D154DRG 27, 31, 34, 142
D154VRC 28, 32, 34, 142
D154VWC 29, 32, 34, 143
D164AWG 28, 32, 34
D164VWC 29, 32, 34
E1DR01 38, 63, 71
E1DR03 38, 63, 71
E1DR06 38, 63, 71
E1DR21 39, 63, 71
E2DR01 39, 64, 71
E2DR03 39, 64, 71
E2DR06 39, 64, 71
E2DR21 40, 64, 71
E2DR31 40, 64, 71
E2DR33 40, 64, 71
E2SR01 41,64,71
E2SR03 41,64,71
E2SR06 41, 64, 71
E2VDD01 41, 64, 71
KD701 44, 65, 72, 147
KD703 44, 65, 72, 147
```

KD706 44, 65, 72, 147

KDR401 42, 64, 71

KDR403 42, 64, 71 KDR601 43, 65, 71, 147 KDR603 43, 65, 71, 147 KDR606 43, 65, 71, 147 KDR651 44, 65, 71, 147 KDR653 44, 65, 71, 147 KDR701 45, 65, 72, 147 KDR703 45, 65, 72, 147 KDR706 45, 65, 72, 147 KDR721 46, 65, 72, 147 KDR801 47, 66, 72 KDR803 47, 66, 72 KDR901 48, 66, 72 KDR903 48, 66, 72 KDR906 48, 66, 72 KDR921 48, 66, 72 KSR401 43, 64, 71 KSR403 43, 64, 71 KSR701 46, 65, 72 KSR703 46, 65, 72 KSR706 46, 65, 72 KSR901 49, 66, 72 KSR903 49, 66, 72 KSR906 49, 66, 72 KVDD701 47, 65, 72, 147 KVDD901 49, 66, 72 P1501DR 42, 64, 71 SDR203 57, 68, 73, 145 SDR303 58, 69, 73, 145 SDR306 58, 69, 73, 145 SED01 55, 68, 73 SEDR01 55, 68, 73 SEDRL1 73 SES01 56, 68, 73 SESR01 56, 68, 73 SS103 56, 68, 73, 145 SS106 56, 68, 73, 145 SSR203 57, 68, 73, 145 SSR303 58, 69, 73, 145 SSR306 58, 69, 73, 145 SVDD303 59, 69, 73, 145 VEDR01 62, 70, 73

8085 53, 67, 72

8086 53, 67, 72

8088 52, 67, 72



## **By Family**

A	CapSure SP Novus	G	Kappa 700 D
Adapta DR	4092 103, 124, 127, 129	GEM	KD701 44, 65, 72, 147
ADD01 36, 63, 71	4592 109, 125, 127, 129	7227 21, 30, 33, 139, 148	KD703 44, 65, 72, 147
ADDR01 36, 63, 71	5092 116, 125, 127, 130	GEM DR	KD706 44, 65, 72, 147
ADDR03 36, 63, 71	5592 118, 126, 128, 130	7271 23, 30, 33, 139	Kappa 700 DR
ADDR06 36, 63, 71	5594 119, 126, 128, 130	GEM II VR	KDR701 45, 65, 72, 147
	CapSure VDD		KDR703 45, 65, 72, 147
ADDRL1 36, 63, 71	5032 136, 137	7229 21, 30, 33, 139, 148,	KDR706 45, 65, 72, 147
ADDRS1 37, 63, 71	CapSure VDD-2	158	KDR721 46, 65, 72, 147
Adapta SR	5038 136, 137	GEM III AT	Kappa 700 SR
ADSR01 37, 63, 71	CapSure Z	7276 25, 31, 33, 140, 158	KSR701 46, 65, 72
ADSR03 37, 63, 71	4033 95, 123, 127, 129	GEM III DR	KSR703 46, 65, 72
ADSR06 37, 63, 71	4533 106, 124, 127, 129	7275 24, 31, 33, 140, 154,	KSR706 46, 65, 72
Adapta VDD	5033 111, 125, 127, 130	158	Kappa 700 VDD
ADVDD01 71	5034 111, 125, 127, 130	GEM III VR	KVDD701 47, 65, 72, 147
AT500	5534 117, 126, 127, 130	7231 22, 30, 33, 139, 158	Kappa 800 DR
7253 38, 63, 71, 156	CapSure Z Novus		KDR801 47, 66, 72
AT501 38, 63, 71, 156	5054 112, 125, 127, 130	1	KDR803 47, 66, 72
Attain	5554 117, 126, 127, 130	1	Kappa 900 DR
2187 77, 79	Concerto	InSync	KDR901 48, 66, 72
2188 77, 79	C154DWK 17, 19, 20, 142	8040 16, 19, 20	
4193 78, 79		InSync ICD	KDR903 48, 66, 72
4194 78, 79	C164AWK 17, 19, 20	7272 13, 18, 20, 33, 139	KDR906 48, 66, 72
	C174AWK 17, 19, 20	InSync Marquis	Kappa 900 SR
6		7277 13, 18, 20, 33, 140,	KSR901 49, 66, 72
C	E	146	KSR903 49, 66, 72
CapSure		InSync Maximo	KSR906 49, 66, 72
4003 92, 123, 127, 129	EnPulse DR	7303 15, 18, 20, 142	Kappa 900 VDD
4003M 92, 123, 127, 129	E1DR01 38, 63, 71	7304 16, 18, 20, 142	KVDD901 49, 66, 72
4004 93, 123, 127, 129, 150	E1DR03 38, 63, 71	InSync Sentry	Kappa 920 DR
4004M 93, 123, 127, 129,	E1DR06 38, 63, 71	7297 14, 18, 20, 141	KDR921 48, 66, 72
150	E1DR21 39, 63, 71	7299 15, 18, 20, 141	
4503 104, 124, 127, 129	EnPulse 2 DR	InSync II Marquis	L
4503M 104, 124, 127, 129	E2DR01 39, 64, 71	7289 14, 18, 20, 141, 146	_
4504 104, 124, 127, 129,	E2DR03 39, 64, 71	InSync II Protect	Legend
149	E2DR06 39, 64, 71	7295 20	8416 50, 66, 72
4504M 104, 124, 127, 129,	E2DR21 40, 64, 71	InSync III Protect	8417 50, 66, 72
149	E2DR31 40, 64, 71	7285 141, 146	8417M 50, 66, 72
5026 110, 125, 127, 130	E2DR33 40, 64, 71	InSync III	8418 50, 66, 72
CapSureFix	EnPulse 2 SR	8042 17, 19, 20	8419 50, 66, 72
4067 98, 123, 127, 129	E2SR01 41,64,71	InSync III Marquis	Legend II
4068 99, 123, 127, 129	E2SR03 41,64,71	7279 140, 146	8424 50, 66, 72
4568 108, 125, 127, 129	E2SR06 41,64,71	Intrinsic	8426 50, 66, 72
	EnPulse 2 VDD		8427 50, 66, 72
5068 113, 125, 127, 130	E2VDD01 41, 64, 71	7288 26, 31, 33, 141	
5568 118, 126, 127, 130	EnRhythm DR	Intrinsic 30	N 4
6940 119, 126, 128, 130	P1501DR 42, 64, 71	7287 33	M
CapSureFix Novus	EnTrust		Marquis DR
4076 102, 124, 127, 129	D153ATG 27, 31, 34, 142	K	7274 24, 30, 33, 140, 146
5076 115, 125, 127, 130	D153DRG 27, 31, 34, 142	Kappa 400 DR	Marquis VR
CapSure Epi	D153VRC 34	11	7230 22, 30, 33, 139, 146
4965 131, 134, 135	D154ATG 27, 31, 34, 142	KDR401 42, 64, 71	Maximo DR
4968 132, 134, 135	D154DRG 27, 31, 34, 142	KDR403 42, 64, 71	7278 25, 31, 33, 140, 146
CapSure Sense	D154VRC 28, 32, 34, 142	Kappa 400 SR	Maximo VR
4073 100, 124, 127, 129	Epicardial Patch	KSR401 43, 64, 71	7232 23, 30, 33, 146
4074 101, 124, 127, 129	6721 80, 88, 89, 90	KSR403 43, 64, 71	Minix/Minix ST
4574 108, 125, 127, 129	6921 80, 88, 89, 90	Kappa 600 DR	8330 51, 67, 72, 152
CapSure SP	0321 00, 00, 03, 30	KDR601 43, 65, 71, 147	8331 51, 67, 72, 152
4023 94, 123, 127, 129		KDR603 43, 65, 71, 147	8331M 51, 67, 72, 152
4024 95, 123, 127, 129		KDR606 43, 65, 71, 147	8340 51, 67, 72, 152
4523 105, 124, 127, 129		KDR651 44, 65, 71, 147	8341 51, 67, 72, 152
4524 106, 124, 127, 129		KDR653 44, 65, 71, 147	8341M 51, 67, 72, 152
5023 109, 125, 127, 129			8342 51, 67, 72, 152
5023M 109, 125, 127, 129			Minuet
5024 110, 125, 127, 130			7107 51, 67, 72
5024M 110, 125, 127, 130			
5524 116, 125, 127, 130			7108 51, 67, 72

5524M 116, 125, 127, 130



## By Family continued

0	Sigma 300 DR	Thera-i S
Onyx	SDR303 58, 69, 73, 145	8964i 61, 69, 73
7290 26, 31, 33, 141	SDR306 58, 69, 73, 145	8965i 61, 69, 73
, ,	Sigma 300 SR	8966i 61, 69, 73
<b>D</b>	SSR303 58, 69, 73, 145	Thera-i SR
P	SSR306 58, 69, 73, 145	8960i 61, 70, 73
Preva DR	Sigma 300 VDD	8961i 61, 70, 73
7088 52, 67, 72	SVDD303 59, 69, 73, 145	8962i 61, 70, 73
7089 52, 67, 72	Spectraflex 4951 131, 134, 135	Thera-i VDD 8968i  62, 70, 73
Preva SR	4951M 131, 134, 135	Transvene
8088 52, 67, 72	6957 120, 126, 128, 130	6934S 90, 148
8089 52, 67, 72 Prevail S	6957J 121, 126, 128, 130	6936 82, 88, 89, 90, 148
8085 53, 67, 72	Sprint	6966 82, 88, 89, 90, 148
8086 53, 67, 72	6932 81, 88, 89, 90, 148	,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,
Prodigy D	6942 83, 88, 89, 90, 148	M
7864 53, 67, 73	6943 84, 88, 89, 90, 148	V
7865 53, 67, 73	6945 85, 88, 89, 90, 148	Versa DR
7866 53, 67, 73	Sprint Fidelis	VEDR01 62, 70, 73
Prodigy DR	6930 80, 88, 89, 90, 144	Virtuoso
7860 54, 67, 73	6931 81, 88, 89, 90, 144	D154AWG 28, 32, 34, 143
7861 54, 67, 73	6948 86, 88, 89, 90, 144	D164AWG 28, 32, 34
7862 54, 67, 73	6949 86, 88, 89, 90, 144	D154VWC 29, 32, 34, 143
Prodigy S	Sprint Quattro	D164VWC 29, 32, 34
8164 54, 68, 73	6944 84, 88, 89, 90	
8165 54, 68, 73	Sprint Quattro Secure	
8166 54, 68, 73	6947 85, 88, 89, 90	
Prodigy SR	Sub-Q Lead 6996 87, 88, 89, 90	
8158 55, 68, 73	Sub-Q Patch	
8160 55, 68, 73	6939 83, 88, 89, 90	
8161 55, 68, 73	6999 83, 88, 89, 90	
8162 55, 68, 73	SureFix	
_	5072 114, 125, 127, 130	
S	SVC/CS	
Screw-In	6933 82, 88, 89, 90	
4057 96, 123, 127, 129	6937 82, 88, 89, 90	
4057M 96, 123, 127, 129	6937A 82, 88, 89, 90	
4058 97, 123, 127, 129	6963 82, 88, 89, 90	
4058M 97, 123, 127, 129		
4557 107, 124, 127, 129	Т	
4557M 107, 124, 127, 129	Target Tip	
4558M 107, 124, 127, 129	4011 93, 123, 127, 129	
SelectSecure 3830 91, 123, 127, 129	4012 94, 123, 127, 129, 151	
Sensia DR	4081 103, 124, 127, 129	
SED01 55, 68, 73	4082 150	
SEDR01 55, 68, 73	4512 105, 124, 127, 129	
SEDRL1 73	4582 149	
Sensia SR	Tenax	
SES01 56, 68, 73	6917 133, 134, 135	
SESR01 56, 68, 73	6917A 133, 134, 135	
Sigma 100 S	6961 121, 126, 128, 130	
SS103 56, 68, 73, 145	6962 122, 126, 128, 130 Thera-i D	
SS106 56, 68, 73, 145	7964i 59, 69, 73	
Sigma 200 DR	7965i 59, 69, 73	
SDR203 57, 68, 73, 145	7966i 59, 69, 73	
Sigma 200 SR	Thera-i DR	
SSR203 57, 68, 73, 145		

7960i 60, 69, 73 7961i 60, 69, 73 7962i 60, 69, 73 7968i 60, 69, 73 If you are looking for a model number or family that is not included in this report, you may call US Technical Services (see page 2).

# **Mailer Kits Available for Returning Product**

Medtronic urges all physicians to return explanted product and to notify Medtronic when a product is no longer in use, regardless of reason for explant or removal from use. The procedures for returning product vary by geographic location.

Mailer kits (pictured right) with prepaid US postage are available for use within the United States to send CRT, ICD, IPG, and leads to Medtronic's CRDM Returned Product Analysis Lab. These mailers are sized to accommodate the devices and leads from a single patient or clinical event and are designed to meet postal regulations for mailing biohazard materials.

If the product being returned is located outside the United States, please contact your local Medtronic representative for instructions.

Medtronic also requests the return of devices from non-clinical sources such as funeral homes, and will assume responsibility for storage and disposal of the product once received. For return of larger quantities of explanted products than the mailer can accommodate, Medtronic has handling and shipping guidelines available upon request.

Both mailers and guidelines can be requested by contacting the Returned Product Lab.

CRDM Returned Product Analysis Laboratory Medtronic, Inc. 7000 Central Avenue NE MS RCE172 Minneapolis, MN 55432-3576 USA

Phone: 1 (800) 328-2518, ext. 44800 email: crdm.returnedproduct@medtronic.com



### www.medtronic.com

#### **World Headquarters**

Medtronic, Inc. 710 Medtronic Parkway Minneapolis, MN 55432-5604 USA

Tel: (763) 514-4000 Fax: (763) 514-4879

Medtronic USA, Inc.
Toll-free: 1 (800) 328-2518
(24-hour technical support for physicians and medical professionals)

#### Europe

Meditronic International Trading Sàrl Route du Molliau 31 CH-1131 Tolochenaz Switzerland

Tel: (41 21) 802 7000 Fax: (41 21) 802 7900

#### Canada

Medtronic of Canada Ltd. 6733 Kitimat Road Mississauga, Ontario L5N 1W3 Canada

Tel: (905) 826-6020 Fax: (905) 826-6620 Toll-free: 1 (800) 268-5346

#### Asia Pacific

Medtronic International, Ltd.
16/F Manulife Plaza
The Lee Gardens, 33 Hysan Avenue
Causeway Bay
Hong Kong

Tel: (852) 2891 4456 Fax: (852) 2891 6830 enquiryap@medtronic.com

### **Latin America**

Medtronic USA, Inc. Doral Corporate Center II 3750 NW 87th Avenue Suite 700 Miami, FL 33178

Tel: (305) 500-9328 Fax: (786) 709-4244

